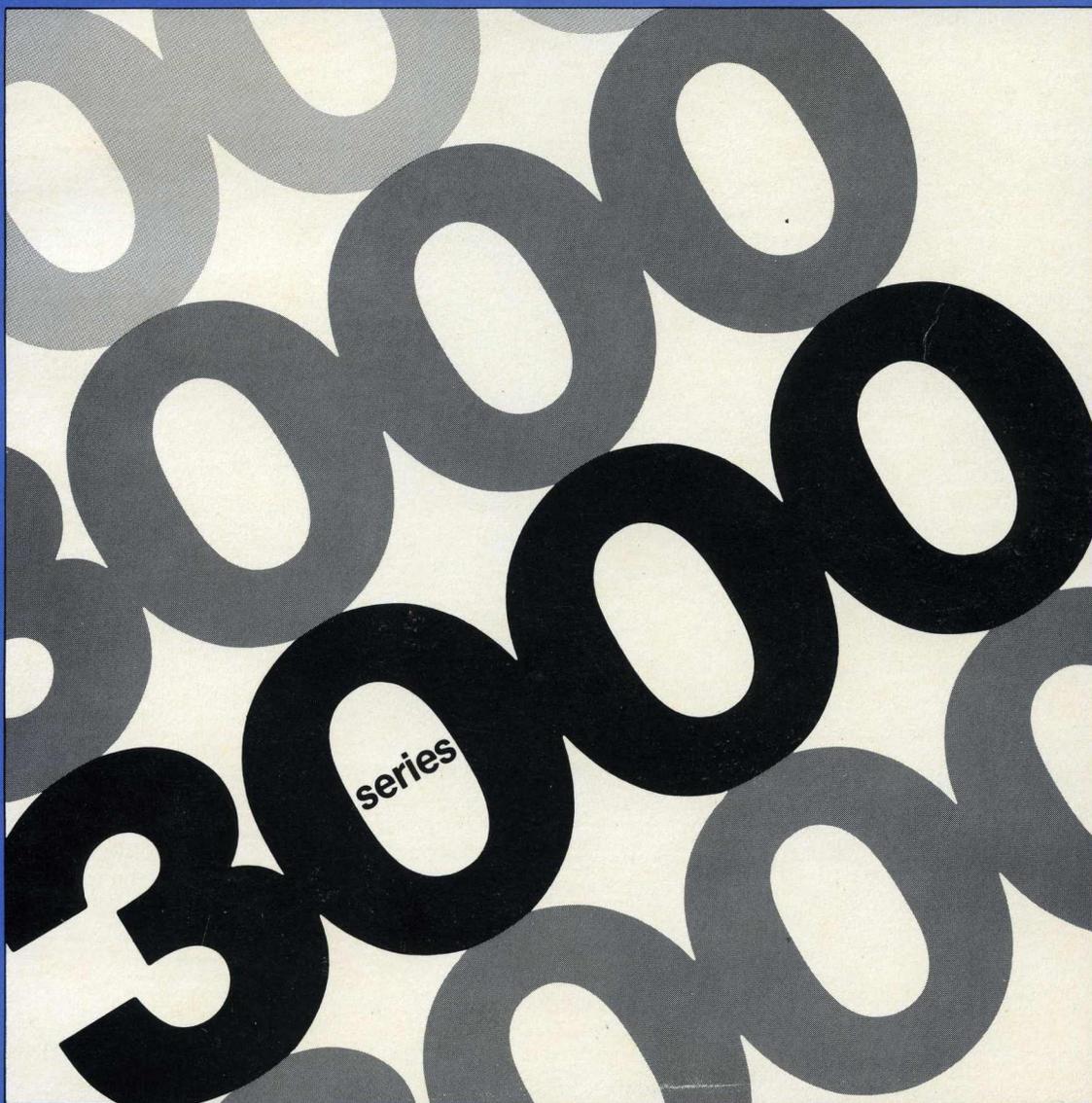


intel  
Series 3000  
Reference Manual

\$5.00





## Series 3000 Family Of Computing Elements — The Total System Solution.

Since its introduction in September, 1974, the Series 3000 family of computing elements has found acceptance in a wide range of high performance applications from disk controllers to airborne CPU's.

The Series 3000 family represents more than a simple collection of bipolar components, it is a complete family of computing elements and hardware/software support that greatly simplifies the task of transforming a design from concept to production.

### The Series 3000 Component Family

A complete set of computing elements that are designed as a system requiring a minimum amount of ancillary circuitry.

3001	Microprogram Control Unit.
3002	Central Processing Element.
3003	Look-Ahead Carry Generator.
3212	Multi-Mode Latch Buffer.
3214	Interrupt Control Unit.
3216/26	Parallel Bi-directional Bus Driver.
ROMs/PROMs	A complete set of bipolar ROMs and PROMs.
RAMs	A Complete family of MOS and bipolar RAMs.

### The Series 3000 Support

A comprehensive support system that assists the designer in writing microprograms, debugging hardware and microcode, and programming prototype and production PROMs.

CROMIS	Cross microprogram assembler.
MDS-800	Microcomputer development system with TTY/CRT, line printer, diskette, PROM programmer and high speed paper tape reader facilities.
ICE-30	In-circuit emulation for the 3001 MCU.
ROM-SIM	ROM simulation for all of Intel's Bipolar ROMs and PROMs.
Application Notes	Central processor and disk controller designs and system timing considerations.
Customer Course	Comprehensive 3 day course covering the component family, CPU and controller designs, microprogramming and the MDS-800, ICE-30 and ROM-SIM operation.

The Series 3000 family is designed to provide a Total System Solution: high performance, minimum package count and total commitment to support.

**Series 3000  
Reference  
Manual**

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# INTRODUCTION

## A family architecture

To reduce component count as far as practical, a multi-chip LSI microcomputer set must be designed as a complete, compatible family of devices. The omission of a bus or a latch or the lack of drive current can multiply the number of miscellaneous SSI and MSI packages to a dismaying extent—witness the reputedly LSI mini-computers now being offered which need over a hundred extra TTL packages on their processor boards to support one or two custom LSI devices. Successful integration should result in a minimum of extra packages, and that includes the interrupt and the input/output systems.

With this objective in mind, the Intel Schottky bipolar LSI microcomputer chip set was developed. Its two major components, the 3001 Microprogram Control Unit (MCU) and the 3002 Central Processing Element (CPE), may be combined by the digital designer with standard bipolar LSI memory to construct high-performance controller-processors (Fig. 1) with a minimum of ancillary logic.

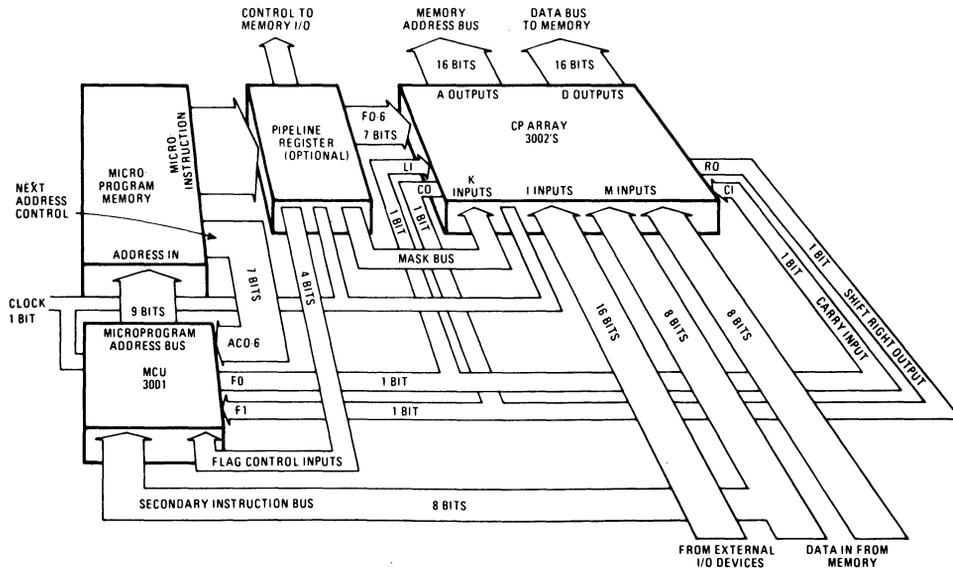
Among the features that minimize package count and improve performance are: the multiple independent data and address busses that eliminate time multiplexing and the need for external latches; the three-state output buffers with high fanout that make bus drivers unnecessary except in the largest systems, and the separate output-enable logic that permits bidirectional

busses to be formed simply by connecting inputs and outputs together.

Each CPE represents a complete two-bit slice through the data-processing section of a computer. Several CPEs may be arrayed in parallel to form a processor of any desired word length. The MCU, which together with the microprogram memory, controls the step-by-step operation of the processor, is itself a powerful microprogrammed state sequencer.

Enhancing the performance and capabilities of these two components are a number of compatible computing elements. These include a fast look-ahead carry generator, a priority interrupt unit, and a multimode latch buffer. A complete summary of the first available members of this family of LSI computing elements and memories is given in the table on this page.

<b>3001</b>	Microprogram control unit
<b>3002</b>	Central processing element
<b>3003</b>	Look-ahead carry generator
<b>3212</b>	Multimode latch buffer
<b>3214</b>	Priority interrupt unit
<b>3216</b>	Noninverting bidirectional bus driver
<b>3226</b>	Inverting bidirectional bus driver
<b>3601</b>	256-by-4-bit programmable read-only memory
<b>3604</b>	512-by-8-bit programmable read-only memory
<b>3301A</b>	256-by-4-bit read-only memory
<b>3304A</b>	512-by-8-bit read-only memory



**1. Bipolar microcomputer.** Block diagram shows how to implement a typical 16-bit controller-processor with new family of bipolar computer elements. An array of eight central processing elements (CPEs) is governed by a microprogram control unit (MCU) through a separate read-only memory that carries the microinstructions for the various processing elements. This ROM may be a fast, off-the-shelf unit.

## CPEs form a processor

Each CPE (Fig. 2) carries two bits of five independent busses. The three input busses can be used in several different ways. Typically, the K-bus is used for micro-program mask or literal (constant) value input, while the other two input busses, M and I, carry data from external memory or input/output devices. D-bus outputs are connected to the CPE accumulator; A-bus outputs are connected to the CPE memory address register. As the CPEs are wired together, all the data paths, registers, and busses expand accordingly.

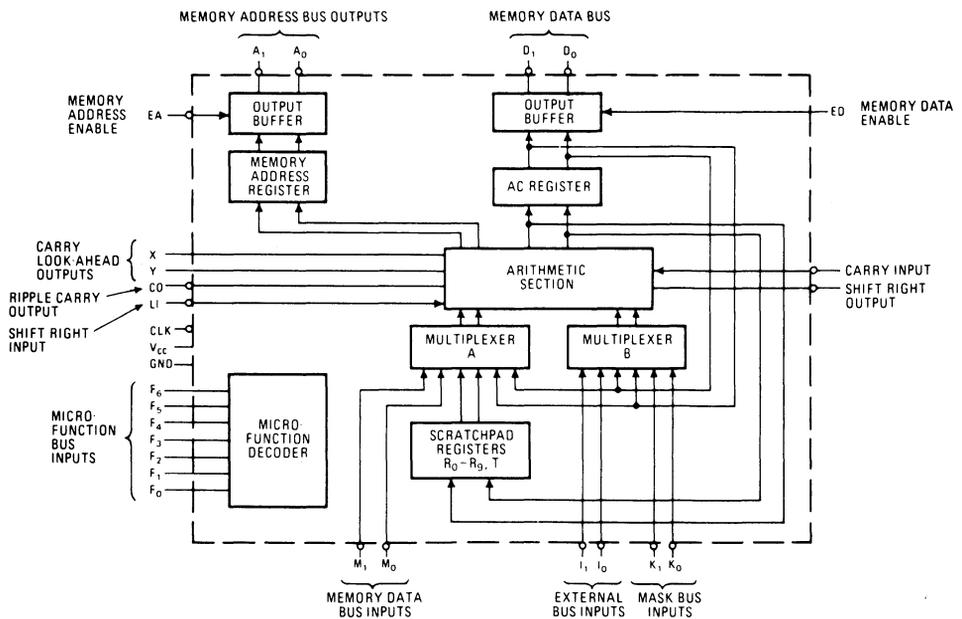
Certain data operations can be performed simply by connecting the busses in a particular fashion. For example, a byte exchange operation, often used in data-communications processors, may be carried out by wiring the D-bus outputs back to the I-bus inputs, exchanging the high-order outputs and low-order inputs. Several other discretionary shifts and rotates can be accomplished in this manner.

A sixth CPE bus, the seven-line microfunction bus, controls the internal operation of the CPE by selecting the operands and the operation to be performed. The arithmetic function section, under control of the microfunction bus decoder, performs over 40 Boolean and binary functions, including 2's complement arithmetic and logical AND, OR, NOT, and exclusive-NOR. It increments, decrements, shifts left or right, and tests for zero.

Unlike earlier MSI arithmetic-logic units, which contain many functions that are rarely used, the microfunction decoder selects only useful CPE operations. Standard carry look-ahead outputs, X and Y, are generated by the CPE for use with available look-ahead devices or the Intel 3003 Look-ahead Carry Generator. Independent carry input, carry output, shift input, and shift output lines are also available.

What's more, since the K-bus inputs are always ANDed with the B-multiplexer outputs into the arithmetic function section, a number of useful functions that in conventional MSI ALUs would require several cycles are generated in a single CPE microcycle. The type of bit masking frequently done in computer control systems can be performed with the mask supplied to the K-bus directly from the microinstruction.

Placing the K-bus in either the all-one or all-zero state will, in most cases, select or deselect the accumulator in the operation, respectively. This toggling effect of the K-bus on the accumulator nearly doubles the CPE's repertoire of microfunctions. For instance, with the K-bus in the all-zero state, the data on the M-bus may be complemented and loaded into the CPE's accumulator. The same function selected with the K-bus in the all-one state will exclusive-NOR the data on the M-bus with the accumulator contents.



**2. Central processing element.** This element contains all the circuits representing a two-bit-wide slice through a small computer's central processor. To build a processor of word width N, all that's necessary is to connect an array of N/2 CPEs together.

### Three Innovations

The power and versatility of the CPE are increased by three rather novel techniques. The first of these is the use of the carry lines and logic during non-arithmetic operations for bit testing and zero detection. The carry circuits during these operations perform a word-wide logical OR (ORing adjacent bits) of a selected result from the arithmetic section. The value of the OR, called the carry OR, is passed along the carry lines to be ORed with the result of an identical operation taking place simultaneously in the adjacent higher-order CPE.

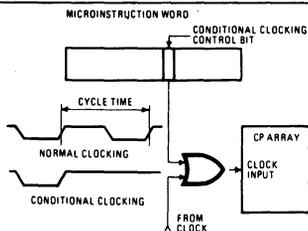
Obviously, the presence of at least one bit in the logical 1 state will result in a true carry output from the highest-order CPE. This output, as explained later, can be used by the MCU to determine which microprogram sequence to follow. With the ability to mask any desired bit, or set of bits, via the K-bus inputs included in the carry OR, a powerful bit-testing and zero-detection facility is realized.

The second novel CPE feature is the use of three-state outputs on the shift right output (RO) and carry output (CO) lines. During a right shift operation, the CO line is placed in the high-impedance (Z) state, and the shift data is active on the RO line. In all other CPE operations, the RO line is placed in the Z state, and the carry data is active on the CO line. This permits the CO and RO lines to be tied together and sent as a single rail input to the MCU for testing and branching. Left shift operations utilize the carry lines, rather than the shift lines, to propagate data.

The third novel CPE capability, called conditional clocking, saves microcode and microcycles by reducing the number of microinstructions required to perform a given test. One extra bit is used in the microinstruction to selectively control the gating of the clock pulse to the central processor (CP) array. Momentarily freezing the clock (Fig. 3) permits the CPE microfunction to be performed, but stops the results from being clocked into the specified registers. The carry or shift data that results from the operation is available because the arithmetic section is combinatorial, rather than sequential. The data can be used as a jump condition by the MCU and in this way permits a variety of nondestructive tests to be performed on register data.

### Microprogram control

The classic form of microprogram control incorporates a next-address field in each microinstruction—any



**3. Conditional clock.** This feature permits an extra bit in microinstruction to selectively control gating of clock pulse to CP array. Carry or shift data thus made available permits tests to be performed on data with fewer microinstructions.

other approach would require some type of program counter. To simplify its logic, the MCU (Fig. 4) uses the classic approach and requires address control information from each microinstruction. This information is not, however, simply the next microprogram address. Rather, it is a highly encoded specification of the next address and one of a set of conditional tests on the MCU bus inputs and registers.

The next-address logic and address control functions of the MCU are based on a unique scheme of memory addressing. Microprogram addresses are organized as a two-dimensional array or matrix. Unlike in ordinary memory, which has linearly sequenced addresses, each microinstruction is pinpointed by its row and column address in the matrix. The 9-bit microprogram address specifies the row address in the upper 5 bits and the column address in the lower 4 bits. The matrix can therefore contain up to 32 row addresses and 16 column addresses for a total of 512 microinstruction addresses.

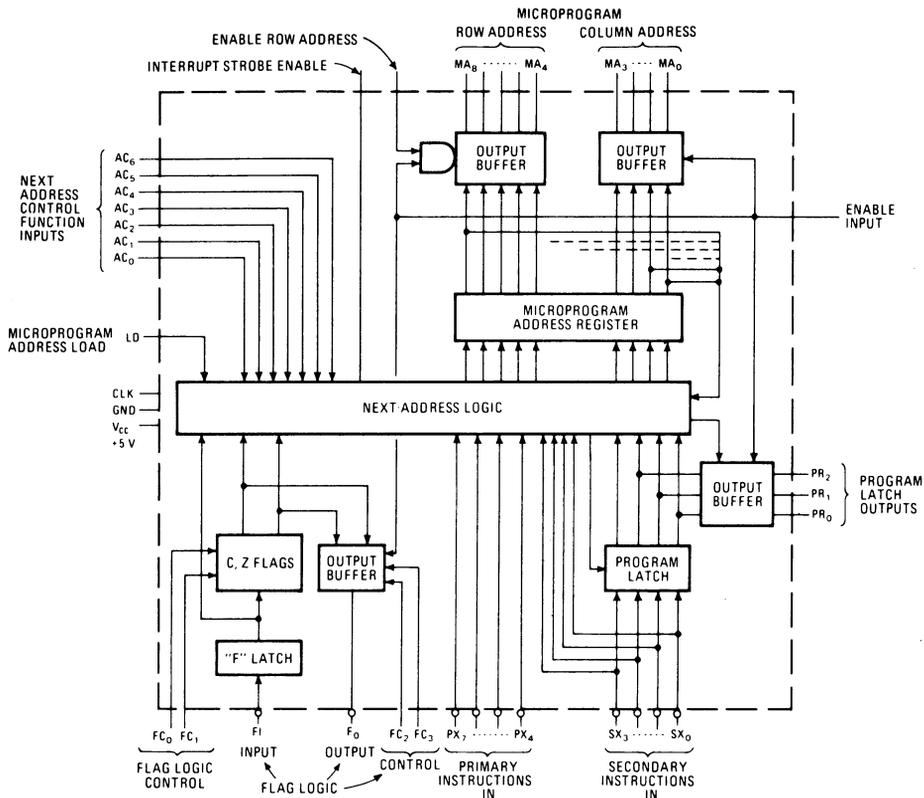
The next-address logic of the MCU makes extensive use of this addressing scheme. For example, from a particular row or column address, it is possible to jump either unconditionally to any other location in that row or column or conditionally to other specified locations, all in one operation. For a given location in the matrix there is a fixed subset of microprogram addresses that may be selected as the next address. These are referred to as a jump set, and each type of MCU address control jump function has a jump set associated with it.

Incorporating a jump operation in every microinstruction improves performance by allowing processing functions to be executed in parallel with program branches. Reductions in microcode are also obtained because common microprogram sequences can be shared without the time-space penalty usually incurred by conditional branching.

Independently controlled flag logic in the MCU is available for latching and controlling the value of the carry and shift inputs to the CP array. Two flags, called C and Z, are used to save the state of the flag input line. Under microprogram control, the flag logic simultaneously sets the state of the flag output line, forcing the line to logical 0, logical 1, or the value of the C or Z flag.

The jump decisions are made by the next-address logic on the basis of: the MCU's current microprogram address; the address control function on the accumulator inputs; and the data that's on the macroinstruction (X) bus or in the program latch or in the flags. Jump decisions may also be based on the instantaneous state of the flag input line without loading the value in one of the flags. This feature eliminates many extra microinstructions that would be required if only the flag flip-flop could be tested.

Microinstruction sequences are normally selected by the operation codes (op codes) supplied by the microinstructions, such as control commands or user instructions in main memory. The MCU decodes these commands by using their bit patterns to determine which is to be the next microprogram address. Each decoding results in a 16-way program branch to the desired microinstruction sequence.



**4. Microprogram control unit.** The MCU's two major control functions include controlling the sequence of microprograms fetched from the microprogram memory, and keeping track of the carry inputs and outputs of the CP array by means of the flag logic control.

### Cracking the op codes

For instance, the MCU can be microprogrammed to directly decode conventional 8-bit op codes. In these op codes the upper 4 bits specify one of up to 16 instruction classes or address modes, such as register, indirect, or indexed. The remaining bits specify the particular subclass such as ADD, SKIP IF ZERO, and so on. If a set of op codes is required to be in a different format, as may occur in a full emulation, an external pre-decoder, such as ROM, can be used in series with the X-bus to reformat the data for the MCU.

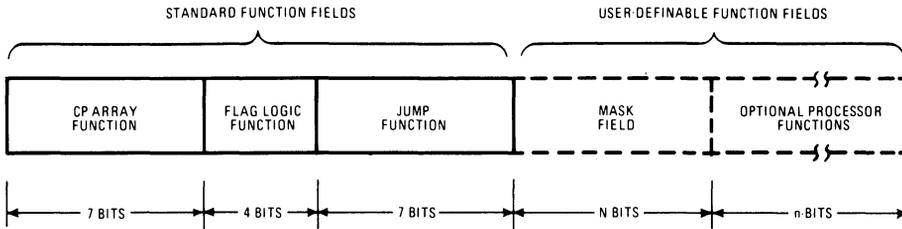
In rigorous decoding situations where speed or space is critical, the full 8-bit macroinstruction bus can be used for a single 256-way branch. Pulling down the load line of the MCU forces the 8 bits of data on the X-bus (typically generated by a predecoder) directly into the microprogram address register.

The data thus directly determines the next microprogram address which should be the start of the desired microprogram sequence. The load line may also be used by external logic to force the MCU, at power-up, into the system re-initialization sequence.

From time to time, a microprocessor must examine the state of its interrupt system to determine whether an interrupt is pending. If one is, the processor must suspend its normal execution sequence and enter an interrupt sequence in the microprogram. This requirement is handled by the MCU in a simple but elegant manner.

When the microprogram flows through address row 0 and column 15, the interrupt strobe enable line of the MCU is raised. The interrupt system, an Intel 3214 Interrupt Control Unit, responds by disabling the row address outputs of the MCU via the enable row address line, and by forcing the row entry address of the microprogram interrupt sequence onto the row address bus. The operation is normally performed just before the macroinstruction fetch cycle, so that a macroprogram is interrupted between, not during, macroinstructions.

The 9-bit microprogram address register and address bus of the MCU directly address 512 microinstructions. This is about twice as many as required by the typical 16-bit disk-controller or central processor.



**5. Microinstruction format.** Only a generalized microinstruction format can be shown since allocation of bits for the mask field and optional processor functions depends on the wishes of the designer and the tradeoffs he decides to make.

Moreover, multiple 512 microinstruction memory planes can easily be implemented simply by adding an extra address bit to the microinstruction each time the number of extra planes is doubled. Incidentally, as the number of bits in the microinstruction is increased, speed is not reduced. The additional planes also permit program jumps to take place in three address dimensions instead of two.

Because of the tremendous design flexibility offered by the Intel computing elements, it is impossible to describe every microinstruction format exactly. But generally speaking, the formats all derive from the one in Fig. 5. The minimum width is 18 bits: 7 bits for the address control functions, plus 4 bits for the flag logic control; plus 7 bits for the CPE microfunction control.

More bits can be added to the microinstruction format to provide such functions as mask field input to the CP array, external memory control, conditional clocking, and so on. Allocation of these bits is left to the designer who organizes the system. He is free to trade off memory costs, support logic, and microinstruction cycles to meet his cost/performance objectives.

### Microprogramming technology

- **Microprogram:** A type of program that directly controls the operation of each functional element in a microprocessor.
- **Microinstruction:** A bit pattern that is stored in a microprogram memory word and specifies the operation of the individual LSI computing elements and related subunits, such as main memory and input/output interfaces.
- **Microinstruction sequence:** The series of microinstructions that the microprogram control unit (MCU) selects from the microprogram to execute a single macroinstruction or control command. Microinstruction sequences can be shared by several macroinstructions.
- **Macroinstruction:** Either a conventional computer instruction (e.g. ADD MEMORY TO REGISTER, INCREMENT, and SKIP, etc.) or device controller command (e.g., SEEK, READ, etc.).

### The cost/performance spectrum

The total flexibility of the Intel LSI computing elements is demonstrated by the broad cost/performance spectrum of the controllers and processors that can be constructed with them. These include:

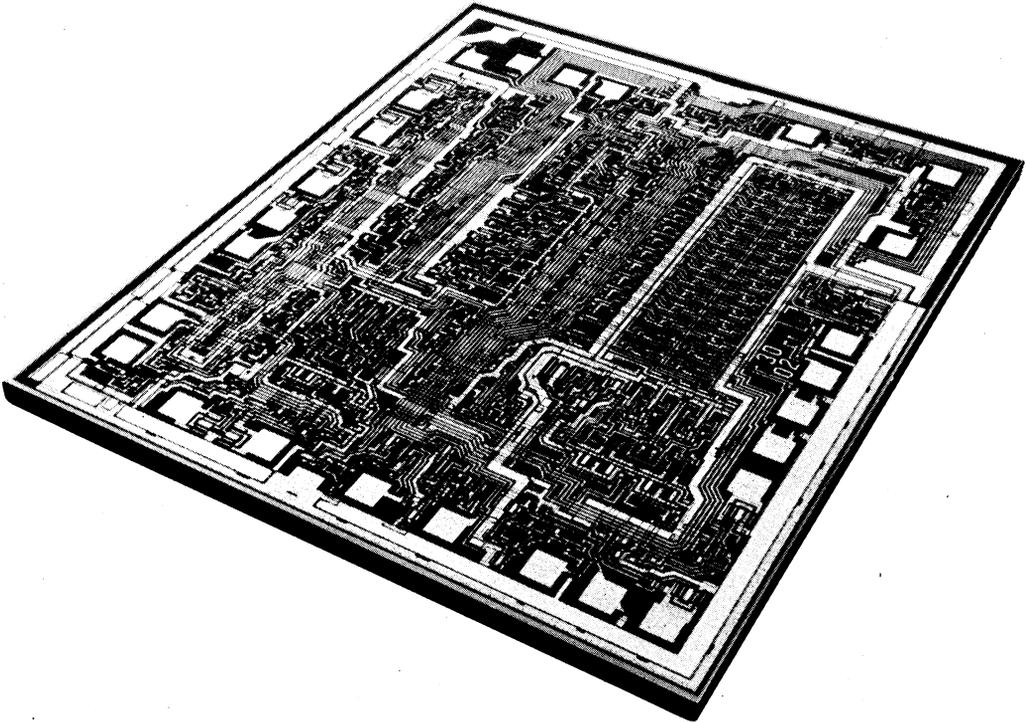
- High-speed controllers, built with a stand-alone ROM-MCU combination that sequences at up to 10 megahertz; it can be used without any CPEs as a system state controller.
- Pipelined look-ahead carry controller-processors, where the overlapped microinstruction fetch/execute cycles and fast-carry logic reduce the 16-bit add time to less than 125 nanoseconds.
- Ripple-carry controller processors (a 16-bit design adds the contents of two registers in 300 nanoseconds).
- Multiprocessors, or networks of any of the above controllers and processors, to provide computation, interrupt supervision, and peripheral control.

These configurations represent a range of microinstruction execution rates of from 3 million to 10 million instructions per second, or up to two orders of magnitude faster, for example, than p-channel microprocessors. Moreover, the increases in processor performance are achieved with relative simplicity. A ripple-carry 16-bit processor uses one MCU, eight CPEs, plus microprogram memory. One extra computing element, the 3003 Look-ahead Carry Generator, enhances the processor with fast carry. Increasing speed further by pipelining, the overlap of microinstruction fetch and execute cycles, requires a few D-type MSI flip-flops.

At the multiprocessor level, the microprogram memory, MCU, or CPE devices can be shared. A 16-bit processor, complete with bus control and microprogram memory, requires some 20 bipolar LSI packages and half that many small-scale ICs. In this configuration, it replaces an equivalent MSI TTL system having more than 200 packages.

Furthermore, systems built with this large-scale integrated circuitry are much smaller and less costly and consume less energy than equivalent designs using lower levels of transistor-transistor-logic integration. Even allowing for ancillary logic circuits, the new bipolar computing elements cut 60% to 80% off the package count in realizing most of today's designs made with small- or medium-scale-integrated TTL.

# COMPONENT FAMILY





# SCHOTTKY BIPOLAR LSI MICROCOMPUTER SET

# 3001 MICROPROGRAM CONTROL UNIT

The INTEL® 3001 Microprogram Control Unit (MCU) controls the sequence in which microinstructions are fetched from the microprogram memory. Its functions include the following:

Maintenance of the microprogram address register.

Selection of the next microinstruction based on the contents of the microprogram address register.

Decoding and testing of data supplied via several input busses to determine the microinstruction execution sequence.

Saving and testing of carry output data from the central processor (CP) array.

Control of carry/shift input data to the CP array.

Control of microprogram interrupts.

High Performance — 85 ns Cycle Time

TTL and DTL Compatible

Fully Buffered Three-State and Open Collector Outputs

Direct Addressing of Standard Bipolar PROM or ROM

512 Microinstruction Addressability

Advanced Organization

9-Bit Microprogram Address Register and Bus

4-Bit Program Latch

Two Flag Registers

Eleven Address Control Functions

Three Jump and Test Latch Functions

16-way Jump and Test Instruction

Bus Function

Eight Flag Control Functions

Four Flag Input Functions

Four Flag Output Functions

40 Pin DIP

## PACKAGE CONFIGURATION

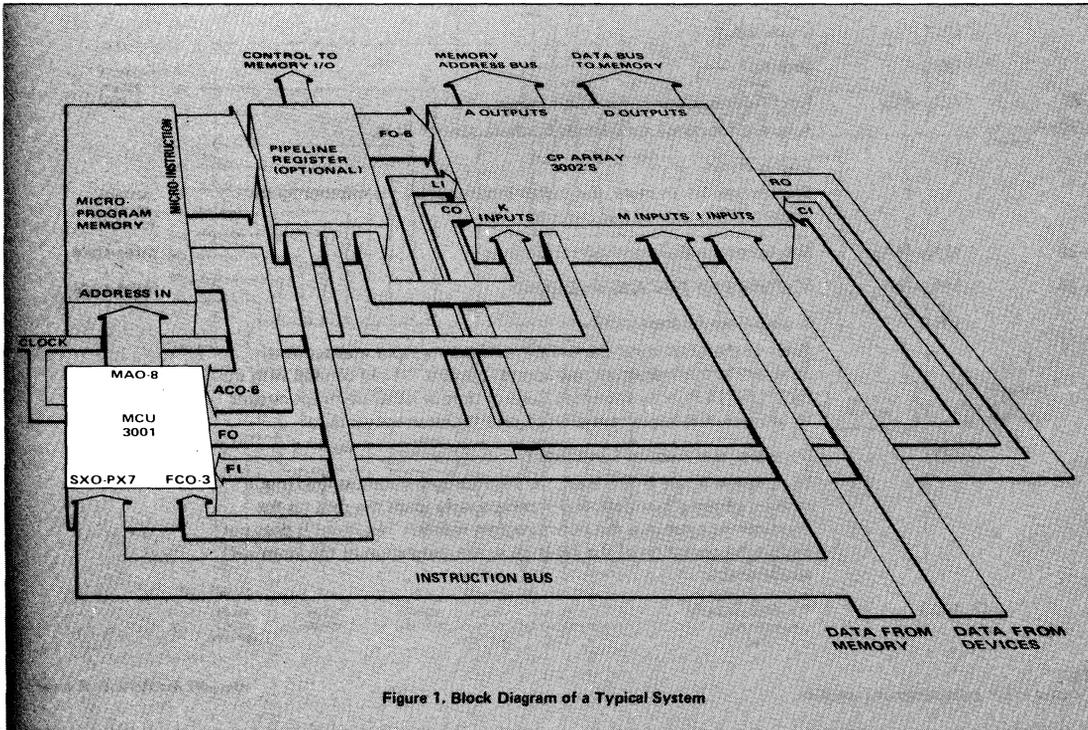
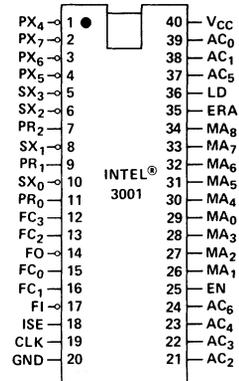


Figure 1. Block Diagram of a Typical System

## PIN DESCRIPTION

PIN	SYMBOL	NAME AND FUNCTION	TYPE <sup>(1)</sup>
1-4	PX <sub>4</sub> -PX <sub>7</sub>	Primary Instruction Bus Inputs Data on the primary instruction bus is tested by the JPX function to determine the next microprogram address.	active LOW
5, 6, 8, 10	SX <sub>0</sub> -SX <sub>3</sub>	Secondary Instruction Bus Inputs Data on the secondary instruction bus is synchronously loaded into the PR-latch while the data on the PX-bus is being tested (JPX). During a subsequent cycle, the contents of the PR-latch may be tested by the JPR, JLL, or JRL functions to determine the next microprogram address.	active LOW
7, 9, 11	PR <sub>0</sub> -PR <sub>2</sub>	PR-Latch Outputs The PR-latch outputs are asynchronously enabled by the JCE function. They can be used to modify microinstructions at the outputs of the microprogram memory or to provide additional control lines.	open collector
12, 13, 15, 16	FC <sub>0</sub> -FC <sub>3</sub>	Flag Logic Control Inputs The flag logic control inputs are used to cross-switch the flags (C and Z) with the flag logic input (FI) and the flag logic output (FO).	
14	FO	Flag Logic Output The outputs of the flags (C and Z) are multiplexed internally to form the common flag logic output. The output may also be forced to a logical 0 or logical 1.	active LOW three-state
17	FI	Flag Logic Input The flag logic input is demultiplexed internally and applied to the inputs of the flags (C and Z). Note: the flag input data is saved in the F-latch when the clock input (CLK) is low.	active LOW
18	ISE	Interrupt Strobe Enable Output The interrupt strobe enable output goes to logical 1 when one of the JZR functions are selected (see Functional Description, page 6). It can be used to provide the strobe signal required by the INTEL 3214 Priority Interrupt Control Unit or other interrupt circuits.	
19	CLK	Clock Input	
20	GND	Ground	
21-24 37-39	AC <sub>0</sub> -AC <sub>6</sub>	Next Address Control Function Inputs All jump functions are selected by these control lines.	
25	EN	Enable Input When in the HIGH state, the enable input enables the microprogram address, PR-latch and flag outputs.	
26-29	MA <sub>0</sub> -MA <sub>3</sub>	Microprogram Column Address Outputs	three-state
30-34	MA <sub>4</sub> -MA <sub>8</sub>	Microprogram Row Address Outputs	three-state
35	ERA	Enable Row Address Input When in the LOW state, the enable row address input independently disables the microprogram row address outputs. It can be used with the INTEL 3214 Priority Interrupt Control Unit or other interrupt circuits to facilitate the implementation of priority interrupt systems.	
36	LD	Microprogram Address Load Input When in the active HIGH state, the microprogram address load input inhibits all jump functions and synchronously loads the data on the instruction busses into the microprogram register. However, it does not inhibit the operation of the PR-latch or the generation of the interrupt strobe enable.	
40	VCC	+5 Volt Supply	

## NOTE:

(1) Active HIGH unless otherwise specified.

## LOGICAL DESCRIPTION

The MCU performs two major control functions. First, it controls the sequence in which microinstructions are fetched from the microprogram memory. For this purpose, the MCU contains a microprogram address register and the associated logic for selecting the next microinstruction address. The second function of the MCU is the control of the two flag flip-flops that are included for interaction with the carry input and carry output logic of the CP array. The logical organization of the MCU is shown in Figure 2.

### NEXT ADDRESS LOGIC

The next address logic of the MCU provides a set of conditional and unconditional address control functions. These address control functions are used to implement a jump or jump/test operation as part of every microinstruction. That is to say, each microinstruction typically contains a jump operation field that specifies the address control function, and hence, the next microprogram address.

In order to minimize the pin count of the MCU, and reduce the complexity of the next address logic, the microprogram address space is organized as a two dimensional array or matrix. Each microprogram address corresponds to a unit of the matrix at a particular row and column location. Thus, the 9-bit microprogram address is treated as specifying not one, but two addresses — the row address in the upper five bits and the column address in the lower four bits. The address matrix can therefore contain, at most, 32 row addresses and 16 column addresses for a total of 512 microinstructions.

The next address logic of the MCU makes extensive use of this two component addressing scheme. For example, from a particular row or column address, it is possible to jump unconditionally in one operation anywhere in that row or column. It is not possible, however, to jump anywhere in the address matrix. In fact, for a given location in the matrix, there is a fixed subset of microprogram addresses that may be selected as the next address. These

possible jump target addresses are referred to as a jump set. Each type of MCU address control (jump) function has a jump set associated with it. Appendix C illustrates the jump set for each function.

### FLAG LOGIC

The flag logic of the MCU provides a set of functions for saving the current value of the carry output of the CP array and for controlling the value of the carry input to the CP array. These two distinct flag control functions are called flag input functions and flag output functions.

The flag logic is comprised of two flip-flops, designated the C-flag and the Z-flag, along with a simple latch, called the F-latch, that indicates the current state of the carry output line of the CP array. The flag logic is used in conjunction with the carry and shift logic of the CP array to implement a variety of shift/rotate and arithmetic functions.

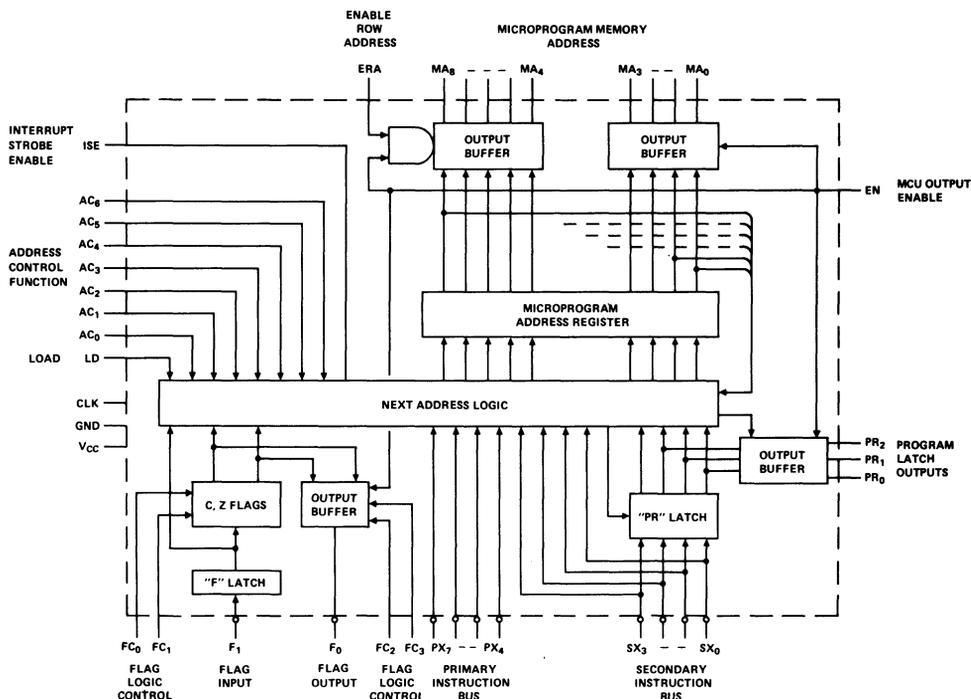
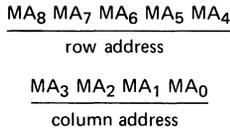


Figure 2. 3001 Block Diagram

**FUNCTIONAL DESCRIPTION**

**ADDRESS CONTROL FUNCTIONS**

The address control functions of the MCU are selected by the seven input lines designated AC<sub>0</sub>-AC<sub>6</sub>. On the rising edge of the clock, the 9-bit microprogram address generated by the next address logic is loaded into the microprogram address register. The next microprogram address is delivered to the microprogram memory via the nine output lines designated MA<sub>0</sub>-MA<sub>8</sub>. The microprogram address outputs are organized into row and column addresses as:



Each address control function is specified by a unique encoding of the data on the function input lines. From three to five bits of the data specify the particular function while the remaining bits are used to select part of either the row or column address desired. Function code formats are given in Appendix A, "Address Control Function Summary."

The following is a detailed description of each of the eleven address control functions. The symbols shown below are used throughout the description to specify row and column addresses.

Symbol	Meaning
row <sub>n</sub>	5-bit next row address where n is the decimal row address.
col <sub>n</sub>	4-bit next column address where n is the decimal column address.

**UNCONDITIONAL ADDRESS CONTROL (JUMP) FUNCTIONS**

The jump functions use the current microprogram address (i.e., the contents of the microprogram address register prior to the rising edge of the clock) and several bits from the address control inputs to generate the next microprogram address.

Mnemonic	Function Description
JCC	Jump in current column. AC <sub>0</sub> -AC <sub>4</sub> are used to select 1 of 32 row addresses in the current column, specified by

MA<sub>0</sub>-MA<sub>3</sub>, as the next address

JZR	Jump to zero row. AC <sub>0</sub> -AC <sub>3</sub> are used to select 1 of 16 column addresses in row <sub>0</sub> , as the next address.
JCR	Jump in current row. AC <sub>0</sub> -AC <sub>3</sub> are used to select 1 of 16 addresses in the current row, specified by MA <sub>4</sub> -MA <sub>8</sub> , as the next address.
JCE	Jump in current column/row group and enable PR-latch outputs. AC <sub>0</sub> -AC <sub>2</sub> are used to select 1 of 8 row addresses in the current row group, specified by MA <sub>7</sub> -MA <sub>8</sub> , as the next row address. The current column is specified by MA <sub>0</sub> -MA <sub>3</sub> . The PR-latch outputs are asynchronously enabled.

**FLAG CONDITIONAL ADDRESS CONTROL (JUMP/TEST) FUNCTIONS**

The jump/test flag functions use the current microprogram address, the contents of the selected flag or latch, and several bits from the address control function to generate the next microprogram address.

Mnemonic	Function Description
JFL	Jump/test F-Latch. AC <sub>0</sub> -AC <sub>3</sub> are used to select 1 of 16 row addresses in the current row group, specified by MA <sub>8</sub> , as the next row address. If the current column group, specified by MA <sub>3</sub> , is col <sub>0</sub> -col <sub>7</sub> , the F-latch is used to select col <sub>2</sub> or col <sub>3</sub> as the next column address. If MA <sub>3</sub> specifies column group col <sub>8</sub> -col <sub>15</sub> , the F-latch is used to select col <sub>10</sub> or col <sub>11</sub> as the next column address.
JCF	Jump/test C-flag. AC <sub>0</sub> -AC <sub>2</sub> are used to select 1 of 8 row addresses in the current

row group, specified by MA<sub>7</sub> and MA<sub>8</sub>, as the next row address. If the current column group specified by MA<sub>3</sub> is col<sub>0</sub>-col<sub>7</sub>, the C-flag is used to select col<sub>2</sub> or col<sub>3</sub> as the next column address. If MA<sub>3</sub> specifies column group col<sub>8</sub>-col<sub>15</sub>, the C-flag is used to select col<sub>10</sub> or col<sub>11</sub> as the next column address.

JZF	Jump/test Z-flag. Identical to the JCF function described above, except that the Z-flag, rather than the C-flag, is used to select the next column address.
-----	---

**PX-BUS AND PR-LATCH CONDITIONAL ADDRESS CONTROL (JUMP/TEST) FUNCTIONS**

The PX-bus jump/test function uses the data on the primary instruction bus (PX<sub>4</sub>-PX<sub>7</sub>), the current microprogram address, and several selection bits from the address control function to generate the next microprogram address. The PR-latch jump/test functions use the data held in the PR-latch, the current microprogram address, and several selection bits from the address control function to generate the next microprogram address.

Mnemonic	Function Description
JPR	Jump/test PR-latch. AC <sub>0</sub> -AC <sub>2</sub> are used to select 1 of 8 row addresses in the current row group, specified by MA <sub>7</sub> and MA <sub>8</sub> , as the next row address. The four PR-latch bits are used to select 1 of 16 possible column addresses as the next column address.
Mnemonic	Function Description
JLL	Jump/test leftmost PR-latch bits. AC <sub>0</sub> -AC <sub>2</sub> are used to select 1 of 8 row addresses in the current row group, specified by MA <sub>7</sub> and MA <sub>8</sub> , as the next row address. PR <sub>2</sub> and PR <sub>3</sub> are used to

## FUNCTIONAL DESCRIPTION (con't)

- select 1 of 4 possible column addresses in col<sub>4</sub> through col<sub>7</sub> as the next column address.
- JRL** Jump/test rightmost PR-latch bits. AC<sub>0</sub> and AC<sub>1</sub> are used to select 1 of 4 high-order row addresses in the current row group, specified by MA<sub>7</sub> and MA<sub>8</sub>, as the next row address. PR<sub>0</sub> and PR<sub>1</sub> are used to select 1 of 4 possible column addresses in col<sub>12</sub> through col<sub>15</sub> as the next column address.
- JPX** Jump/test PX-bus and load PR-latch. AC<sub>0</sub> and AC<sub>1</sub> are used to select 1 of 4 row addresses in the current row group, specified by MA<sub>6</sub>-MA<sub>8</sub>, as the next row address. PX<sub>4</sub>-PX<sub>7</sub> are used to select 1 of 16 possible column addresses as the next column address. SX<sub>0</sub>-SX<sub>3</sub> data is locked in the PR-latch at the rising edge of the clock.

## FLAG CONTROL FUNCTIONS

The flag control functions of the MCU are selected by the four input lines designated FC<sub>0</sub>-FC<sub>3</sub>. Function code formats are given in Appendix B, "Flag Control Function Summary."

The following is a detailed description of each of the eight flag control functions.

## FLAG INPUT CONTROL FUNCTIONS

The flag input control functions select which flag or flags will be set to the current value of the flag input (FI) line. Data on FI is stored in the F-latch when the clock is low. The content of the F-latch is loaded into the C and/or Z flag on the rising edge of the clock.

Mnemonic	Function Description
SCZ	Set C-flag and Z-flag to FI. The C-flag and the Z-flag are both set to the value of FI.
STZ	Set Z-flag to FI. The Z-flag is set to the value of FI. The C-flag is unaffected.
STC	Set C-flag to FI. The C-flag is set to the value of FI. The Z flag is unaffected.
HCZ	Hold C-flag and Z-flag. The values in the C-flag and Z-flag are unaffected.

## FLAG OUTPUT CONTROL FUNCTIONS

The flag output control functions select the value to which the flag output (FO) line will be forced.

Mnemonic	Function Description
FF0	Force FO to 0. FO is forced to the value of logical 0.
FFC	Force FO to C. FO is forced to the value of the C-flag.
FFZ	Force FO to Z. FO is forced to the value of the Z-flag.
FF1	Force FO to 1. FO is forced to the value of logical 1.

## LOAD AND INTERRUPT STROBE FUNCTIONS

The load function of the MCU is controlled by the input line designated LD. If the LD line is active HIGH at the rising edge of the clock, the data on the primary and secondary instruction buses, PX<sub>4</sub>-PX<sub>7</sub> and SX<sub>0</sub>-SX<sub>3</sub>, is loaded into the microprogram address register. PX<sub>4</sub>-PX<sub>7</sub> are loaded into MA<sub>0</sub>-MA<sub>3</sub> and SX<sub>0</sub>-SX<sub>3</sub> are loaded into MA<sub>4</sub>-MA<sub>7</sub>. The high-order bit of the microprogram address register MA<sub>8</sub> is set to a logical 0. The bits from the primary instruction bus select 1 of 16 possible column addresses. Likewise, the bits from the secondary instruction bus select 1 of the first 16 row addresses.

The interrupt strobe enable of the MCU is available on the output line designated ISE. The line is placed in the active high state whenever a JZR to col<sub>15</sub> is selected as the address control function. Customarily, the start of a macroinstruction fetch sequence is situated at row<sub>0</sub> and col<sub>15</sub> so that the INTEL 3214 Priority Interrupt Control Unit may be enabled at the beginning of the fetch/execute cycle. The priority interrupt control unit may respond to the interrupt by pulling the enable row address (ERA) input line down to override the selected next row address from the MCU. Then by gating an alternative next row address on to the row address lines of the microprogram memory, the microprogram may be forced to enter an interrupt handling routine. The alternative row address placed on the microprogram memory address lines does not alter the contents of the microprogram address register. Therefore, subsequent jump functions will utilize the row address in the register, and not the alternative row address, to determine the next microprogram address.

Note, the load function always overrides the address control function on AC<sub>0</sub>-AC<sub>6</sub>. It does not, however, override the latch enable or load sub-functions of the JCE or JPX instruction, respectively. In addition, it does not inhibit the interrupt strobe enable or any of the flag control functions.

## D.C. AND OPERATING CHARACTERISTICS

## ABSOLUTE MAXIMUM RATINGS\*

Temperature Under Bias	0°C to 70°C
Storage Temperature	-65°C to +160°C
All Output and Supply Voltages	-0.5V to +7V
All Input Voltages	-1.0V to +5.5V
Output Currents	100 mA

\*COMMENT: Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum ratings for extended periods may affect device reliability.

$$T_A = 0^\circ\text{C to } 70^\circ\text{C} \quad V_{CC} = 5.0\text{V} \pm 5\%$$

SYMBOL	PARAMETER	MIN	TYP <sup>(1)</sup>	MAX	UNIT	CONDITIONS
V <sub>C</sub>	Input Clamp Voltage (All Input Pins)		-0.8	-1.0	V	I <sub>C</sub> = -5 mA
I <sub>F</sub>	Input Load Current:					
	CLK Input		-0.075	-0.75	mA	V <sub>F</sub> = 0.45V
	EN Input		-0.05	-0.50	mA	
	All Other Inputs		-0.025	-0.25	mA	
I <sub>R</sub>	Input Leakage Current:					
	CLK			120	μA	V <sub>R</sub> = 5.25V
	EN Input			80	μA	
	All Other Inputs			40	μA	
V <sub>IL</sub>	Input Low Voltage			0.8	V	V <sub>CC</sub> = 5.0V
V <sub>IH</sub>	Input High Voltage	2.0			V	
I <sub>CC</sub>	Power Supply Current <sup>(2)</sup>		170	240	mA	
V <sub>OL</sub>	Output Low Voltage (All Output Pins)		0.35	0.45	V	I <sub>OL</sub> = 10 mA
V <sub>OH</sub>	Output High Voltage (MA <sub>0</sub> -MA <sub>8</sub> , ISE, FO)	2.4	3.0		V	I <sub>OH</sub> = -1 mA
I <sub>OS</sub>	Output Short Circuit Current (MA <sub>0</sub> -MA <sub>8</sub> , ISE, FO)	-15	-28	-60	mA	V <sub>CC</sub> = 5.0V
I <sub>O(off)</sub>	Off-State Output Current:					
	MA <sub>0</sub> -MA <sub>8</sub> , FO			-100	μA	V <sub>O</sub> = 0.45V
	MA <sub>0</sub> -MA <sub>8</sub> , FO, PR <sub>0</sub> -PR <sub>2</sub>			100	μA	V <sub>O</sub> = 5.25V

## NOTES:

(1) Typical values are for T<sub>A</sub> = 25°C and nominal supply voltage.

(2) EN input grounded, all other inputs and outputs open.

**A.C. CHARACTERISTICS AND WAVEFORMS**  $T_A = 0^\circ\text{C}$  to  $70^\circ\text{C}$ ,  $V_{CC} = 5.0\text{V} \pm 5\%$ 

SYMBOL	PARAMETER	MIN	TYP <sup>(1)</sup>	MAX	UNIT
$t_{CY}$	Cycle Time <sup>(2)</sup>	85	60		ns
$t_{WP}$	Clock Pulse Width	30	20		ns
	Control and Data Input Set-Up Times:				
$t_{SF}$	LD, AC <sub>0</sub> -AC <sub>6</sub>	10	0		ns
$t_{SK}$	FC <sub>0</sub> , FC <sub>1</sub>	0			ns
$t_{SX}$	SX <sub>0</sub> -SX <sub>3</sub> , PX <sub>4</sub> -PX <sub>7</sub>	35	25		ns
$t_{SI}$	FI	15	5		ns
	Control and Data Input Hold Times:				
$t_{HF}$	LD, AC <sub>0</sub> -AC <sub>6</sub>	5	0		ns
$t_{HK}$	FC <sub>0</sub> , FC <sub>1</sub>	0			ns
$t_{HX}$	SX <sub>0</sub> -SX <sub>3</sub> , PX <sub>4</sub> -PX <sub>7</sub>	20	5		ns
$t_{HI}$	FI	20	8		ns
$t_{CO}$	Propagation Delay from Clock Input (CLK) to Outputs (MA <sub>0</sub> -MA <sub>8</sub> , FO)	10	30	45	ns
$t_{KO}$	Propagation Delay from Control Inputs FC <sub>2</sub> and FC <sub>3</sub> to Flag Out (FO)		16	30	ns
$t_{FO}$	Propagation Delay from Control Inputs AC <sub>0</sub> -AC <sub>6</sub> to Latch Outputs (PR <sub>0</sub> -PR <sub>2</sub> )		26	40	ns
$t_{EO}$	Propagation Delay from Enable Inputs EN and ERA to Outputs (MA <sub>0</sub> -MA <sub>8</sub> , FO, PR <sub>0</sub> -PR <sub>2</sub> )		21	32	ns
$t_{FI}$	Propagation Delay from Control Inputs AC <sub>0</sub> -AC <sub>6</sub> to Interrupt Strobe Enable Output (ISE)		24	40	ns

## NOTE:

(1) Typical values are for  $T_A = 25^\circ\text{C}$  and nominal supply voltage.(2)  $t_{CY} = t_{WP} + t_{SF} + t_{CO}$ 

## TEST CONDITIONS:

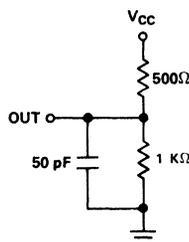
Input pulse amplitude of 2.5 volts.

Input rise and fall times of 5 ns between 1 volt and 2 volts.

Output load of 10 mA and 50 pF.

Speed measurements are taken at the 1.5 volt level.

## TEST LOAD CIRCUIT:

CAPACITANCE<sup>(2)</sup>  $T_A = 25^\circ\text{C}$ 

SYMBOL	PARAMETER	MIN	TYP	MAX	UNIT
$C_{IN}$	Input Capacitance:				
	CLK, EN		11	16	pF
	All Other Inputs		5	10	pF
$C_{OUT}$	Output Capacitance		6	12	pF

## NOTE:

(2) This parameter is periodically sampled and is not 100% tested. Condition of measurement is  $f = 1\text{ MHz}$ ,  $V_{BIAS} = 2.5\text{V}$ ,  $V_{CC} = 5\text{V}$  and  $T_A = 25^\circ\text{C}$ .

## D.C. AND OPERATING CHARACTERISTICS

## ABSOLUTE MAXIMUM RATINGS\*

Temperature Under Bias	-55°C to +125°C
Storage Temperature	-65°C to +160°C
All Output and Supply Voltages	-0.5V to +7V
All Input Voltages	-1.0V to +5.5V
Output Currents	100 mA

\*COMMENT: Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum ratings for extended periods may affect device reliability.

$T_A = -55^\circ\text{C}$  to  $+125^\circ\text{C}$ ,  $V_{CC} = 5.0\text{V} \pm 10\%$

SYMBOL	PARAMETER	MIN	TYP <sup>(1)</sup>	MAX	UNIT	CONDITIONS
$V_C$	Input Clamp Voltage (All Input Pins)		-0.8	-1.2	V	$I_C = -5\text{ mA}$
$I_F$	Input Load Current:					$V_F = 0.45\text{V}$
	CLK Input		-75	-750	$\mu\text{A}$	
	EN Input		-50	-500	$\mu\text{A}$	
	All Other Inputs		-25	-250	$\mu\text{A}$	
$I_R$	Input Leakage Current:					$V_R = 5.5\text{V}$
	CLK			120	$\mu\text{A}$	
	EN Input			80	$\mu\text{A}$	
	All Other Inputs			40	$\mu\text{A}$	
$V_{IL}$	Input Low Voltage			0.8	V	$V_{CC} = 5.0\text{V}$
$V_{IH}$	Input High Voltage	2.0			V	
$I_{CC}$	Power Supply Current <sup>(2)</sup>		170	250	mA	
$V_{OL}$	Output Low Voltage (All Output Pins)		0.35	0.45	V	$I_{OL} = 10\text{ mA}$
$V_{OH}$	Output High Voltage (MA <sub>0</sub> -MA <sub>8</sub> , ISE, FO)	2.4	3.0		V	$I_{OH} = -1\text{ mA}$
$I_{OS}$	Output Short Circuit Current (MA <sub>0</sub> -MA <sub>8</sub> , ISE, FO)	-15	-28	-60	mA	$V_{CC} = 5.0\text{V}$
$I_{O(off)}$	Off-State Output Current:					
	MA <sub>0</sub> -MA <sub>8</sub> , FO			-100	$\mu\text{A}$	$V_O = 0.45\text{V}$
	MA <sub>0</sub> -MA <sub>8</sub> , FO, PR <sub>0</sub> -PR <sub>2</sub>			100	$\mu\text{A}$	$V_O = 5.5\text{V}$

## NOTES:

(1) Typical values are for  $T_A = 25^\circ\text{C}$  and nominal supply voltage.

(2) EN input grounded, all other inputs and outputs open.

**A.C. CHARACTERISTICS AND WAVEFORMS**  $T_A = -55^\circ\text{C}$  to  $+125^\circ\text{C}$ ,  $V_{CC} = 5.0\text{V} \pm 10\%$ 

SYMBOL	PARAMETER	MIN	TYP <sup>(1)</sup>	MAX	UNIT
$t_{CY}$	Cycle Time <sup>(2)</sup>	95	60		ns
$t_{WP}$	Clock Pulse Width	40	20		ns
	Control and Data Input Set-Up Times:				
$t_{SF}$	LD, AC <sub>0</sub> -AC <sub>6</sub>	10	0		ns
$t_{SK}$	FC <sub>0</sub> , FC <sub>1</sub>	0			ns
$t_{SX}$	SX <sub>0</sub> -SX <sub>3</sub> , PX <sub>4</sub> -PX <sub>7</sub>	35	25		ns
$t_{SI}$	FI	15	5		ns
	Control and Data Input Hold Times:				
$t_{HF}$	LD, AC <sub>0</sub> -AC <sub>6</sub>	5	0		ns
$t_{HK}$	FC <sub>0</sub> , FC <sub>1</sub>	0			ns
$t_{HX}$	SX <sub>0</sub> -SX <sub>3</sub> , PX <sub>4</sub> -PX <sub>7</sub>	25	5		ns
$t_{HI}$	FI	22	8		ns
$t_{CO}$	Propagation Delay from Clock Input (CLK) to Outputs (MA <sub>0</sub> -MA <sub>8</sub> , FO)	10	30	45	ns
$t_{KO}$	Propagation Delay from Control Inputs FC <sub>2</sub> and FC <sub>3</sub> to Flag Out (FO)		16	50	ns
$t_{FO}$	Propagation Delay from Control Inputs AC <sub>0</sub> -AC <sub>6</sub> to Latch Outputs (PR <sub>0</sub> -PR <sub>2</sub> )		26	50	ns
$t_{EO}$	Propagation Delay from Enable Inputs EN and ERA to Outputs (MA <sub>0</sub> -MA <sub>8</sub> , FO, PR <sub>0</sub> -PR <sub>2</sub> )		21	35	ns
$t_{FI}$	Propagation Delay from Control Inputs AC <sub>0</sub> -AC <sub>6</sub> to Interrupt Strobe Enable Output (ISE)		24	40	ns

## NOTE:

(1) Typical values are for  $T_A = 25^\circ\text{C}$  and nominal supply voltage.(2)  $t_{CY} = t_{WP} + t_{SF} + t_{CO}$ 

## TEST CONDITIONS:

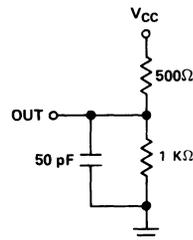
Input pulse amplitude of 2.5 volts.

Input rise and fall times of 5 ns between 1 volt and 2 volts.

Output load of 10 mA and 50 pF.

Speed measurements are taken at the 1.5 volt level.

## TEST LOAD CIRCUIT:

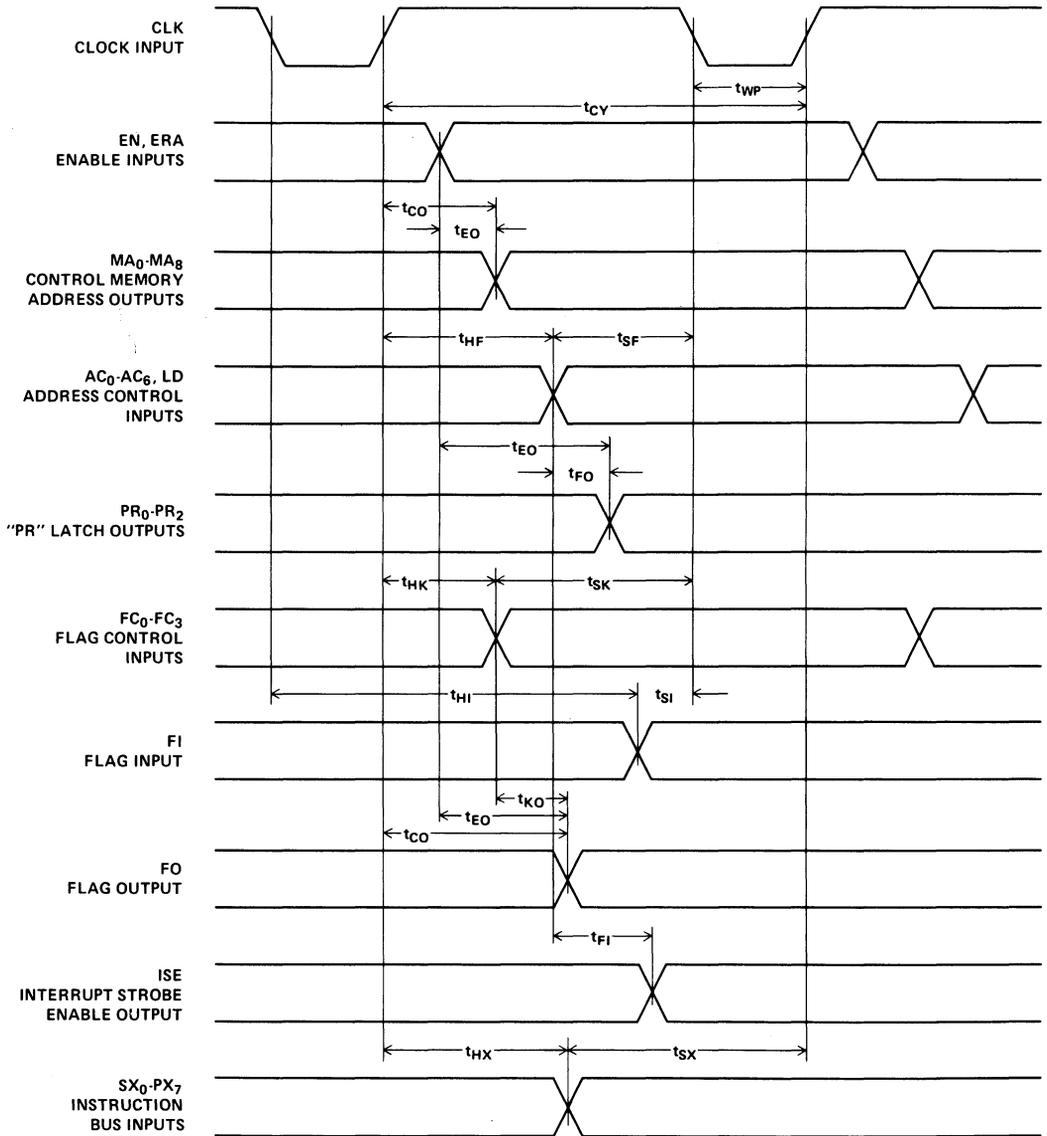
CAPACITANCE<sup>(2)</sup>  $T_A = 25^\circ\text{C}$ 

SYMBOL	PARAMETER	MIN	TYP	MAX	UNIT
$C_{IN}$	Input Capacitance:				
	CLK, EN		11	16	pF
	All Other Inputs		5	10	pF
$C_{OUT}$	Output Capacitance		6	12	pF

## NOTE:

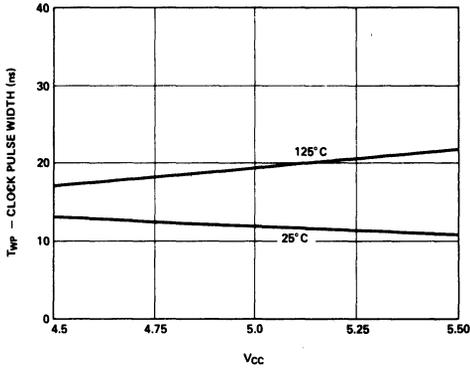
(2) This parameter is periodically sampled and is not 100% tested. Condition of measurement is  $f = 1\text{ MHz}$ ,  $V_{BIAS} = 2.5\text{V}$ ,  $V_{CC} = 5\text{V}$  and  $T_A = 25^\circ\text{C}$ .

3001 WAVEFORMS

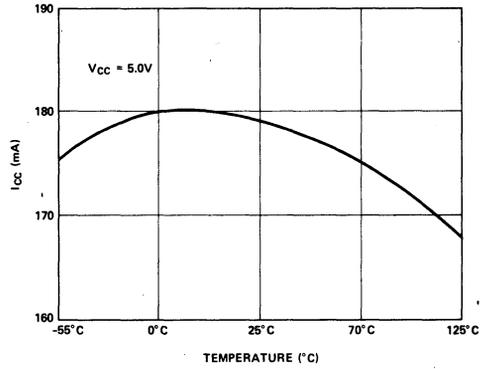


TYPICAL AC AND DC CHARACTERISTICS

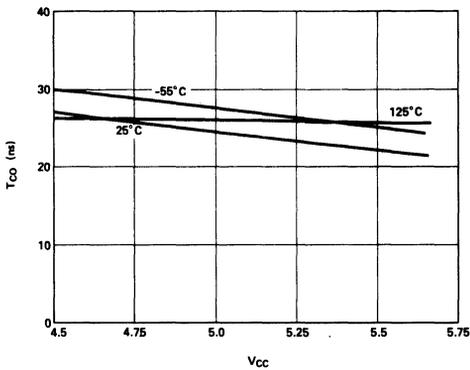
CLOCK PULSE WIDTH VS.  $V_{CC}$  AND TEMPERATURE



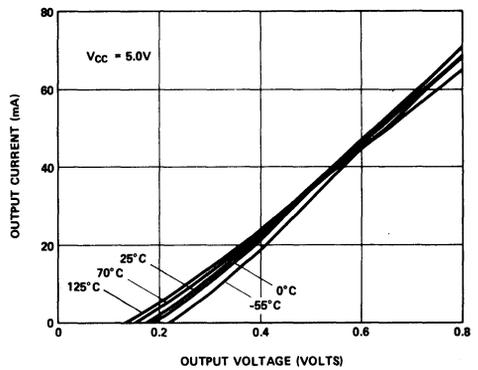
$I_{CC}$  VS. TEMPERATURE



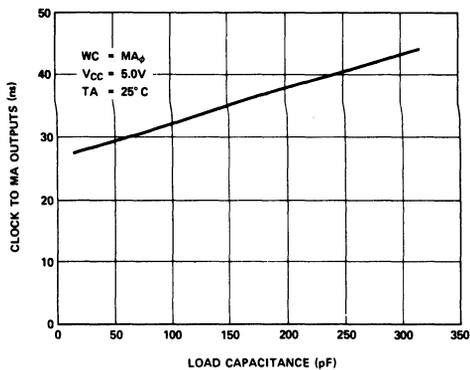
CLOCK TO mA OUTPUTS VS. LOAD CAPACITANCE



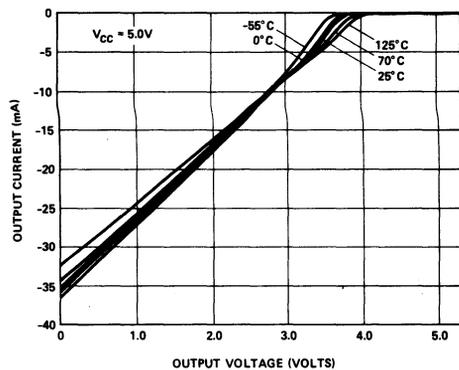
OUTPUT CURRENT VS. OUTPUT LOW VOLTAGE



CLOCK TO mA OUTPUTS VS. LOAD CAPACITANCE



OUTPUT CURRENT VS. OUTPUT HIGH VOLTAGE



## APPENDIX A ADDRESS CONTROL FUNCTION SUMMARY

MNEMONIC	DESCRIPTION	FUNCTION							NEXT ROW				NEXT COL				
		AC <sub>6</sub>	5	4	3	2	1	0	MA <sub>8</sub>	7	6	5	4	MA <sub>3</sub>	2	1	0
JCC	Jump in current column	0	0	d <sub>4</sub>	d <sub>3</sub>	d <sub>2</sub>	d <sub>1</sub>	d <sub>0</sub>	d <sub>4</sub>	d <sub>3</sub>	d <sub>2</sub>	d <sub>1</sub>	d <sub>0</sub>	m <sub>3</sub>	m <sub>2</sub>	m <sub>1</sub>	m <sub>0</sub>
JZR	Jump to zero row	0	1	0	d <sub>3</sub>	d <sub>2</sub>	d <sub>1</sub>	d <sub>0</sub>	0	0	0	0	0	d <sub>3</sub>	d <sub>2</sub>	d <sub>1</sub>	d <sub>0</sub>
JCR	Jump in current row	0	1	1	d <sub>3</sub>	d <sub>2</sub>	d <sub>1</sub>	d <sub>0</sub>	m <sub>8</sub>	m <sub>7</sub>	m <sub>6</sub>	m <sub>5</sub>	m <sub>4</sub>	d <sub>3</sub>	d <sub>2</sub>	d <sub>1</sub>	d <sub>0</sub>
JCE	Jump in column/enable	1	1	1	0	d <sub>2</sub>	d <sub>1</sub>	d <sub>0</sub>	m <sub>8</sub>	m <sub>7</sub>	d <sub>2</sub>	d <sub>1</sub>	d <sub>0</sub>	m <sub>3</sub>	m <sub>2</sub>	m <sub>1</sub>	m <sub>0</sub>
JFL	Jump/test F-latch	1	0	0	d <sub>3</sub>	d <sub>2</sub>	d <sub>1</sub>	d <sub>0</sub>	m <sub>8</sub>	d <sub>3</sub>	d <sub>2</sub>	d <sub>1</sub>	d <sub>0</sub>	m <sub>3</sub>	0	1	f
JCF	Jump/test C-flag	1	0	1	0	d <sub>2</sub>	d <sub>1</sub>	d <sub>0</sub>	m <sub>8</sub>	m <sub>7</sub>	d <sub>2</sub>	d <sub>1</sub>	d <sub>0</sub>	m <sub>3</sub>	0	1	c
JZF	Jump/test Z-flag	1	0	1	1	d <sub>2</sub>	d <sub>1</sub>	d <sub>0</sub>	m <sub>8</sub>	m <sub>7</sub>	d <sub>2</sub>	d <sub>1</sub>	d <sub>0</sub>	m <sub>3</sub>	0	1	z
JPR	Jump/test PR-latches	1	1	0	0	d <sub>2</sub>	d <sub>1</sub>	d <sub>0</sub>	m <sub>8</sub>	m <sub>7</sub>	d <sub>2</sub>	d <sub>1</sub>	d <sub>0</sub>	p <sub>3</sub>	p <sub>2</sub>	p <sub>1</sub>	p <sub>0</sub>
JLL	Jump/test left PR bits	1	1	0	1	d <sub>2</sub>	d <sub>1</sub>	d <sub>0</sub>	m <sub>8</sub>	m <sub>7</sub>	d <sub>2</sub>	d <sub>1</sub>	d <sub>0</sub>	0	1	p <sub>3</sub>	p <sub>2</sub>
JRL	Jump/test right PR bits	1	1	1	1	1	d <sub>1</sub>	d <sub>0</sub>	m <sub>8</sub>	m <sub>7</sub>	1	d <sub>1</sub>	d <sub>0</sub>	1	1	p <sub>1</sub>	p <sub>0</sub>
JPX	Jump/test PX-bus	1	1	1	1	0	d <sub>1</sub>	d <sub>0</sub>	m <sub>8</sub>	m <sub>7</sub>	m <sub>6</sub>	d <sub>1</sub>	d <sub>0</sub>	x <sub>7</sub>	x <sub>6</sub>	x <sub>5</sub>	x <sub>4</sub>

## SYMBOL MEANING

d <sub>n</sub>	Data on address control line n
m <sub>n</sub>	Data in microprogram address register bit n
p <sub>n</sub>	Data in PR-latch bit n
x <sub>n</sub>	Data on PX-bus line n (active LOW)
f, c, z	Contents of F-latch, C-flag, or Z-flag, respectively

## APPENDIX B FLAG CONTROL FUNCTION SUMMARY

TYPE	MNEMONIC	DESCRIPTION	FC <sub>1</sub>	0
Flag Input	SCZ	Set C-flag and Z-flag to f	0	0
	STZ	Set Z-flag to f	0	1
	STC	Set C-flag to f	1	0
	HCZ	Hold C-flag and Z-flag	1	1

TYPE	MNEMONIC	DESCRIPTION	FC <sub>3</sub>	2
Flag Output	FF0	Force FO to 0	0	0
	FFC	Force FO to C-flag	0	1
	FFZ	Force FO to Z-flag	1	0
	FF1	Force FO to 1	1	1

LOAD FUNCTION	NEXT ROW				NEXT COL				
LD	MA <sub>8</sub>	7	6	5	4	MA <sub>3</sub>	2	1	0
0	see Appendix A				see Appendix A				
1	0	x <sub>3</sub>	x <sub>2</sub>	x <sub>1</sub>	x <sub>0</sub>	x <sub>7</sub>	x <sub>6</sub>	x <sub>5</sub>	x <sub>4</sub>

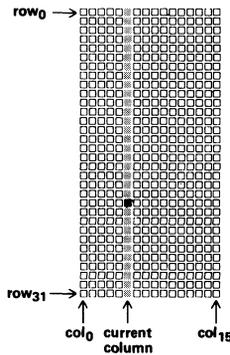
## SYMBOL MEANING

f	Contents of the F-latch
x <sub>n</sub>	Data on PX- or SX-bus line n (active LOW)

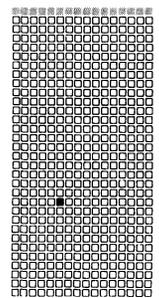
APPENDIX C JUMP SET DIAGRAMS

The following ten diagrams illustrate the jump set for each of the eleven jump and jump/test functions of the MCU. Location 341, indicated by the black square, represents one current row ( $row_{21}$ ) and current column ( $col_5$ ) address. The grey boxes indicate the microprogram locations that may be selected by the particular function as the next address.

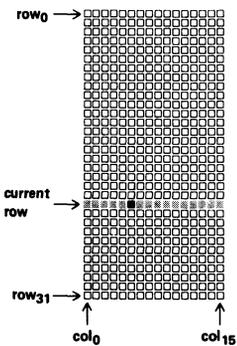
**JCC**  
Jump in Current Column



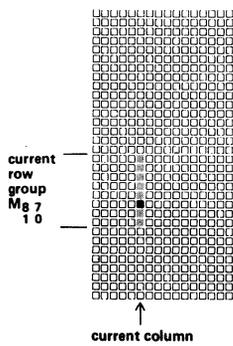
**JZR**  
Jump to Zero Row



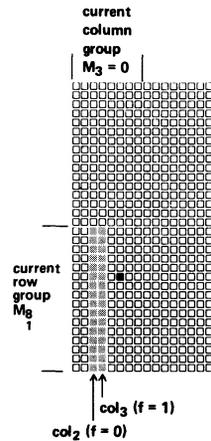
**JCR**  
Jump in Current Row



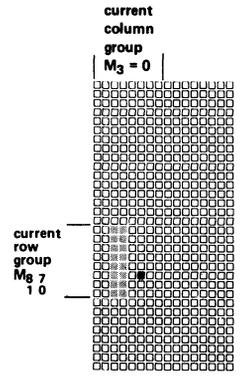
**JCE**  
Jump Column/Enable



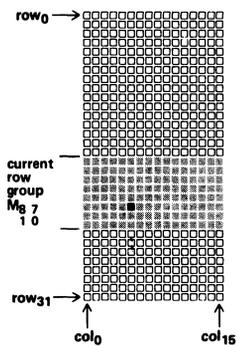
**JFL**  
Jump/Test F-Latch



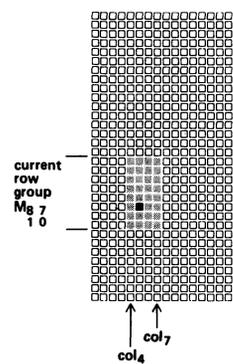
**JCF, JZF**  
Jump/Test C-Flag  
Jump/Test Z-Flag



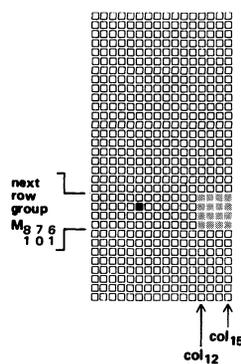
**JPR**  
Jump/Test PR-Latch



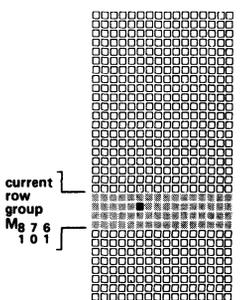
**JLL**  
Jump/Test Left Latch



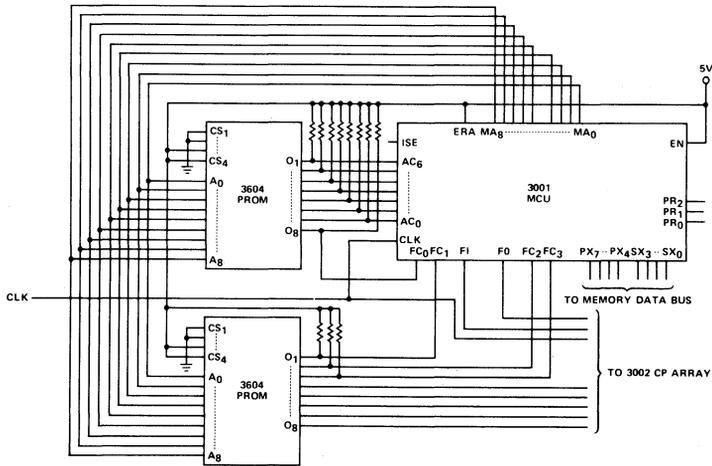
**JRL**  
Jump/Test Right Latch



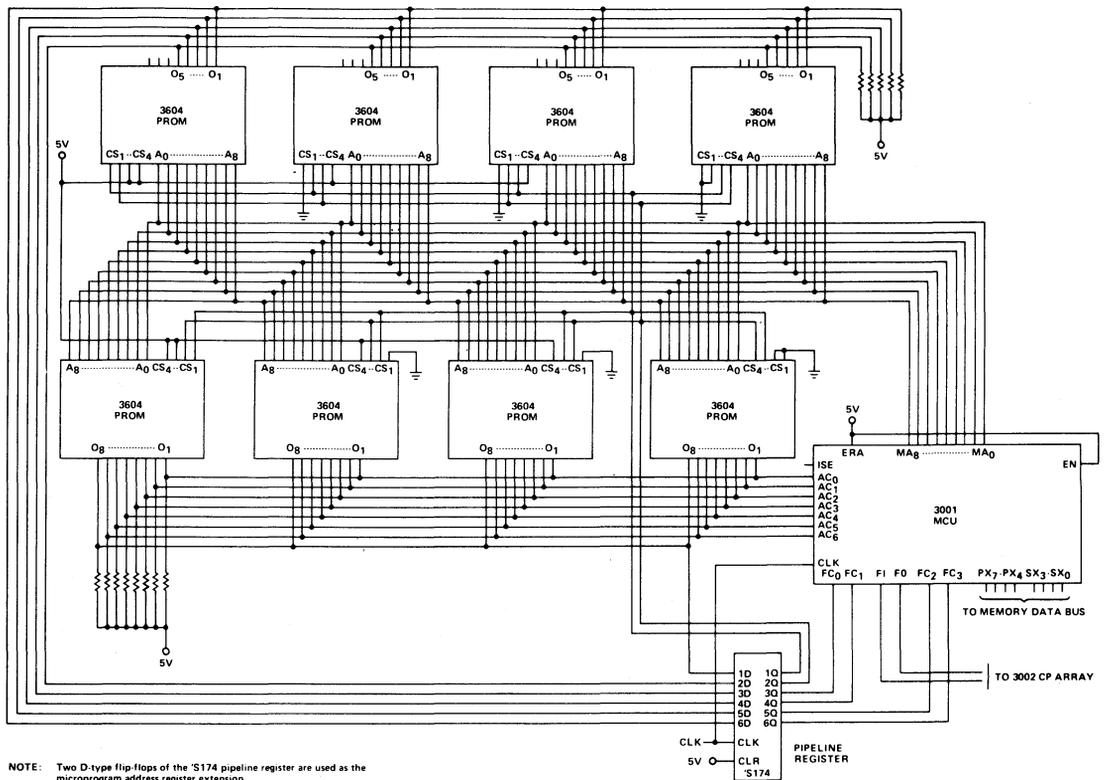
**JPX**  
Jump/Test PX-Bus



TYPICAL CONFIGURATIONS



Non-Pipelined Configuration with 512 Microinstruction Addressability



NOTE: Two D-type flip-flops of the 'S174 pipeline register are used as the microprogram address register extension.

Pipelined Configuration with 2048 Microinstruction Addressability



# SCHOTTKY BIPOLAR LSI MICROCOMPUTER SET

# 3002 CENTRAL PROCESSING ELEMENT

The INTEL® 3002 Central Processing Element contains all of the circuits that represent a 2-bit wide slice through the data processing section of a digital computer. To construct a complete central processor for a given word width N, it is simply necessary to connect an array of N/2 CPE's together. When wired together in such an array, a set of CPE's provide the following capabilities:

- 2's complement arithmetic
- Logical AND, OR, NOT and exclusive-OR
- Incrementing and decrementing
- Shifting left or right
- Bit testing and zero detection
- Carry look-ahead generation
- Multiple data and address busses

High Performance – 100 ns Cycle Time  
TTL and DTL Compatible

- N-Bit Word Expandable Multi-Bus Organization
- 3 Input Data Busses
- 2 Three-State Fully Buffered Output Data Busses
- 11 General Purpose Registers
- Full Function Accumulator
- Independent Memory Address Register
- Cascade Outputs for Full Carry Look-Ahead
- Versatile Functional Capability
- 8 Function Groups
- Over 40 Useful Functions
- Zero Detect and Bit Test

Single Clock  
28 Pin DIP

## PACKAGE CONFIGURATION

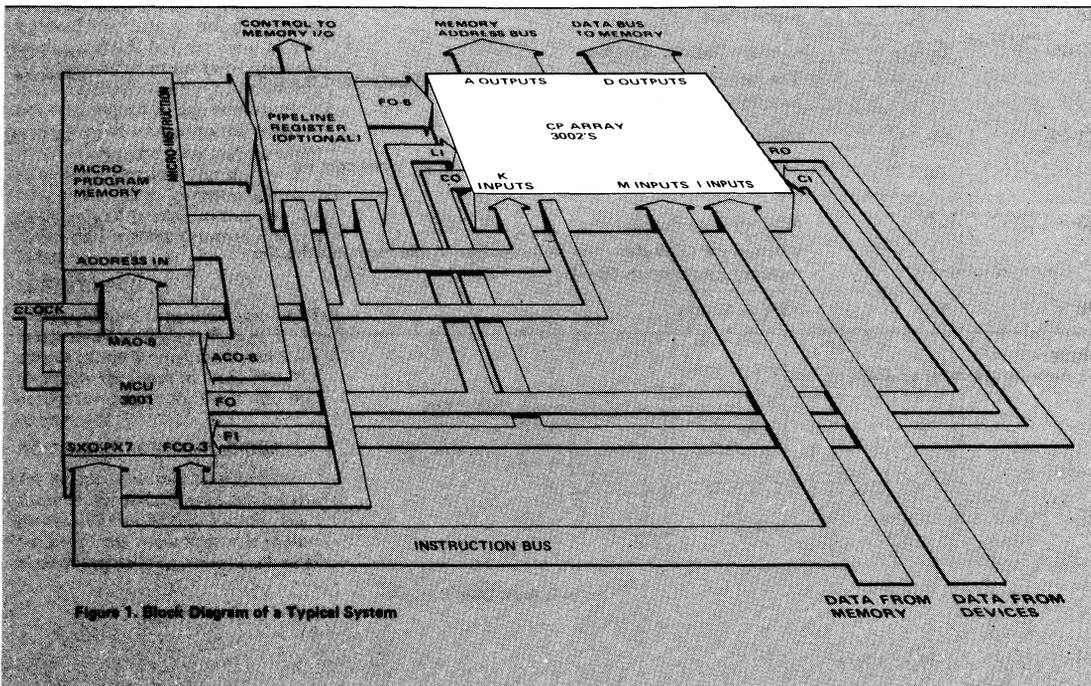
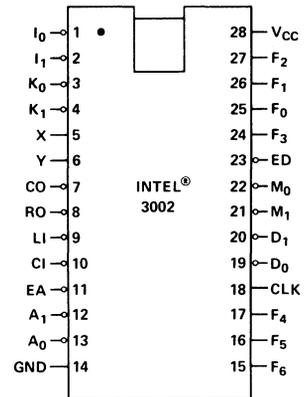


Figure 1. Block Diagram of a Typical System

## PIN DESCRIPTION

PIN	SYMBOL	NAME AND FUNCTION	TYPE <sup>(1)</sup>
1, 2	I <sub>0</sub> -I <sub>1</sub>	External Bus Inputs The external bus inputs provide a separate input port for external input devices.	Active LOW
3, 4	K <sub>0</sub> -K <sub>1</sub>	Mask Bus Inputs The mask bus inputs provide a separate input port for the microprogram memory, to allow mask or constant entry.	Active LOW
5, 6	X, Y	Standard Carry Look-Ahead Cascade Outputs The cascade outputs allow high speed arithmetic operations to be performed when they are used in conjunction with the INTEL 3003 Look-Ahead Carry Generator.	
7	CO	Ripple Carry Output The ripple carry output is only disabled during shift right operations.	Active LOW Three-state
8	RO	Shift Right Output The shift right output is only enabled during shift right operations.	Active LOW Three-state
9	LI	Shift Right Input	Active LOW
10	CI	Carry Input	Active LOW
11	EA	Memory Address Enable Input When in the LOW state, the memory address enable input enables the memory address outputs (A <sub>0</sub> -A <sub>1</sub> ).	Active LOW
12-13	A <sub>0</sub> -A <sub>1</sub>	Memory Address Bus Outputs The memory address bus outputs are the buffered outputs of the memory address register (MAR).	Active LOW Three-state
14	GND	Ground	
15-17, 24-27,	F <sub>0</sub> -F <sub>6</sub>	Micro-Function Bus Inputs The micro-function bus inputs control ALU function and register selection.	
18	CLK	Clock Input	
19-20	D <sub>0</sub> -D <sub>1</sub>	Memory Data Bus Outputs The memory data bus outputs are the buffered outputs of the full function accumulator register (AC).	Active LOW Three-state
21-22	M <sub>0</sub> -M <sub>1</sub>	Memory Data Bus Inputs The memory data bus inputs provide a separate input port for memory data.	Active LOW
23	ED	Memory Data Enable Input When in the LOW state, the memory data enable input enables the memory data outputs (D <sub>0</sub> -D <sub>1</sub> )	Active LOW
28	V <sub>CC</sub>	+5 Volt Supply	

## NOTE:

1. Active HIGH, unless otherwise specified.

## LOGICAL DESCRIPTION

The CPE provides the arithmetic, logic and register functions of a 2-bit wide slice through a microprogrammed central processor. Data from external sources such as main memory, is brought into the CPE on one of the three separate input busses. Data being sent out of the CPE to external devices is carried on either of the two output busses. Within the CPE, data is stored in one of eleven scratchpad registers or in the accumulator. Data from the input busses, the registers, or the accumulator is available to the arithmetic/logic section (ALS) under the control of two internal multiplexers. Additional inputs and outputs are included for carry propagation, shifting, and micro-function selection. The complete logical organization of the CPE is shown below.

### MICRO-FUNCTION BUS AND DECODER

The seven micro-function bus input lines of the CPE, designated  $F_0$ - $F_6$ , are decoded internally to select the ALS function, generate the scratchpad address, and control the A and B multiplexers.

### M-BUS AND I-BUS INPUTS

The M-bus inputs are arranged to bring data from an external main memory into the CPE. Data on the M-bus is multiplexed internally for input to the ALS.

The I-bus inputs are arranged to bring data from an external I/O system into the CPE. Data on the I-bus is also multiplexed internally, although independently of the M-bus, for input to the ALS. Separation of the two busses permits a relatively lightly loaded memory bus even though a large number of I/O devices are connected to the I-bus.

Alternatively, the I-bus may be wired to perform a multiple bit shift (e.g., a byte exchange) by connecting it to one of the output busses. In this case, I/O device data is gated externally onto the M-bus.

### SCRATCHPAD

The scratchpad contains eleven registers designated  $R_0$  through  $R_9$  and T. The output of the scratchpad is multiplexed internally for input to ALS. The ALS output is returned for input into the scratchpad.

### ACCUMULATOR AND D-BUS

An independent register called the accumulator (AC) is available for storing the result of an ALS operation. The output of the accumulator is multiplexed internally for input back to the

ALS and is also available via a three-state output buffer on the D-bus outputs. Conventional usage of the D-bus is for data being sent to the external main memory or to external I/O devices.

### A AND B MULTIPLEXERS

The A and B multiplexers select the two inputs to the ALS specified on the micro-function bus. Inputs to the A-multiplexer include the M-bus, the scratchpad, and the accumulator. The B-multiplexer selects either the I-bus, the accumulator, or the K-bus. The selected B-multiplexer input is always logically ANDed with the data on the K-bus (see below) to provide a flexible masking and bit testing capability.

### ALS AND K-BUS

The ALS is capable of a variety of arithmetic and logic operations, including 2's complement addition, incrementing, and decrementing, plus logical AND, inclusive-OR, exclusive-NOR, and logical complement. The result of an ALS operation may be stored in the accumulator or one of the scratchpad registers. Separate left input and right output lines, designated LI and RO, are available for use in right shift operations. Carry input and carry output lines, designated CI and CO are provided for normal ripple carry propaga-

tion. CO and RO data are brought out via two alternately enabled tri-state buffers. In addition, standard look ahead carry outputs, designated X and Y, are available for full carry look ahead across any word length.

The ability of the K-bus to mask inputs to the ALS greatly increases the versatility of the CPE. During non-arithmetic operations in which carry propagation has no meaning, the carry circuits are used to perform a word-wise inclusive-OR of the bits, masked by the K-bus, from the register or bus selected by the function decoder. Thus, the CPE provides a flexible bit testing capability. The K-bus is also used during arithmetic operations to mask portions of the field being operated upon. An additional function of the K-bus is that of supplying constants to the CPE from the microprogram.

### MEMORY ADDRESS REGISTER AND A-BUS

A separate ALS output is also available to the memory address register (MAR) and to the A-bus via a three-state output buffer. Conventional usage of the MAR and A-bus is for sending addresses to an external main memory. The MAR and A-bus may also be used to select an external device when executing I/O operations.

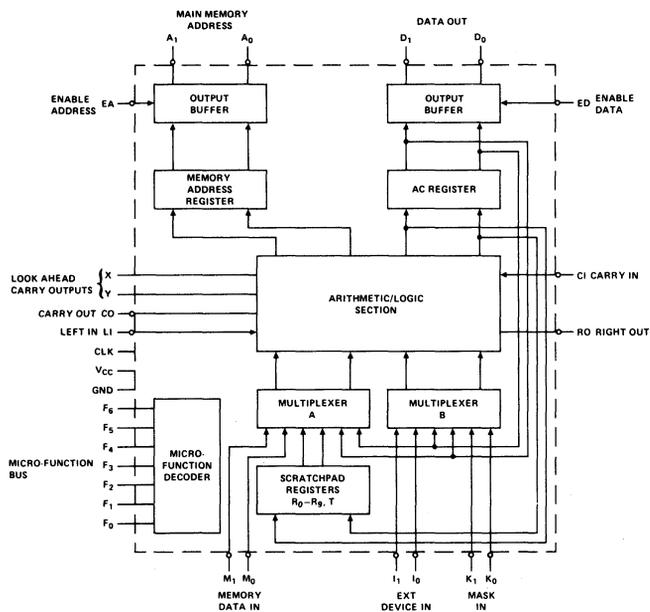


Figure 2. 3002 Block Diagram

## FUNCTIONAL DESCRIPTION

During each micro-cycle, a micro-function is applied to F-bus inputs of the CPE. The micro-function is decoded, the operands are selected by the multiplexers, and the specified operation is performed by ALS. If a negative going clock edge is applied, the result of the ALS operation is either deposited in the accumulator or written into the selected scratchpad register. In addition, certain operations permit related address data to be deposited in the MAR. A new micro-function should only be applied following the rising edge of the clock.

By externally gating the clock input to CPE, referred to as conditional clocking, the clock pulse may be selectively omitted during a micro-cycle. Since the carry, shift, and look-ahead circuits are not clocked, their outputs may be used to perform a variety of non-destructive tests on data in the accumulator or in the scratchpad. No register contents are modified by the operation due to the absence of the clock pulse.

The micro-function to be performed is determined from the function group (F-Group) and register group (R-Group) selected by the data on the F-bus. The F-Group is specified by the upper three bits of data,  $F_4$ - $F_6$ . The R-Group is specified by the lower four bits of data,  $F_0$ - $F_3$ . R-Group I contains  $R_0$  through  $R_9$ , T, and AC and is denoted by the symbol  $R_n$ . R-Group II and R-Group III contain only T and AC. F-Group and R-Group formats are summarized in Appendix A.

The following is a detailed explanation of each of the CPE micro-functions. A general functional description of each operation is given followed by two additional descriptions which explain the result of the micro-function with both K-bus inputs at logical 0 or both at logical 1. In most cases, the effect of placing the K-bus in the all-one or the all-zero state is to either select or de-select the accumulator in the operation, respectively. A micro-function mnemonic is included with each description for reference purposes and to assist in the design of micro-assembly languages. The micro-functions are summarized in Appendix A. The effective micro-functions for the all-zero and the all-one K-bus states are summarized in Appendix B.

<b>F-GROUP 0</b>	<b>R-GROUP I</b>	<b>F-GROUP 1</b>	<b>R-GROUP I</b>
Logically AND the contents of AC with the data on the K-bus. Add the result to the contents of $R_n$ and the value of the carry input (CI). Deposit the sum in AC and $R_n$ .		Logically OR the contents of $R_n$ with the data on the K-bus. Deposit the result in MAR. Add the data on the K-bus to contents of $R_n$ and CI. Deposit the result in $R_n$ .	
<b>ILR</b>	<b>K-BUS = 00</b>	<b>LMI</b>	<b>K-BUS = 00</b>
Conditionally increment $R_n$ and load the result in AC. Used to load AC from $R_n$ or to increment $R_n$ and load a copy of the result in AC.		Load MAR from $R_n$ . Conditionally increment $R_n$ . Used to maintain a macro-instruction program counter.	
<b>ALR</b>	<b>K-BUS = 11</b>	<b>DSM</b>	<b>K-BUS = 11</b>
Add AC and CI to $R_n$ and load the result in AC. Used to add AC to a register. If $R_n$ is AC, then AC is shifted left one bit position.		Set MAR to all one's. Conditionally decrement $R_n$ by one. Used to force MAR to its highest address and to decrement $R_n$ .	
<b>F-GROUP 0</b>	<b>R-GROUP II</b>	<b>F-GROUP 1</b>	<b>R-GROUP II</b>
Logically AND the contents of AC with the data on the K-bus. Add the result to CI and the data on the M-bus. Deposit the sum in AC or T, as specified.		Logically OR the data on the M-bus with the data on the K-bus. Deposit the result in MAR. Add the data on the K-bus to the data on the M-bus and CI. Deposit the sum in AC or T, as specified.	
<b>ACM</b>	<b>K-BUS = 00</b>	<b>LMM</b>	<b>K-BUS = 00</b>
Add CI to the data on the M-bus. Load the result in AC or T, as specified. Used to load memory data in the specified register, or to load incremented memory data in the specified register.		Load MAR from the M-bus. Add CI to the data on the M-bus. Deposit the result in AC or T. Used to load the address register with memory data for macro-instructions using indirect addressing.	
<b>AMA</b>	<b>K-BUS = 11</b>	<b>LDM</b>	<b>K-BUS = 11</b>
Add the data on the M-bus to AC and CI, and load the result in AC or T, as specified. Used to add memory data or incremented memory data to AC and store the sum in the specified register.		Set MAR to all ones. Subtract one from the data on the M-bus. Add CI to the difference and deposit the result in AC or T, as specified. Used to load decremented memory data in AC or T.	
<b>F-GROUP 0</b>	<b>R-GROUP III</b>	<b>F-GROUP 1</b>	<b>R-GROUP III</b>
(General description omitted, see Appendix A.)		Logically OR the data on the K-bus with the complement of the contents of AC or T, as specified. Add the result to the logical AND of the contents of specified register with the data on the K-bus. Add the sum to CI. Deposit the result in the specified register.	
<b>SRA</b>	<b>K-BUS = 00</b>	<b>CIA</b>	<b>K-BUS = 00</b>
Shift the contents of AC or T, as specified, right one bit position. Place the previous low order bit value on RO and fill the high order bit from the data on LI. Used to shift or rotate AC or T right one bit. (K-bus = 11 description omitted, see Appendix B.)		Add CI to the complement of the contents of AC or T, as specified. Deposit the result in the specified register. Used to form the 1's or 2's complement of AC or T.	
		<b>DCA</b>	<b>K-BUS = 11</b>
		Subtract one from the contents of AC or T, as specified. Add CI to the difference and deposit the sum in the specified register. Used to decrement AC or T.	

## FUNCTIONAL DESCRIPTION (con't)

<b>F-GROUP 2</b> Logically AND the data on the K-bus with the contents of AC. Subtract one from the result and add the difference to CI. Deposit the sum in $R_n$ .	<b>R-GROUP I</b> <b>CSR</b> K-BUS = 00 Subtract one from CI and deposit the difference in $R_n$ . Used to conditionally clear or set $R_n$ to all 0's or 1's, respectively. <b>SDR</b> K-BUS = 11 Subtract one from AC and add the difference to CI. Deposit the sum in $R_n$ . Used to store AC in $R_n$ or to store the decremented value of AC in $R_n$ .	<b>F-GROUP 3</b> Logically AND the contents of AC with the data on the K-bus. Add the contents of $R_n$ and CI to the result. Deposit the sum in $R_n$ . <b>INR</b> K-BUS = 00 Add CI to the contents of $R_n$ and deposit the sum in $R_n$ . Used to increment $R_n$ . <b>ADR</b> K-BUS = 11 Add the contents of AC to $R_n$ . Add the result to CI and deposit the sum in $R_n$ . Used to add the accumulator to a register or to add the incremented value of the accumulator to a register.	<b>R-GROUP I</b>	<b>F-GROUP 4</b> Logically AND the data on the K-bus with the contents of AC. Logically AND the result with the data on the M-bus. Deposit the final result in AC or T, as specified. Logically OR the value of CI with the word-wise OR of the bits of the final result. Place the value of the carry OR on CO. <b>CLA</b> K-BUS = 00 Clear AC or T, as specified, to all 0's. Force CO to CI. Used to clear the specified register and force CO to CI. <b>ANM</b> K-BUS = 11 Logically AND the data on the M-bus with the contents of AC. Deposit the result in AC or T, as specified. Force CO to one if the result is non-zero. Used to AND M-bus data to the accumulator and test for a zero result.	<b>R-GROUP II</b>
<b>F-GROUP 2</b> Logically AND the data on the K-bus with the contents of AC. Subtract one from the result and add the difference to CI. Deposit the sum in AC or T, as specified. <b>CSA</b> K-BUS = 00 Subtract one from CI and deposit the difference in AC or T, as specified. Used to conditionally clear or set AC or T. <b>SDA</b> K-BUS = 11 Subtract one from AC and add the difference to CI. Deposit the sum in AC or T, as specified. Used to store AC in T, or decrement AC, or store the decremented value of AC in T.	<b>R-GROUP II</b>	<b>F-GROUP 3</b> (All descriptions omitted, identical to F-Group O/R-Group II described above.) <b>F-GROUP 3</b> <b>R-GROUP III</b> Logically AND the data on the K-bus with the data on the I-bus. Add CI and the contents of AC or T, as specified, to the result. Deposit the sum in the specified register. <b>INA</b> K-BUS = 00 Conditionally increment the contents of AC or T, as specified. Used to increment AC or T. <b>AIA</b> K-BUS = 11 Add the data on the I-bus to the contents of AC or T, as specified. Add CI to the result and deposit the sum in the specified register. Used to add input data or incremented input data to the specified register.	<b>R-GROUP II</b>	<b>F-GROUP 4</b> <b>R-GROUP III</b> Logically AND the data on the I-bus with the data on the K-bus. Logically AND the result with the contents of AC or T, as specified. Deposit the final result in the specified register. Logically OR CI with the word-wise OR of the bits of the final result. Place the value of the carry OR on CO. (K-bus = 00 description omitted, see CLA above.) <b>ANI</b> K-BUS = 11 Logically AND the data on the I-bus with the contents of AC or T, as specified. Deposit the result in the specified register. Force CO to one if the result is non-zero. Used to AND the I-bus to the accumulator and test for a zero result.	
<b>F-GROUP 2</b> Logically AND the data of the K-bus with the data on the I-bus. Subtract one from the result and add the difference to CI. Deposit the sum in AC or T, as specified. (K-bus = 00 description omitted, see CSA above.) <b>LDI</b> K-BUS = 11 Subtract one from the data on the I-bus and add the difference to CI. Deposit the sum in AC or T, as specified. Used to load input bus data or decremented input bus data in the specified register.	<b>R-GROUP III</b>	<b>F-GROUP 4</b> <b>R-GROUP I</b> Logically AND the data on the K-bus with the contents of AC. Logically AND the result with the contents of $R_n$ . Deposit the final result in $R_n$ . Logically OR the value of CI with the word-wise OR of the bits of the final result. Place the value of the carry OR on the carry output (CO) line. <b>CLR</b> K-BUS = 00 Clear $R_n$ to all 0's. Force CO to CI. Used to clear a register and force CO to CI. <b>ANR</b> K-BUS = 11 Logically AND AC with $R_n$ . Deposit the result in $R_n$ . Force CO to one if the result is non-zero. Used to AND the accumulator with a register and test for a zero result.	<b>R-GROUP I</b>	<b>F-GROUP 5</b> <b>R-GROUP I</b> Logically AND the data on the K-bus with the contents of $R_n$ . Deposit the result in $R_n$ . Logically OR CI with the word-wise OR of the result. Place the value of the carry OR on CO. (K-bus = 00 description omitted, see CLR above.) <b>TZR</b> K-BUS = 11 Force CO to one if $R_n$ is non-zero. Used to test a register for zero. Also used to AND K-bus data with a register (see general description) for masking and, optionally, testing for a zero result.	

## FUNCTIONAL DESCRIPTION (con't)

<b>F-GROUP 5</b> Logically AND the data on the K-bus with the data on the M-bus. Deposit the result in AC or T, as specified. Logically OR CI with the word-wise OR of the result. Place the value of the carry OR on CO. (K-bus = 00 description omitted, see CLA above.)	<b>R-GROUP II</b>	<b>F-GROUP 6</b> Logically OR CI with the word-wise OR of the logical AND of AC and the data on the K-bus. Place the value of the carry OR on CO. Logically OR the data on the M-bus, with the logical AND of AC and the data on the K-bus. Deposit the final result in AC or T, as specified.	<b>R-GROUP II</b>	<b>XNR</b> Force CO to one if the logical AND of AC and $R_n$ is non-zero. Exclusive-NOR the contents of AC with the contents of $R_n$ . Deposit the result in $R_n$ . Used to exclusive-NOR the accumulator with a register.	<b>K-BUS = 11</b>
<b>LTM</b> Load AC or T, as specified, with data from the M-bus. Force CO to one if the result is non-zero. Used to load the specified register from memory and test for a zero result. Also used to AND K-bus data with M-bus data (see general description) for masking and, optionally, testing for a zero result.	<b>K-BUS = 11</b>	<b>LMF</b> Load AC or T, as specified, from the M-bus. Force CO to CI. Used to load the specified register with memory data and force CO to CI.	<b>K-BUS = 00</b>	<b>F-GROUP 7</b> Logically OR CI with the word-wise OR of the logical AND of the contents of AC and the data on the K-bus and M-bus. Place the value of the carry OR on CO. Logically AND the data on the K-bus with the contents of AC. Exclusive-NOR the result with the data on the M-bus. Deposit the final result in AC or T, as specified.	<b>R-GROUP II</b>
<b>F-GROUP 5</b> Logically AND the data on K-bus with contents of AC or T, as specified. Deposit the result in the specified register. Logically OR CI with the word-wise OR of the result. Place the value of the carry OR on CO. (K-bus = 00 description omitted, see CLA above.)	<b>R-GROUP III</b>	<b>ORM</b> Force CO to one if AC is non-zero. Logically OR the data on the M-bus with the contents of AC. Deposit the result in AC or T, as specified. Used to OR memory data with the accumulator and, optionally, test the previous value of the accumulator for zero.	<b>K-BUS = 11</b>	<b>LCM</b> Load the complement of the data on the M-bus into AC or T, as specified. Force CO to CI.	<b>K-BUS = 00</b>
<b>TZA</b> Force CO to one if AC or T, as specified, is non-zero. Used to test the specified register for zero. Also used to AND K-bus data to the specified register (see general description) for masking and, optionally, testing for a zero result.	<b>K-BUS = 11</b>	<b>F-GROUP 6</b> Logically OR CI with the word-wise OR of the logical AND of the data on the I-bus and the data on the K-bus. Place the value of the carry OR on CO. Logically AND the data on the K-bus with the data on the I-bus. Logically OR the result with the contents of AC or T, as specified. Deposit the final result in the specified register. (K-bus = 00 description omitted, see NOP above.)	<b>R-GROUP III</b>	<b>XNM</b> Force CO to one if the logical AND of AC and the M-bus data is non-zero. Exclusive-NOR the contents of AC with the data on the M-bus. Deposit the result in AC or T, as specified. Used to exclusive-NOR memory data with the accumulator.	<b>K-BUS = 11</b>
<b>F-GROUP 6</b> Logically OR CI with the word-wise OR of the logical AND of AC and the data on the K-bus. Place the result of the carry OR on CO. Logically OR the contents of $R_n$ with the logical AND of AC and the data on the K-bus. Deposit the result in $R_n$ .	<b>R-GROUP I</b>	<b>ORI</b> Force CO to one if the data on the I-bus is non-zero. Logically OR the data on the I-bus to the contents of AC or T, as specified. Deposit the result in the specified register. Used to OR I-bus data with the specified register and, optionally, test the I-bus data for zero.	<b>K-BUS = 11</b>	<b>F-GROUP 7</b> Logically OR CI with the word-wise OR of the logical AND of the contents of the specified register and the data on the I-bus and K-bus. Place the value of the carry OR on CO. Logically AND the data on the K-bus with the data on the I-bus. Exclusive-NOR the result with the contents of AC or T, as specified. Deposit the final result in the specified register.	<b>R-GROUP III</b>
<b>NOP</b> Force CO to CI. Used as a null operation or to force CO to CI.	<b>K-BUS = 00</b>	<b>F-GROUP 7</b> Logically OR CI with the word-wise OR of the logical AND of the contents of $R_n$ and AC and the data on the K-bus. Place the value of the carry OR on CO. Logically AND the data on the K-bus with the contents of AC. Exclusive-NOR the result with the contents of $R_n$ . Deposit the final result in $R_n$ .	<b>R-GROUP I</b>	<b>CMA</b> Complement AC or T, as specified. Force CO to CI.	<b>K-BUS = 00</b>
<b>ORR</b> Force CO to one if AC is non-zero. Logically OR the contents of the accumulator to the contents of $R_n$ . Deposit the result in $R_n$ . Used to OR the accumulator to a register and, optionally, test the previous accumulator value for zero.	<b>K-BUS = 11</b>	<b>CMR</b> Complement the contents of $R_n$ . Force CO to CI.	<b>K-BUS = 00</b>	<b>XNI</b> Force CO to one if the logical AND of the contents of AC or T, as specified, and the I-bus data is non-zero. Exclusive-NOR the contents of the specified register with the data on the I-bus. Deposit the result in AC or T, as specified. Used to exclusive-NOR input data with the accumulator.	<b>K-BUS = 11</b>

## D.C. AND OPERATING CHARACTERISTICS

## ABSOLUTE MAXIMUM RATINGS\*

Temperature Under Bias	0°C to 70°C
Storage Temperature	-65°C to +160°C
All Output and Supply Voltages	-0.5V to +7V
All Input Voltages	-1.0V to +5.5V
Output Currents	100 mA

\*COMMENT: Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum ratings for extended periods may effect device reliability.

$T_A = 0^\circ\text{C to } +70^\circ\text{C}$ ,  $V_{CC} = 5.0\text{V} \pm 5\%$

SYMBOL	PARAMETER	LIMITS			UNIT	CONDITIONS
		MIN	TYP <sup>(1)</sup>	MAX		
$V_C$	Input Clamp Voltage (All Input Pins)		-0.8	-1.0	V	$I_C = -5 \text{ mA}$
$I_F$	Input Load Current:					
	$F_0$ - $F_6$ , CLK, $K_0$ , $K_1$ , EA, ED		-0.05	-0.25	mA	$V_F = 0.45\text{V}$
	$I_0$ , $I_1$ , $M_0$ , $M_1$ , LI		-0.85	-1.5	mA	
$I_R$	Input Leakage Current:					
	$F_0$ - $F_6$ , CLK, $K_0$ , $K_1$ , EA, ED			40	$\mu\text{A}$	$V_R = 5.25\text{V}$
	$I_0$ , $I_1$ , $M_0$ , $M_1$ , LI			60	$\mu\text{A}$	
	CI			180	$\mu\text{A}$	
$V_{IL}$	Input Low Voltage			0.8	V	$V_{CC} = 5.0\text{V}$
$V_{IH}$	Input High Voltage	2.0			V	
$I_{CC}$	Power Supply Current <sup>(2)</sup>		145	190	mA	
$V_{OL}$	Output Low Voltage (All Output Pins)		0.3	0.45	V	$I_{OL} = 10 \text{ mA}$
$V_{OH}$	Output High Voltage (All Output Pins)	2.4	3.0		V	$I_{OH} = -1 \text{ mA}$
$I_{OS}$	Short Circuit Output Current (All Output Pins)	-15	-25	-60	mA	$V_{CC} = 5.0\text{V}$
$I_{O(off)}$	Off State Output Current			-100	$\mu\text{A}$	$V_O = 0.45\text{V}$
	$A_0$ , $A_1$ , $D_0$ , $D_1$ , CO and RO			100	$\mu\text{A}$	$V_O = 5.25\text{V}$

## NOTES:

(1) Typical values are for  $T_A = 25^\circ\text{C}$  and nominal supply voltage

(2) CLK input grounded, other inputs open.

## A.C. CHARACTERISTICS AND WAVEFORMS

 $T_A = 0^\circ\text{C to } 70^\circ\text{C}, V_{CC} = 5\text{V} \pm 5\%$ 

SYMBOL	PARAMETER	MIN	TYP <sup>(1)</sup>	MAX	UNIT
$t_{CY}$	Clock Cycle Time <sup>(2)</sup>	100	70		ns
$t_{WP}$	Clock Pulse Width	33	20		ns
$t_{FS}$	Function Input Set-Up Time ( $F_0$ through $F_6$ )	60	40		ns
$t_{DS}$	Data Set-Up Time:				
$t_{SS}$	$I_0, I_1, M_0, M_1, K_0, K_1$ LI, CI	50 27	30 13		ns ns
$t_{FH}$	Data and Function Hold Time:				
$t_{DH}$	$F_0$ through $F_6$	5	-2		ns
$t_{SH}$	$I_0, I_1, M_0, M_1, K_0, K_1$ LI, CI	5 15	-4 2		ns ns
$t_{XF}$	Propagation Delay to X, Y, RO from: Any Function Input		37	52	ns
$t_{XD}$	Any Data Input		29	42	ns
$t_{XT}$	Trailing Edge of CLK		40	60	ns
$t_{XL}$	Leading Edge of CLK	20			ns
$t_{CL}$	Propagation Delay to CO from: Leading Edge of CLK	20			ns
$t_{CT}$	Trailing Edge of CLK		48	70	ns
$t_{CF}$	Any Function Input		43	65	ns
$t_{CD}$	Any Data Input		30	55	ns
$t_{CC}$	CI (Ripple Carry)		14	25	ns
$t_{DL}$	Propagation Delay to $A_0, A_1, D_0, D_1$ from: Leading Edge of CLK	5	32	50	ns
$t_{DE}$	Enable Input ED, EA		12	25	ns

## NOTE:

(1) Typical values are for  $T_A = 25^\circ\text{C}$  and nominal supply voltage.(2)  $t_{CY} = t_{DS} + t_{DL}$ .

## TEST CONDITIONS:

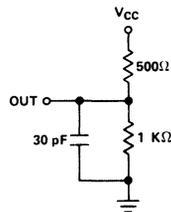
Input pulse amplitude: 2.5 V

Input rise and fall times of 5 ns between 1 and 2 volts.

Output loading is 10 mA and 30 pF.

Speed measurements are made at 1.5 volt levels.

## TEST LOAD CIRCUIT:

CAPACITANCE<sup>(2)</sup>  $T_A = 25^\circ\text{C}$ 

SYMBOL	PARAMETER	MIN	TYP	MAX	UNIT
$C_{IN}$	Input Capacitance		5	10	pF
$C_{OUT}$	Output Capacitance		6	12	pF

## NOTE:

(2) This parameter is periodically sampled and is not 100% tested. Condition of measurement is  $f = 1\text{ MHz}$ ,  $V_{BIAS} = 2.5\text{V}$ ,  $V_{CC} = 5.0\text{V}$  and  $T_A = 25^\circ\text{C}$ .

## D.C. AND OPERATING CHARACTERISTICS

## ABSOLUTE MAXIMUM RATINGS\*

Temperature Under Bias	-55°C to +125°C
Storage Temperature	-65°C to +160°C
All Output and Supply Voltages	-0.5V to +7V
All Input Voltages	-1.0V to +5.5V
Output Currents	100 mA

\*COMMENT: Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum ratings for extended periods may effect device reliability.

$T_A = -55^\circ\text{C}$  to  $+125^\circ\text{C}$ ,  $V_{CC} = 5.0\text{V} \pm 10\%$ .

SYMBOL	PARAMETER	LIMITS			UNIT	CONDITIONS
		MIN	TYP <sup>(1)</sup>	MAX		
$V_C$	Input Clamp Voltage (All Input Pins)		-0.8	-1.2	V	$I_C = -5\text{ mA}$
$I_F$	Input Load Current:					
	$F_0$ - $F_6$ , CLK, $K_0$ , $K_1$ , EA, ED		-0.05	-0.25	mA	$V_F = 0.45\text{V}$
	$I_0$ , $I_1$ , $M_0$ , $M_1$ , LI		-0.85	-1.5	mA	
	CI		-2.3	-4.0	mA	
$I_R$	Input Leakage Current:					
	$F_0$ - $F_6$ , CLK, $K_0$ , $K_1$ , EA, ED			40	$\mu\text{A}$	$V_R = 5.5\text{V}$
	$I_0$ , $I_1$ , $M_0$ , $M_1$ , LI			100	$\mu\text{A}$	
	CI			250	$\mu\text{A}$	
$V_{IL}$	Input Low Voltage			0.8	V	$V_{CC} = 5.0\text{V}$
$V_{IH}$	Input High Voltage	2.0			V	
$I_{CC}$	Power Supply Current		145	210	mA	
$V_{OL}$	Output Low Voltage (All Output Pins)		0.3	0.45	V	$I_{OL} = 10\text{ mA}$
$V_{OH}$	Output High Voltage (All Output Pins)	2.4	3.0		V	$I_{OH} = -1\text{ mA}$
$I_{OS}$	Short Circuit Output Current (All Output Pins)	-15	-25	-60	mA	$V_{CC} = 5.0\text{V}$
$I_{O(off)}$	Off State Output Current			-100	$\mu\text{A}$	$V_O = 0.45\text{V}$
	$A_0$ , $A_1$ , $D_0$ , $D_1$ , CO and RO			100	$\mu\text{A}$	$V_O = 5.5\text{V}$

## NOTES:

(1) Typical values are for  $T_A = 25^\circ\text{C}$  and nominal supply voltage

(2) CLK input grounded, other inputs open.

## A.C. CHARACTERISTICS AND WAVEFORMS

$T_A = -55^\circ\text{C}$  to  $+125^\circ\text{C}$ ,  $V_{CC} = 5.0\text{V} \pm 10\%$ .

SYMBOL	PARAMETER	MIN	TYP <sup>(1)</sup>	MAX	UNIT
$t_{CY}$	Clock Cycle Time <sup>[2]</sup>	120	70		ns
$t_{WP}$	Clock Pulse Width	42	20		ns
$t_{FS}$	Function Input Set-Up Time ( $F_0$ through $F_6$ )	70	40		ns
$t_{DS}$	Data Set-Up Time:				
$t_{SS}$	$I_0, I_1, M_0, M_1, K_0, K_1$ $LI, CI$	60 30	30 13		ns ns
$t_{FH}$	Data and Function Hold Time:				
$t_{DH}$	$F_0$ through $F_6$	5	-2		ns
$t_{SH}$	$I_0, I_1, M_0, M_1, K_0, K_1$ $LI, CI$	5 15	-4 2		ns ns
$t_{XF}$	Propagation Delay to X, Y, RO from: Any Function Input		37	65	ns
$t_{XD}$	Any Data Input		29	55	ns
$t_{XT}$	Trailing Edge of CLK		40	75	ns
$t_{XL}$	Leading Edge of CLK	22			ns
$t_{CL}$	Propagation Delay to CO from: Leading Edge of CLK	22			ns
$t_{CT}$	Trailing Edge of CLK		48	85	ns
$t_{CF}$	Any Function Input		43	75	ns
$t_{CD}$	Any Data Input		30	65	ns
$t_{CC}$	CI (Ripple Carry)		14	30	ns
$t_{DL}$	Propagation Delay to $A_0, A_1, D_0, D_1$ from: Leading Edge of CLK	5	32	60	ns
$t_{DE}$	Enable Input ED, EA		12	35	ns

## NOTE:

(1) Typical values are for  $T_A = 25^\circ\text{C}$  and nominal supply voltage.

(2)  $t_{CY} = t_{DS} + t_{DL}$

## TEST CONDITIONS:

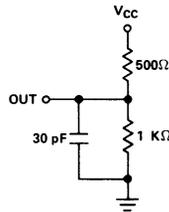
Input pulse amplitude: 2.5 V

Input rise and fall times of 5 ns between 1 and 2 volts.

Output loading is 10 mA and 30 pF.

Speed measurements are made at 1.5 volt levels.

## TEST LOAD CIRCUIT:

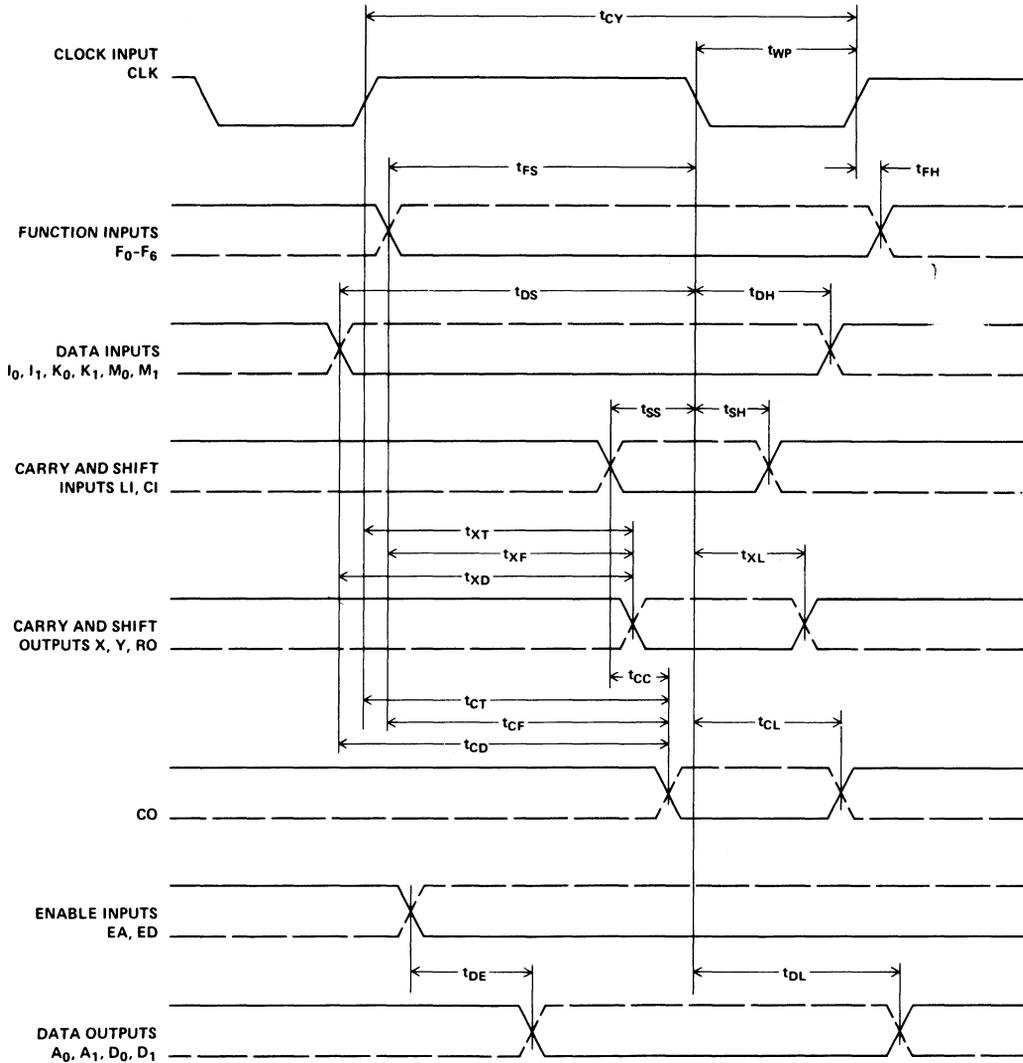
CAPACITANCE<sup>(2)</sup>  $T_A = 25^\circ\text{C}$ 

SYMBOL	PARAMETER	MIN	TYP	MAX	UNIT
$C_{IN}$	Input Capacitance		5	10	pF
$C_{OUT}$	Output Capacitance		6	12	pF

## NOTE:

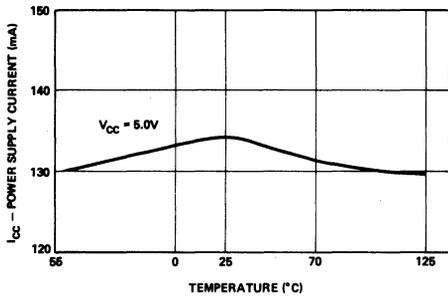
(2) This parameter is periodically sampled and is not 100% tested. Condition of measurement is  $f = 1\text{ MHz}$ ,  $V_{BIAS} = 2.5\text{V}$ ,  $V_{CC} = 5.0\text{V}$  and  $T_A = 25^\circ\text{C}$ .

3002 WAVEFORMS

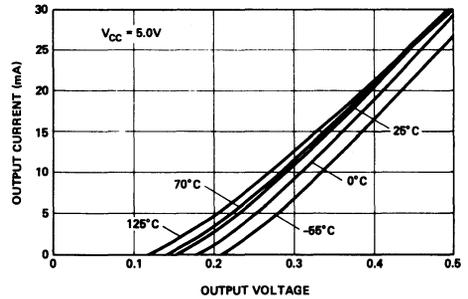


TYPICAL AC AND DC CHARACTERISTICS

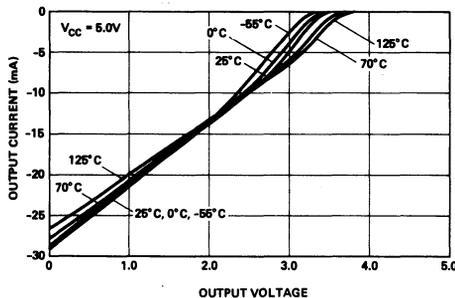
POWER SUPPLY CURRENT VS. TEMPERATURE



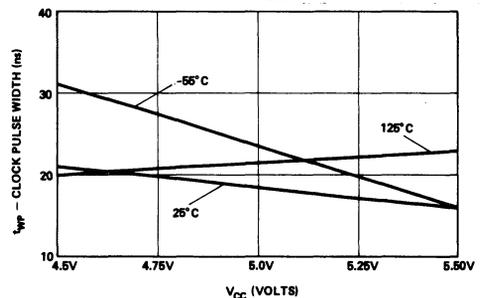
OUTPUT CURRENT VS. OUTPUT LOW VOLTAGE



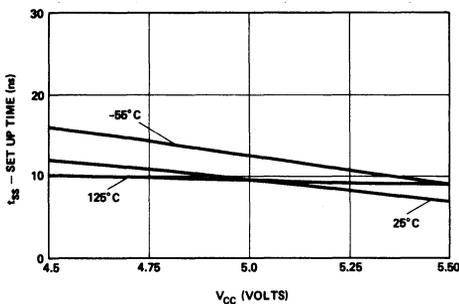
OUTPUT CURRENT VS. OUTPUT VOLTAGE



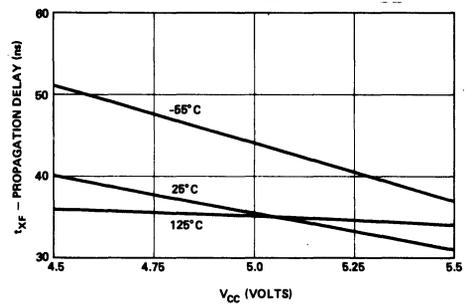
CLOCK PULSE WIDE VS. Vcc AND TEMPERATURE



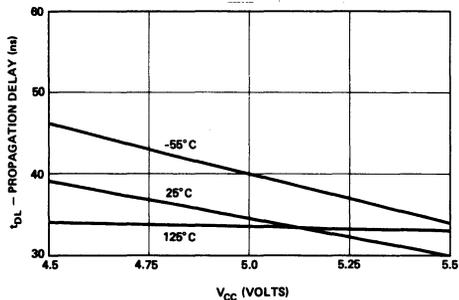
CARRY IN SET UP TIME VS. Vcc AND TEMPERATURE



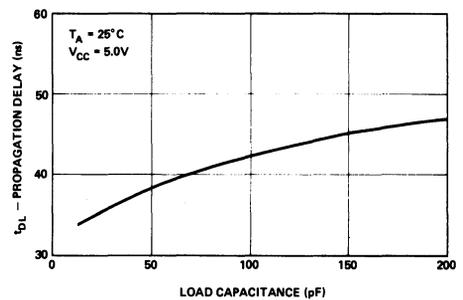
PROPAGATION DELAY FROM FUNCTION INPUTS TO CASCADE OUTPUTS VS. Vcc AND TEMPERATURE



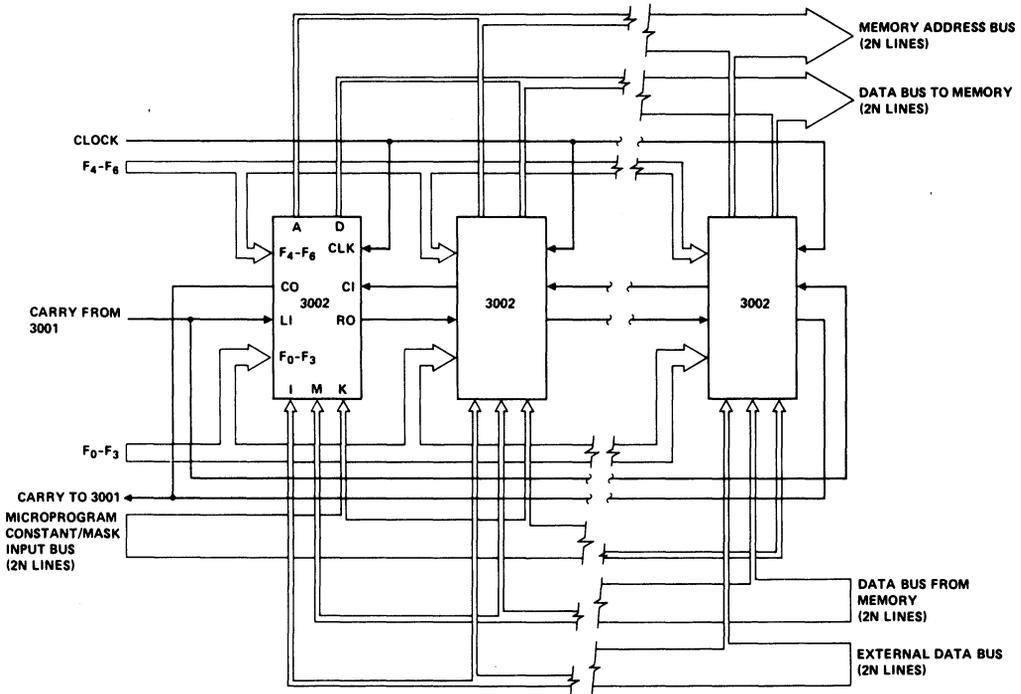
PROPAGATION DELAY - CLOCK TO "A" AND "D" DATA OUTPUT VS. Vcc AND TEMPERATURE



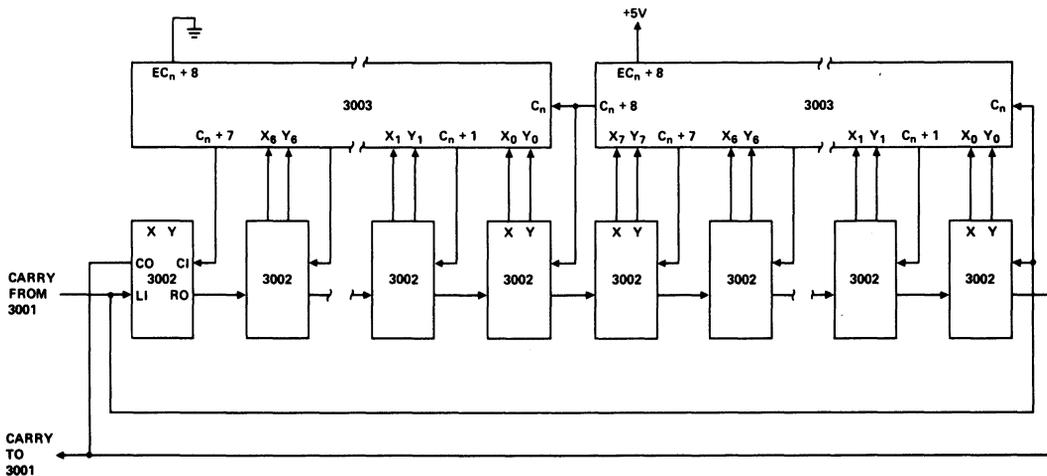
PROPAGATION DELAY - CLOCK TO "A" AND "D" DATA OUTPUT VS. LOAD CAPACITANCE



TYPICAL CONFIGURATIONS



Ripple-Carry Configuration  
(N 3002 CPE's)



Carry Look-Ahead Configuration  
With Ripple Through the Left Slice  
(32 Bit Array)

## APPENDIX A MICRO-FUNCTION SUMMARY

F-GROUP	R-GROUP	MICRO-FUNCTION
0	I	$R_n + (AC \wedge K) + CI \rightarrow R_n, AC$
	II	$M + (AC \wedge K) + CI \rightarrow AT$
	III	$AT_L \wedge (\overline{I_L} \wedge K_L) \rightarrow RO$ $LI \vee [(I_H \wedge K_H) \wedge AT_H] \rightarrow AT_H$ $[AT_L \wedge (\overline{I_L} \wedge K_L)] \vee [AT_H \vee (I_H \wedge K_H)] \rightarrow AT_L$
1	I	$K \vee R_n \rightarrow MAR$ $R_n + K + CI \rightarrow R_n$
	II	$K \vee M \rightarrow MAR$ $M + K + CI \rightarrow AT$
	III	$(\overline{AT} \vee K) + (AT \wedge K) + CI \rightarrow AT$
2	I	$(AC \wedge K) - 1 + CI \rightarrow R_n$
	II	$(AC \wedge K) - 1 + CI \rightarrow AT$
	III	$(I \wedge K) - 1 + CI \rightarrow AT$
3	I	$R_n + (AC \wedge K) + CI \rightarrow R_n$
	II	$M + (AC \wedge K) + CI \rightarrow AT$
	III	$AT + (I \wedge K) + CI \rightarrow AT$
4	I	$CI \vee (R_n \wedge AC \wedge K) \rightarrow CO$ $R_n \wedge (AC \wedge K) \rightarrow R_n$
	II	$CI \vee (M \wedge AC \wedge K) \rightarrow CO$ $M \wedge (AC \wedge K) \rightarrow AT$
	III	$CI \vee (AT \wedge I \wedge K) \rightarrow CO$ $AT \wedge (I \wedge K) \rightarrow AT$
5	I	$CI \vee (R_n \wedge K) \rightarrow CO$ $K \wedge R_n \rightarrow R_n$
	II	$CI \vee (M \wedge K) \rightarrow CO$ $K \wedge M \rightarrow AT$
	III	$CI \vee (AT \wedge K) \rightarrow CO$ $K \wedge AT \rightarrow AT$
6	I	$CI \vee (AC \wedge K) \rightarrow CO$ $R_n \vee (AC \wedge K) \rightarrow R_n$
	II	$CI \vee (AC \wedge K) \rightarrow CO$ $M \vee (AC \wedge K) \rightarrow AT$
	III	$CI \vee (I \wedge K) \rightarrow CO$ $AT \vee (I \wedge K) \rightarrow AT$
7	I	$CI \vee (R_n \wedge AC \wedge K) \rightarrow CO$ $R_n \overline{\oplus} (AC \wedge K) \rightarrow R_n$
	II	$CI \vee (M \wedge AC \wedge K) \rightarrow CO$ $M \overline{\oplus} (AC \wedge K) \rightarrow AT$
	III	$CI \vee (AT \wedge I \wedge K) \rightarrow CO$ $AT \overline{\oplus} (I \wedge K) \rightarrow AT$

## NOTES:

- 2's complement arithmetic adds 111 . . . 11 to perform subtraction of 000 . . . 01.
- $R_n$  includes T and AC as source and destination registers in R-group 1 micro-functions.
- Standard arithmetic carry output values are generated in F-group 0, 1, 2 and 3 instructions.

SYMBOL	MEANING
I, K, M	Data on the I, K, and M busses, respectively
CI, LI	Data on the carry input and left input, respectively
CO, RO	Data on the carry output and right output, respectively
$R_n$	Contents of register n including T and AC (R-Group I)
AC	Contents of the accumulator
AT	Contents of AC or T, as specified
MAR	Contents of the memory address register
L, H	As subscripts, designate low and high order bit, respectively
+	2's complement addition
-	2's complement subtraction
$\wedge$	Logical AND
$\vee$	Logical OR
$\overline{\oplus}$	Exclusive-NOR
$\rightarrow$	Deposit into

## APPENDIX B ALL-ZERO AND ALL-ONE K-BUS MICRO-FUNCTIONS

K-BUS = 00 MICRO-FUNCTION	MNEMONIC	K-BUS = 11 MICRO-FUNCTION	MNEMONIC
$R_n + CI \rightarrow R_n, AC$	ILR	$AC + R_n + CI \rightarrow R_n, AC$	ALR
$M + CI \rightarrow AT$	ACM	$M + AC + CI \rightarrow AT$	AMA
$AT_L \rightarrow RO \quad AT_H \rightarrow AT_L \quad LI \rightarrow AT_H$	SRA	(See Appendix A)	—
$R_n \rightarrow MAR \quad R_n + CI \rightarrow R_n$	LMI	$11 \rightarrow MAR \quad R_n - 1 + CI \rightarrow R_n$	DSM
$M \rightarrow MAR \quad M + CI \rightarrow AT$	LMM	$11 \rightarrow MAR \quad M - 1 + CI \rightarrow AT$	LDM
$\overline{AT} + CI \rightarrow AT$	CIA	$AT - 1 + CI \rightarrow AT$	DCA
$CI - 1 \rightarrow R_n$ See Note 1	CSR	$AC - 1 + CI \rightarrow R_n$ See Note 1	SDR
$CI - 1 \rightarrow AT$ See Notes 1,4 (See CSA above)	CSA	$AC - 1 + CI \rightarrow AT$ See Notes 1,4 $I - 1 + CI \rightarrow AT$	SDA LDI
$R_n + CI \rightarrow R_n$ (See ACM above)	INR	$AC + R_n + CI \rightarrow R_n$ (See AMA above)	ADR
$AT + CI \rightarrow AT$	INA	$I + AT + CI \rightarrow AT$	AIA
$CI \rightarrow CO \quad 0 \rightarrow R_n$	CLR	$CI \vee (R_n \wedge AC) \rightarrow CO \quad R_n \wedge AC \rightarrow R_n$	ANR
$CI \rightarrow CO \quad 0 \rightarrow AT$ (See CLA above)	CLA	$CI \vee (M \wedge AC) \rightarrow CO \quad M \wedge AC \rightarrow AT$ $CI \vee (AT \wedge I) \rightarrow CO \quad AT \wedge I \rightarrow AT$	ANM ANI
(See CLR above)	—	$CI \vee R_n \rightarrow CO \quad R_n \rightarrow R_n$	TZR
(See CLA above)	—	$CI \vee M \rightarrow CO \quad M \rightarrow AT$	LTM
(See CLA above)	—	$CI \vee AT \rightarrow CO \quad AT \rightarrow AT$	TZA
$CI \rightarrow CO \quad R_n \rightarrow R_n$	NOP	$CI \vee AC \rightarrow CO \quad R_n \vee AC \rightarrow R_n$	ORR
$CI \rightarrow CO \quad M \rightarrow AT$ (See NOP above)	LMF	$CI \vee AC \rightarrow CO \quad M \vee AC \rightarrow AT$ $CI \vee I \rightarrow CO \quad I \vee AT \rightarrow AT$	ORM ORI
$CI \rightarrow CO \quad \overline{R_n} \rightarrow R_n$	CMR	$CI \vee (R_n \overline{AC}) \rightarrow CO \quad R_n \overline{\oplus} AC \rightarrow R_n$	XNR
$CI \rightarrow CO \quad \overline{M} \rightarrow AT$	LCM	$CI \vee (M \overline{AC}) \rightarrow CO \quad M \overline{\oplus} AC \rightarrow AT$	XNM
$CI \rightarrow CO \quad \overline{AT} \rightarrow AT$	CMA	$CI \vee (AT \overline{I}) \rightarrow CO \quad I \overline{\oplus} AT \rightarrow AT$	XNI

4. The more general operations, CSR and SDR, should be used in place of the CSA and SDA operations, respectively.

## APPENDIX C FUNCTION AND REGISTER GROUP FORMATS

FUNCTION GROUP	F <sub>6</sub>	5	4
0	0	0	0
1	0	0	1
2	0	1	0
3	0	1	1
4	1	0	0
5	1	0	1
6	1	1	0
7	1	1	1

REGISTER GROUP	REGISTER	F <sub>3</sub>	2	1	0
	R <sub>0</sub>	0	0	0	0
	R <sub>1</sub>	0	0	0	1
	R <sub>2</sub>	0	0	1	0
	R <sub>3</sub>	0	0	1	1
	R <sub>4</sub>	0	1	0	0
	R <sub>5</sub>	0	1	0	1
	R <sub>6</sub>	0	1	1	0
	R <sub>7</sub>	0	1	1	1
	R <sub>8</sub>	1	0	0	0
	R <sub>9</sub>	1	0	0	1
	T	1	1	0	0
	AC	1	1	0	1
II	T	1	0	1	0
	AC	1	0	1	1
III	T	1	1	1	0
	AC	1	1	1	1



# SCHOTTKY BIPOLAR LSI MICROCOMPUTER SET

# 3003 LOOK-AHEAD CARRY GENERATOR

The INTEL® 3003 Look-Ahead Carry Generator (LCG) is a high speed circuit capable of anticipating a carry across a full 16-bit 3002 Central Processing Array. When used with a larger 3002 CP Array multiple 3003 carry generators provide high speed carry look-ahead capability for any word length.

The LCG accepts eight pairs of active high cascade inputs (X, Y) and an active low carry input and generates active low carries for up to eight groups of binary adders.

**High Performance – 10 ns typical propagation delay**

**Compatible with INTEL 3001 MCU and 3002 CPE**

**DTL and TTL compatible**

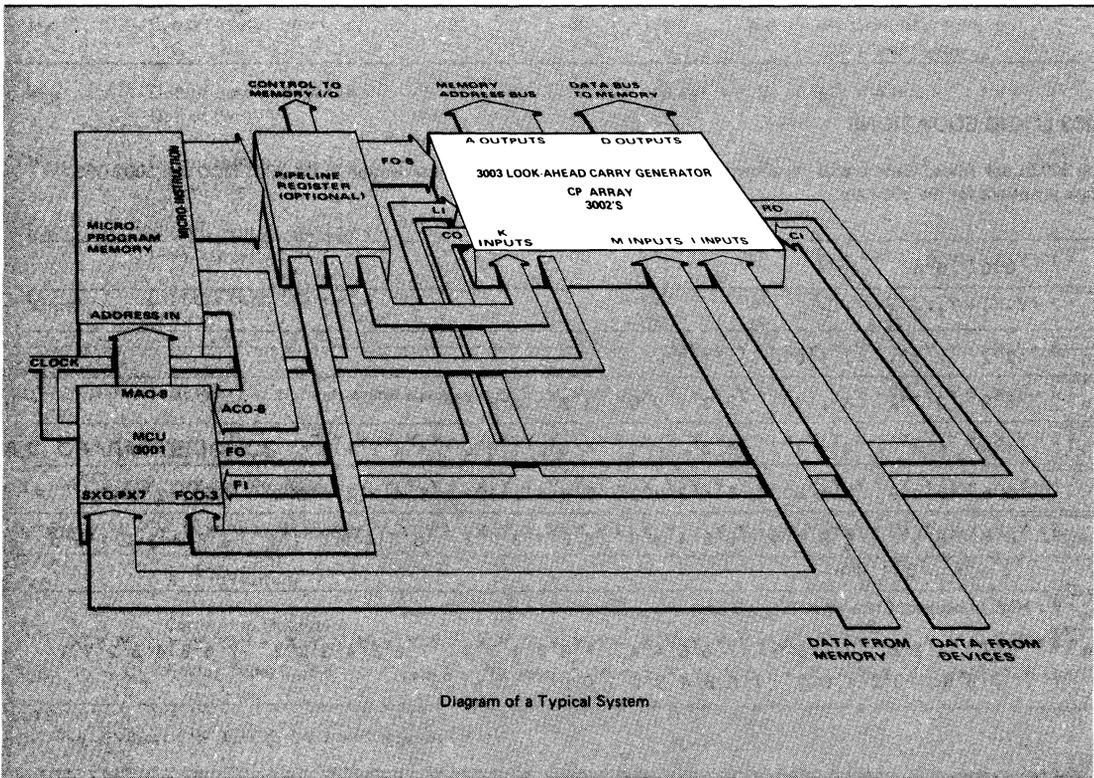
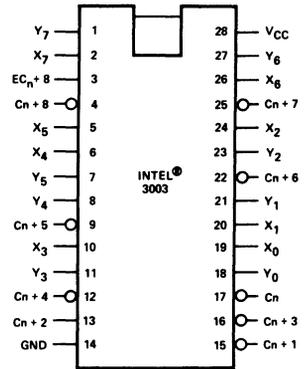
**Full look-ahead across 8 adders**

**Low voltage diode input clamp**

**Expandable**

**28-pin DIP**

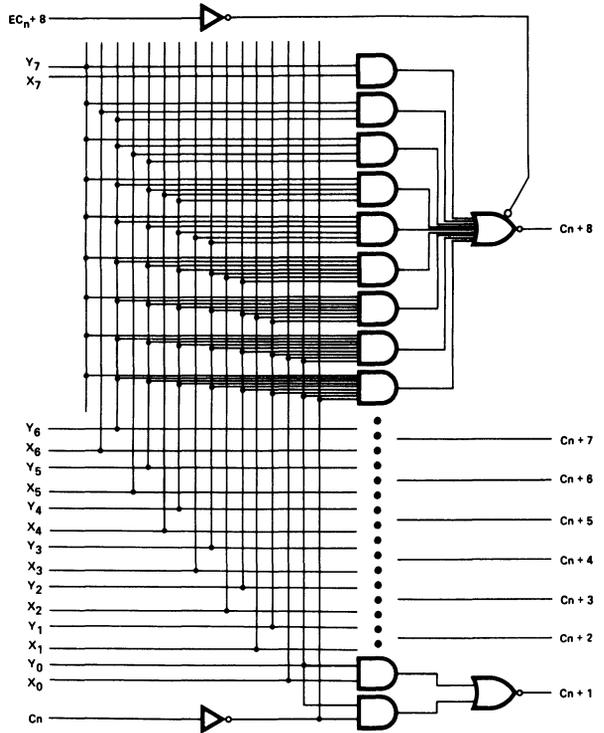
## PACKAGE CONFIGURATION



**PIN DESCRIPTION**

PIN	SYMBOL	NAME AND FUNCTION	TYPE
1,7,8,11 18,21,23 27	Y <sub>0</sub> -Y <sub>7</sub>	Standard carry look-ahead inputs	Active HIGH
2,5,6,10 19,20,24 26	X <sub>0</sub> -X <sub>7</sub>	Standard carry look-ahead inputs	Active HIGH
17	C <sub>n</sub>	Carry input	Active LOW
4,9,12 13,15,16	C <sub>n+1</sub> - C <sub>n+8</sub>	Carry outputs	Active LOW
3	EC <sub>n+8</sub>	C <sub>n+8</sub> carry output enable	Active HIGH
28	V <sub>CC</sub>	+5 volt supply	
14	GND	Ground	

**LOGIC DIAGRAM**



**3003 LOGIC EQUATIONS**

The 3003 Look-Ahead Generator is implemented in a compatible form for direct connection to the 3001 MCU and 3002 CPE. Logic equations for the 3003 are:

$$\overline{C_{n+1}} = Y_0 X_0 + Y_0 \overline{C_n}$$

$$\overline{C_{n+2}} = Y_1 X_1 + Y_1 Y_0 X_0 + Y_1 Y_0 \overline{C_n}$$

$$\overline{C_{n+3}} = Y_2 X_2 + Y_2 Y_1 X_1 + Y_2 Y_1 Y_0 X_0 + Y_2 Y_1 Y_0 \overline{C_n}$$

$$\overline{C_{n+4}} = Y_3 X_3 + Y_3 Y_2 X_2 + Y_3 Y_2 Y_1 X_1 + Y_3 Y_2 Y_1 Y_0 X_0 + Y_3 Y_2 Y_1 Y_0 \overline{C_n}$$

$$\overline{C_{n+5}} = Y_4 X_4 + Y_4 Y_3 X_3 + Y_4 Y_3 Y_2 X_2 + Y_4 Y_3 Y_2 Y_1 X_1 + Y_4 Y_3 Y_2 Y_1 Y_0 X_0 + Y_4 Y_3 Y_2 Y_1 Y_0 \overline{C_n}$$

$$\overline{C_{n+6}} = Y_5 X_5 + Y_5 Y_4 X_4 + Y_5 Y_4 Y_3 X_3 + Y_5 Y_4 Y_3 Y_2 X_2 + Y_5 Y_4 Y_3 Y_2 Y_1 X_1 + Y_5 Y_4 Y_3 Y_2 Y_1 Y_0 X_0 + Y_5 Y_4 Y_3 Y_2 Y_1 Y_0 \overline{C_n}$$

$$\overline{C_{n+7}} = Y_6 X_6 + Y_6 Y_5 X_5 + Y_6 Y_5 Y_4 X_4 + Y_6 Y_5 Y_4 Y_3 X_3 + Y_6 Y_5 Y_4 Y_3 Y_2 X_2 + Y_6 Y_5 Y_4 Y_3 Y_2 Y_1 X_1 + Y_6 Y_5 Y_4 Y_3 Y_2 Y_1 Y_0 X_0 + Y_6 Y_5 Y_4 Y_3 Y_2 Y_1 Y_0 \overline{C_n}$$

$$\overline{C_{n+8}} = \text{High Impedance State when } EC_{n+8} \text{ Low}$$

$$\overline{C_{n+8}} = Y_7 X_7 + Y_7 Y_6 X_6 + Y_7 Y_6 Y_5 X_5 + Y_7 Y_6 Y_5 Y_4 X_4 + Y_7 Y_6 Y_5 Y_4 Y_3 X_3 + Y_7 Y_6 Y_5 Y_4 Y_3 Y_2 X_2 + Y_7 Y_6 Y_5 Y_4 Y_3 Y_2 Y_1 X_1 + Y_7 Y_6 Y_5 Y_4 Y_3 Y_2 Y_1 Y_0 X_0 + Y_7 Y_6 Y_5 Y_4 Y_3 Y_2 Y_1 Y_0 \overline{C_n} \text{ when } EC_{n+8} \text{ high}$$

**D.C. AND OPERATING CHARACTERISTICS****ABSOLUTE MAXIMUM RATINGS\***

Temperature Under Bias	0°C to 70°C
Storage Temperature	-65°C to +160°C
All Output and Supply Voltages	-0.5V to +7V
All Input Voltages	-1.0V to +5.5V
Output Current	100 mA

\*COMMENT: Stresses above those listed under "Absolute Maximum Rating" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or at any other condition above those indicated in the operational sections of this specification is not implied.

$$T_A = 0^\circ\text{C to } 70^\circ\text{C} \quad V_{CC} = 5.0\text{V } \pm 5\%$$

SYMBOL	PARAMETER	MIN.	TYP. <sup>(1)</sup>	MAX.	UNIT	CONDITIONS
$V_C$	Input Clamp Voltage (All Input Pins)		-0.8	-1.0	V	$I_C = -5 \text{ mA}$
$I_F$	Input Load Current: X <sub>6</sub> , X <sub>7</sub> , C <sub>n</sub> , EC <sub>n</sub> + 8 Y <sub>7</sub> , X <sub>0</sub> -X <sub>5</sub> , Y <sub>0</sub> -Y <sub>6</sub>		-0.07 -0.200 -0.6	-0.25 -0.500 -1.5	mA mA mA	$V_F = 0.45\text{V}$
$I_R$	Input Leakage Current: C <sub>n</sub> and EC <sub>n</sub> + 8 All Other Inputs			40 100	$\mu\text{A}$ $\mu\text{A}$	$V_R = 5.25\text{V}$
$V_{IL}$	Input Low Voltage			0.8	V	$V_{CC} = 5.0\text{V}$
$V_{IH}$	Input High Voltage	2.0			V	$V_{CC} = 5.0\text{V}$
$I_{CC}$	Power Supply Current		80	130	mA	All Y and EC <sub>n</sub> + 8 high, All X and C <sub>n</sub> low
$V_{OL}$	Output Low Voltage (All Output Pins)		0.35	0.45	V	$I_{OL} = 4 \text{ mA}$
$V_{OH}$	Output High Voltage (All Output Pins)	2.4	3		V	$I_{OH} = -1 \text{ mA}$
$I_{OS}$	Short Circuit Output Current (All Output Pins)	-15	-40	-65	mA	$V_{CC} = 5\text{V}$
$I_{O(\text{off})}$	Off-State Output Current (C <sub>n</sub> + 8)			-100 +100	$\mu\text{A}$ $\mu\text{A}$	$V_O = 0.45\text{V}$ $V_O = 5.25\text{V}$

NOTE:

(1) Typical values are for  $T_A = 25^\circ\text{C}$  and nominal supply voltage.

**A.C. CHARACTERISTICS**

$$T_A = 0^\circ\text{C to } 70^\circ\text{C}, V_{CC} = +5\text{V } \pm 5\%$$

SYMBOL	PARAMETER	MIN.	TYP. <sup>(1)</sup>	MAX.	UNIT
$t_{XC}$	X, Y to Outputs	3	10	20	ns
$t_{CC}$	Carry In to Outputs		13	30	ns
$t_{EN}$	Enable Time, C <sub>n</sub> + 8		20	40	ns

NOTE:

(1) Typical values are for  $T_A = 25^\circ\text{C}$  and nominal supply voltage.

**D.C. AND OPERATING CHARACTERISTICS****ABSOLUTE MAXIMUM RATINGS\***

Temperature Under Bias	-55°C to +125°C
Storage Temperature	-65°C to +160°C
All Output and Supply Voltages	-0.5V to +7V
All Input Voltages	-1.0V to +5.5V
Output Current	100 mA

\*COMMENT: Stresses above those listed under "Absolute Maximum Rating" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or at any other condition above those indicated in the operational sections of this specification is not implied.

$T_A = -55^\circ\text{C}$  to  $+125^\circ\text{C}$ ,  $V_{CC} = 5.0\text{V} \pm 10\%$ .

SYMBOL	PARAMETER	MIN.	TYP. <sup>(1)</sup>	MAX.	UNIT	CONDITIONS
$V_C$	Input Clamp Voltage (All Input Pins)		-0.8	-1.2	V	$I_C = -5\text{ mA}$
$I_F$	Input Load Current: X <sub>6</sub> , X <sub>7</sub> , C <sub>n</sub> , EC <sub>n</sub> +8 Y <sub>7</sub> , X <sub>0</sub> -X <sub>5</sub> , Y <sub>0</sub> -Y <sub>6</sub>		-0.07 -0.200 -0.6	-0.25 -0.500 -1.5	mA mA mA	$V_F = 0.45\text{V}$
$I_R$	Input Leakage Current: C <sub>n</sub> and EC <sub>n</sub> + 8 All Other Inputs			40 100	$\mu\text{A}$ $\mu\text{A}$	$V_{CC} = 5.25\text{V}$ , $V_R = 5.5\text{V}$
$V_{IL}$	Input Low Voltage			0.8	V	$V_{CC} = 5.0\text{V}$
$V_{IH}$	Input High Voltage	2.1			V	$V_{CC} = 5.0\text{V}$
$I_{CC}$	Power Supply Current		80	130	mA	All Y and EC <sub>n</sub> + 8 high, All X and C <sub>n</sub> low
$V_{OL}$	Output Low Voltage (All Output Pins)		0.35	0.45	V	$I_{OL} = 4\text{ mA}$
$V_{OH}$	Output High Voltage (All Output Pins)	2.4	3		V	$I_{OH} = -1\text{ mA}$
$I_{OS}$	Short Circuit Output Current (All Output Pins)	-15	-40	-65	mA	$V_{CC} = 5\text{V}$
$I_{O(off)}$	Off-State Output Current (C <sub>n</sub> + 8)			-100 +100	$\mu\text{A}$ $\mu\text{A}$	$V_O = 0.45\text{V}$ $V_O = 5.5\text{V}$

NOTE:

(1) Typical values are for  $T_A = 25^\circ\text{C}$  and nominal supply voltage.

**A.C. CHARACTERISTICS**

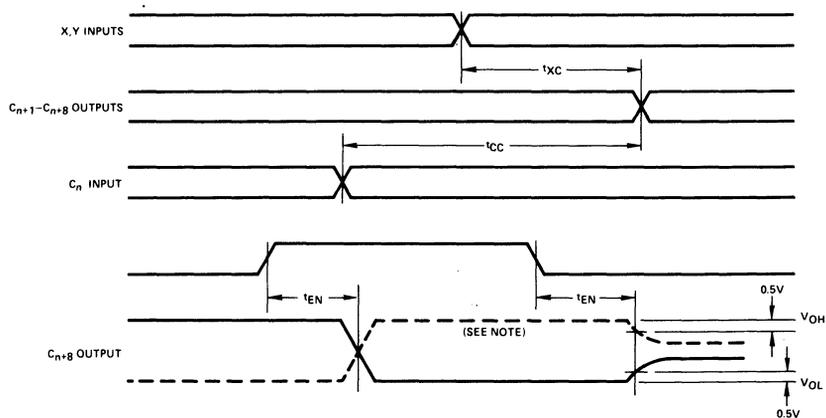
$T_A = -55^\circ\text{C}$  to  $+125^\circ\text{C}$ ,  $V_{CC} = +5.0\text{V} \pm 10\%$

SYMBOL	PARAMETER	MIN.	TYP. <sup>(1)</sup>	MAX.	UNIT
$t_{XC}$	X, Y to Outputs	3	10	25	ns
$t_{CC}$	Carry In to Outputs		13	40	ns
$t_{EN}$	Enable Time, C <sub>n</sub> + 8		20	50	ns

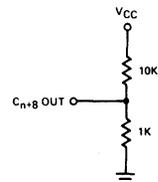
NOTE:

(1) Typical values are for  $T_A = 25^\circ\text{C}$  and nominal supply voltage.

## WAVEFORMS



NOTE: ALTERNATE TEST LOAD:

CAPACITANCE<sup>(2)</sup>  $T_A = 25^\circ\text{C}$ 

SYMBOL	PARAMETER	MIN	TYP	MAX	UNIT
$C_{IN}$	Input Capacitance		12	20	pF
$C_{OUT}$	Output Capacitance		7	12	pF

NOTE:

(2) This parameter is periodically sampled and is not 100% tested. Condition of measurement is  $f = 1\text{ MHz}$ ,  $V_{BIAS} = 5.0\text{V}$ ,  $V_{CC} = 5.0\text{V}$  and  $T_A = 25^\circ\text{C}$ .

## TEST CONDITIONS:

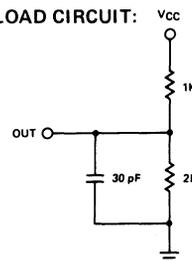
Input pulse amplitude of 2.5V.

Input rise and fall times of 5 ns between 1 and 2 volts.

Output loading is 5 mA and 30 pF.

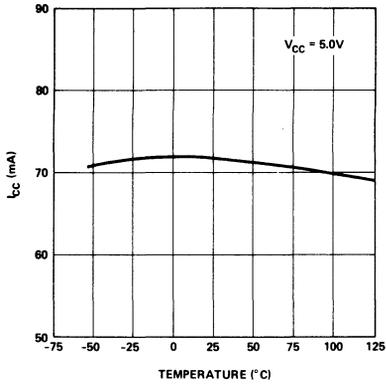
Speed measurements are made at 1.5 volt levels.

## TEST LOAD CIRCUIT:

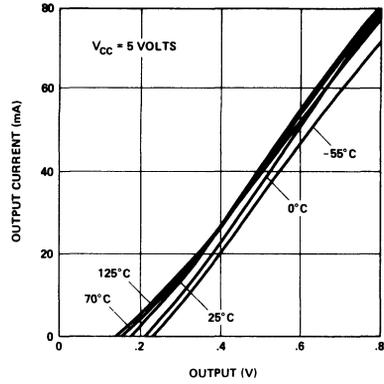


TYPICAL A.C. AND D.C. CHARACTERISTICS

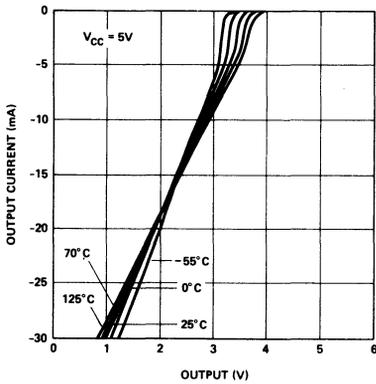
I<sub>CC</sub> VS. TEMPERATURE



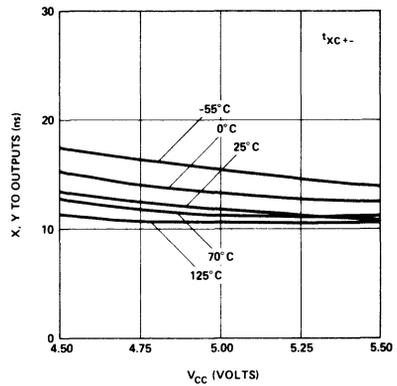
OUTPUT CURRENT VS. OUTPUT LOW VOLTAGE



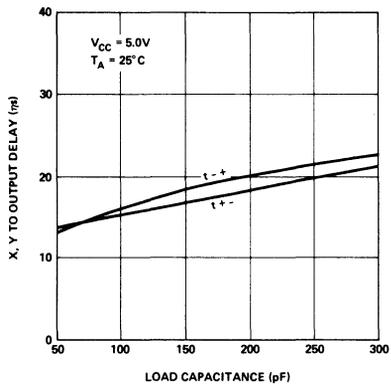
OUTPUT CURRENT VS. OUTPUT HIGH VOLTAGE



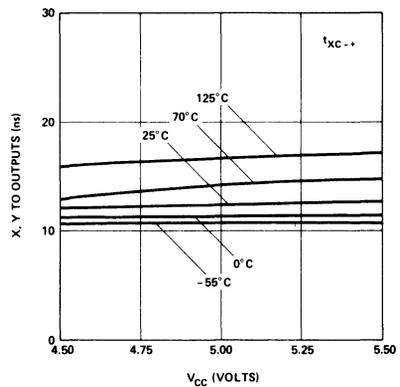
X, Y TO OUTPUTS VS. V<sub>CC</sub> AND TEMPERATURE



X, Y TO OUTPUT DELAY VS. LOAD CAPACITANCE



X, Y TO OUTPUTS VS. V<sub>CC</sub> AND TEMPERATURE



## TYPICAL CONFIGURATIONS

The 3003 LCG can be directly tied to the 3001 MCU and a 3002 CP array of any word length. The following figures represent typical configurations of 16- and 32-bit CP arrays. Figures 1 and 2 illustrate use of the 3003 in a system where the carry output (CO) to the 3001 MCU is rippled through the high order CPE slice. Figure 3 illustrates use of the 3003 in a system where tri-state output  $C_{n+8}$  is connected directly to the flag input on the 3001 MCU.  $C_{n+8}$  is disabled during shift right by decoding that instruction externally, thus multiplexing  $C_{n+8}$  with the shift right (RO) output of the low order CPE slice.

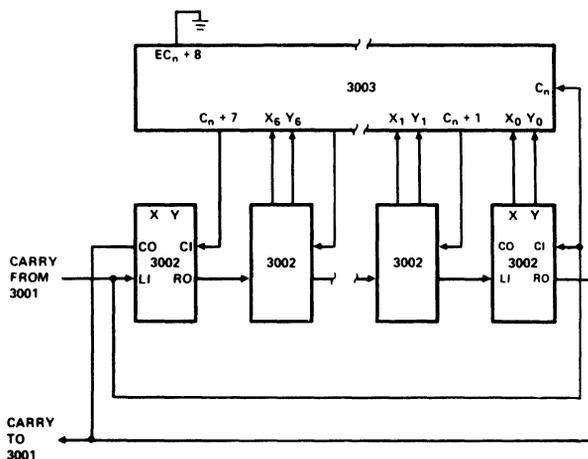


Figure 1. Carry Look-Ahead Configuration with Ripple through the Left Slice (16-Bit Array)

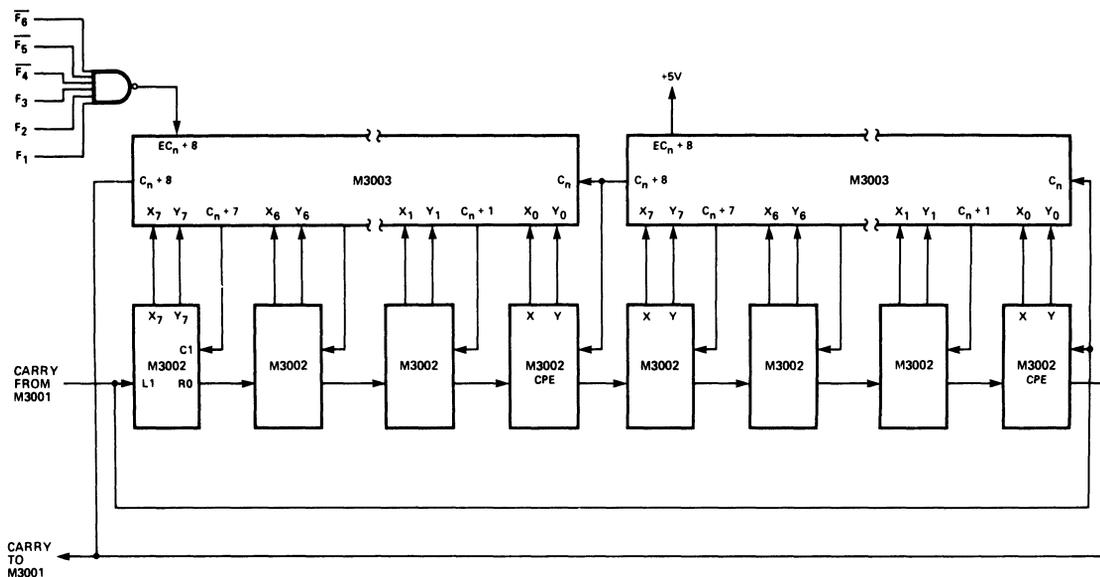


Figure 2. Carry Look-Ahead Configuration with No Carry Ripple through the Left Slice (32-Bit Array)



# SCHOTTKY BIPOLAR LSI MICROCOMPUTER SET

# 3212 MULTI-MODE LATCH BUFFER SET

The INTEL<sup>®</sup> 3212 Multi-Mode Latch Buffer is a versatile 8-bit latch with three-state output buffers and built-in device select logic. It also contains an independent service request flip-flop for the generation of central processor interrupts. Because of its multi-mode capabilities, one or more 3212's can be used to implement many types of interface and support systems for Series 3000 computing elements including:

- Simple data latches
- Gated data buffers
- Multiplexers
- Bi-directional bus drivers
- Interrupting input/output ports

**High Performance – 50 ns Write Cycle Time**

**Low Input Load Current – 250  $\mu$ A Maximum**

**Three-State Fully Buffered Outputs**

**High Output Drive Capability**

**Independent Service Request Flip-Flop**

**Asynchronous Data Latch Clear**

**24 Pin DIP**

## PACKAGE CONFIGURATION

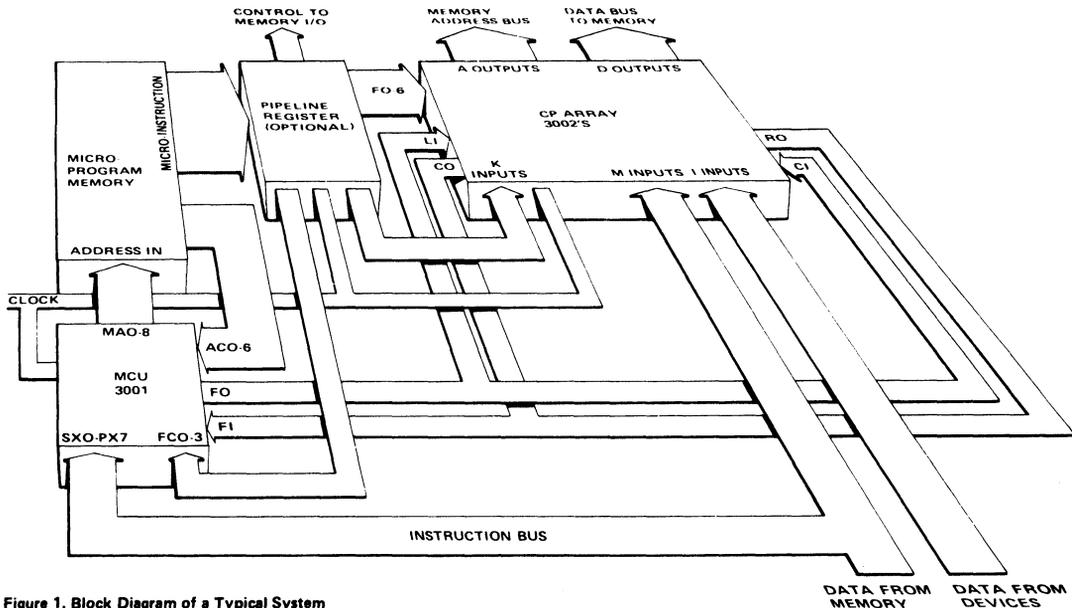
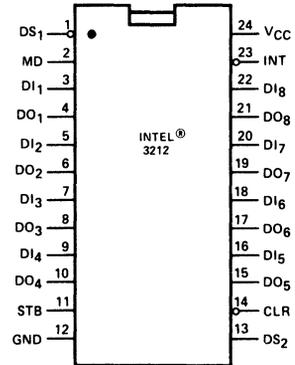


Figure 1. Block Diagram of a Typical System

## PIN DESCRIPTION

PIN	SYMBOL	NAME AND FUNCTION	TYPE <sup>(1)</sup>
1	DS <sub>1</sub>	Device Select Input 1	active LOW
2	MD	Mode Input When MD is high (output mode) the output buffers are enabled and the write signal to the data latches is obtained from the device select logic. When MD is low (input mode) the output buffer state is determined by the device select logic and the write signal is obtained from the strobe (STB) input.	
3, 5, 7, 9, 16, 18, 20, 22	DI <sub>1</sub> –DI <sub>8</sub>	Data Inputs The data inputs are connected to the D-inputs of the data latches.	
4, 6, 8, 10, 15, 17, 19, 21	DO <sub>1</sub> –DO <sub>8</sub>	Data Outputs The data outputs are the buffered outputs of the eight data latches.	three-state
11	STB	Strobe Input When MD is in the LOW state, the STB input provides the clock input to the data latch.	
12	GND	Ground	
13	DS <sub>2</sub>	Device Select Input 2 When DS <sub>1</sub> is low and DS <sub>2</sub> is high, the device is selected.	
14	CLR	Clear	active LOW
23	INT	Interrupt Output The interrupt output will be active LOW (interrupting state) when either the service request flip-flop is low or the device is selected.	active LOW

## NOTE:

(1) Active HIGH, unless otherwise specified.

## FUNCTIONAL DESCRIPTION

The 3212 contains eight D-type data latches, eight three-state output buffers, a separate D-type service request flip-flop, and a flexible device select/mode control section.

### DATA LATCHES

The Q-output of each data latch will follow the data on its corresponding data input line ( $DI_1$ – $DI_8$ ) while its clock input is high. Data will be latched when the internal write line WR is brought low. The output of each data latch is connected to a three-state, non-inverting output buffer. The internal enable line EN is bussed to each buffer. When the EN is high, the buffers are enabled and the data in each latch is available on its corresponding data output line ( $DO_0$ – $DO_8$ ).

### DEVICE SELECT LOGIC

Two input lines  $DS_1$  and  $DS_2$  are provided for device selection. When  $DS_1$  is low and  $DS_2$  is high, the 3212 is selected.

### MODE CONTROL SECTION

The 3212 may be operated in two modes. When the mode input line MD is low, the device is in the input mode. In this mode, the output buffers are enabled whenever the 3212 is selected; the internal WR line follows the STB input line.

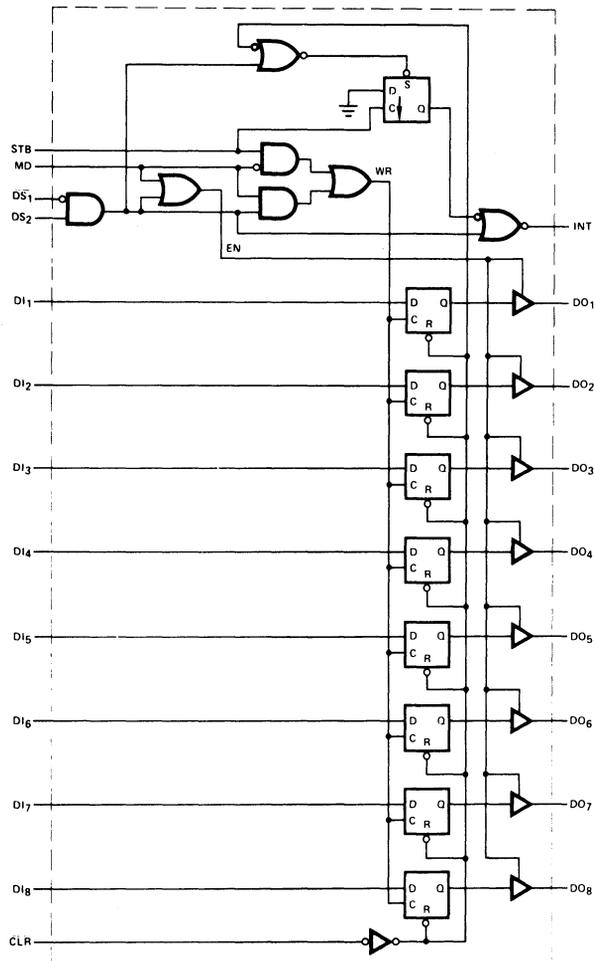
When MD is high, the device is in the output mode and, as a result, the output buffers are enabled. In this mode, the write signal for the data latch is obtained from the device select logic.

### SERVICE REQUEST FLIP-FLOP AND STROBE

The service request flip-flop SR is used to generate and control central processor interrupt signals. For system reset, the SR flip-flop is placed in the non-interrupting state (i.e., SR is set) by bringing the CLR line low. This simultaneously clears (resets) the 8-bit data latch.

The Q output of the SR flip-flop is logically ORed with the output of device select logic and then inverted to provide the interrupt output INT. The 3212 is considered to be in the interrupting state when the INT output is low. This allows direct connection to the active LOW priority request inputs of the INTEL<sup>®</sup>3214 Interrupt Control Unit.

When operated in the input mode (i.e., MD low) the strobe input STB is used to synchronously write data into the data latch and place the SR flip-flop in the interrupting (reset) state. The interrupt is removed by the central processor when the interrupting 3212 is selected.



M3212 Logic Diagram

## D.C. AND OPERATING CHARACTERISTICS

## ABSOLUTE MAXIMUM RATINGS\*

Temperature Under Bias . . . . .	.0°C to 70°C
Storage Temperature . . . . .	-65°C to +160°C
All Output and Supply Voltages . . . . .	-0.5V to +7V
All Input Voltages . . . . .	-1.0V to +5.5V
Output Currents . . . . .	100 mA

\*COMMENT: Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum ratings for extended periods may affect device reliability.

$T_A = 0^\circ\text{C to } +75^\circ\text{C}$      $V_{CC} = +5V \pm 5\%$

Symbol	Parameter	Min.	Typ.	Max.	Unit	Conditions
$I_F$	Input Load Current STB, DS <sub>2</sub> , CLR, DI <sub>1</sub> -DI <sub>8</sub> Inputs			-.25	mA	$V_F = .45V$
$I_F$	Input Load Current MD Input			-.75	mA	$V_F = .45V$
$I_F$	Input Load Current DS <sub>1</sub> Input			-1.0	mA	$V_F = .45V$
$I_R$	Input Leakage Current STB, DS, CLR, DI <sub>1</sub> -DI <sub>8</sub> Inputs			10	$\mu A$	$V_R = 5.25V$
$I_R$	Input Leakage Current MD Input			30	$\mu A$	$V_R = 5.25V$
$I_R$	Input Leakage Current DS <sub>1</sub> Input			40	$\mu A$	$V_R = 5.25V$
$V_C$	Input Forward Voltage Clamp			-1	V	$I_C = -5\text{ mA}$
$V_{IL}$	Input "Low" Voltage			.85	V	
$V_{IH}$	Input "High" Voltage	2.0			V	
$V_{OL}$	Output "Low" Voltage			.45	V	$I_{OL} = 15\text{ mA}$
$V_{OH}$	Output "High" Voltage	3.65	4.0		V	$I_{OH} = -1\text{ mA}$
$I_{SC}$	Short Circuit Output Current	-15		-75	mA	$V_{CC} = 5.0V$
$ I_O $	Output Leakage Current High Impedance State			20	$\mu A$	$V_O = .45V/5.25V$
$I_{CC}$	Power Supply Current		90	130	mA	

**A.C. CHARACTERISTICS**  $T_A = 0^\circ\text{C to } 75^\circ\text{C}$ ,  $V_{CC} = +5.0\text{V} \pm 5\%$ 

Symbol	Parameter	Min.	Typ.	Max.	Unit
$t_{PW}$	Pulse Width	25			ns
$t_{PD}$	Data To Output Delay			30	ns
$t_{WE}$	Write Enable To Output Delay			40	ns
$t_{SET}$	Data Setup Time	15			ns
$t_H$	Data Hold Time	20			ns
$t_R$	Reset To Output Delay			40	ns
$t_S$	Set To Output Delay			30	ns
$t_E$	Output Enable Time			45	ns $C_L = 30\text{ pf}$
$t_C$	Clear To Output Display			45	ns

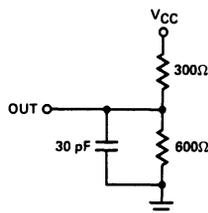
**TEST CONDITIONS:**

Input pulse amplitude of 2.5 volts.

Input rise and fall times of 5 ns between 1 volt and 2 volts.

Output load of 15 mA and 30 pF.

Speed measurements are taken at the 1.5 volt level.

**TEST LOAD CIRCUIT:****CAPACITANCE<sup>(1)</sup>**

Symbol	Test	LIMITS			Units
		Min.	Typ.	Max.	
$C_{IN}$	$DS_1$ , MD Input Capacitance		9	12	pf
$C_{IN}$	$DS_2$ , CLR, STB, $DI_1$ – $DI_8$ Input Capacitance		5	9	pf
$C_{OUT}$	$DO_1$ – $DO_8$ Output Capacitance		8	12	pf

**NOTE:**

(1) This parameter is periodically sampled and is not 100% tested. Condition of measurement is  $f = 1\text{ MHz}$ ,  $V_{BIAS} = 2.5\text{V}$ ,  $V_{CC} = 5\text{V}$  and  $T_A = 25^\circ\text{C}$ .

## D.C. AND OPERATING CHARACTERISTICS

## ABSOLUTE MAXIMUM RATINGS\*

Temperature Under Bias . . . . .	-55°C to +125°C
Storage Temperature . . . . .	-65°C to +160°C
All Output and Supply Voltages . . . . .	-0.5V to +7V
All Input Voltages . . . . .	-1.0V to +5.5V
Output Currents . . . . .	100 mA

\*COMMENT: Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum ratings for extended periods may affect device reliability.

$T_A = -55^\circ\text{C to } +125^\circ\text{C}; V_{CC} = 5.0\text{V} \pm 10\%$

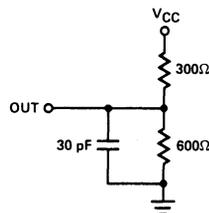
Symbol	Parameter	Min.	Typ.	Max.	Unit	Conditions
$I_F$	Input Load Current STB, DS <sub>2</sub> , CLR, DI <sub>1</sub> -DI <sub>8</sub> Inputs			-.25	mA	$V_F = .45\text{V}$
$I_F$	Input Load Current MD Input			-.75	mA	$V_F = .45\text{V}$
$I_F$	Input Load Current DS <sub>1</sub> Input			-1.0	mA	$V_F = .45\text{V}$
$I_R$	Input Leakage Current STB, DS, CLR, DI <sub>1</sub> -DI <sub>8</sub> Inputs			10	$\mu\text{A}$	$V_R = 5.5\text{V}$
$I_R$	Input Leakage Current MD Input			30	$\mu\text{A}$	$V_R = 5.5\text{V}$
$I_R$	Input Leakage Current DS <sub>1</sub> Input			40	$\mu\text{A}$	$V_R = 5.5\text{V}$
$V_C$	Input Forward Voltage Clamp			1.2	V	$I_C = -5\text{ mA}$
$V_{IL}$	Input "Low" Voltage			.80	V	
$V_{IH}$	Input "High" Voltage	2.0			V	
$V_{OL}$	Output "Low" Voltage			.45	V	$I_{OL} = 10\text{ mA}$
$V_{OH}$	Output "High" Voltage	3.5	4.0		V	$I_{OH} = .5\text{ mA}$
$I_{SC}$	Short Circuit Output Current	-15		-75	mA	$V_{CC} = 5.0\text{V}$
$ I_O $	Output Leakage Current High Impedance State			20	$\mu\text{A}$	$V_O = .45\text{V}/5.5\text{V}$
$I_{CC}$	Power Supply Current		90	145	mA	

**A.C. CHARACTERISTICS**  $T_A = -55^{\circ}\text{C}$  to  $+125^{\circ}\text{C}$ ,  $V_{CC} = 5.0\text{V} \pm 10\%$ 

Symbol	Parameter	Min.	Typ.	Max.	Unit
$t_{PW}$	Pulse Width	40			ns
$t_{PD}$	Data To Output Delay			30	ns
$t_{WE}$	Write Enable To Output Delay			50	ns
$t_{SET}$	Data Setup Time	20			ns
$t_H$	Data Hold Time	30			ns
$t_R$	Reset To Output Delay			55	ns
$t_S$	Set To Output Delay			35	ns
$t_E$	Output Enable Time			50	ns $C_L = 30\text{ pf}$
$t_C$	Clear To Output Display			55	ns

**TEST CONDITIONS:**

Input pulse amplitude of 2.5 volts.  
 Input rise and fall times of 5 ns between 1 volt and 2 volts.  
 Output load of 15 mA and 30 pF.  
 Speed measurements are taken at the 1.5 volt level.

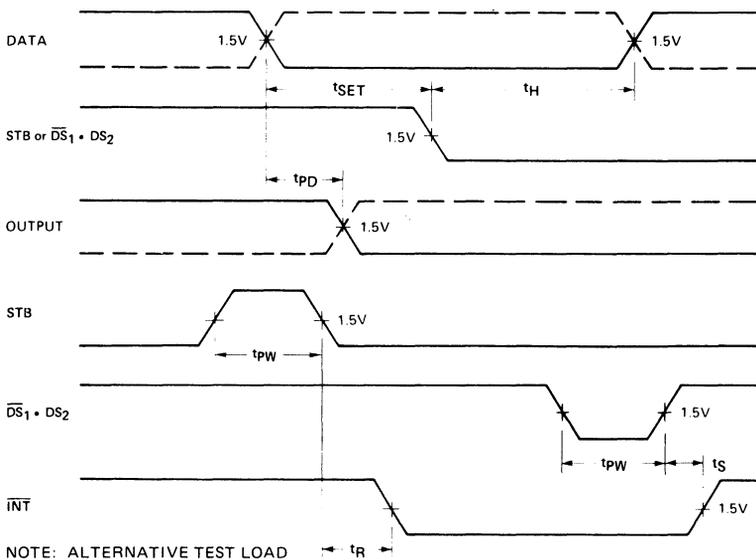
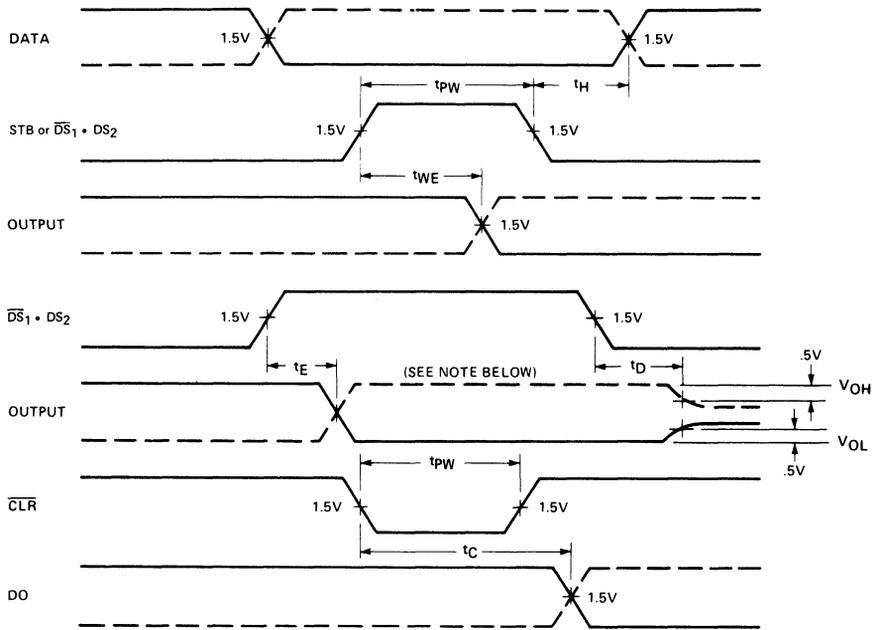
**TEST LOAD CIRCUIT:****CAPACITANCE<sup>(1)</sup>**

Symbol	Test	LIMITS			Units
		Min.	Typ.	Max.	
$C_{IN}$	$DS_1$ , MD Input Capacitance		9	12	pf
$C_{IN}$	$DS_2$ , CLR, STB, $DI_1$ – $DI_8$ Input Capacitance		5	9	pf
$C_{OUT}$	$DO_1$ – $DO_8$ Output Capacitance		8	12	pf

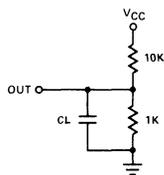
**NOTE:**

(1) This parameter is periodically sampled and is not 100% tested. Condition of measurement is  $f = 1\text{ MHz}$ ,  $V_{BIAS} = 2.5\text{V}$ ,  $V_{CC} = 5\text{V}$  and  $T_A = 25^{\circ}\text{C}$ .

WAVEFORMS

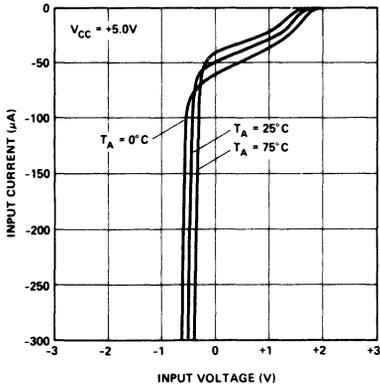


NOTE: ALTERNATIVE TEST LOAD

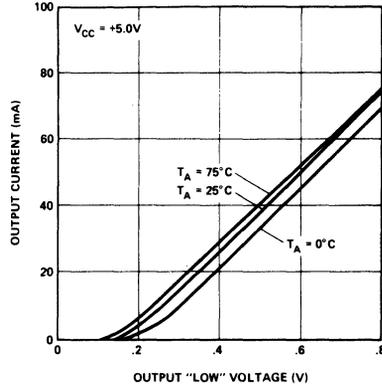


TYPICAL A.C. AND D.C. CHARACTERISTICS

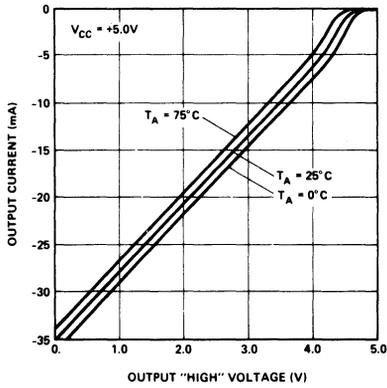
INPUT CURRENT VS. INPUT VOLTAGE



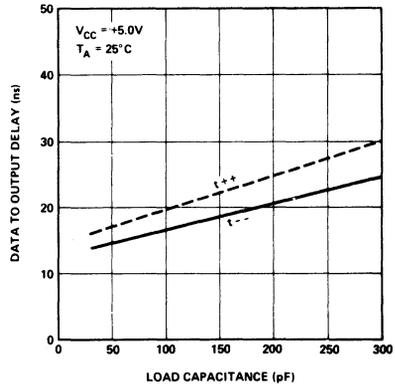
OUTPUT CURRENT VS. OUTPUT "LOW" VOLTAGE



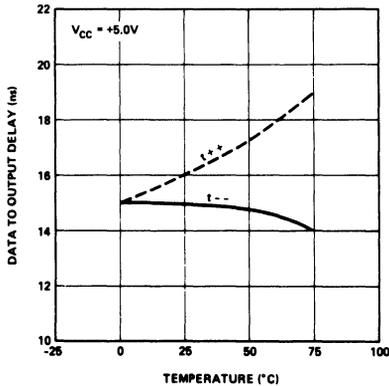
OUTPUT CURRENT VS. OUTPUT "HIGH" VOLTAGE



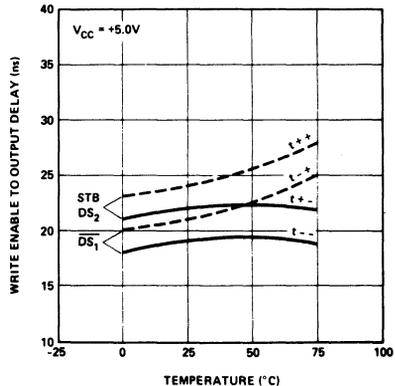
DATA TO OUTPUT DELAY VS. LOAD CAPACITANCE



DATA TO OUTPUT DELAY VS. TEMPERATURE

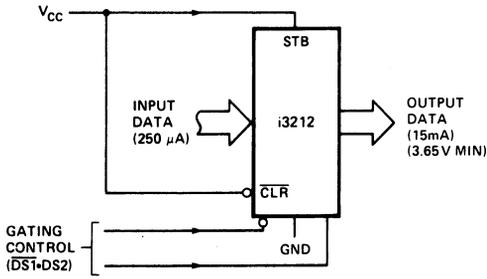


WRITE ENABLE TO OUTPUT DELAY VS. TEMPERATURE

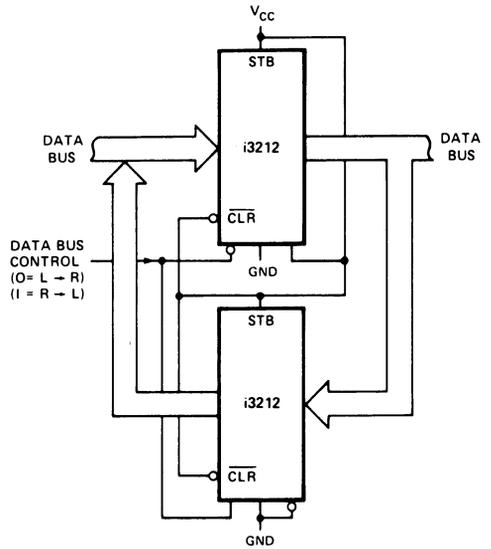


TYPICAL CONFIGURATIONS

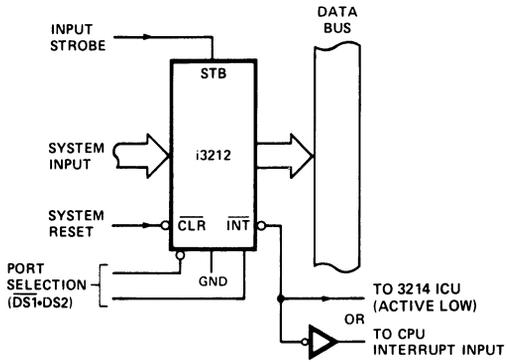
GATED BUFFER (TRI-STATE)



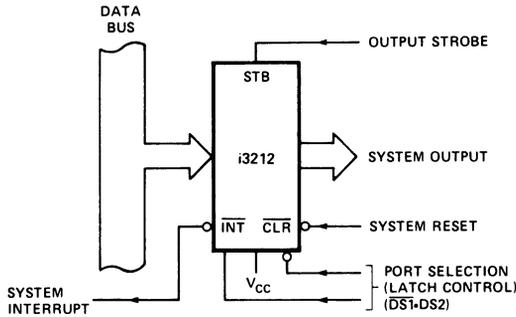
BI-DIRECTIONAL BUS DRIVER



INTERRUPTING INPUT PORT



OUTPUT PORT (WITH HAND-SHAKING)





# SCHOTTKY BIPOLAR LSI MICROCOMPUTER SET

# 3214 INTERRUPT CONTROL UNIT

The Intel®3214 Interrupt Control Unit (ICU) implements multi-level interrupt capability for systems designed with Series 3000 computing elements.

The ICU accepts an asynchronous interrupt strobe from the 3001 Microprogram Control Unit or a bit in microprogram memory and generates a synchronous interrupt acknowledge and an interrupt vector which may be directed to the MCU or CP Array to uniquely identify the interrupt source.

The ICU is fully expandable in 8-level increments and provides the following system capabilities:

- Eight unique priority levels per ICU
- Automatic Priority Determination
- Programmable Status
- N-level expansion capability
- Automatic interrupt vector generation

High Performance – 80 ns Cycle Time

Compatible with Intel 3001 MCU and 3002 CPE

8-Bit Priority Interrupt Request Latch

4-Bit Priority Status Latch

3-Bit Priority Encoder with Open Collector Outputs

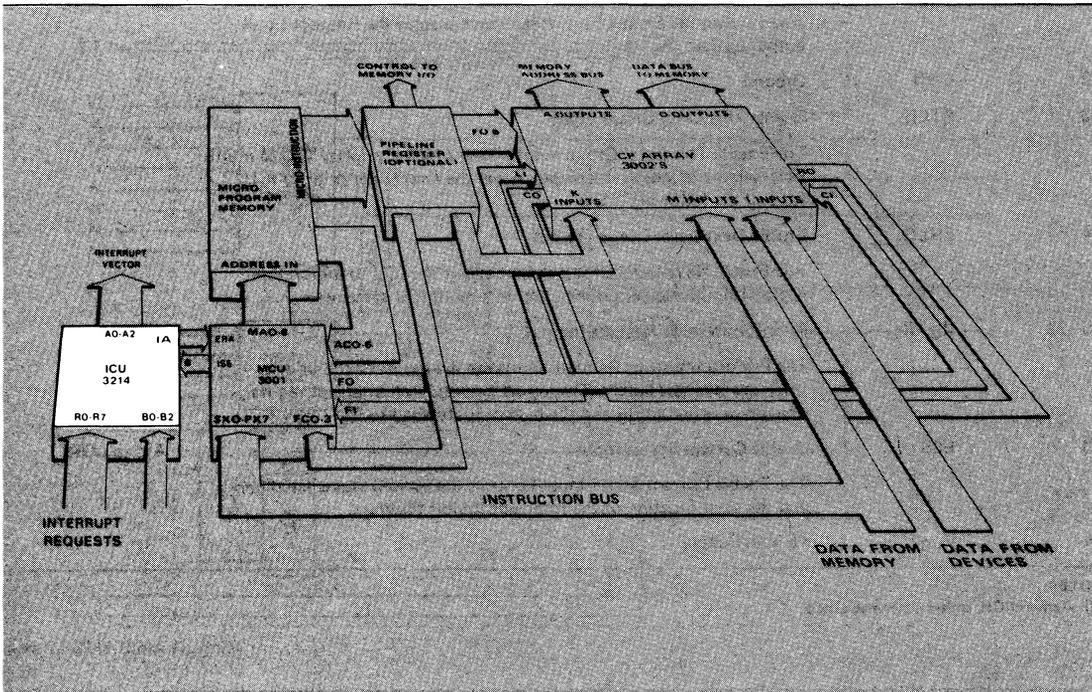
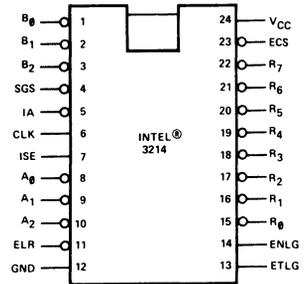
DTL and TTL Compatible

8-Level Priority Comparator

Fully Expandable

24-Pin DIP

## PACKAGE CONFIGURATION



## PIN DESCRIPTION

PIN	SYMBOL	NAME AND FUNCTION	TYPE <sup>(1)</sup>
1–3	B <sub>0</sub> –B <sub>2</sub>	Current Status Inputs  The Current Status inputs carry the binary value modulo 8 of the current priority level to the current status latch.	Active LOW
4	SGS	Status Group Select Input  The Status Group Select input informs the ICU that the current priority level does belong to the group level assigned to the ICU.	Active LOW
5	IA	Interrupt Acknowledge  The Interrupt Acknowledge Output will only be active from the ICU (multi-ICU system) which has received a priority request at a level superior to the current status. It signals the controlled device (usually the processor) and the other ICUs OR-tied on the Interrupt Acknowledge line that an interrupt request has been recognized.  The IA signal also sets the Interrupt Disable flip-flop (it overrides the clear function of the ECS input).	Active LOW Open-Collector Output
6	CLK	Clock Input  The Clock input is used to synchronize the interrupt acknowledge with the operation of the device which it controls.	
7	ISE	Interrupt Strobe Enable Input  The Interrupt Strobe Enable input informs the ICU that it is authorized to enter the interrupt mode.	
8–10	A <sub>0</sub> –A <sub>2</sub>	Request Level Outputs  When valid, the Request Level outputs carry the binary value (modulo 8) of the highest priority request present at the priority request inputs or stored in the priority request latch. The request level outputs can become active only with the ICU which has received the highest priority request with a level superior to the current status.	Active LOW Open-Collector
11	ELR	Enable Level Read Input  When active, the Enable Level Read input enables the Request Level output buffers (A <sub>0</sub> –A <sub>2</sub> ).	Active LOW
12	GND	Ground	
13	ETLG	Enable This Level Group Input  The Enable This Level Group input allows a higher priority ICU in multi-ICU systems to inhibit interrupts within the next lower priority ICU (and all the following ICUs).	
14	ENLG	Enable Next Level Group Output  The Enable Next Level Group output allows the ICU to inhibit interrupts within the lower priority ICU in a multi-ICU system.	
15–22	R <sub>0</sub> –R <sub>7</sub>	Priority Interrupt Request Inputs  The Priority Interrupt Request inputs are the inputs of the priority Interrupt Request Latch. The lowest priority level interrupt request signal is attached to R <sub>0</sub> and the highest is attached to R <sub>7</sub> .	Active LOW
23	ECS	Enable Current Status Input  The Enable Current Status input controls the current status latch and the clear function of the Interrupt Inhibit flip-flop.	Active LOW
24	V <sub>CC</sub>	+5 Volt Supply	

## NOTE:

(1) Active HIGH, unless otherwise noted.

## FUNCTIONAL AND LOGICAL DESCRIPTION

The ICU adds interrupt capability to suitably microprogrammed processors or controllers. One or more of these units allows external signals called interrupt requests to cause the processor/controller to suspend execution of the active process, save its status, and initiate execution of a new task as requested by the interrupt signal.

It is customary to strobe the ICU at the end of each instruction execution. At that time, if an interrupt request is acknowledged by the ICU, the MCU is forced to follow the interrupt microprogram sequence.

Figure 1 shows the block diagram of the ICU. Interrupt requests pass through the interrupt request latch and priority encoder to the magnitude comparator. The output of the priority encoder is the binary equivalent of the highest active priority request. At the comparator, this value is compared with the Current Status (currently active priority level) contained in the current status latch. A request, if acknowledged at interrupt strobe time, will cause the interrupt flip-flop to enter the "interrupt active" state for one microinstruction cycle. This action causes the interrupt acknowledge (IA) signal to go low and sets the interrupt disable flip-flop.

The IA signal constitutes the interrupt command to the processor. It can directly force entry into the interrupt service routine as demonstrated in the appendix. As part of this routine, the microprogram normally reads the requesting level via the request level output bus. This information which is saved in the request latch can be enabled onto one of the processor input data buses using the enable level read input. Once the interrupt handler has determined the requesting level, it normally writes this level back into the current status register of the ICU. This action resets the interrupt disable flip-flop and acts to block any further request at this level or lower levels.

Entry into a macro level interrupt service routine may be vectored using the request level information to generate a subroutine address which corresponds to the level. Exit from such a macroprogram should normally restore the prior status in the current status latch.

The Enable This Level Group (ETLG) input and the Enable Next Level Group (ENLG) output can be used in a daisy chain fashion, as each ICU is capable of inhibiting interrupts from all of the following ICUs in a multiple ICU configuration.

The interrupt acknowledge flip-flop is set to the active LOW state on the rising edge of the clock when the following conditions are met:

An active request level ( $R_0-R_7$ ) is greater than the current status  $B_0-B_2$

The interrupt mode (ISE) is active  
ETLG is enabled

The interrupt disable flip-flop is reset

When active, the IA signal asynchronously sets the disable flip-flop and holds the requests in the request latch until new current status information ( $B_0-B_2$ , SGS) is enabled (ECS) into the current status latch. The disable flip-flop is reset at the completion of this load operation.

During this process, ENLG will be enabled only if the following conditions are met:

ETLG is enabled

The current status (SGS) does not belong to this level group

There is no active request at this level

The request level outputs  $A_0-A_2$  and the IA output are open-collector to permit bussing of these lines in multi-ICU configuration.

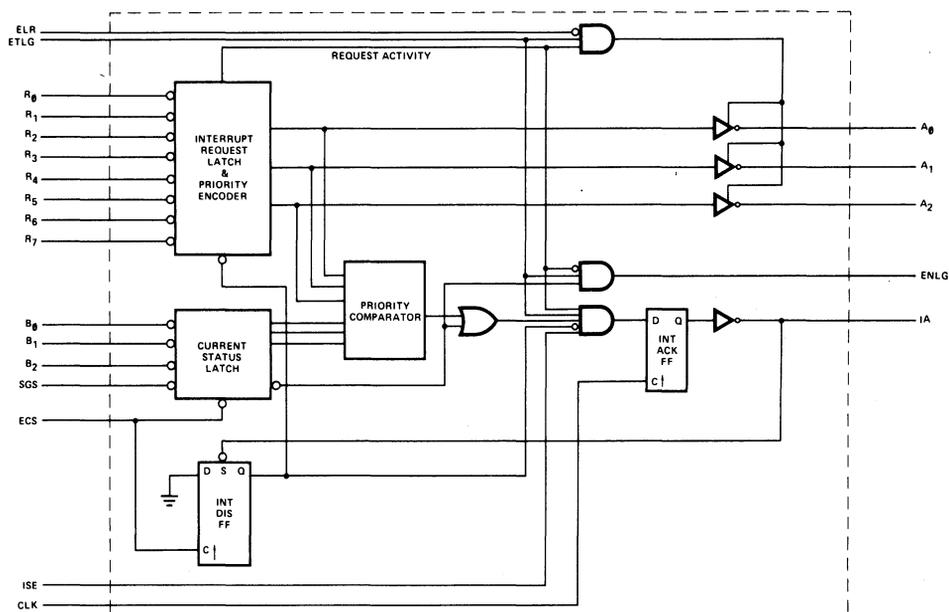


Figure 1. 3214 Block Diagram.

## D.C. AND OPERATING CHARACTERISTICS

## ABSOLUTE MAXIMUM RATINGS\*

Temperature Under Bias		
Ceramic . . . . .		-65°C to +75°C
Plastic . . . . .		0°C to +75°C
Storage Temperature . . . . .		-65°C to +160°C
All Output and Supply Voltages . . . . .		-0.5V to +7V
All Input Voltages . . . . .		-1.0V to +5.5V
Output Currents . . . . .		100 mA

\*COMMENT: Stresses above those listed under "Absolute Maximum Rating" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or at any other condition above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum ratings for extended periods may affect device reliability.

$T_A = 0^\circ\text{C to } +75^\circ\text{C}$ ,  $V_{CC} = 5.0\text{V } \pm 5\%$

SYMBOL	PARAMETER	LIMITS			UNIT	CONDITIONS
		MIN	TYP(1)	MAX		
$V_C$	Input Clamp Voltage (all inputs)			-1.0	V	$I_C = -5\text{ mA}$
$I_F$	Input Forward Current:	ETLG input	-0.15	-0.5	mA	$V_F = 0.45\text{V}$
		all other inputs	-0.08	-0.25	mA	
$I_R$	Input Reverse Current:	ETLG input		80	$\mu\text{A}$	$V_R = 5.25\text{V}$
		all other inputs		40	$\mu\text{A}$	
$V_{IL}$	Input LOW Voltage:			0.8	V	$V_{CC} = 5.0\text{V}$
$V_{IH}$	Input HIGH Voltage:	2.0			V	$V_{CC} = 5.0\text{V}$
$I_{CC}$	Power Supply Current <sup>(2)</sup>		90	130	mA	
$V_{OL}$	Output LOW Voltage:		.3	.45	V	$I_{OL} = 15\text{ mA}$
$V_{OH}$	Output HIGH Voltage:	2.4	3.0		V	$I_{OH} = -1\text{ mA}$
$I_{OS}$	Short Circuit Output Current: ENLG output	-20	-35	-55	mA	$V_{CC} = 5.0\text{V}$
$I_{CEX}$	Output Leakage Current: IA and A <sub>0</sub> -A <sub>2</sub> outputs			100	$\mu\text{A}$	$V_{CEX} = 5.25\text{V}$

## NOTES:

(1) Typical values are for  $T_A = 25^\circ\text{C}$  and nominal supply voltage.

(2) B<sub>0</sub>-B<sub>2</sub>, SGS, CLK, R<sub>0</sub>-R<sub>4</sub> grounded, all other inputs and all outputs open.

## A.C. CHARACTERISTICS

 $T_A = 0^\circ\text{C to } +75^\circ\text{C}$ ,  $V_{CC} = +5\text{V} \pm 5\%$ 

SYMBOL	PARAMETER	LIMITS			UNIT
		MIN	TYP <sup>(1)</sup>	MAX	
$t_{CY}$	CLK Cycle Time	80			ns
$t_{PW}$	CLK, ECS, IA Pulse Width	25	15		ns
	<i>Interrupt Flip-Flop Next State Determination:</i>				
$t_{ISS}$	ISE Set-Up Time to CLK	16	12		ns
$t_{ISH}$	ISE Hold Time After CLK	20	10		ns
$t_{ETCS}^2$	ETLG Set-Up Time to CLK	25	12		ns
$t_{ETCH}^2$	ETLG Hold Time After CLK	20	10		ns
$t_{ECCS}^3$	ECS Set-Up Time to CLK (to clear interrupt inhibit prior to CLK)	80	25		ns
$t_{ECCH}^3$	ECS Hold Time After CLK (to hold interrupt inhibit)	0			ns
$t_{ECRS}^3$	ECS Set-Up Time to CLK (to enable new requests through the request latch)	110	70		ns
$t_{ECRH}^3$	ECS Hold Time After CLK (to hold requests in request latch)	0			ns
$t_{ECSS}^2$	ECS Set-Up Time to CLK (to enable new status through the status latch)	75	70		ns
$t_{ECSH}^2$	ECS Hold Time After CLK (to hold status in status latch)	0			ns
$t_{DCS}^2$	SGS and $B_0$ - $B_2$ Set-Up Time to CLK (current status latch enabled)	70	50		ns
$t_{DCH}^2$	SGS and $B_0$ - $B_2$ Hold Time After CLK (current status latch enabled)	0			ns
$t_{RCS}^3$	$R_0$ - $R_7$ Set-Up Time to CLK (request latch enabled)	90	55		ns
$t_{RCH}^3$	$R_0$ - $R_7$ Hold Time After CLK (request latch enabled)	0			ns
$t_{ICS}$	IA Set-Up Time to CLK (to set interrupt inhibit F.F. before CLK)	55	35		ns
$t_{CI}$	CLK to IA Propagation Delay		15	25	ns
	<i>Contents of Request Latch and Request Level Output Status Determination:</i>				
$t_{RIS}^4$	$R_0$ - $R_7$ Set-Up Time to IA	10	0		ns
$t_{RIH}^4$	$R_0$ - $R_7$ Hold Time After IA	35	20		ns
$t_{RA}$	$R_0$ - $R_7$ to $A_0$ - $A_2$ Propagation Delay (request latch enabled)		80	100	ns
$t_{ELA}$	ELR to $A_0$ - $A_2$ Propagation Delay		40	55	ns
$t_{ECA}$	ECS to $A_0$ - $A_2$ Propagation Delay (to enable new requests through request latch)		100	120	ns
$t_{ETA}$	ETLG to $A_0$ - $A_2$ Propagation Delay		35	70	ns

**A.C. CHARACTERISTICS (CONT)**

SYMBOL	PARAMETER	LIMITS			UNIT
		MIN	TYP <sup>(1)</sup>	MAX	
<i>Contents of Current Priority Status Latch Determination:</i>					
t <sub>DECS</sub> <sup>4</sup>	SGS and B <sub>0</sub> -B <sub>2</sub> Set-Up Time to ECS	15	10		ns
t <sub>DECH</sub> <sup>4</sup>	SGS and B <sub>0</sub> -B <sub>2</sub> Hold Time After ECS	15	10		ns
<i>Enable Next Level Group Determination:</i>					
t <sub>REN</sub>	R <sub>0</sub> -R <sub>7</sub> to ENLG Propagation Delay		45	70	ns
t <sub>TEN</sub>	ETLG to ENLG Propagation Delay		20	25	ns
t <sub>ECRN</sub>	ECS to ENLG Propagation Delay (enabling new request through the request latch)		85	90	ns
t <sub>ECSN</sub>	ECS to ENLG Propagation Delay (enabling new SGS through status latch)		35	55	ns

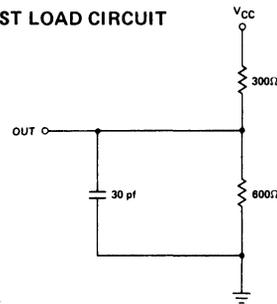
**NOTES:**

- (1) Typical values are for T<sub>A</sub> = 25°C and nominal supply voltage.
- (2) Required for proper operation if ISE is enabled during next clock pulse.
- (3) These times are not required for proper operation but for desired change in interrupt flip-flop.
- (4) Required for new request or status to be properly loaded.
- (5) t<sub>CY</sub> = t<sub>ICS</sub> + t<sub>CI</sub>

**TEST CONDITIONS:**

Input pulse amplitude: 2.5 volts.  
 Input rise and fall times: 5 ns between 1 and 2 volts.  
 Output loading of 15 mA and 30 pf.  
 Speed measurements taken at the 1.5V levels.

**TEST LOAD CIRCUIT**



**CAPACITANCE<sup>(5)</sup>**

T<sub>A</sub> = 25°C

SYMBOL	PARAMETER	LIMITS			UNIT
		MIN	TYP <sup>(1)</sup>	MAX	
C <sub>IN</sub>	Input Capacitance		5	10	pf
C <sub>OUT</sub>	Output Capacitance		7	12	pf

**TEST CONDITIONS:**

V<sub>BIAS</sub> = 2.5V, V<sub>CC</sub> = 5V, T<sub>A</sub> = 25°C, f = 1 MHz

**NOTE:**

- (5) This parameter is periodically sampled and not 100% tested.

**D.C. AND OPERATING CHARACTERISTICS**

**ABSOLUTE MAXIMUM RATINGS\***

Temperature Under Bias

CerDip	-55°C to +125°C
Storage Temperature	-65°C to +160°C
All Output and Supply Voltages	-0.5V to +7V
All Input Voltages	-1.0V to +5.5V
Output Currents	100 mA

\*COMMENT: Stresses above those listed under "Absolute Maximum Rating" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or at any other condition above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum ratings for extended periods may affect device reliability.

**T<sub>A</sub> = -55°C to +125°C; V<sub>CC</sub> = 5.0V ± 10%**

SYMBOL	PARAMETER	LIMITS			UNIT	CONDITIONS
		MIN	TYP <sup>(1)</sup>	MAX		
V <sub>C</sub>	Input Clamp Voltage (all inputs)			-1.2	V	I <sub>C</sub> = -5 mA
I <sub>F</sub>	Input Forward Current: ETLG input all other inputs		-0.15	-0.5	mA	V <sub>F</sub> = 0.45V
			-0.08	-0.25	mA	
I <sub>R</sub>	Input Reverse Current: ETLG input all other inputs			80	μA	V <sub>R</sub> = 5.5V
				40	μA	
V <sub>IL</sub>	Input LOW Voltage: all inputs			0.8	V	V <sub>CC</sub> = 5.0V
V <sub>IH</sub>	Input HIGH Voltage: all inputs	2.0			V	V <sub>CC</sub> = 5.0V
I <sub>CC</sub>	Power Supply Current <sup>(2)</sup>		90	130	mA	
V <sub>OL</sub>	Output LOW Voltage: all outputs		.3	.45	V	I <sub>OL</sub> = 10 mA
V <sub>OH</sub>	Output HIGH Voltage: ENLG output	2.4	3.0		V	I <sub>OH</sub> = -1 mA
I <sub>OS</sub>	Short Circuit Output Current: ENLG output	-15	-35	-55	mA	V <sub>CC</sub> = 5.0V
I <sub>CEX</sub>	Output Leakage Current: IA and A <sub>0</sub> -A <sub>3</sub> outputs			100	μA	V <sub>CEX</sub> = 5.5V

NOTES:

- (1) Typical values are for T<sub>A</sub> = 25°C and nominal supply voltage.
- (2) B<sub>0</sub>-B<sub>2</sub>, SGS, CLK, R<sub>0</sub>-R<sub>4</sub> grounded, all other inputs and all outputs open.

## A.C. CHARACTERISTICS

 $T_A = -55^\circ\text{C to } +125^\circ\text{C}; V_{CC} = 5.0\text{V} \pm 10\%$ 

SYMBOL	PARAMETER	LIMITS			UNIT
		MIN	TYP <sup>(1)</sup>	MAX	
t <sub>CY</sub>	CLK Cycle Time <sup>(5)</sup>	85			ns
t <sub>PW</sub>	CLK, ECS, IA Pulse Width	25	15		ns
	<i>Interrupt Flip-Flop Next State Determination:</i>				
t <sub>ISS</sub>	ISE Set-Up Time to CLK	16	12		ns
t <sub>ISH</sub>	ISE Hold Time After CLK	20	10		ns
t <sub>ETCS</sub> <sup>2</sup>	ETLG Set-Up Time to CLK	25	12		ns
t <sub>ETCH</sub> <sup>2</sup>	ETLG Hold Time After CLK	20	10		ns
t <sub>ECCS</sub> <sup>3</sup>	ECS Set-Up Time to CLK (to clear interrupt inhibit prior to CLK)	85	25		ns
t <sub>ECCH</sub> <sup>3</sup>	ECS Hold Time After CLK (to hold interrupt inhibit)	0			ns
t <sub>ECRS</sub> <sup>3</sup>	ECS Set-Up Time to CLK (to enable new requests through the request latch)	110	70		ns
t <sub>ECRH</sub> <sup>3</sup>	ECS Hold Time After CLK (to hold requests in request latch)	0			ns
t <sub>ECSS</sub> <sup>2</sup>	ECS Set-Up Time to CLK (to enable new status through the status latch)	85	70		ns
t <sub>ECSH</sub> <sup>2</sup>	ECS Hold Time After CLK (to hold status in status latch)	0			ns
t <sub>DCS</sub> <sup>2</sup>	SGS and B <sub>0</sub> -B <sub>2</sub> Set-Up Time to CLK (current status latch enabled)	90	50		ns
t <sub>DCH</sub> <sup>2</sup>	SGS and B <sub>0</sub> -B <sub>2</sub> Hold Time After CLK (current status latch enabled)	0			ns
t <sub>RCS</sub> <sup>3</sup>	R <sub>0</sub> -R <sub>7</sub> Set-Up Time to CLK (request latch enabled)	100	55		ns
t <sub>RCH</sub> <sup>3</sup>	R <sub>0</sub> -R <sub>7</sub> Hold Time After CLK (request latch enabled)	0			ns
t <sub>ICS</sub>	IA Set-Up Time to CLK (to set interrupt inhibit F.F. before CLK)	55	35		ns
t <sub>CI</sub>	CLK to IA Propagation Delay		15	30	ns
	<i>Contents of Request Latch and Request Level Output Status Determination:</i>				
t <sub>RIS</sub> <sup>4</sup>	R <sub>0</sub> -R <sub>7</sub> Set-Up Time to IA	10	0		ns
t <sub>RIH</sub> <sup>4</sup>	R <sub>0</sub> -R <sub>7</sub> Hold Time After IA	35	20		ns
t <sub>RA</sub>	R <sub>0</sub> -R <sub>7</sub> to A <sub>0</sub> -A <sub>2</sub> Propagation Delay (request latch enabled)		80	100	ns
t <sub>ELA</sub>	ELR to A <sub>0</sub> -A <sub>2</sub> Propagation Delay		40	55	ns
t <sub>ECA</sub>	ECS to A <sub>0</sub> -A <sub>2</sub> Propagation Delay (to enable new requests through request latch)		100	130	ns
t <sub>ETA</sub>	ETLG to A <sub>0</sub> -A <sub>2</sub> Propagation Delay		35	70	ns

## A.C. CHARACTERISTICS (CON'T)

SYMBOL	PARAMETER	LIMITS			UNIT
		MIN	TYP(1)	MAX	
<i>Contents of Current Priority Status Latch Determination:</i>					
$t_{DECS}^4$	SGS and B <sub>0</sub> -B <sub>2</sub> Set-Up Time to ECS	20	10		ns
$t_{DECH}^4$	SGS and B <sub>0</sub> -B <sub>2</sub> Hold Time After ECS	20	10		ns
<i>Enable Next Level Group Determination:</i>					
$t_{REN}$	R <sub>0</sub> -R <sub>7</sub> to ENLG Propagation Delay		45	70	ns
$t_{ETEN}$	ETLG to ENLG Propagation Delay		20	30	ns
$t_{ECRN}$	ECS to ENLG Propagation Delay (enabling new request through the request latch)		85	110	ns
$t_{ECSN}$	ECS to ENLG Propagation Delay (enabling new SGS through status latch)		35	55	ns

## NOTES:

- (1) Typical values are for  $T_A = 25^\circ\text{C}$  and nominal supply voltage.
- (2) Required for proper operation if ISE is enabled during next clock pulse.
- (3) These times are not required for proper operation but for desired change in interrupt flip-flop.
- (4) Required for new request or status to be properly loaded.
- (5)  $t_{CY} = t_{ICS} + t_{CI}$

## TEST CONDITIONS:

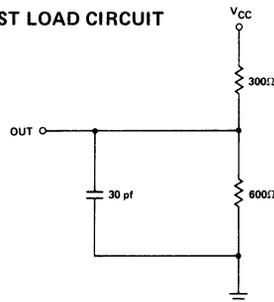
Input pulse amplitude: 2.5 volts.

Input rise and fall times: 5 ns between 1 and 2 volts.

Output loading of 15 mA and 30 pf.

Speed measurements taken at the 1.5V levels.

## TEST LOAD CIRCUIT

CAPACITANCE<sup>(5)</sup>

$T_A = 25^\circ\text{C}$

SYMBOL	PARAMETER	LIMITS			UNIT
		MIN	TYP(1)	MAX	
$C_{IN}$	Input Capacitance		5	10	pf
$C_{OUT}$	Output Capacitance		7	12	pf

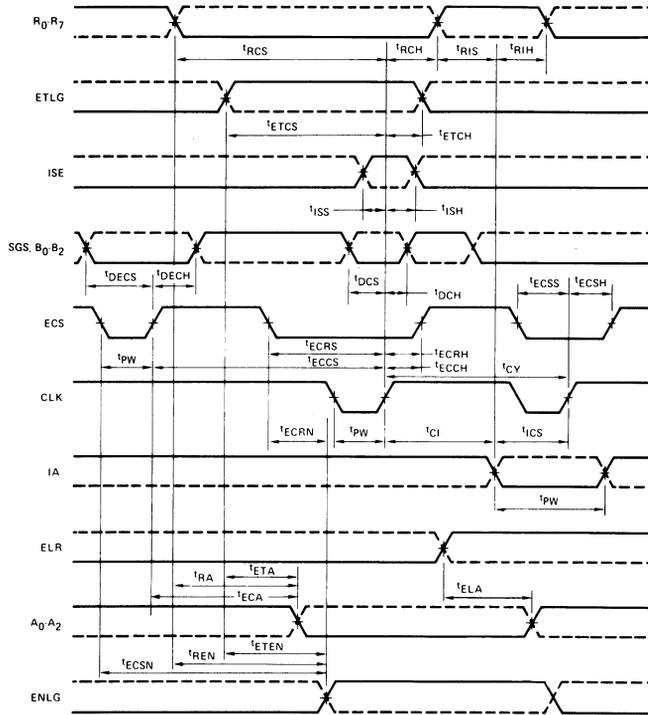
## TEST CONDITIONS:

$V_{BIAS} = 2.5\text{V}$ ,  $V_{CC} = 5\text{V}$ ,  $T_A = 25^\circ\text{C}$ ,  $f = 1\text{MHz}$

## NOTE:

- (5) This parameter is periodically sampled and not 100% tested.

## WAVEFORMS



## TYPICAL CONFIGURATIONS

The ICU has been designed for use with the INTEL Series 3000 Bipolar Microcomputer Set. It operates from the single common system clock and can accept an interrupt strobe (ISE) generated by the 3001 Microprogram Control Unit or by a bit in microprogram memory as shown in Figures 2 and 3.

The ICU responds to interrupt requests of sufficient priority by entering the interrupt active mode. Its output (IA) can be tied to the row enable input (ERA) of the 3001 MCU. This gates an alternate row address onto the microprogram memory ad-

dress bus which forces the system to execute an interrupt handling routine. Alternatively, the ICU output can be used to directly modify the MCU jump instruction (AC inputs) so that the next microprogram address corresponds to the start of the interrupt routine rather than the start of the macroinstruction fetch sequence. Of course, in the case of this particular implementation, the interrupt strobe must be generated one clock period earlier and the ISE output of the MCU should not be used.

As shown in Figure 4, when several ICUs are used together to provide a

multiple of 8 priority levels, most control lines will be bussed. The Intel 3205 Decoder may be used to decode the high order bits of the request level, the information being derived from the daisy-chain group level signals.

As mentioned in the functional description, the request level information ( $A_0-A_2$ ) may be sent to the 3001 MCU or the 3002 CP array as a constant through the Mask (K) bus or as data through the memory (M) or data (I) busses. Similarly, the status information can be generated by the CP array and carried to the ICU by the data (D) output bus of the CP array.

TYPICAL CONFIGURATIONS (CON'T)

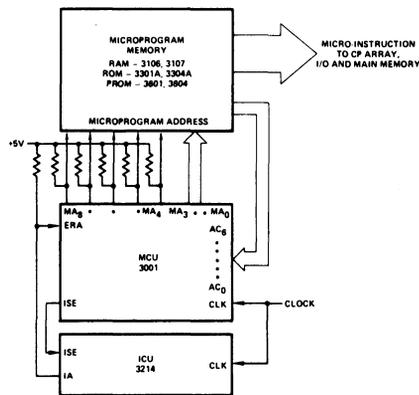


Figure 2. Interfacing 3214 with 3001.

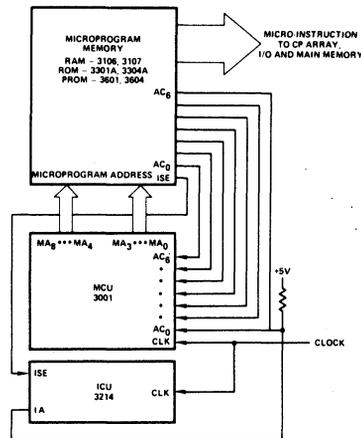


Figure 3. Interfacing 3214 with 3001.

Interrupt strobe generated by MCU.  
 Interrupt routine start address at column 15 row 31.  
 Macro-instruction fetch start address at column 15 row 0.

Interrupt strobe generated by the microprogram memory.  
 Interrupt routine start address at column 14 row 0.  
 Macro-instruction fetch start address at column 15 row 0.

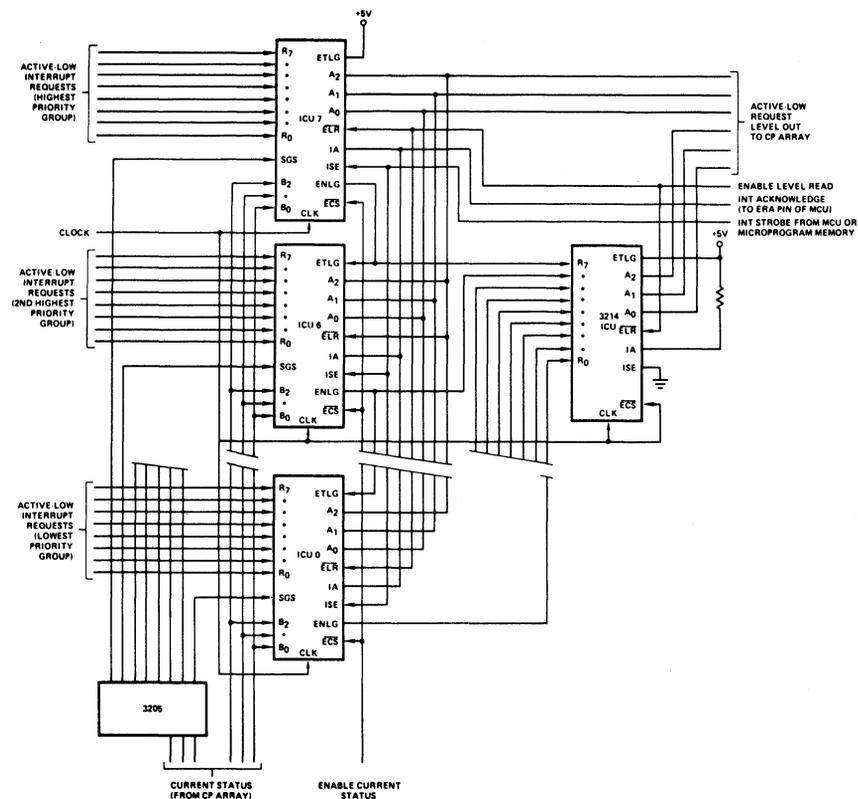


Figure 4. Using Several 3214 Interrupt Chips to Provide more than Eight Priority Levels. (The 3214 at the upper right is used to encode the high order bits of the requesting level)



# SCHOTTKY BIPOLAR LSI MICROCOMPUTER SET

# 3216/3226 PARALLEL BIDIRECTIONAL BUS DRIVER

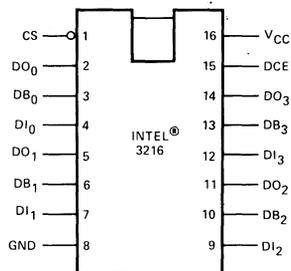
The INTEL<sup>®</sup> 3216 is a high-speed 4-bit Parallel, Bidirectional Bus Driver. Its three-state outputs enable it to isolate and drive external bus structures associated with Series 3000 systems

The INTEL 3226 is a high-speed 4-bit Parallel, Inverting Bidirectional Bus Driver. Its three-state outputs enable it to isolate and drive external bus structures associated with Series 3000 systems.

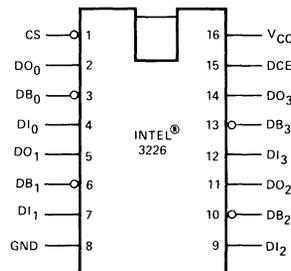
The 3216/3226 driver and receiver gates have three state outputs with PNP inputs. When the drivers or receivers are tri-stated the inputs are disabled, presenting a low current load, typically less than 40  $\mu$ amps, to the system bus structure.

- High Performance—25 ns typical propagation delay**
- Low Input Load Current—0.25 mA maximum**
- High Output Drive Capability for Driving System Data Busses**
- Three-State Outputs**
- TTL Compatible**
- 16-pin DIP**

## PACKAGE CONFIGURATION

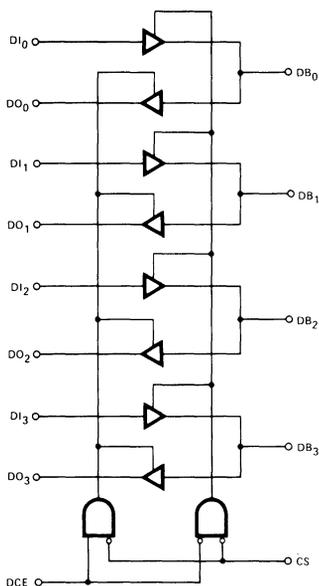


**3216**

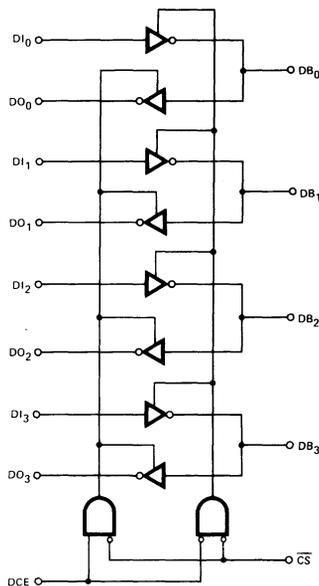


**3226**

## LOGIC DIAGRAM 3216



## LOGIC DIAGRAM 3226



## D.C. AND OPERATING CHARACTERISTICS

### ABSOLUTE MAXIMUM RATINGS\*

Temperature Under Bias

Ceramic . . . . .	-65°C to +75°C
Plastic . . . . .	0°C to +75°C

Storage Temperature . . . . . -65°C to +160°C

All Output and Supply Voltages . . . . . -0.5V to +7V

All Input Voltages . . . . . -1.0V to +5.5V

Output Currents . . . . . 125 mA

\*COMMENT: Stresses above those listed under "Absolute Maximum Rating" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or at any other condition above those indicated in the operational sections of this specification is not implied.

T<sub>A</sub> = 0°C to +75°C, V<sub>CC</sub> = +5.0V ±5%

Symbol	Parameter	Limit			Unit	Condition
		Min.	Typ.	Max.		
I <sub>F</sub>	Input Load Current					
	DCE, $\overline{CS}$ Inputs		-0.15	-0.5	mA	V <sub>F</sub> = 0.45V
	All Other Inputs		-0.08	-0.25	mA	
I <sub>R</sub>	Input Leakage Current					
	DCE, $\overline{CS}$ Inputs			80	μA	V <sub>R</sub> = 5.25V
	DI Inputs			40	μA	
V <sub>C</sub>	Input Clamp Voltage			-1	V	I <sub>C</sub> = -5mA
V <sub>IL</sub>	Input Low Voltage			0.95	V	V <sub>CC</sub> = 5.0V
V <sub>IH</sub>	Input High Voltage	2.0			V	V <sub>CC</sub> = 5.0V
V <sub>OL1</sub>	Output Low Voltage		0.3	0.45	V	DO Outputs I <sub>OL</sub> = 15mA DB Outputs I <sub>OL</sub> = 25mA
V <sub>OL2</sub>	Output Low Voltage		0.5	0.6	V	DB Outputs I <sub>OL</sub> = 50mA
V <sub>OH1</sub>	Output High Voltage	3.65	4.0		V	I <sub>OH</sub> = -1mA
V <sub>OH2</sub>	Output High Voltage	2.4	3.0		V	I <sub>OH</sub> = -10mA
I <sub>SC</sub>	Output Short Circuit Current					
	DO Outputs	-15	-35	-65	mA	V <sub>CC</sub> = 5.0V
	DB Outputs	-30	-75	-120	mA	
I <sub>O</sub>	Output Leakage Current					
	High Impedance State					
	DO Outputs			20	μA	V <sub>O</sub> = 0.45V/5.25V
DB Outputs			100	μA		
I <sub>CC</sub>	Power Supply Current	3216	95	130	mA	
		3226	85	120	mA	

NOTE: Typical values are for T<sub>A</sub> = 25°C

**A.C. CHARACTERISTICS**  $T_A = 0^\circ\text{C}$  to  $+75^\circ\text{C}$ ,  $V_{CC} = +5.0\text{V} \pm 5\%$

Symbol	Parameter	Min.	Limit		Unit	Condition
			Typ.	Max.		
T <sub>PD1</sub>	Input to Output Delay	3216	15	25	ns	C <sub>L</sub> =30pF, R <sub>1</sub> =300Ω, R <sub>2</sub> =600Ω
	DO Outputs	3226	14	25		
T <sub>PD2</sub>	Input to Output Delay	3216	19	30	ns	C <sub>L</sub> =300pF, R <sub>1</sub> =90Ω, R <sub>2</sub> =180Ω
	DB Outputs	3226	16	25		
T <sub>E</sub>	Output Enable Time	3216	42	65	ns <sup>(2)</sup>	DO Outputs: C <sub>L</sub> =30pF, R <sub>1</sub> =300Ω/10KΩ, R <sub>2</sub> =600Ω/1KΩ  DB Outputs: C <sub>L</sub> =300pF, R <sub>1</sub> =90Ω/10KΩ, R <sub>2</sub> =180Ω/1KΩ
	DCE, CS	3226	36	54		
T <sub>D</sub>	Output Disable Time		16	35	ns <sup>(2)</sup>	DO Outputs: C <sub>L</sub> =5pF, R <sub>1</sub> =300Ω/10KΩ, R <sub>2</sub> =600Ω/1KΩ  DB Outputs: C <sub>L</sub> =5pF, R <sub>1</sub> =90Ω/10KΩ, R <sub>2</sub> =180Ω/1KΩ
	DCE, CS					

NOTE: (1) Typical values are for T<sub>A</sub> = 25°C and nominal supply voltage.

(2) The test load circuit is set for worst case source and sink loading on the outputs. The two resistor values for R<sub>1</sub> and R<sub>2</sub> correspond to worst case sink and source loading, respectively.

**CAPACITANCE<sup>(2)</sup>** T<sub>A</sub> = 25°C

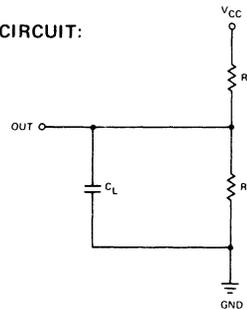
Symbol	Parameter	Limit		
		Min.	Typ.	Max.
C <sub>IN</sub>	Input Capacitance	4	6	pF
C <sub>OUT</sub>	Output Capacitance			
	DO Outputs	6	10	pF
	DB Outputs	13	18	pF

Note:  
 (2) This parameter is periodically sampled and is not 100% tested.  
 Condition of measurement is f = 1MHz, V<sub>BIAS</sub> = 2.5V,  
 V<sub>CC</sub> = 5.0V and T<sub>A</sub> = 25°C.

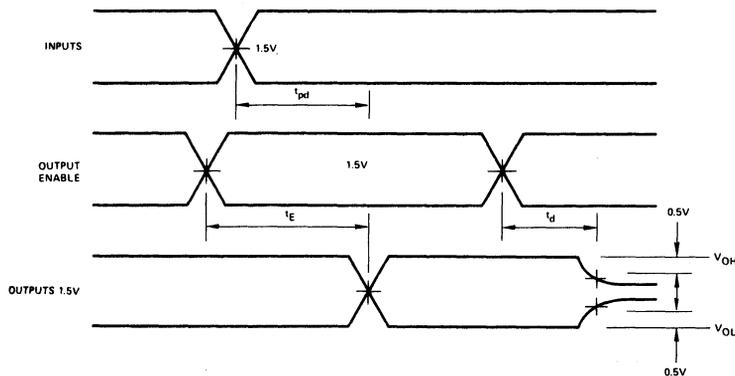
**TEST CONDITIONS:**

Input pulse amplitude of 2.5V.  
 Input rise and fall times of 5 ns between 1 and 2 volts.  
 Output loading is 5 mA and 10 pF.  
 Speed measurements are made at 1.5 volt levels.

**TEST LOAD CIRCUIT:**



**WAVEFORMS**



## D.C. AND OPERATING CHARACTERISTICS

## ABSOLUTE MAXIMUM RATINGS\*

## Temperature Under Bias

Ceramic . . . . . -65°C to +75°C

Storage Temperature . . . . . -65°C to +160°C

All Output and Supply Voltages . . . . . -0.5V to +7V

All Input Voltages . . . . . -1.0V to +5.5V

Output Currents . . . . . 125 mA

\*COMMENT: Stresses above those listed under "Absolute Maximum Rating" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or at any other condition above those indicated in the operational sections of this specification is not implied.

 $T_A = -55^\circ\text{C to } +125^\circ\text{C}, V_{CC} = +5.0\text{V } \pm 10\%$ 

Symbol	Parameter	Min.	Limit Typ.	Max.	Unit	Condition		
I <sub>F</sub>	Input Load Current							
	DCE, $\overline{\text{CS}}$ Inputs		-0.15	-0.5	mA	V <sub>F</sub> = 0.45V		
	All Other Inputs		-0.08	-0.25	mA			
I <sub>R</sub>	Input Leakage Current							
	DCE, $\overline{\text{CS}}$ Inputs			80	μA	V <sub>R</sub> = 5.5V		
	DI Inputs			40	μA			
V <sub>C</sub>	Input Clamp Voltage			-1.2	V	I <sub>C</sub> = -5mA		
V <sub>IL</sub>	Input Low Voltage	M3216		0.95	V	V <sub>CC</sub> = 5.0V		
		M3226		0.90	V			
V <sub>IH</sub>	Input High Voltage	2.0			V	V <sub>CC</sub> = 5.0V		
V <sub>OL1</sub>	Output Low Voltage	DO, DB Outputs		0.3	0.45	V	DO Outputs I <sub>OL</sub> = 15mA	
							DB Outputs I <sub>OL</sub> = 25mA	
V <sub>OL2</sub>	Output Low Voltage		0.5	0.6	V	DB Outputs I <sub>OL</sub> = 45mA		
V <sub>OH1</sub>	Output High Voltage	DO Outputs Only		3.4	3.8	V	I <sub>OH</sub> = -0.5mA	
							I <sub>OH</sub> = -2.0mA	
V <sub>OH2</sub>	Output High Voltage	2.4	3.0		V	I <sub>OH</sub> = -5mA		
I <sub>SC</sub>	Output Short Circuit Current	DO Outputs		-15	-35	mA	V <sub>CC</sub> = 5.0V	
			DB Outputs		-30	-75		mA
								-120
I <sub>O</sub>	Output Leakage Current	High Impedance State					V <sub>O</sub> = 0.45V/5.5V	
			DO Outputs			20		μA
				DB Outputs				100
I <sub>CC</sub>	Power Supply Current	M3216	95	130	mA			
		M3226	85	120	mA			

NOTE: Typical values are for T<sub>A</sub> = 25°C

**A.C. CHARACTERISTICS**  $T_A = -55^{\circ}\text{C}$  to  $+125^{\circ}\text{C}$ ,  $V_{CC} = 5.0\text{V} \pm 10\%$

Symbol	Parameter	Min.	Limit		Unit	Condition
			Typ.	Max.		
$T_{PD1}$	Input to Output Delay DO Outputs		15	25	ns	$C_L = 30\text{pF}$ , $R_1 = 300\Omega$ , $R_2 = 600\Omega$
$T_{PD2}$	Input to Output Delay DB Outputs	M3216 M3226	19 16	33 25	ns	$C_L = 300\text{pF}$ , $R_1 = 90\Omega$ , $R_2 = 180\Omega$
$T_E$	Output Enable Time	M3216 M3226	42 36	75 62	ns <sup>(2)</sup>	DO Outputs: $C_L = 30\text{pF}$ , $R_1 = 300\Omega/10\text{K}\Omega$ , $R_2 = 600\Omega/1\text{K}\Omega$  DB Outputs: $C_L = 300\text{pF}$ , $R_1 = 90\Omega/10\text{K}\Omega$ , $R_2 = 180\Omega/1\text{K}\Omega$
$T_D$	Output Disable Time	M3216 M3226	16 16	40 38	ns <sup>(2)</sup>	DO Outputs: $C_L = 5\text{pF}$ , $R_1 = 300\Omega/10\text{K}\Omega$ , $R_2 = 600\Omega/1\text{K}\Omega$  DB Outputs: $C_L = 5\text{pF}$ , $R_1 = 90\Omega/10\text{K}\Omega$ , $R_2 = 180\Omega/1\text{K}\Omega$

NOTE: (1) Typical values are for  $T_A = 25^{\circ}\text{C}$  and nominal supply voltage.  
 (2) The test load circuit is set for worst case source and sink loading on the outputs. The two resistor values for R1 and R2 correspond to worst case sink and source loading, respectively.

**CAPACITANCE<sup>(2)</sup>**  $T_A = 25^{\circ}\text{C}$

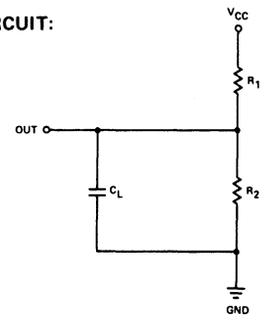
Symbol	Parameter	Limit			Unit
		Min.	Typ.	Max.	
$C_{IN}$	Input Capacitance	4	6		pF
$C_{OUT}$	Output Capacitance				
	DO Outputs	6	10		pF
	DB Outputs	13	18		pF

Note:  
 (2) This parameter is periodically sampled and is not 100% tested.  
 Condition of measurement is  $f = 1\text{MHz}$ ,  $V_{BIAS} = 2.5\text{V}$ ,  
 $V_{CC} = 5.0\text{V}$  and  $T_A = 25^{\circ}\text{C}$ .

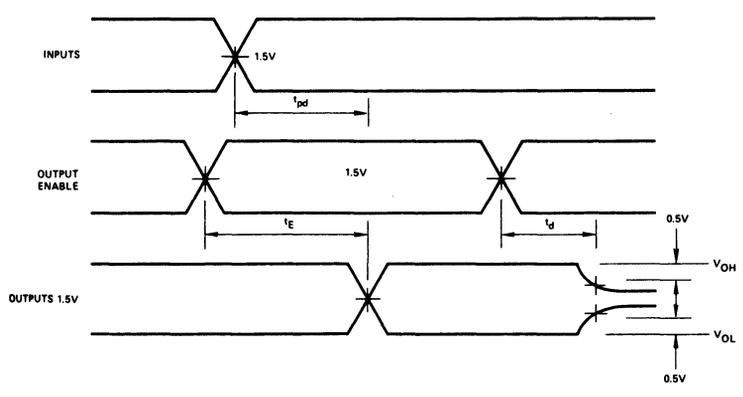
**TEST CONDITIONS:**

Input pulse amplitude of 2.5V.  
 Input rise and fall times of 5 ns between 1 and 2 volts.  
 Output loading is 5 mA and 10 pF.  
 Speed measurements are made at 1.5 volt levels.

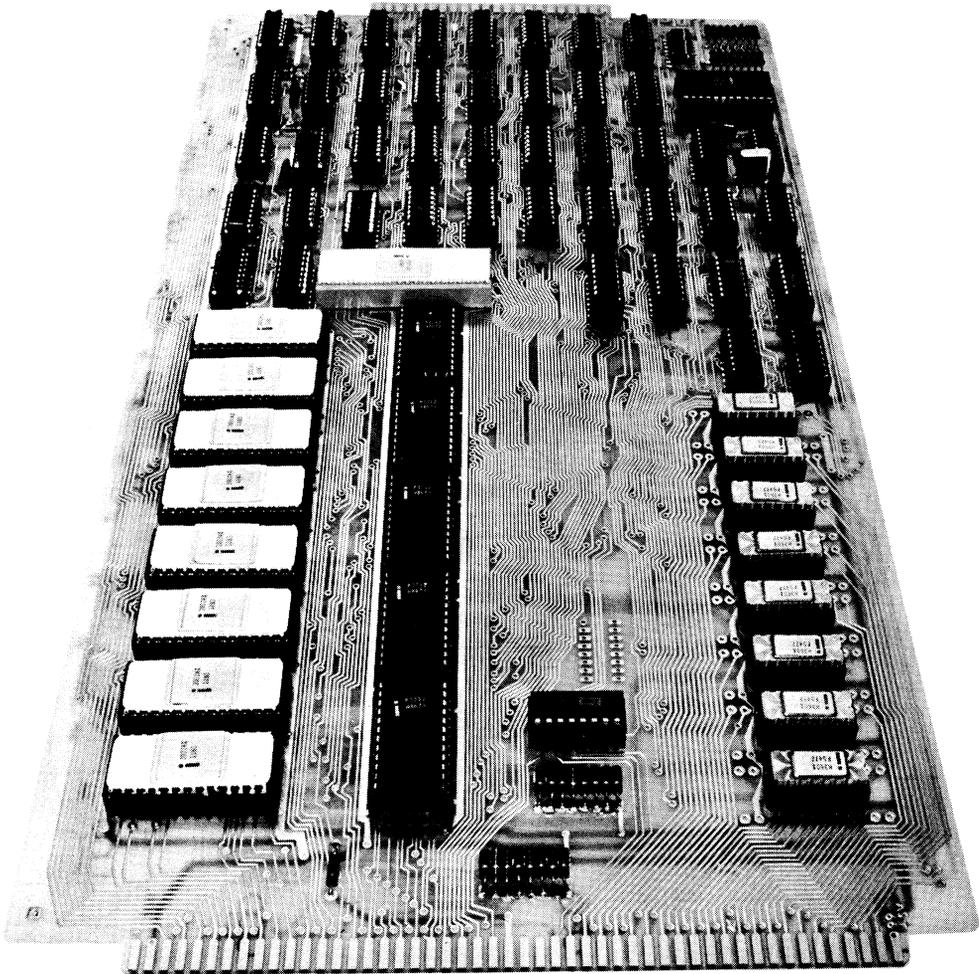
**TEST LOAD CIRCUIT:**



**WAVEFORMS**



# APPLICATIONS



## Series 3000 System Timing Considerations

by Gary Fielland

While the timing for each component in Intel's 3000 Series Schottky Bipolar Microcomputer Set is clearly specified, the composite system timing must be derived. This system timing is highly dependent on the particular configuration implemented, and hence, must be carefully considered for each implementation.

Though Intel cannot generate the system timing for every possible configuration, an effort has been made to study a few simple variations. By examining these examples and taking note of considerations given, it should be easier for the system designer to realize those times which are critical, and to generate the appropriate timing for his particular system.

The designer must consider many different factors in determining this "proper" system timing. Several simplifications are made to facilitate this discussion. Intel commercial grade parts are specified over a wide temperature range (0°C - 70°C) and so variations in timing due to temperature will not be considered, except for a short note at the end.

Whenever a signal must traverse a conductor between two points, there is a finite delay introduced into the signal path that is not accounted for by any data sheet. This is the delay due to such factors as the

length of the conductor, its transmission properties, and the characteristics of the driver and receiver. When a TTL totempole output drives a TTL input a short distance away this delay is usually negligible compared to other delays in the signal path. However, if there are many loads (increasing the capacitance), or the driver is of the open-collector type (limiting the drive), or if the receiver is physically far removed, the designer should consider and allow for any possible deleterious effects of this delay. For this discussion, except in one special case, the delay introduced by interconnection is not considered.

Aside from these simplifications, it should be realized that this note is not an extensive study of the timing of any particular system, but rather a compendium of typical considerations which a designer might examine.

Consider the basic "data sheet" 16-bit processor configuration as shown in Figure 1. It utilizes pipeline registers, full carry look-ahead, and a priority interrupt mechanism. To implement any such system the designer must be very careful to provide the proper timing for all components under all possible operating conditions. Such a system is highly complex and the analysis is best approached in a piecemeal fashion.

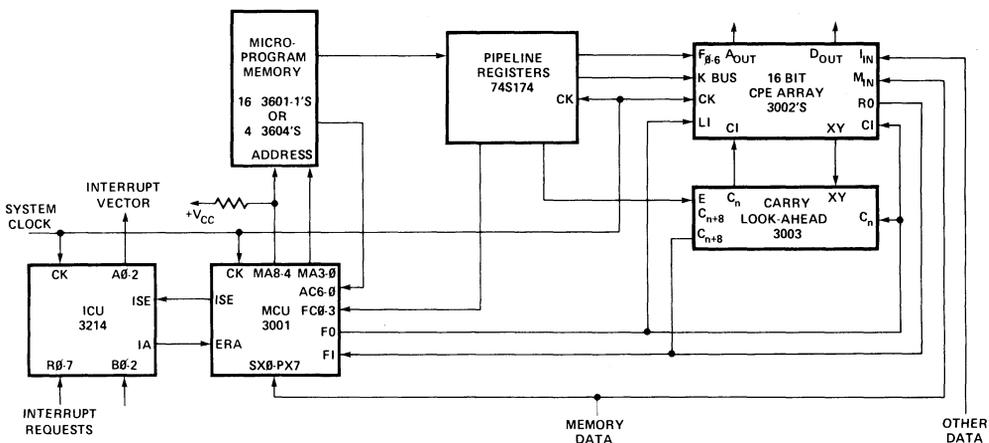


Figure 1. Basic 16-Bit Processor Configuration

# System Timing

## ARITHMETIC DELAY PATHS

First an analysis will be made of the arithmetic paths and delays. Imagine cycles in which arithmetic is being done within the CPE array. The carries must have time to propagate through the arithmetic portion and reach the MCU so that a conditional jump may be made based on that carry out bit. For the moment ignore other critical paths, and examine Figure 2 which illustrates these arithmetic cycles.

The cycle begins with the rising edge of the system clock as it clocks the pipeline registers. After the delay ( $t_{PLR}$ ) introduced by the pipeline, the function is available at the CPE array. There is a delay ( $t_{XF}$ ) while all the CPE's decode the function and generate their X and Y outputs for the operation. Once the X and Y outputs are stable, the Carry Look-Ahead circuit takes some time ( $t_{XC}$ ) to simultaneously generate all the carry outputs, including the one which goes to the MCU flag input. Time must be provided to allow for the carry-input setup time of the CPE's ( $t_{SS}$ ) and the MCU ( $t_{SI}$ ). Finally, adding in enough time for the clock pulse, which acts as a write pulse for the CPE register array, the cycle time is determined. Note the time for the MCU flag output to stabilize ( $t_{KO}$ ) was ignored as it is not a limiting specification for this configuration.

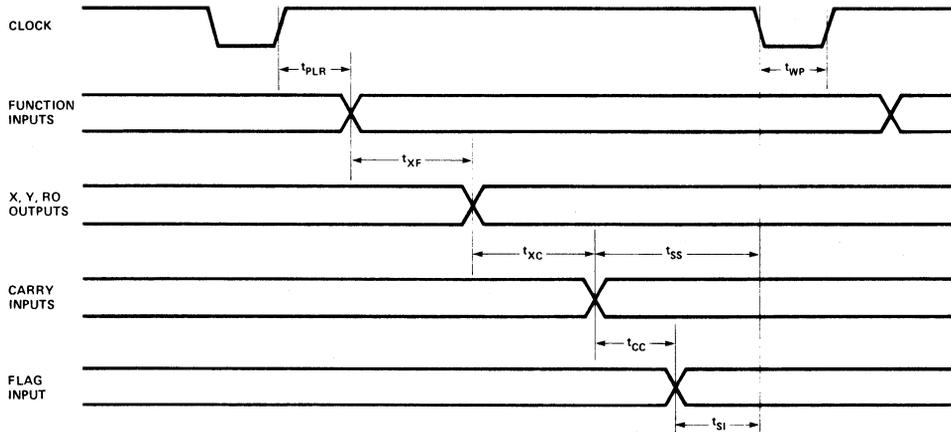
$$t_{CYCLE} = t_{PLR} + t_{XF} + t_{XC} + t_{SS} + t_{WP}$$

Keeping the same train of thought, consider individually the effects of variants from the configuration of Figure 1. If full carry look-ahead is not used and the carry is allowed to ripple through only the last slice, an additional delay path is introduced. After the 3003 has generated the carry outputs there is the CPE carry-in setup time ( $t_{SS}$ ) which must be met as before. However, the carry-out of the last slice will not be available to the MCU flag input until it has rippled through ( $t_{CC}$ ) that slice. Finally, the MCU flag input setup time ( $t_{SI}$ ) must be satisfied.

$$t_{CYCLE} = t_{PLR} + t_{XF} + t_{XC} + t_{CC} + t_{SI} + t_{WP}$$

If the 3003 Look-Ahead Carry circuit is not used, there will be considerable delay added to the basic cycle due to ripple carry time. Once the CPE function-inputs are stable, the function must be decoded and the carry-out of the least significant slice generated ( $t_{CF}$ ). The carry must ripple through six slices ( $6 * t_{CC}$ ) and meet the carry setup time ( $t_{SS}$ ) of the most significant slice. However, it must also ripple through this last slice ( $t_{CC}$ ) and meet the MCU flag input setup time which is a more severe restriction.

$$t_{CYCLE} = t_{PLR} + t_{CF} + (7 * t_{CC}) + t_{SI} + t_{WP}$$



$t_{PLR}$	CLK $\uparrow$ to pipeline register outputs (74S174)	17 nsec
$t_{XF}$	Function inputs to X, Y, RO outputs	52
$t_{XC}$	Lookahead - X, Y inputs to carry outputs	20
$t_{SS}$	Data set-up time, LI & CI	27
$t_{CC}$	Ripple carry (CI to CO) delay	25
	NOTE: $t_{CC}$ included only if carry ripples through last slice.	
$t_{SI}$	Flag input set-up time	15
$t_{WP}$	Clock pulse width	33
$t_{CYCLE}$	Full fast carry $t_{PLR} + t_{XF} + t_{XC} + t_{SS} + t_{WP}$	149
	Last slice ripple $t_{PLR} + t_{XF} + t_{XC} + t_{CC} + t_{SI} + t_{WP}$	162

If pipeline registers are not used; replace  $t_{PLR}$  with the sum of  $t_{CO}$  (CLK  $\uparrow$  to MA<sub>p-g</sub> outputs, 44 nsec) plus  $t_{ROM}$  (access time; 50 nsec for 3601-1, 70 nsec for 3604).

If 3003 fast carry is not used; replace  $t_{XF}$  with  $t_{CF}$  (function IN to CO output, 65 nsec); replace  $t_{XC} + t_{CC}$  with  $(N-1) * t_{CC}$ , where "N" is the number of slices used.

Figure 2. Non-Interrupt 16-Bit Processor Cycle Timing

If pipeline registers are not used, there will be additional delay. It takes some time ( $t_{CO}$ ) after the rising edge of the clock for the next address to propagate through the MCU address register and buffers. Then, when this address is stable the ROMs must be accessed and there will be a delay ( $t_{ROM}$ , access time) before their output and hence the CPE function-input is stable. Thus, the cycle time for a non-pipelined system with carry look-ahead is:

$$t_{CYCLE} = t_{CO} + t_{ROM} + t_{XF} + t_{XC} + t_{SS} + t_{WP}$$

In the previous discussion it was assumed that the operands in the arithmetic operations were internal registers and the K-bus as implemented. If one of the operands is the M-bus or the I-bus, additional consideration should be given. This situation will typically arise at the completion of a Memory-Read or Input cycle. Typically, these cycles are implemented such that the processor clock stops in its high state to wait for the data to be available, while the processor is in the midst of executing an LMM or similar instruction. Thus, it is often the case that the pipeline registers have long since been accessed and the function decoded.

Then, when the data becomes available a clock pulse is issued and normal operation continues. It is the time from the point the data becomes available until the clock pulse is issued (Data Input Setup Time) that is of concern here.

Consider first a special case. Namely, the data is input via an LTM instruction and no test will be made on the carry-output. This implies that for this specific instruction, carry propagation is unimportant and it is acceptable to have an erroneous carry-output. For such a case, it is sufficient to only allow for the CPE data setup time ( $t_{DS}$ ).

$$t_{SETUP} = t_{DS}$$

For the more general case where arithmetic is done on input and the carry-output may be tested, the above analysis is incomplete. While the above condition must be met, it is no longer the determining factor. Time must be allowed for carry propagation. See Figure 3, which illustrates this case.

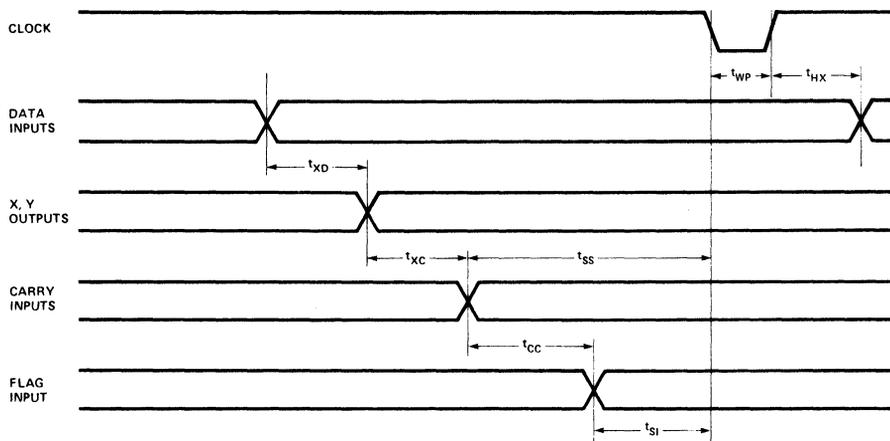
From the point in time when the data becomes stable at the CPE inputs, there is a delay ( $t_{XD}$ ) while the CPE generates the X and Y outputs. If Ripple Carry is employed, the delay ( $t_{CD}$ ) is in waiting for the carry-output of the least significant slice. After either of these delays the rest of the setup time is allocated analogously to that depicted in Figure 2 and discussed previously in relation to arithmetic cycle times.

$$t_{SETUP} (\text{Basic}) = t_{XD} + t_{XC} + t_{SS}$$

$$t_{SETUP} (\text{Last Slice Ripple}) = t_{XD} + t_{XC} + t_{CC} + t_{SI}$$

$$t_{SETUP} (\text{Ripple Carry}) = t_{CD} + (7 * t_{CC}) + t_{SI}$$

$$t_{SETUP} (\text{No Pipeline}) - \text{Same as Basic}$$



$t_{XD}$	Data inputs to X, Y outputs	42 nsec
$t_{HX}$	SX, PX input hold time	20
$t_{SET-UP}$	Full fast carry $t_{XD} + t_{XC} + t_{SS}$	89
	Last slice ripple $t_{XD} + t_{XC} + t_{CC} + t_{SI}$	102

If 3003 fast carry is not used; replace  $t_{XD}$  with  $t_{CD}$  (data input to CO output, 55 nsec); replace  $t_{XC} + t_{CC}$  with  $(N-1) * t_{CC}$  then  $t_{SET-UP}$  (ripple carry). 245

NOTE: This diagram is usually of concern only in relation to memory-read, or input cycles.

Figure 3. 16-Bit Processor Data Input Set-Up Times

# System Timing

## CONTROL DELAY PATHS

After carefully examining the arithmetic paths and delays it is appropriate to push all of this information onto your "mental stack" and begin again with a consideration of the control paths and delays. After this study the stack can be popped and information merged to yield overall system requirements.

Consider the MCU as it cycles in normal operation (see Figure 4). At the rising edge of the clock the new microprogram address is loaded into its holding register and through the output buffers. Thus, the new address reaches the ROM after a delay ( $t_{CO}$ ). Then there is a wait ( $t_{ROM}$ ) while the ROMs are accessed before the outputs are valid. At this time the MCU address control inputs (which are never pipelined) are valid and this must be early enough in the cycle to satisfy the MCU address control input setup time ( $t_{SF}$ ). Adding the time for the clock pulse ( $t_{WP}$ ) yields the cycle time requirement. Note this paragraph has ignored the generation of the ISE output.

$$t_{CYCLE} = t_{CO} + t_{ROM} + t_{SF} + t_{WP}$$

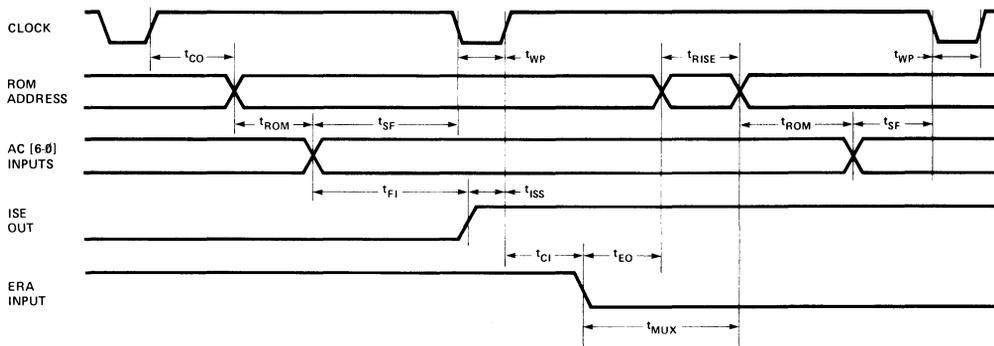
In the basic configuration shown in Figure 1 the ISE output is used to strobe the 3214 Interrupt Control Unit each time a JZR 15 (usually a jump to macro-instruction fetch) is recognized at the MCU address

control inputs. Some consideration must be given to the additional requirements on timing imposed by the use of this ISE output. After the ROM has been accessed and the MCU address control inputs are valid, it takes the MCU some time ( $t_{FI}$ ) to decode the JZR 15 operation and raise the ISE output. This output is used as the 3214 ISE input and must be valid early enough to meet that input setup time ( $t_{ISS}$ ). As this setup time is relative to the rising edge of the clock, the clock pulse width need not be added in.

$$t_{CYCLE} = t_{CO} + t_{ROM} + t_{FI} + t_{ISS}$$

Recalling the basic configuration depicted in Figure 1 and the situation described in the last paragraph, imagine that an interrupt request had been active long enough to meet the request setup time ( $t_{RCS}$ ) of the ICU. Then since the ISE input went high and satisfied the input setup time, the Interrupt Acknowledge flip-flop within the 3214 will change state and lower the MCUs ERA input after a delay ( $t_{CI}$ ). After the row address outputs are disabled ( $t_{EO}$ ), the pull-up resistors will begin to pull these lines high and after the voltage on these lines rises to 2.0V ( $t_{RISE}$ ) the ROM address will be valid. The remainder of this cycle is the same as previously described and usually will not be required to again generate an ISE pulse.

$$t_{CYCLE} = t_{CI} + t_{EO} + t_{RISE} + t_{ROM} + t_{SF} + t_{WP}$$



$t_{CO}$	CLK $\uparrow$ to MA[8~0] outputs	44 nsec
$t_{ROM}$	ROM access time (70 nsec for 3604) 3601-1	50
$t_{SF}$	AC[6~0] input set-up time	10
$t_{FI}$	AC[6~0] input to ISE output	40
$t_{ISS}$	ISE input (3214) set-up	16
$t_{CI}$	CLK $\uparrow$ to IA output (3214)	25
$t_{EO}$	ERA input to MA[8~4] output	32
$t_{RISE}$	RISE time to 2.0 V with 1 K $\Omega$ pull-ups: (16*3601-1) (4*3604)	84 21
$t_{MUX}$	Multiplexer switch time (74S158)	12
$t_{CYCLE}$	Ignoring ISE output $t_{CO} + t_{ROM} + t_{SF} + t_{WP}$ (3601-1) (3604)	137 157
	Using ISE output $t_{CO} + t_{ROM} + t_{FI} + t_{ISS}$ (3601-1)	150
	Interrupt using pull-ups $t_{CI} + t_{EO} + t_{RISE} + t_{ROM} + t_{SF} + t_{WP}$ (3601-1)	234
	Interrupt using MUX* $t_{CI} + t_{MUX} + t_{ROM} + t_{SF} + t_{WP}$ (3601-1)	130
	(*MUX adds $t_{MUX-PROP}$ [6 nsec] to $t_{CO}$ )	

Figure 4. MCU & Interrupt Cycle Timing

Examining the times shown on Figure 4 for this case of an interrupt cycle using pull-up resistors, it is clear that unless something is done this will be the limiting cycle time requirement. There are several techniques which may be used to ease this requirement.

Since interrupt cycles are relatively infrequent in comparison with other cycles, one solution might be to extend just that cycle. In other words, the system cycle time would be determined by all considerations previously mentioned, but ignoring the abnormal interrupt cycle requirement. Then the clock circuit would be designed such that it could extend a cycle in response to a signal from the 3214 Interrupt Control Unit (see Figure 5).

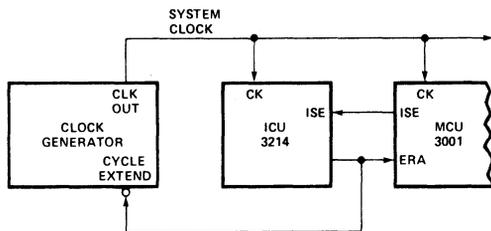


Figure 5. Interrupt Cycle Extension

The interrupt cycle would still be exactly as depicted in Figure 4, but the length of the interrupt cycle would be longer than a normal cycle, and in fact long enough to accommodate the interrupt cycle requirement.

It can be seen that a significant portion of the interrupt cycle is lost waiting for the pull-up resistors to charge the capacitance on the address lines. Thus, another method of easing the interrupt cycle requirement would be to reduce the address line rise time ( $t_{RISE}$ ). Reducing the resistance of the pull-ups would help but this technique is limited by the available MCU address output fanout. Alternatively, the MCU row address outputs (MA8-4) could be connected to the ROM address lines through a multiplexer such as the 74S158 (see Figure 6). With such a connection the interrupt cycle time is reduced since the MCU enable time ( $t_{EO}$ ) plus the address line rise time ( $t_{RISE}$ ) may be replaced with simply the multiplexer select time ( $t_{MUX}$ ) as shown in Figure 4. However, it should be noted that such a connection adds delay to the MCU address outputs, thus effectively lengthening this existing delay ( $t_{CO}$ ) by the multiplexer propagate time ( $t_{MUX-PROP}$ ) and hence lengthening any cycle which was dependent on the MCU delay ( $t_{CO}$ ).

$$t_{CYCLE} (\text{Interrupt with MUX}) =$$

$$t_{CI} + t_{MUX} + t_{ROM} + t_{SF} + t_{WP}$$

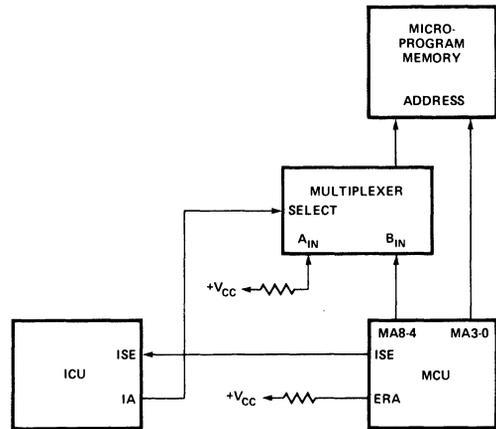


Figure 6. Multiplexer to Reduce Address Rise Time

A third alternative to solve the long interrupt cycle requirement is to implement the interrupts in quite a different way. Rather than changing the MCU address outputs, the MCU address control input least significant bit ( $AC\phi$ ) may be altered (see Figure 7). Using this technique an extra ROM bit (Interrupt Strobe) is required to strobe the 3214 ICU since the MCU's ISE output occurs one cycle too late. Implementing the same mechanism (interrupt strobe on JZR 15) could be done by using the interrupt strobe bit to strobe the ICU (see Figure 7) the cycle before the JZR 15 code appears. An added benefit of this method is that the interrupt structure may be strobed at points other than the beginning of an instruction fetch cycle, facilitating PAUSE or WAIT instructions.

Examining the timing diagrams in Figure 7, it can be seen that this implementation of interrupts does not limit the system cycle time. Rather, this interrupt mechanism's timing is less restrictive than timing for a normal cycle. The only requirements are that the interrupt strobe bit from the ROM reaches the 3214 ICU ISE-input within its setup time ( $t_{ISS}$ ). In the next cycle it is only necessary that the IA-output has gone low ( $t_{CI}$ ) early enough to meet the MCU address control input setup time ( $t_{SF}$ ). Thus, for the price of one bit of ROM interrupts can be implemented with no penalty in time.

At this point both major delay paths (arithmetic and control) have been examined for the implementation in question. After the designer has assured himself

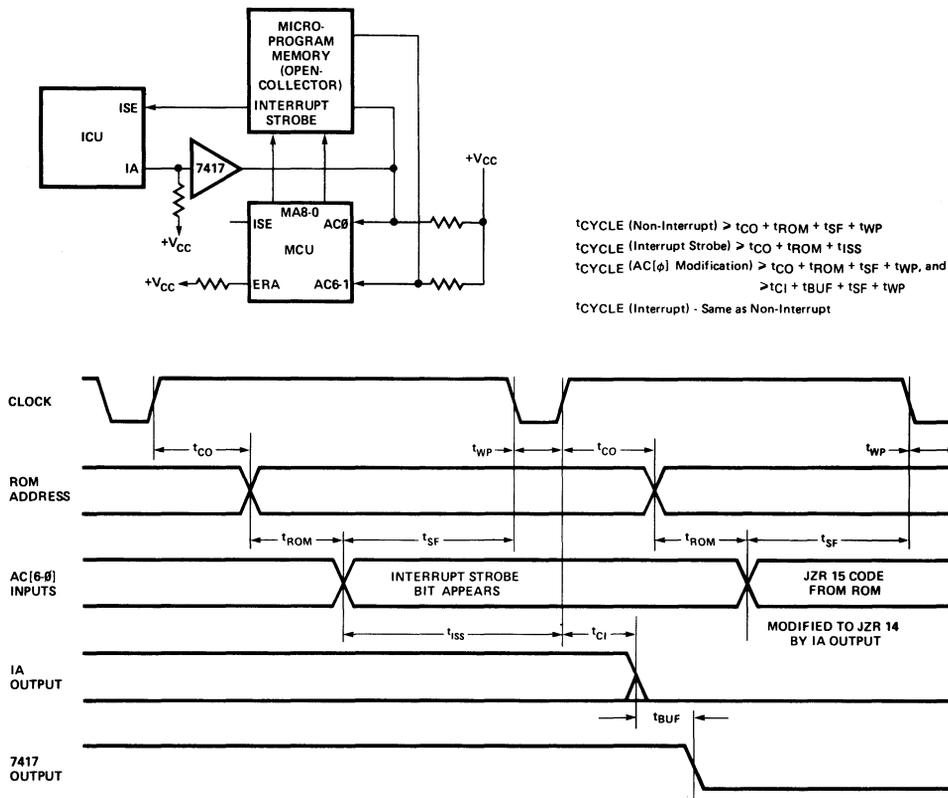


Figure 7. Interrupt Using AC [φ] Modification

there are no other delays which he may have overlooked, such as introducing external circuitry into the paths, he may merge the various requirements generated into a uniform set of system requirements. Any change introduced after these requirements have been generated must be closely examined that it does not subtly alter any system requirements. Delays that are negligible in one configuration may be dominant in a slightly different structure.

## WHAT HASN'T BEEN MENTIONED?

1. In the introduction it was explained that temperature would not be considered in the examples since Intel specifies products over the 0°C to 70°C temperature range. This deserves further comment. A quick glance at an Intel Data Sheet will verify that Intel parts are specified and guaranteed over the 0°C to 70°C ambient temperature range and concurrently with a five percent tolerance power supply. This is a reasonable range and allows the designer to guarantee circuit operation.

Unfortunately, the standard Schottky MSI line (74SXX) is only specified at 25°C ambient and  $V_{CC} = 5V$ . The variance of parameters over the allowable temperature and supply voltage is unspecified and left to the designer's experience. Due to this uncertainty the designer should "appropriately" modify any times attributable to non-Intel parts to allow for variations over temperature and supply voltage.

2. In the examples given it was always assumed that setup times would be honored. Though most of a computing system is asynchronous, it typically has to interface with asynchronous events. It is at this interface that difficulty may be encountered. Consider a popular circuit (Figure 8) used to "synchronize" asynchronous signals.

In this circuit the output delay is guaranteed only if the input setup time is met. But since the input is asynchronous, this setup time may not always be satisfied, as at the second event depicted in Figure 8. What happens? Though the results are highly dependent on the flip-flop circuit design,

some general observations may be made. Typically, the effect is to stretch out the flip-flop delay time as the event approaches arbitrarily close to the clock edge. Theoretically, the delay will go to infinity if the event falls precisely on the clock edge. Some flip-flops also exhibit a characteristic in which the output may change state and some time later return to the original state. This phenomena is known as "hang-up" and has been observed to last for twenty nanoseconds on a 74S74. It cannot be absolutely prevented when asynchronous signals are introduced into a synchronous system, but the probability of the "hung" flip-flop causing an error can be reduced without limit. The technique is simply to cascade these interfaces.

If two such flip-flops are cascaded there is some probability  $P_1$  ( $P_1 < 1$ ) that the asynchronous event will fall close enough to the clock edge to hang the first flip-flop. Given that it hangs, there is some probability  $P_2$  that it will hang for very nearly an entire clock period and into the hang-up zone of the second flip-flop. Then, there is a probability  $P_3$  that the second flip-flop will hang long enough to cause an error. Thus, the probability of error is  $P_E = P_1 * P_2 * P_3$ . Hence, by cascading flip-flops the probability of error can be reduced without limit.

Recall the 3214 Interrupt Control Unit and its request setup time ( $t_{RCS}$ ) and its IA output delay ( $t_{CI}$ ). This delay is in several critical system paths as shown by the examples. Of course, the IA output delay specified also presumes the IA flip-flop setup time was met. When deliberately violating the IA flip-flop setup time, a hang-up of 50 nsec has been observed. What is a designer to do?

Slowing down the system such that it could tolerate any expected hang-up would be the easiest solution. This may not always be as bad as it sounds. Recalling the situation depicted in Figure 7, note that some flip-flop hang-up is tolerable. [ $t_{IA-HANG} = t_{CYCLE} - (t_{SF} + t_{WP})$ ]. An alternative would be to "synchronize" the asynchronous interrupt requests using the technique previously described. An octal D flip-flop such as the 74S374 would be suitable.

3. In the examples given it has been assumed that the system, including all the CPEs, the MCU, and the ICU, operates from a single clock. If a circuit, such as in Figure 9, that provides a separate clock for different components is used, the possible clock skew must also be considered when determining system timing.

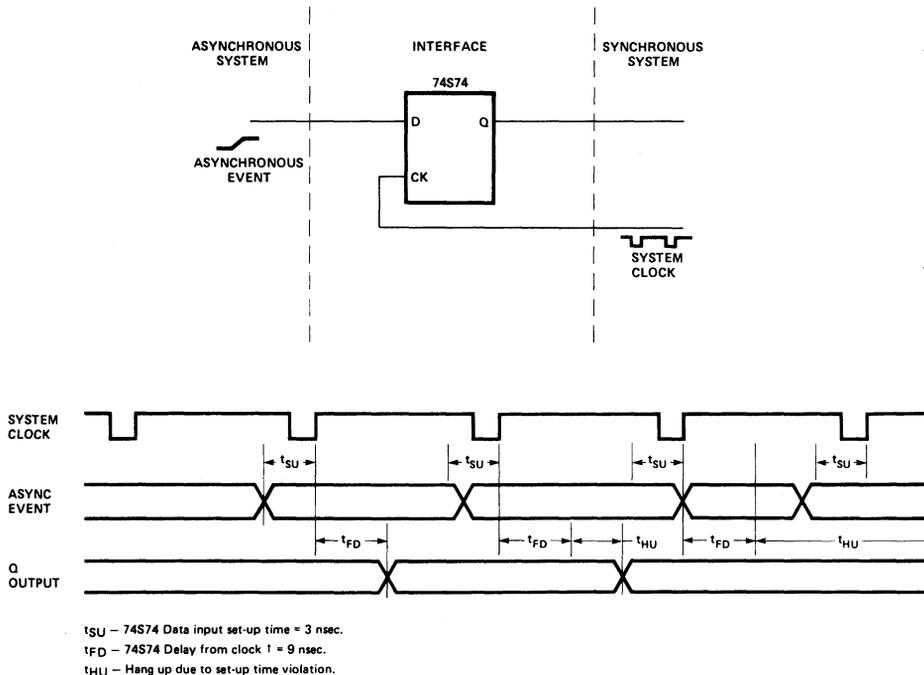


Figure 8. Synchronizing Circuit Exhibiting Hang-Up

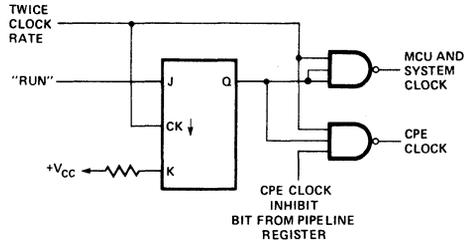


Figure 9. CPE Clock Inhibit Circuit

## SUMMARY

Generating the correct timing for a complex system in which parameters may vary with temperature, power supply voltage, lead length and the like is no trivial task. Fortunately, large scale integration such as Intel's 3000 family is making the task much easier. With the 3000 family of compatible parts the designer need only worry about the interfaces and may be assured the internal timing is correct. Such a system is best analyzed by separately considering the various delay paths and later combining the sundry results. And of course, with Murphy on vacation the designer can be confident of a flawless design on the first pass.

4. Though not explicitly mentioned, it has been assumed that all input hold times would be observed. Usually these times are satisfied with no conscious effort required of the system designer. However, parameters such as the MCU SX and PX input hold time must be carefully considered. These inputs are used for macro instruction decoding and typically are used at the end of an instruction fetch cycle. When using these inputs the designer must provide the necessary data hold time before allowing the data to change.

## Disk Controller Designed With Series 3000 Computing Elements

by Glenn Louie

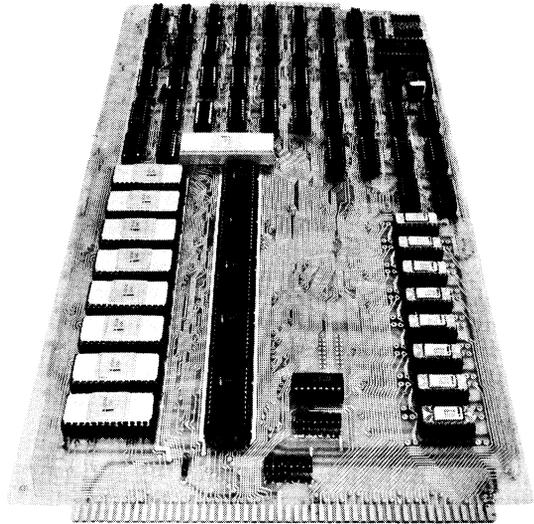


Figure 1. Bipolar Microprogrammed Disk Controller

With the introduction of the first microprocessor, digital designers began a massive switch to programmable LSI technology, away from hard-wired random logic. Designers found that with these new LSI components and the availability of low cost ROMs they could easily implement structured designs which were both cost effective and flexible. However, not all digital designs were amenable to the microcomputer approach. One of the basic limitations was the speed at which a particular critical program sequence could be executed by a microprocessor. The early P-channel MOS microprocessors, such as Intel's 4004 and 8008, were able to solve a broad class of logic problems where speed was not essential. With the introduction of the more powerful n-channel MOS microprocessors, such as the Intel<sup>®</sup> 8080, the range of applications was significantly broadened, but there still existed a class of applications that even these newer devices were not fast enough to handle.

Recently, two new Schottky bipolar LSI computing elements, members of the Intel Bipolar Microcomputer Set, were introduced which expand the range of microcomputer applications to include high speed peripheral controllers and communication equipment. The new elements are the 3001 Microprogram Control Unit (MCU) and the 3002 Central Processing Element (CPE). These two components facilitate the design of specialized, high

speed microprocessors that together with a minimum of external logic perform the intricate program sequences required by high speed peripheral controllers.

A multi-chip bipolar microprocessor differs from the single chip MOS microprocessor in that the bipolar microprocessor is programmed at the microinstruction level rather than at the macroinstruction level. This means that instead of specifying the action via a macroprogram using a fixed instruction set, a designer can specify the detailed action occurring inside the microprocessor hardware via a microprogram using his own customized microinstructions.

In general, microinstructions are wider than macroinstructions (e.g. 24 to 32 bits) and have a number of independent fields that specify simultaneous operations. In a single microcycle, an arithmetic operation can be executed while a constant is stored into external logic and a conditional jump is being performed.

A bipolar LSI microprocessor design is similar to a general MSI/SSI microprocessor design where the intricacies of the application are imbedded in the program patterns in ROM. However, the large amount of logic necessary to access the microcode has been replaced by the LSI MCU chip. Also,

# Disk Controller Design

the MSI logic required to provide the arithmetic and register capabilities has been replaced by the functionally denser LSI CPE slices. Because of these new LSI chips, microprogramming with all its advantages can now be applied to designs which previously were unable to justify microprogramming overhead.

The effectiveness of these new LSI components in a high speed peripheral controller design has been demonstrated by the Applications Research group at Intel with the design of a 2310/5440 moving head disk controller (BMDC). The BMDC has a total of 67 IC chips and is packaged on a printed circuit board measuring 8" x 15", as shown in Figure 1. Disk controllers of equivalent complexity realized with conventional components typically require between 150 and 250 I.C.'s. The BMDC performs all the operations required to interface up to four "daisy chained" moving head disk drives, with a combined storage capacity of 400 megabits, to a typical minicomputer. It is fast enough to keep up with the drive's 2.5 MHz bit serial data stream while performing the requisite data channel functions of incrementing an address register, decrementing a word count register, and terminating upon completion of a block transfer.

The BMDC interacts with the minicomputer's disk operating system (DOS) via I/O commands, interrupts and direct memory access (DMA) cycles. The I/O commands recognized by the BMDC's microprogram are:

- Conditions In
- Seek Cylinder
- Write Data
- Read Data
- Verify Data
- Format Data

The BMDC sends an interrupt to the minicomputer when either a command is successfully executed, a command is aborted, or a drive has finished seeking. The DOS then interrogates the BMDC with a Conditions In command. The following flags specify the conditions which the BMDC can detect:

- Done flag
- Malfunction flag
- Not Ready flag
- Change In Seek Status flag
- Program Error flag
- Address Error flag
- Data Error flag
- Data Overrun flag

Data transfers between the minicomputer and the disk BMDC occur during DMA cycles. DMA cycles are also used for passing command information from the minicomputer to the BMDC.

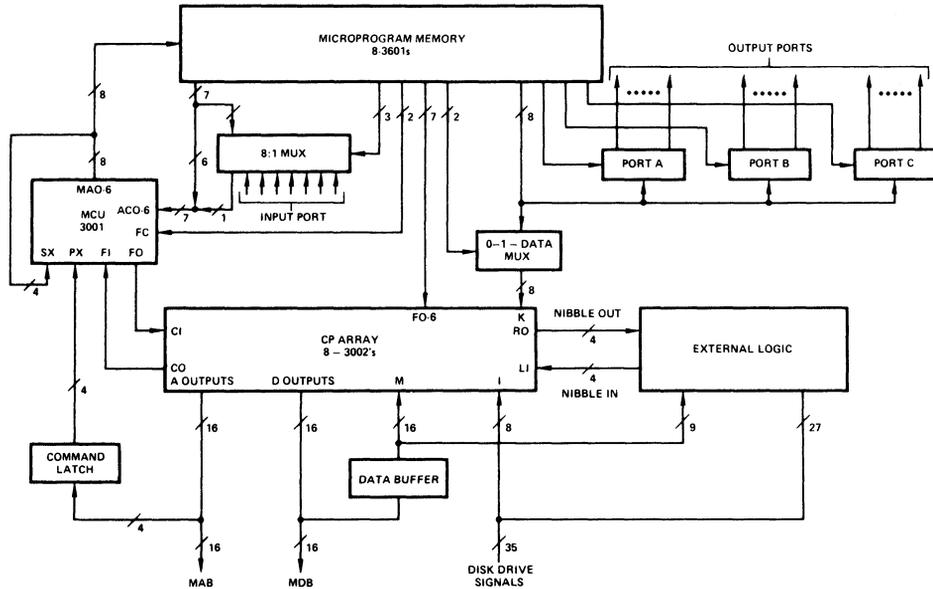
The bipolar LSI microcomputer in the BMDC performs the necessary command decoding, address checking, sector counting, overlap seeking, direct memory accessing, write protection, password protection, overrun detection, drive and read selection, and formatting. External hardware assists the microprocessor in updating the sector counter, performing parallel-to-serial and serial-to-parallel conversion, and generating the CRC data checking information. The BMDC uses a special purpose microprocessor, configured with the components listed in Table A. The LSI microprocessor uses an MCU, an 8:1 multiplexer, eight 3601 PROMs, a command latch, a data buffer, and an array of eight CPE slices (Fig. 2). The characteristics of this design, only one of many possible with the 3000 family, are as follows:

- 400 nsec system clock
- 16-bit wide CP array
- Ripple carry CPE configuration
- Non-pipelined architecture
- One level subroutining
- 230 32-bit microinstructions
- Word to 4-bit nibble serialization

The MCU controls the sequence in which microinstructions are executed. It has a set of unconditional and conditional jump instructions which is based on a 2-dimensional array for the microprogram address space called the MCU Jump Map. <sup>(1)</sup>

PART #	DESCRIPTION	QUANTITY
3001	MCU	1
3002	CPE	8
3212	8 bit I/O Port	6
3205	1 of 8 Decoder	2
3601	1K PROM	8
3404	6 bit Latch	1
74173	4 bit Gated D F/F	1
74174	6 bit D F/F	1
74175	4 bit D F/F	1
74151	8:1 Multiplexer	1
8233	Dual 4:1 Multiplexer	2
9300	4 bit Shift Register	1
9316	4 bit Binary Counter	1
8503	CRC Generator	1
7474	Dual D F/F	5
7473	Dual J-K F/F	2
7451	And-Or-Invert Gate	1
7404	Hex Inverter	6
7400	Quad 2 Input Nand Gate	9
74H08	Quad 2 Input And Gate	1
7403	Quad 2 Input Nand O.C. Gate	2
7438	Quad O.C. Drivers	4
74H103	Dual J-K F/F	2
	Total	67 I.C. Packages

Table A. I.C. Component List for Disk Controller



**Figure 2. Disk Controller** – The various elements of a specialized microprogrammed processor is shown with the external logic which together is the entire disk controller.

In addition, the MCU is connected in such a manner as to perform command decoding, external input testing, and one level subrouting.

Command decoding is achieved by connecting the command latch to the Primary Instruction (PX) bus inputs and using the JPX instruction (Fig. 3). The testing of external input signals is performed by routing the least significant bit (LSB) of the seven bit jump code through an eight-to-one multiplexer (Fig. 2). The multiplexer is controlled by a 3-bit Input Select Code which selects either the LSB of the jump code or one of 7 external input signals to be routed to the MCU. This technique has the effect of conditionally modifying an unconditional jump code so that the next address will either be an odd or even location (Fig. 3). A one instruction wait for external signal loop can be simply implemented in this fashion.

One level subrouting is achieved by feeding the four least significant bits of the address microprogram outputs back into the secondary instruction (SX) inputs. Enough program status information can then be saved in the internal PR latch when a subroutine is called with a JPX instruction so that

upon exiting, a subroutine with a JPR instruction, control can be returned to the procedure which called it (Fig. 4). This technique saves a significant amount of microcode in the BMDC because some long sequences do not have to be repeated.

The microprogram control store is an array of eight 3601 PROMs organized to give 256 words x 32 bits (230 words were required for the BMDC). The 32-bit wide word is divided into the following subcontrol fields:

1. Jump Code field	7 bits
2. Flag Control field	2 bits
3. CPE Function field	7 bits
4. Input Select field	3 bits
5. Output Select field	3 bits
6. Mask or Data field	8 bits
7. Mask Control field	2 bits
<b>TOTAL</b>	<b>32 bits</b>

The command latch and data buffer retain command information from the computer so that the memory bus will not be held up if the BMDC should be busy performing an updating task. The data buffer also retains the next data word during a Write Data to disk operation.

# Disk Controller Design

The CP array is connected in a ripple carry configuration as shown in Figure 5. The eight CPE slices provide the BMDC with a 16-bit arithmetic, logic and register section. Word to nibble serialization is made possible by connecting the Shift Right Outputs (RO) of the first, third, fifth, and seventh CPE to the Nibble Out bus. By using only four shift right operations a word in a register can be converted into four 4-bit nibbles. The final serialization of these nibbles is done in the external

logic. Similarly, the Shift Right Inputs (LI) of the second, fourth, sixth, and eighth CPE are connected to the Nibble In bus so that with only four shift right operations, a word can be assembled from four nibbles.

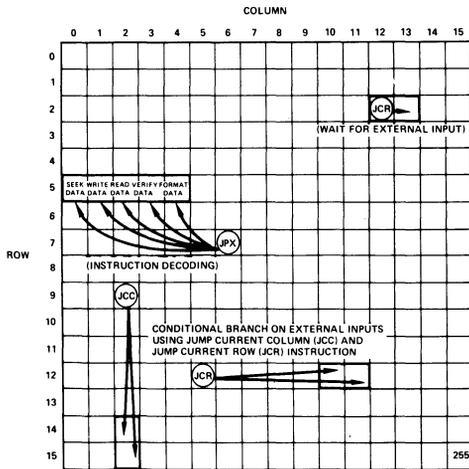


Figure 3. MCU Jump Map for instruction decoding and conditional branching on external inputs

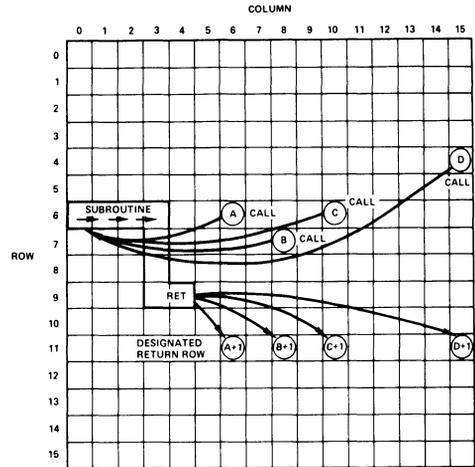


Figure 4. MCU Jump Map for one level subroutine call and return. A subroutine is called from four different places in the program each with a unique column number. Upon returning from the subroutine, control will be transferred back to the portion of program which called it. A subroutine may be called from a maximum of 16 different places.

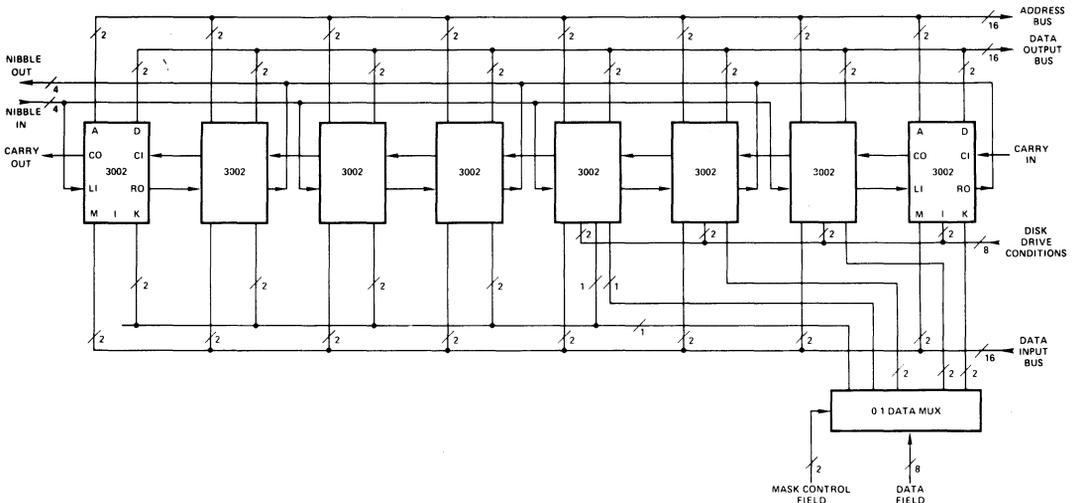


Figure 5. CPE Array - A 16-bit arithmetic, logic and register section is built up with 8 CPE slices connected in a ripple carry configuration. The K, I, and M bus is used for loading information into the CPE slices. The LI inputs and RO outputs are connected to make up the Nibble In and Nibble Out buses.

An eight bit mask bus is connected to the mask inputs of the least significant half of the array. The mask inputs of the most significant half of the CP array are all tied to the eighth mask bit. A constant with a value between +127 and -128 can therefore be loaded into the array from the microprogram. The mask bus comes from the data field of the microprogram via a 0-1 data multiplexer. When the CP array requires either an all one or all zero mask, the data field is freed to provide data to external logic.

The 3002 CPE is an extremely flexible component which makes it particularly attractive for controller designs. The Memory Address Register makes an ideal DMA address register.<sup>(1)</sup> The accumulator (AC) register, which also has its own output bus can be used as a data word buffer during a write DMA cycle. Concurrently, another word can be assembled in the T register using the shift right operation. The three separate input buses provide a multiplexing capability for routing different data into the CPE. In the BMDC, the I-bus is used for loading disk drive conditions, the K-bus for loading mask or constant information, and the M-bus for reading an external data buffer. The arithmetic logic section performs zero detection and bit testing with the result delivered to the

MCU chip via the carry out line. Finally, the eleven scratchpad registers allow the controller to retain data and status for the processor.

The CP array in the microprocessor performs the following for the BMDC with its registers and arithmetic functions.

1. Sector counting
2. Word to nibble serialization
3. Drive seek status monitoring
4. Header checking
5. DMA address incrementing
6. Word counting
7. Multi-sector length counting
8. Automatic resynchronization of sector counter
9. Accessing of additional information from memory
10. Time delays

The organization of the microprocessor was chosen to maximize the use of the MCU and CPE in performing the various tasks required for disk control. However, there are some specialized tasks which are more economically performed by external logic. The microprocessor controls this external logic by output ports which are selected by the output select field in the microinstruction. The

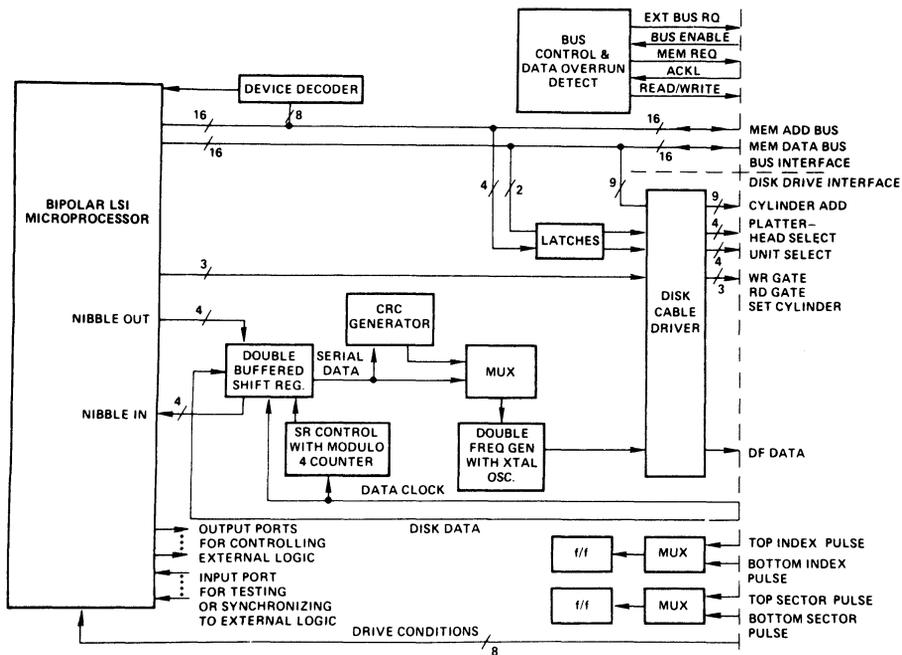


Figure 6. External Logic — Microprocessor monitors and controls external logic via input-output port to perform specialized disk controller functions.

# Disk Controller Design

data to these ports is delivered from the shared data field.

The external logic section of the BMDC (Fig. 6) has a double buffered 4-bit shift register which is used for initial packing and the final serialization of data. It is controlled by a modulo-4 counter circuit. During a write operation, serial data from the shift register is encoded by the clock controlled double frequency encoder and sent to the drive. As data is being transferred to a cyclic redundancy code (CRC) is generated and then appended to the end of the data stream to be recorded on the disk. The external logic also contains addressing latches and flag flip-flops to capture sector and index pulses. It also contains main memory bus control circuitry for performing bus protocol, bus acquisition, and data overrun detection.

The microprogram for the BMDC microprocessor directly implements the six I/O commands. The program controls the sequential action of the various elements of the microprocessor and of the external logic needed to decode and execute the commands. In Figure 7, the flow chart of the Read command shows the actions required to read a file off the disc. The BMDC first selects the drive specified by the command and checks its ready status. It then uses a memory pointer passed to it by the command to access four more words from the main memory using DMA cycles. The first word is the Header, which contains the track address and sector address information. The second word is the Starting Address specifying the first location in memory where the data is to be stored. The third word is the Block Length of the file to be retrieved. All of the address information and the Block Length are stored in several CPE registers for further processing. The fourth word is the Password which is compared against a microprogram word to insure that the command from the computer is a valid one and not a program error. The password can prevent an erroneous command, due to a user programming error, from destroying important files on the disc.

After the password check, the BMDC resynchronizes the sector counter if necessary and waits for the desired sector by monitoring the sector pulse flag. When the desired sector arrives, the BMDC synchronizes itself to a start nibble and reads the header which it compares to the desired header to insure that the head is positioned properly. It then reads and stores 128 words of data at sequential locations in memory. A cyclic redundancy code is compiled during the read oper-

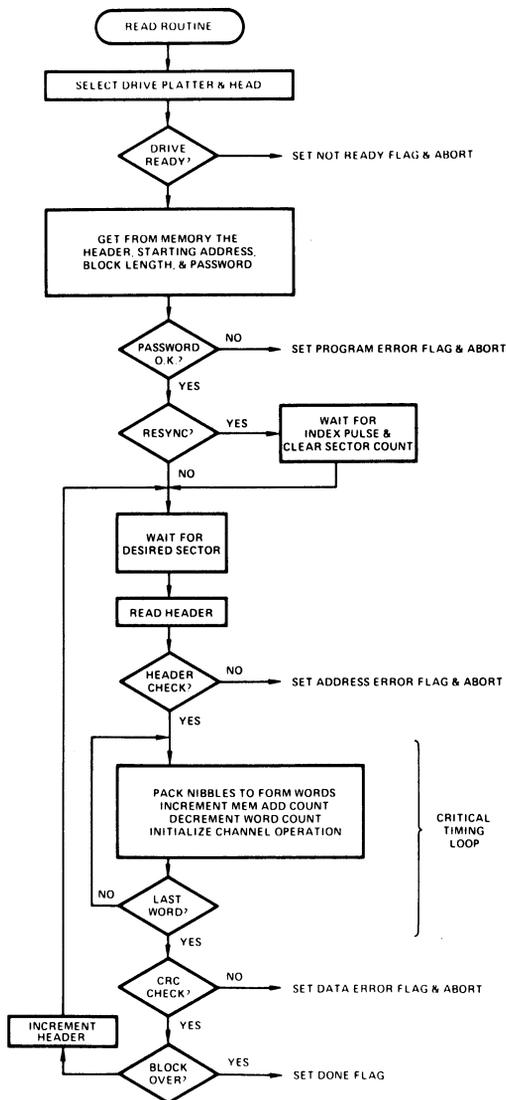


Figure 7. Read Command Flowchart – This flowchart is coded in the microprogram which when executed performs the disk Read operation.

ation and compared against the CRC word read in after the data. At the end of each sector the block length is decremented to see if it is the last sector. If it is not, the sector address is incremented and another sector is read.

In addition to the command routines, the microprogram has an idle loop routine (Fig. 8) which the BMDC executes when it is not busy with a command. While in the loop, the BMDC updates the sector count, monitors the drives seeks status lines and decodes any disc commands from the disc operating system in the minicomputer.

The design process for the BMDC began with an evaluation of what disc controller operations could effectively be handled by the microprocessor. This also determined what had to be performed by external logic. A microprocessor configuration was then established and certain critical sequences were programmed to verify that the configuration was fast enough. A flow chart was produced and the microprogram coded directly from it. All attempts were made to use the MCU and CPE slices effectively and keep the microprogram within 256 words. The assignment of MCU addresses which initially appeared difficult, was, with a little experience, quite straight forward and less restrictive than a state counter design. After the coding, the microprogram was assembled and loaded into the microprocessor's control memory.

The BMDC design demonstrates how a specialized high speed microprocessor can be designed using standard bipolar LSI devices and microprogrammed to perform disc control functions with the addition of a small amount of external logic. The flexibility of Series 3000 allows a designer to optimize the configuration for his application. For extremely high speed applications, the designer can add fast carry logic and microinstruction pipelining to his microprocessor to achieve a 150 nsec 16-bit microprocessor.

At Intel, our design experience with the BMDC design exercise has shown that the use of the MCU and CPE results in a clean, well structured design. The complexity of the design resides primarily in the microprogram leaving the external logic relatively simple. During debugging, most of the problems encountered were restricted to the microprogram which was easily modified and debugged using bipolar RAM for the control memory.

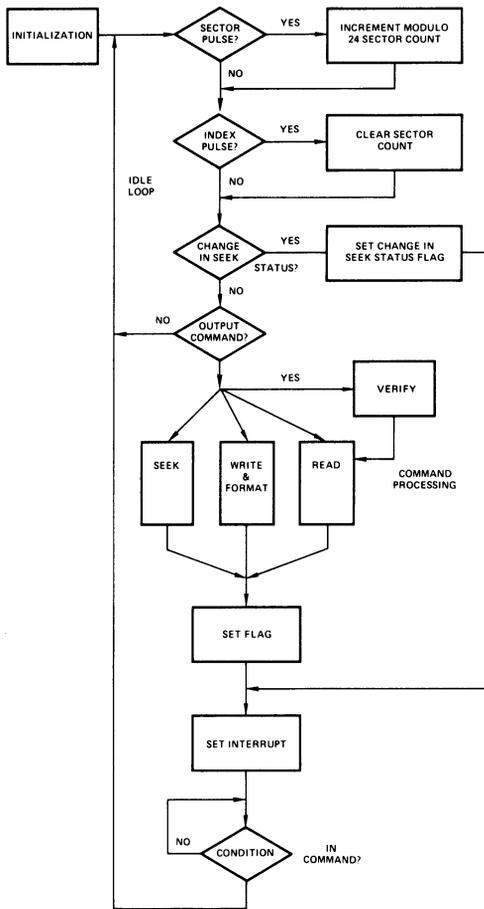


Figure 8. BMDC Flowchart — The BMDC runs in the idle loop when it is not busy doing command processing.

## References

1. J. Rattner, J. Cornet, M. E. Hoff, Jr., "Bipolar LSI Computing Elements Usher In New Era of Digital Design," ELECTRONICS, September 5, 1974, pp 89-96.





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by  
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## INTRODUCTION

Until recently, the area of high performance, general purpose and special purpose central processors was unaffected by the microprocessor revolution. Although they covered a broad range of applications, the P-channel and N-channel microprocessors' performance limitation prevented their use in applications where high speed was necessary.

The introduction of the Series 3000 Computing Elements has expanded the spectrum of microprocessor applications to include both high performance central processors and controllers. Utilizing Intel's Schottky bipolar technology, the Series 3000 components realized a level of performance that was not possible with MOS microprocessors. For example, a 16-bit processor with a micro-instruction cycle time of 150 nanoseconds can be built with the 3000 components. In addition, the components of the family can be arranged into a number of different configurations and microprogrammed by the system designer to perform in a variety of processing environments from front end processing to arithmetic intensive computation.<sup>1</sup>

This application note describes a systematic procedure for designing central processors with the Series 3000. Using a CPU design example, simple guidelines are given for tasks such as macro-instruction opcode assignment, macro-instruction decoding and execution and microprogram memory assignment.

## THE SERIES 3000 FAMILY

The Intel® Series 3000 Bipolar Microcomputer Set is a family of Schottky bipolar LSI computing elements which simplify the construction of microprogrammed central processors and device controllers. These processors and controllers are truly microprogrammed in the sense that their control functions are determined by the contents of a control memory. This control memory may be realized with standard read-only (ROM) memory, read/write (RAM) memory or programmable read-only memory (PROM) elements.

The two most important computing elements in the family are the 3001 Microprogram Control

Unit (MCU) and the 3002 Central Processing Element (CPE). The MCU determines the sequence of micro-instruction execution and controls carry/shift data to and from the CPE array. The CPE provides a complete two-bit wide slice through the data processing section of a central processing unit. CPEs may be arrayed in parallel to form a processor of any desired word length. For example, to produce a 16-bit wide data path, eight CPEs would be used.

All of the above components use standard TTL logic levels, as some designers may wish to utilize SSI and MSI TTL logic to control external circuitry, or to add functions not included in the basic set to increase the speed of certain operations.

Other members of the family currently include the following computing elements:

- 3003 Look-Ahead Carry Generator
- 3212 Multi-Mode Latch Buffer
- 3214 Interrupt Control Unit
- 3216 Bidirectional Bus Driver
- 3226 Inverting Bidirectional Bus Driver

The control and main memory portion of the central processor may be implemented with any of the standard bipolar or MOS memory components shown on page 2.

## AN INTRODUCTION TO MICROPROGRAMMING

The central processing unit of a general purpose computer usually consists of two portions: an arithmetic portion and a control portion. The control portion determines the sequence of instructions to be executed and presides over their fetching and execution while the arithmetic portion performs arithmetic and logical operations.

The basic operation of the control portion consists of selecting the next instruction from memory, then executing a series of states based upon the instruction fetched. This sequence may be implemented via a combination of flip-flop and random logic, or by the use of tables in control memory.

<sup>1</sup>J. Rattner, J. Cornet, and M. E. Hoff, Jr., "Bipolar LSI Computing Elements Usher In New Era of Digital Design," ELECTRONICS, September 5, 1974, pp 89-96.

## Standard Bipolar and MOS Memory Components

PART NUMBER	NUMBER OF PINS	TECHNOLOGY	DATA ORGANIZATION	ACCESS TIME
<b>CONTROL MEMORY</b>				
3601	16	Bipolar PROM	256X4	70 nS*
3602	16	Bipolar PROM	512X4	70 nS
3604	24	Bipolar PROM	512X8	70 nS
3624	24	Bipolar PROM	512X8	70 nS
3301A	16	Bipolar ROM	256X4	45 nS
3302	16	Bipolar ROM	512X4	70 nS
3304A	24	Bipolar ROM	512X8	70 nS
3324A	24	Bipolar ROM	512X8	70 nS
3106A	16	Bipolar RAM	256X1	60 nS
3107A	16	Bipolar RAM	256X1	60 nS
<b>MAIN MEMORY</b>				
1702A	24	Static MOS EPROM	256X8	1000 nS
2704	24	Static MOS EPROM	512X8	500 nS
2708	24	Static MOS EPROM	1024X8	500 nS
1302	24	Static MOS ROM	256X8	1000 nS
2308	24	Static MOS ROM	1024X8	500 nS
2316	24	Static MOS ROM	2048X8	850 nS
2101	22	Static MOS RAM	256X4	1000 nS*
2102	16	Static MOS RAM	1024X1	1000 nS*
2111	18	Static MOS RAM	256X4	1000 nS*
2112	16	Static MOS RAM	256X4	1000 nS*
2104	16	Dynamic MOS RAM	4096X1	
2107B	22	Dynamic MOS RAM	4096X1	200 nS
5101	22	Static CMOS RAM	256X4	650 nS

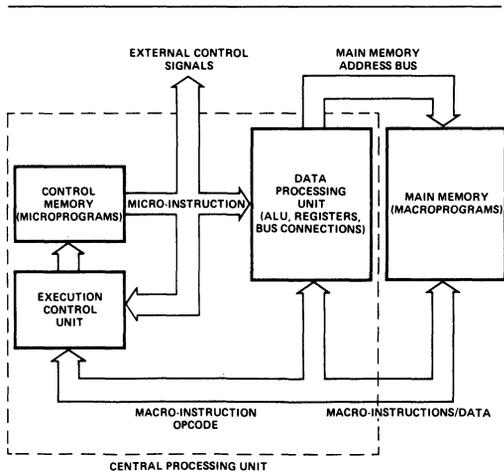
\*Higher speed versions of these devices are available. Consult the Intel Data Catalog.

When the latter technique is used, the central processor is said to be microprogrammed.

The functions of the control portion of a microprogrammed central processing unit are very similar to that of a central processing unit itself. To avoid confusion, the terms "micro" and "macro" are used to distinguish those operations in the control unit from those of the realized central processor. For example, the central processor, under the direction of micro-instructions read from its control memory, fetches macro-instructions from main

memory. Each macro-instruction is then executed as a series of micro-instructions. Main memory contains macroprograms, while control memory contains microprograms which define the realized central processor.

Figure 1 shows a block diagram of a microprogrammed central processing unit (defined by the dotted boundary). The control unit issues addresses to the control memory and fetches micro-instructions. This control unit uses the contents of control memory (micro-instructions) to drive the data processing unit, external circuits, and to select the



**Figure 1. Block Diagram – Microprogrammed Computer**

next micro-instruction. The data processing unit performs the actual computations, logical operations, etc.

In the Intel® Bipolar Microcomputer set, the 3001 MCU performs the control unit function, while the 3002 CPE is the basic building block for the data processing section.

Thus, within a microprogrammed machine, there are at least two levels of control and two levels of programming to be considered. The designer of a central processor is usually concerned with the definition of the macro-instruction set and its realization as a microprogram. The Intel® Series 3000 Bipolar Microcomputer Set establishes a micro-instruction set which is used as a base for the microprograms which generate macro-instruction sets.

The reason for using this microprogrammed approach is that very complex macro-instruction sets can be realized as sequences of relatively primitive micro-instructions. The logic of the final macro-machine remains relatively simple, with most of the design complexity residing in the micro-instruction sequences contained in control memory.

The final user of the computer seldom needs to be aware that the CPU was realized with microprograms rather than hardwired logic. A functional description of the macro-instruction set is usually sufficient for his purposes. However, the user will benefit from the microprogrammed approach if he

finds it necessary to alter or enhance the basic macro-instruction set in some fashion. The tabular or programming approach offered by the micro-programmed architecture makes such changes far easier than would be possible in a processor realized via hardwired logic.

## CONSTRUCTING CENTRAL PROCESSING UNITS

### Basic Design Steps

To realize a central processor with the Series 3000 computing elements, several steps are necessary:

1. Definition of hardware organization.
2. Definition of the central processor macro-instruction set.
3. Implementation of microprograms which realize the desired macro-instruction set.

### Hardware Organization

A typical CPU constructed utilizing the Series 3000 computing elements will consist of an array of CPE chips, one MCU, and a control memory. The array of CPE chips realizes the arithmetic, logical functions and registers of the CPU, while the combination of the MCU and control memory realizes the control portion. The microprogram contained in control memory initializes the machine when power is first turned on and supervises the fetching and execution of macro-level instructions. In addition, routines to handle such special functions as interrupts will also be contained within the control memory.

The 3002 CPE array contains six buses for communication with external circuitry. Four of these buses are used primarily to communicate with memory and I/O devices while the remaining two, the function control bus (F-Bus) and the control memory data bus (K-Bus), enable the control portion of the processor to drive the CPE array. The function control bus is driven by control memory outputs which direct the CPE array to execute the desired operation. The K-Bus allows the control memory to supply various constants and/or masks to the CPE array.

Because 8 bits of operation code information can be passed directly to the MCU, the set is best adapted to macro-instruction sets in which all of the operation code information is defined by 8 bits (256 unique macro-instructions). However, larger macro-instruction sets can be realized by saving any remaining bits of the operation code in the CPE array or in an external register. The saved bits can

then be tested later by routing them to the MCU, through its 8-bit input port.

A “pipelined” mode of operation may be implemented by placing a register of edge triggered D flip-flops between control memory outputs and the circuitry controlled by those outputs. This register causes the execution of a micro-instruction to overlap the fetching of the next micro-instruction. The control lines which issue micro-instruction sequence information to the MCU are not routed through the pipeline register when the pipelined mode is used; they are routed directly from the microprogram memory outputs to the AC0–AC6 inputs of the MCU.

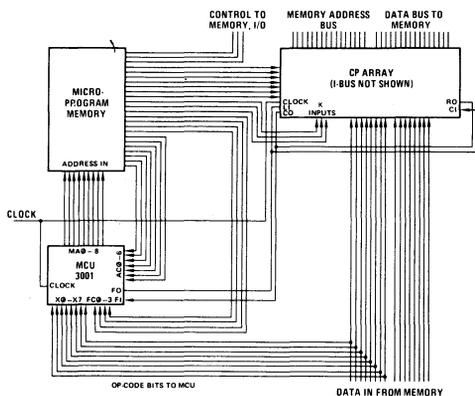
Microprograms written to realize a given macro-instruction set will differ for pipelined and non-pipelined machines. The major differences are associated with conditional jumps in the microprogram which test the results of arithmetic or logical operations executed by the CPE array. In a pipelined machine, these results are delayed by one micro-instruction, so that conditional jumps must be delayed by at least one micro-instruction before execution. More detailed information concerning these differences is contained in the microprogramming section of this application note.

Figure 2 shows block diagrams illustrating the organization of standard and pipelined central processing units. The block diagrams show the basic modules of standard and pipelined CPUs: the MCU, CPE array, microprogram memory and the pipeline register. The six buses associated with the CPE array are shown:

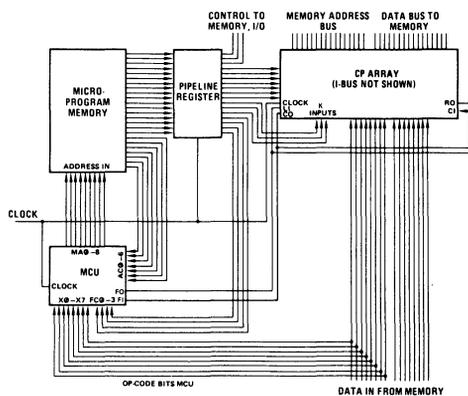
- The address bus (A-Bus) to main memory
- The data bus (D-Bus) to memory
- The data bus (M-Bus) from memory with its path for operation code data to the MCU
- The external device input bus (I-Bus), not shown
- The micro-function bus (F-Bus) from the pipeline register
- The constant bus (K-Bus) from the pipeline register

In addition, the carry logic bus to and from the MCU and the micro-instruction sequence logic bus from control memory to the MCU are shown. Additional control fields to such external logic as memory and I/O control are shown as an output bus from control memory.

The number of bits required for each word of control memory, i.e., each micro-instruction, is determined by the number of logical functions the micro-instruction controls. A minimum of 18 bits is usually required for basic hardware control: 7 bits of micro-instruction sequence control to the MCU, (AC0–AC6), 4 bits of carry control to the MCU, (FC0–FC3), and 7 bits of micro-function selection to the CPE array, (F0–F6). That is, the basic hardware requires at least three control word fields of 7 bits, 4 bits, and 7 bits width respectively. Almost every processor will require additional fields to control other logical functions such as main memory control, I/O control, and constant generation. Figure 3 illustrates a typical micro-instruction word format with several typical user defined control fields added.



**Figure 2. Bipolar Microcomputer Non-Pipelined Organization**



**Figure 2. Bipolar Microcomputer Pipelined Organization**

The constant bus to the CPE array seldom needs to be as wide as the data buses. For example, consider a 16-bit machine where an array of eight CPEs is used. While the constant bus is nominally 16 bits wide, if a limited set of masking operations are used, the number of bits can be reduced significantly. Figure 4 shows how 4 bits can be used to generate the masks for such a machine where the only masks needed are for separating high and low order data bytes, for testing the sign and magnitude of the data word, and for testing the least significant bit of the word.

As an example of the use of additional logic to enhance the set, consider the use of a control field (1-bit width) to inhibit the CPE clock. This operation allows non-destructive testing of CPE registers via the MCU carry logic. The carry logic in the MCU responds just as if the micro-instruction were executed, but the fact that the CPE clock was inhibited leaves the CPE registers unaltered. An example of conditional clocking is given in a later section called "Programming Techniques."

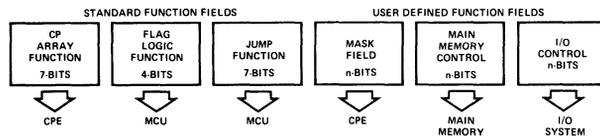


Figure 3. General Micro-Instruction Format

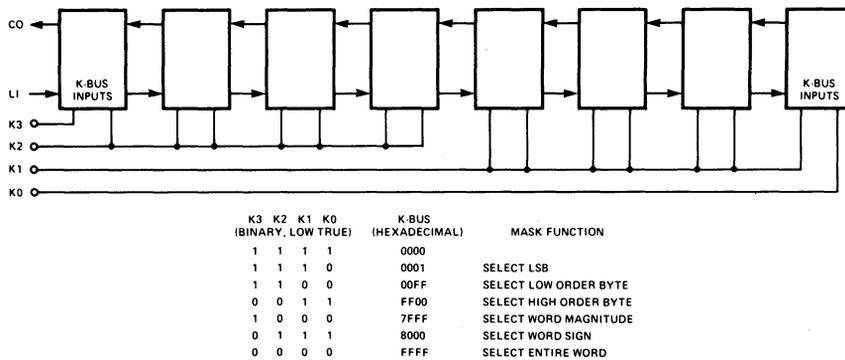


Figure 4. Wiring the K-Bus Using 4-Bits

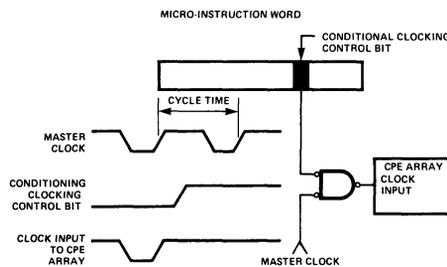


Figure 5. Conditional Clocking

## Writing of Microprograms

Once the hardware design is established and the macro-instruction set chosen, the designer should proceed to implement the microprograms for the system. To assist in the writing of these microprograms, Intel has developed CROMIS, a complete microprogramming system for Series 3000 computing elements.

CROMIS consists of two major software subsystems, XMAS and XMAP. XMAS is a symbolic microassembler which is extensible in both micro-instruction length and memory address space. XMAP is a complementary subsystem which maps the micro-instruction bit patterns produced by XMAS into compatible ROM/PROM programming files for use with standard memory components.

Programs written in the microassembly language have two main parts, a declaration part in which various aspects of the micro-instruction word are defined and a specification part in which micro-instruction contents are symbolically declared. Provision is made for comment statements throughout the program so that the programmer may explain the functions being performed.

The main body of the program, the specification part, defines the sequences of states to be executed, and the operations which take place for each state. The main effort in writing a microprogram will be expended in developing this section.

Each statement of the specification part of the program defines the action (and location) of one micro-instruction, i.e., one word of control memory. The statement will declare, either directly or by default, the contents of each control field for the specified micro-instruction. Furthermore, the statement will include assignment information designating the address in control memory where the statement is located.

A specification statement consists of one or more labels followed by a series of control field specifications. A colon after an entry indicates that it is a label. The contents of the control fields are indicated symbolically, using either standard MCU or CPE symbols or user-defined symbols, or by an equation of the type

$$FNM = 101B$$

where FNM is a name associated with the field. The entry 101B implies the binary value 101.

Each symbol is associated with only one field, so that the various symbols can be uniquely interpreted by the assembler. A number of symbols are predefined for the assembler, and are not to be used except as provided by the assembler. These reserved symbols include the standard symbols for the MCU and CPE functions, and a number of directives to the assembler.

## DEFINITION OF CONTROL FIELDS

Each control field added by the hardware designer must be declared to the microprogram assembler. In addition, each bit pattern to be assembled into a word in the control field may be symbolically designated. A FIELD definition statement in the declaration part of the microprogram is used to declare the field by name and define any states.

As an example, let a 2-bit field be defined for memory control. If the programmer wishes to name this field MEMC, and define symbols for the states with 01 corresponding to READ, 10 corresponding to WRITE, and 11 signalling RMW (read-modify-write) and default to 00 if READ, WRITE or RMW is not specified, the statement:

```
MEMC FIELD MICROPS (READ=01B, WRITE=10B, RMW=11B)
LENGTH=2 DEFAULT=00B;
```

would perform the definition. The words FIELD, MICROPS, LENGTH, and DEFAULT are directives to the microprogram assembler.

Additional directives include IMPLY, STRING, KBUS, and ADDRESS. The use of these words, and other features of CROMIS are covered in the Series 3000 Cross Microprogramming System Specification.

A typical statement of the specification section might take the form:

```
7BH: LAB: ILR(R3) FFO STZ JFL(INC TC);
```

The number 7BH (hexadecimal) followed by a colon tells the assembler that the micro-instruction is assigned to row 7 column 11 of control memory (when control memory is treated as an array of 32 rows and 16 columns). The symbolic label LAB

(the colon indicates a label) is also associated with this location. ILR(R3) indicates that the contents of register 3 are to be conditionally incremented and copied to the AC register, while FFO forces the carry input to a logic zero, so that the increment operation does not take place. STZ indicates that the Z flip-flop is to be set by the results, so that, as no carry can result, the Z flip-flop will be set to a logic zero. These symbols are standard symbols, with ILR associated with the CPE and FFO and STZ associated with the MCU carry logic. The JFL tests the carry output line for a conditional jump to either the statement labeled NC or to the statement labeled TC. JFL is also a standard symbol. Note that, if the machine is pipelined, the conditional jump tests the results of the previous instruction, not of the present one. The semicolon indicates the end of the statement.

In the statement above, no information was provided for the K-Bus. It is assumed the assembler will provide the appropriate default value associated with the ILR operation, i.e., the K-Bus at all zeros.

The reader is referred to the Intel® Series 3000 Cross Microprogramming System Specification for detailed information concerning CROMIS.

## ASSIGNMENT TO CONTROL MEMORY

The nature of the MCU next state address control requires the programmer to assign control memory locations to each micro-instruction. While this may at first seem unfamiliar, it can usually be easily accomplished if the following sequence is followed:

1. The microprogram should be written without regard to address assignment. Then conditional jumps are assigned using the basic conditional jumps provided by the MCU (JFL, JCF, JZF, JPR, JLL, JRL, JPX), noting the number of possible destinations for the conditional jumps chosen. When a sequence of instructions is to be executed unconditionally and does not indicate what jump codes will be used to advance to the next state (unless the JCE enable feature is required), use the non-committal code JMP rather than selecting a JCC, JZR or JCR.
2. Prepare a state sequence flowchart for the program (see example, Figure 7). According to the programmer's preference, this may be done before, during or after the actual writing of the code. Label the conditional jump points on the flowchart.

3. Using the flowchart as a guide, perform the assignment. In general, conditional jumps should be assigned first, with clusters of conditional jumps assigned before isolated jumps. Leave long chains of unconditional sequences for last. The process of assignment can be assisted by using a diagram of the control memory showing the 32 rows and 16 columns. As each state is assigned, the control memory diagram is marked to show occupancy of that word and the flowchart marked to show the assignment of the state. With the assignment complete, the addresses are copied from the memory diagram.

One other procedure in microprogram memory assignment has been found to be useful. When the control memory diagram is marked as each state is assigned, it is helpful to include state linkage information in the diagram, i.e., memory location(s) that reference the current location and memory location(s) referenced by the current location. With the additional information, micro-instruction sequences can be easily traced on the control memory diagram.

The state linkage information can be quite useful when most of the microcode has been assigned and only a few locations are left to assign the remaining states. If reassignment of memory locations becomes necessary in order to assign the remaining microcode, or modify the existing microcode, the state linkage information will greatly simplify the task.

When reassignment becomes necessary, sequences of unconditional micro-instructions should be considered first since they are the easiest to move. Therefore, these types of states are useful to annotate.

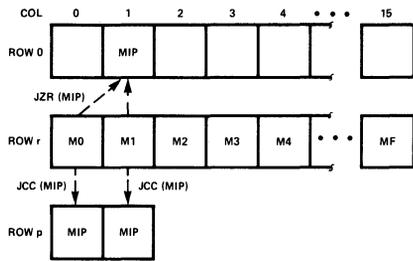
In some cases, a particular sequence may be impossible to assign as written. For example, consider the following section of microprogram:

```

/* ENTER WITH INSTRUCTION DISPLACEMENT "0" IN AC, SAVE AT R9 */
175:  SDR(9)  FF1 JPX(M0, M1, M2, M3, M4, M5, M6, M7, M8, M9, MA, MB, MC,
      MD, ME, MF); /* ALSO TESTS HIGH 4 BITS OF MACRO-INSTRUCTION */

/* M0 - MACRO INSTRUCTION GROUP 1, FETCH R2 */
128:  M0:  ILR(R2)  FFO  JMP(M1P);
129:  M1:  ILR(R3)  FFO;
      M1P:  ADR(R9)  FFO;

```



**Figure 6. Operation MIP Can Be Reached From Both M0 and M1 by Locating MIP in Row 0 or Duplicating it in Both Column 0 and Column 1**

In the above example, MIP follows both M0 and M1. Since the row in which M0 and M1 reside is completely filled, MIP must be located in row zero (because the JZR jump operation allows a location in row zero to be reached from anywhere in memory). If row zero were already fully occupied, the assignment could not be made. However, in this case the state represented by MIP might be duplicated so that it can be reached from state M0 and M1. No extra execution time is added by this modification, although one more memory location is used.

When assigning to memory, row zero locations should be used judiciously, but not sparingly, because only they can be reached from anywhere else in the program using a single JZR jump function.

Finally, in a 512-word microprogram memory there are 64 possible destination pairs for the JCF, JZF and JFL conditional jump functions, since all three use columns 2 and 3 or columns 10 and 11 as their jump target. It is therefore important to insure that enough destination pairs are available for the conditional jumps used in a microprogram.

## PROGRAMMING TECHNIQUES

Because of the flexibility of both the micro-operations and the architecture of the Series 3000 computing elements, a number of programming “tricks” can be used to implement a desired operation. As the programmer becomes more familiar with the set, he will find new ways to perform different functions. The list of operations given here are intended as examples. In general, the labels indicating assignments to memory are not shown. In all of the examples, KB is the name associated with the K-Bus field of the micro-instruction. Statements bounded by /\*. . .\*/ are comments and do not affect the assembly.

1. Forcing a fixed address to access a predetermined location in memory or to select a specific I/O device. (Also may be used to load literals.)

```
CLR(N)      :
LMI(N) KB=DESAD :
```

The first operation clears the register selected by N, while the second loads the logical OR of the contents of N and the contents of the K-Bus to the memory address register (MAR) of the CPE array and into register N. DESAD is a symbol for the desired address value previously defined by the programmer. The pair of micro-ops above may also be used to set any register to any desired constant, although the contents of the MAR are destroyed.

2. Any register may be set to all 1's by the operation

```
CSR(N) FF0 :
```

3. A value read from memory or I/O into the AC may be split into bytes and stored in another register as follows:

```
SDR(N) FF1 KFF00 : /* STORE RIGHT BYTE IN REG N */
SDR(AC) FF1 K00FF : /* SET LEFT BYTE OF AC TO ZERO */
```

where KFF00 is a symbol which causes the K-Bus to be set to 1111 1111 0000 0000 in binary, and K00FF is a symbol for setting the K-Bus to 0000 0000 1111 1111 in binary. The high order byte is placed in the upper byte of register N while the low order byte remains in the low position of the AC. The low byte of register N and high byte of the AC are cleared.

4. *Sign Testing and Absolute Magnitude* – To test sign bits most effectively, an inhibit operation at the CPE clock is very desirable. In the following examples the symbol INH implies a signal from the control memory to inhibit the CPE clock. This prevents modification of the AC register.

The operations

```
TZR(AC) K8000 INH JFL(AP,ANI) :
AN: CIA(AC) :
AP: ... :
```

generate the absolute magnitude of AC in AC for the non-pipelined case (note K8000 implies 1000 0000 0000 0000 on the K-Bus) while

```
TZR(AC) K8000 INH :
NOP JFL(AP,ANI) :
AN: CIA(AC) :
AP: ... :
```

performs the same operation for the pipelined case.

When two numbers in AC and T must be converted to positive numbers and the signs saved, as well as the sign of the product, the following routine may be used for a pipelined machine.

```

/* ENTER WITH VALUES IN T, AC */
/* FIRST CLEAR SIGN AREA - REGISTER 9 FOR THIS EXAMPLE */
CLR(R9)
/* NEXT TEST SIGNS OF AC, THEN T */
TZ(RIAC) K8000 INH /* TEST AC SIGN BIT */
TZ(RIT) K8000 INH JFLIAP,ANI /* TEST T SIGN BIT */
AP: LMI(R9) K8000 FF1 JFLI(TP,TN) /* SET HIGH AND LOW ORDER BIT */
AN: CIA(AC) JFLI(TP,TN) /* COMPLEMENT AC */
TP: LMI(R9) K4000 FF1 JMP(NXOP) /* SET BIT 15 */
TN: CIA(T) /* COMPLEMENT T */
NXOP: ...
    
```

Upon reaching label NXOP, both AC and T will contain positive numbers (high order bit = 0) and register 9 will contain a 1 in the high order bit if and only if AC was originally positive, a 1 in the second bit from the top if and only if T was originally positive, and a zero in the low order bit if and only if the signs were the same. A one will appear in the second lowest order bit if and only if both numbers were originally positive. Execution of the sequence takes 5 micro-instruction cycles.

- Pipelined Multiply** – Assume that AC and T represent the partial product and multiplier respectively, while register 9 contains the multiplicand and register 8 will be used as a loop counter. Register 7 is used for temporary storage. It is assumed that both numbers are positive.

```

/* SET UP LOOP COUNTER */
MCL CSR(R9) K0000 /* SET RB TO FFFF HEX */
TZ(RI9) KFFFF /* SET RB TO FFFF HEX */
/* CLEAR PARTIAL PRODUCT (AC) */
CLR(AC)
/* FETCH AND TEST MULTIPLIER LOW ORDER BIT */
SRA(IT)
/* MAIN LOOP - EXECUTE MULTIPLIER BIT TEST, ADD IF NECESSARY */
MLP LMI(R9) FF1 STZ JFL(MBZ,MB1) /* INCREMENT LOOP COUNTER SAVE IN Z */
/* ADD SEQUENCE */
MB1 SDR(R7) FF1 /* SAVE AC IN REG 7 */
(LR(R9) FFO /* PLACE MULTIPLICAND, RB, IN AC */
ALR(R7) FFO /* ADD MULTIPLICAND TO PARTIAL PRODUCT */
/* NOW ROTATE, THEN TEST LOOP COUNT - SAVED IN Z */
/* NOTE - PIPELINE ALLOWS USE OF Z FOR SHIFT BIT PROPAGATION */
/* NOTE - THE SDR(R7), (LR(R9), AND ALR(R7)) MICRO INSTRUCTIONS CAN BE
REPLACED WITH AN ANA MICRO INSTRUCTION ELIMINATING 2 INSTRUCTIONS
FROM THE INNER LOOP IF DATA IS LATCHED ON THE M BUS */
MBZ SRA(AC) FFO STZ /* SHIFT PARTIAL PRODUCT, SAVE LSB */
SRA(IT) FFZ JZF(MLP,MEX) /* Z TEST IF OF LOOP COUNT1 */
MEX: ...
    
```

Note that the pipeline causes the JZF (or a JCF) to test the contents of the flip-flop as set two or more instructions earlier.

A state sequence flow diagram for the multiply sequence might be drawn as shown in Figure 7.

Note that in Figure 7, each symbolically labeled state is noted, and each conditional jump is indicated and the conditions corresponding to each jump are noted. A flowchart like that of Figure 7 contains sufficient information to perform the assignment to memory. An assignment might be as shown in Figure 8.

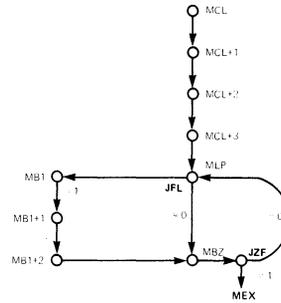


Figure 7. State Sequence Flow Diagram – Multiply Loop

	COL 0	COL 1	COL 2	COL 3	COL 4	COL 5
ROW 9	MCL	MCL +1	MLP	MEX	MCL +2	MCL +3
ROW 10	MB1 +1	MB1 +2	MBZ	MB1		

Figure 8. An Assignment of the Multiply Loop to Control Memory

Because MLP and MEX are the two destinations of a JZF jump function, they must be in the same row, in columns two and three respectively or in columns 10 and 11 respectively. Since MLP executes a JFL to MBZ, MB1, then MBZ and MB1 must be in the same pair of columns as MLP and MEX. For the example, rows 9 and 10 were chosen, and columns 2 and 3, and the four states MLP, MEX, MBZ, MB1 are assigned first. Next the states following MBL (indicated by MB1+1 and MB1+2) and MBZ are assigned. As all of these jumps are unconditional, the operations JCC, JCR, and JZR are used. As the JZR is usually reserved for entry to commonly used routines, only the JCC and JCR jumps are used here.

To demonstrate the techniques introduced above, a central processing unit design cycle will be carried through from initial specification to final microprogram memory assignment.

### A DESIGN EXAMPLE

The following design example illustrates some of the basic techniques which may be used in developing a central processor with the Intel® Series 3000 Bipolar Microcomputer Set. The basic design sequence consists of stating the machine objectives, then designing the hardware configuration and microprograms. For this example, it is assumed that the designer has the freedom to specify operation code assignments, and to modify the instruction set to take greatest advantage of the chip set's capabilities.

## Initial Specifications

Let the following list of design objectives represent the initial specifications for a central processor instruction set.

1. The machine should use a 16-bit data path, with instructions containing an opcode portion and a data or displacement portion.
2. Machine registers should include a program counter, P, a stack pointer, S, an accumulator, A, an index register, X, and two base registers, B and E. B is a base register for data and E is a base register for program. In addition, a carry flip-flop may be a bit in the status word, W.
3. References to memory for data should be relative to the B register, using the displacement portion of the instruction (designated D). Memory reference modes include direct ( $\text{Address}=\text{B}+\text{D}$ ), indirect (address equals the contents of B+D), and indirect indexed (address equals the value given by the sum of X and the contents of the word at address B+D). Indirect and indirect-indexed modes should include both absolute and B relative (i.e., the address is relative to the contents of the B register) forms so that indirections may be computed both at time of assembly and during program execution.
4. Memory reference instructions include: load address to A, load data to A, AND data to A, OR data to A, XOR data to A, add data to A, subtract data from A, push address to stack, push data to stack, store A at computed address, pop stack to computed address, load address to X, load data to X, add data to X, subtract data from X, store X at computed address (operations involving X may not need to implement indirect-indexed modes).
5. Immediate instructions using the displacement portion of the instruction as the data, include, load A, load X, add to A, add to X. A two word "load immediate" instruction may also be implemented.
6. Jump instructions include a short relative jump ( $\text{Address}=\text{P}+\text{D}-\text{K}$ , where K is a constant), an indirect jump to an address relative to the E base register, and an indirect call operation.
7. The call (to a subroutine) operation saves the P, E, B, and W registers (global call), or the P register (local call) on the stack and loads the

P register with the starting address of the routine. Similarly, a return instruction restores the appropriate registers. Some jumps may also be conditional, checking the status of the C flip-flop, or the sign or magnitude of the A register.

8. Additional operations may involve manipulations of data in the A and X registers and the ability to move data between the X and the W, B, E or S registers.
9. Byte load and store operations should include automatic packing and unpacking of bytes in a 16-bit memory location.
10. Input/output instructions should use either the displacement or the X register to specify the I/O device address.

In addition to the definition of the macro-instruction set, the designer should also prepare descriptions of the initialization operations (i.e., at "power on") and interrupt handling to be used. For this machine, let it be considered necessary for the machine to start at power up with W, A, and X cleared and for S to be set to the contents of word 0, B to be set to the contents of word 1 of memory, E set to the contents of word 2, and P set to the contents of the memory location pointed to by E.

Let I/O device 0 represent a source of interrupt level information (level requesting in) and a destination for current level out, consistent with the use of the 3214 Interrupt Control chip. In addition, let the low order bits of W contain current interrupt level information.

When servicing an interrupt, the processor will execute a jump to subroutine which will reload P and E while saving all registers except S on the stack. The service routine will interrogate the interrupt hardware to determine the level of the request and will restore former status upon exit from the interrupt program. For this purpose, a return and restore status instruction will be provided.

In parallel with the specification of the design objectives, a first pass at the CPU's architecture can be made. The block diagram in Figure 9 shows a general CPU architecture as defined in the initial specification above.

The design example machine uses a pipelined architecture and includes a control structure which implements eight basic memory bus and clock operations. A 3-bit field is used to control this structure. The states for this field are designated

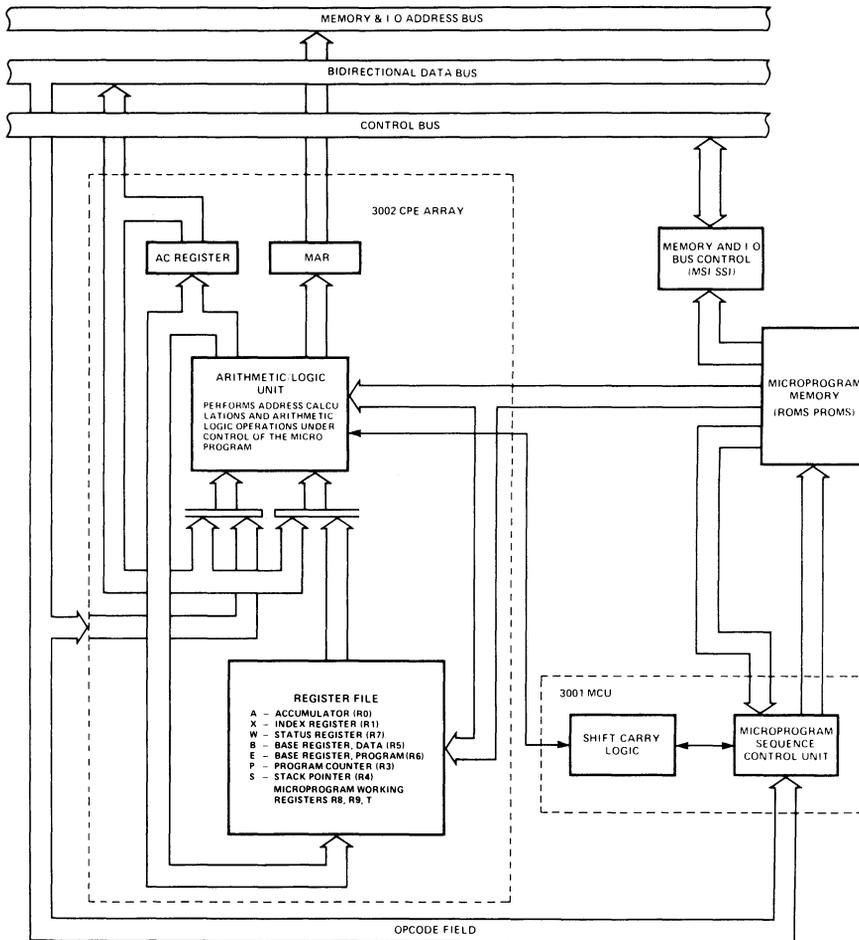


Figure 9. Block Diagram of CPU Architecture

NBO (No Bus Operation), INH (Inhibit CPE Clock), CNB (CPE uses bus), RMW (read modify write signal to memory – starts a read cycle and prevents release of bus until the CPU executes a write cycle), RRM (Request read cycle from memory), RWM (Request write to memory), RIN (Request input from an I/O device), and ROT (Request an output to an I/O device).

The stack has been designed to run “backwards” through memory, with a pop incrementing the

stack pointer and a push decrementing it. This direction is preferred, as it leaves the stack pointer pointing at the topmost entry in the stack. In addition, pops usually appear more often than pushes (pushes share code) and the increment operation requires fewer micro-instructions.

The designer must select the actual instructions to be used. Let the instructions and their associated mnemonics shown in Table I be selected in the first design pass.

**Table I. Proposed Instruction Set**

MEMORY REFERENCE GROUP			JUMP GROUP (continued)		
MNEMONIC	FUNCTION		MNEMONIC	FUNCTION	
	RELATIVE	INDIRECT			
LAA					
LDA			JRCZ	JICZ	Jump if C=0
ADA			JRXL	JIXL	Jump if $X \leq A$
SDA			JRLE	JILE	Jump if $A \leq 0$
NDA			JRGT	JIGT	Jump if $A > 0$
ODA			JRCN	JICN	Jump if $C \neq 0$
XDA			JRXE	JIXE	Jump if $X = A$
PAS			Jump relative: $P = P + D - 128$		
PDS			Jump indirect: $P = (E + D) + E$		
SAM			<b>STACK PUSH AND POP GROUP</b>		
PSM					
LAX			MNEMONIC	FUNCTION	
LDX			PHAX	Push A and X onto stack	
ADX			PPAX	Pop A and X from top of stack	
SDX			<b>SPECIAL MEMORY REFERENCE INSTRUCTION</b>		
SXM			MNEMONIC	FUNCTION	
			ISZ	Increment location B+D and skip if zero	
			<b>SUBROUTINE CALL GROUP</b>		
			MNEMONIC	FUNCTION	
			CLS	Call local subroutine, push P onto stack $P = E + (E + D)$	
			CVS	Call value subroutine, push W, B, E, P onto stack $E = E + (E + D)$ $P = E' + (E')$ where $E' = E + (E + D)$	
			CAS	Call absolute subroutine, push W, B, E, P onto stack $P = (D)$	
			<b>SUBROUTINE RETURN GROUP</b>		
			MNEMONIC	FUNCTION	
			RLS	Return from local subroutine, pop P from stack	
			RVS	Return from value subroutine, pop P, E, B, W from stack	
			RSA	Return from subroutine, restore all, pop A, X, P, E, B, W from stack	
IMMEDIATE GROUP					
MNEMONIC	FUNCTION				
LAI	Load to A immediate				
AAI	Add to A immediate				
NAI	AND to A immediate				
OAI	OR to A immediate				
XAI	Exclusive OR to A immediate				
PSI	Push to stack immediate				
LXI	Load to X immediate				
AXI	Add to X immediate				
If D is equal to zero, the contents of the memory location following the instruction is used as the immediate value.					
			<b>JUMP GROUP</b>		
			MNEMONIC	FUNCTION	
	RELATIVE	INDIRECT			
JRU	JIU		JRU	JIU	Jump unconditional
JRGE	JIGE		JRGE	JIGE	Jump if $A \geq 0$
JRLT	JILT		JRLT	JILT	Jump if $A < 0$
JRXG	JIXG		JRXG	JIXG	Jump if $X > A$
JREZ	JIEZ		JREZ	JIEZ	Jump if $A = 0$
JRNZ	JINZ		JRNZ	JINZ	Jump if $A \neq 0$

Table I. Proposed Instruction Set (continued)

BYTE LOAD AND STORE GROUP	
MNEMONIC	FUNCTION
LBA	Load byte absolute
LBR	Load byte relative
SBA	Store byte absolute
SBR	Store byte relative
Absolute mode:	Byte address = (B+D)+X/2
Relative mode:	Byte address = (B+D)+B+X/2
The least significant bit of the X register is treated as the byte pointer in main memory as follows:	
X Reg. LSB = 0	the left or high order byte is selected
= 1	the right or low order byte is selected
For load operations, the selected byte is loaded into the right byte position of the A register and the left byte is cleared. For store operations, the right byte of the A register is stored at the selected byte location leaving the unselected byte of the word unaltered.	

REGISTER MANIPULATION GROUP	
MNEMONIC	FUNCTION
RAR	Rotate A right, include CFF
RAX	Rotate A and X right, include CFF
SAX	Shift A and X right, preserve sign
SAL	Shift A left, fill with zeros

The shift count is given by D if D is non-zero or by the least significant seven bits of the X register if D is zero.

BASE AND STATUS REGISTER MOVE GROUP	
MNEMONIC	FUNCTION
MSX	Move S to X, adjust
MBX	Move B to X, adjust
MEX	Move E to X, adjust
MWX	Move W to X, adjust
MXS	Move X to S, adjust
MXB	Move X to B, adjust
MXE	Move X to E, adjust
MXW	Move X to W, adjust

The destination register is adjusted by D-128 (i.e., D-128 is added to the destination register).

INPUT/OUTPUT GROUP	
MNEMONIC	FUNCTION
IND	Input one word to the A register
OTD	Output one word from the A register
D serves as the address for the I/O port.	
INX	Input one word to the A register
OTX	Output one word from the A register
The X register provides the address for the I/O port.	

Given the basic design objectives, the next step is to write the sequences of micro-instructions to implement the macro-instruction described above. Each macro-instruction must be assigned a unique operation code. The operation code (opcode) will be used by the 3001 MCU to generate the appropriate address for the micro-instruction which executes that macro-instruction.

**Macro-Instruction Decoding**

To take full advantage of the 3001 MCU's eight input lines (SX0-3, PX4-7) for instruction decoding, all macro-instruction operations should be completely specified in an 8-bit opcode field and use the remaining 8 bits for displacement values. In Figure 10 the 8-bit opcode of a macro-instruction being read in on the memory data bus is gated directly to the 3001 MCU. While the displacement is being stored in the CPE array, a JPX operation is

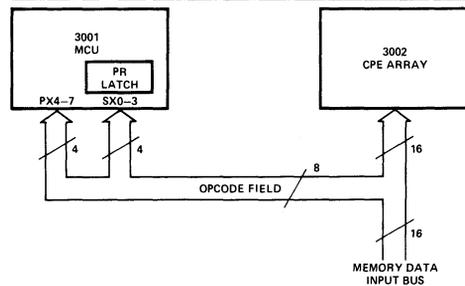
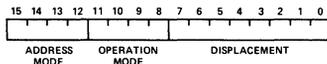


Figure 10. Macro-Instruction Decoding with the 3001

executed by the 3001. The JPX operation executes a 16 way branch based on the 4 bits of the PX lines and also stores the 4 bits on the SX lines in the PR latches for later decoding. For best microcode efficiency then, the opcode field should be arranged in such a manner that the first 4 bits tested (by the JPX operation) select the initial processing (usually an address calculation) of the macro-instruction. A possible instruction format is shown in Figure 11.



**Figure 11. Possible Macro-Instruction Format**

In the case of the CPU design example, the initial processing involves address calculations and/or operand fetching. Table II contains the initial processing modes for the design example.

**Table II. Memory Modes**

In the description below, the letters A, X, B, S, P, W, and E represent the contents of the respective registers. D represents the 8-bit displacement treated as a positive number ranging from 0 to 255. D' represents D-128. ( ) are used to designate contents of memory. For example, (B+D) means the contents of the memory location whose address is equal to the sum of the contents of B and the displacement D. It is assumed that, when the instruction is fetched, P is incremented prior to instruction execution.

**MEMORY REFERENCE MODES**

1. Direct: Address = B+D
2. Indirect: Address = (B+D)
3. Indirect relative: Address = (B+D)+B
4. Indirect indexed: Address = (B+D)+X
5. Indirect indexed relative: Address = (B+D)+B+X

**IMMEDIATE MODES**

6. If D≠0, Data = D-128  
If D=0, Data = (P), P=P+1

**JUMP MODES**

7. Jump relative: P=P+D-128
8. Jump indirect: P=(E+D)+E
9. Call relative: P=(E+D)+E
10. Call indirect: P=E'+(E') where E'=E+(E+D)

**REGISTER MODE**

11. Fetch source register

Using the instruction format shown in Figure 11, the high order 4 bits (bits 12 to 15) will be used to select one of the modes listed in Table II. Thus, by executing a JPX operation, a 16 way branch on the PX0-PX3 bus can be performed to determine the address mode specified. At the same time the SX bus bits (the Operation Code field) will be stored in the PR latches for later use. A possible assignment of the first 4 bits (bits 12 through 15) might be as shown in Table III.

In addition to the initial address mode processing input/output, register to register, and other special function operations can be specified in the first 4 bits, as shown in Table III.

**Microprogram Implementation**

Having assigned the first 4 bits of the macro-instruction operation code, the next 4 may be tentatively assigned. These 4 bits will have different meanings for different instruction classes. To improve microcode efficiency it is desirable to share as much code as possible between different microprogram segments. For example, the ADA and AAI instructions might share the add operation once the data has been fetched.

**MEMORY REFERENCE AND IMMEDIATE GROUP**

The assignment shown in Table IV might be used for the memory reference and immediate group instructions. The clustering has been chosen in a way that should allow JPR and JLL and JRL micro-operations to be used effectively and to allow code sharing between the two groups.

An initial flowchart for the memory reference and immediate group instructions is shown in Figure 12. In the flowchart, the boxes indicate the operations performed. The appropriate jump operations (JPX, JLL and JRL) are indicated along with the bit patterns that select each box.

It is possible that when the actual code for the sequence is written, some improvements in efficiency may still be made. In addition, some of the boxes shown as dummies may be eliminated by suitable placement of the JLL and JRL instructions.

Knowledge of the MCU assignment restrictions may also influence some choices here. For example, the MCU provides twice as many possible JLL jump destinations as JRL jump destinations, while the sequence shown uses twice as many JRLs as JLLs. As a result, an easier assignment might be obtained if the JLLs and JRLs were exchanged, which is equivalent to a reassignment of the macro-operation codes.

Also, recognizing that the MCU's JCC type jump facilitates jumping from one JLL destination to another, it is desirable to assign the macro-operation codes so that operations which share final segments are aligned in columns. For example, the SDA instruction would typically be achieved by complementing the data, then adding it to A, which may share the code for ADA. As a result, a

**Table III. Mode Bit Assignments**

ADDRESS MODE BITS	MODE	INITIAL PROCESS	SUBSEQUENT PROCESSING
0000	No operation		
0001	Jump relative	P+D'	Condition testing
0010	Jumps (index, etc.)	(E+D)+E	
0011	Immediate	D' or (P)	LAI, AAI, etc.
0100	Direct memory reference	B+D	
0101	Indirect memory reference	(B+D)	
0110	Indirect index	(B+D)+X	LAA, LDA, etc.
0111	Indirect index relative	(B+D)+X+B	
1000	I/O input	D → MAR	
1001	I/O input	X → MAR	
1010	I/O output	D → MAR	
1011	I/O output	X → MAR	
1100	Move group		
1101	Special function group		Shift A
1110	Indirect relative memory reference	(B+D)+B	
1111	No operation		

**Table IV. Memory Reference and Immediate Op Code Assignment**

OP FIELD BITS	MEMORY REFERENCE FUNCTION	IMMEDIATE FUNCTION
0000	ADA	AAI
0001	ADX	AXI
0010	NDA	NAI
0011	ODA	OAI
0100	LDA	LAI
0101	LDX	LXI
0110	PDS	PSI
0111	XDA	XAI
1000	LAA	
1001	LAX	
1010	PAS	
1011	SDA	
1100	SAM	
1101	SXM	
1110	PSM	
1111	SDX	

better assignment of opcodes might be achieved by placing ADA and SDA in the same column. For example, see the assignment shown in Table V. Table V also assumes exchange of the JLL and JRL instructions.

**Table V. Modified Memory Reference Op Code Assignments**

0000 = NDA	0100 = ODA	1000 = XDA	1100 = ADA
0001 = LDA	0101 = LDX	1001 = PDS	1101 = ADX
0010 = LAA	0110 = LAX	1010 = PAS	1110 = SDA
0011 = SAM	0111 = SXM	1011 = PSM	1111 = SDX

Except for those considerations mentioned above, the code is most easily written without regard to memory assignment. Also, it is assumed that reassignments of macro-operations codes are made when efficiency can be improved.

Let the CPE register assignments be made as shown in Table VI.

The code which follows represents the specification portion of the microprogram in which the various fields are identified, and symbols defined.

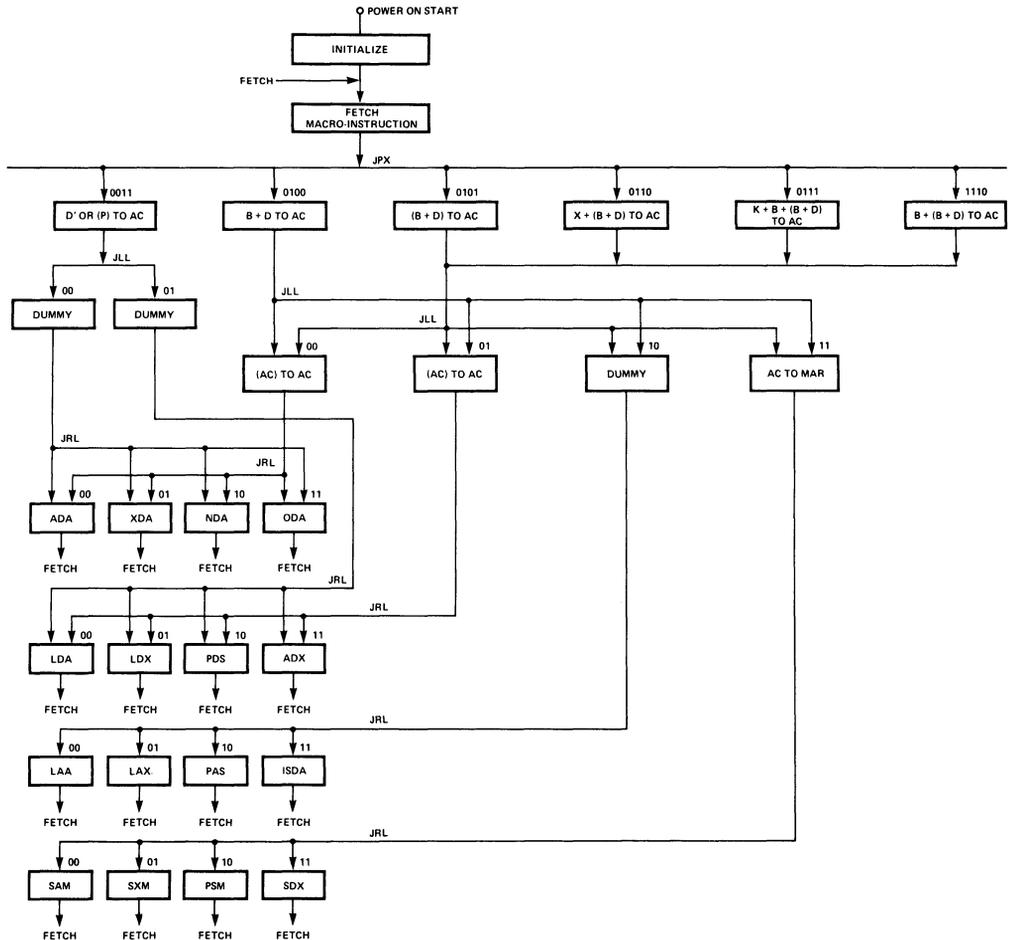


Figure 12. First Pass of Memory Reference Group Flowchart

/\* BIPOLAR MICROCOMPUTER MACRO-MACHINE  
 REGISTER MACHINE-- 12/13/74  
 UPDATED 3/18/75

MACHINE HAS 7 REGISTERS AS FOLLOWS:

A	ACCUMULATOR	R0
X	INDEX REGISTER	R1
P	PROGRAM COUNTER	R3
S	STACK POINTER	R4
B	DATA BASE REG	R5
E	PROG. BASE REG.	R6
W	STATUS WORD	R7

C=CARRY, LINK FLIP-FLOP=HOB OF W

DEFINITION OF KBUS FIELD \*/

```

KB      FIELD   LENGTH=4           DEFAULT=0
        MICROPS(K0000=0   K007F=1   K000FF=3   K7FFF=7
                K8000=8   KFF00=12  KFF80=14   KFFFF=15);

KB      KBUS;

/* DEFINITION OF BUS CONTROL FIELD */

MCF     FIELD   LENGTH=3           DEFAULT=0
        MICROPS(NBO=000B  INH=001B   RMW=010B   CNB=011B
                RIN=100B  ROT=101B   RRM=110B   RWM=111B);

/*
NBO     NO BUS OPERATION
INH     INHIBIT CPE ARRAY
RMW     READ-MODIFY-WRITE
CNB     CPU NEEDS BUS
RIN     REQUEST INPUT
ROT     REQUEST OUTPUT
RRM     REQUEST READ MEM.
RWM     REQUEST WRITE MEM.

SET UP FOR SYMBOLIC REPRESENTATION OF REGISTER DESIGNATIONS */

A       STRING  'R0';
X       STRING  'R1';
P       STRING  'R3';
S       STRING  'R4';
B       STRING  'R5';
E       STRING  'R6';
W       STRING  'R7';

/* SET UP A SPECIAL NO.OP STRING */

NO.OP   STRING  'NOP(R3)';

/* NEXT WE SPECIFY A DEFAULT TO FF1 IN THE FO FIELD FOR THE SDR
MICROP IN THE CPE FIELD. SDR IS NORMALLY USED AS A STORE
OPERATION. WHEN A DECREMENT OPERATION IS ALSO DESIRED, FFO
WILL HAVE TO BE EXPLICITLY SPECIFIED */

SDR     IMPLY   FO=11B;

```

Table VI. Register Assignments

R0	= A
R1	= X
R3	= P
R4	= S
R5	= B
R6	= E
R7	= W (C is high order bit of W)

The next portion of the code represents the machine initialization (in which registers are set to initial values during power up), and the memory reference and immediate group of instructions. The

elementary flowchart followed is that of Figure 13, reflecting the reassignment shown in Table V.

A number of programming “tricks” can be found in the microcode. For example, the C flag of the MCU (not to be confused with the C flip-flop of the macro machine) is set each time the machine executes a fetch instruction by the SDR micro-operation. SDR adds 111...1 to the AC (as masked by the K-Bus) so that whenever the carry input of the CPE array is a 1, the masked AC register will be stored unchanged into the designated register, and the carry output of the CPE array will be 1. Similarly, a ILR micro-operation (KBUS = 0) with a carry-in of zero never generates a carry, so that it can be used to clear the C flag if so desired.

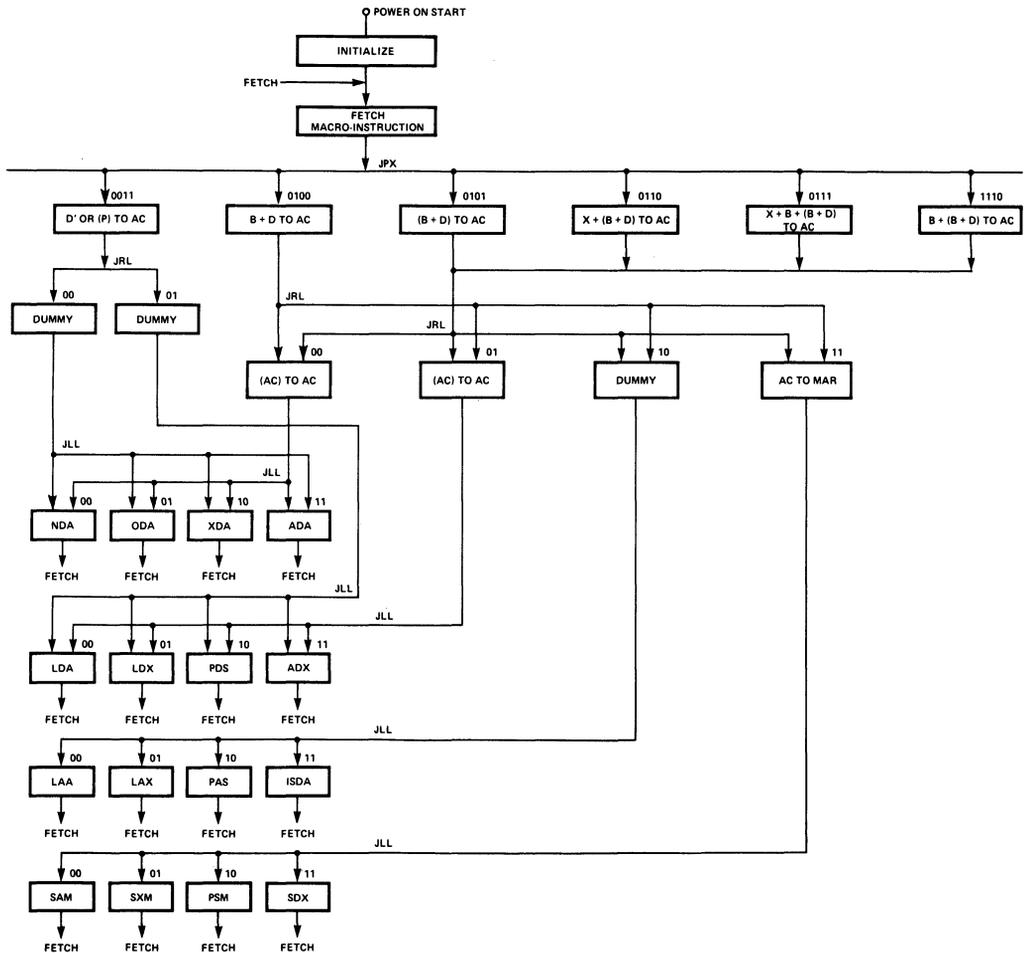


Figure 13. Second Pass of Memory Reference Group Flowchart

The C flag is used to implement a type of microcode subroutine where code is shared by two “calling” routines, one which leaves the C flag unchanged and the other which clears it. Upon exit from the shared code sequence, the C flag is tested giving a unique exit for each of the two calling routines (see Figure 14).

The inhibit operation, indicated by the “INH” micro-operation, inhibits the clock to the CPE array. For these operations the carry function and conditional jump results are the same as if the operation were executed. However, none of the CPE registers are altered when the clock is inhibited.

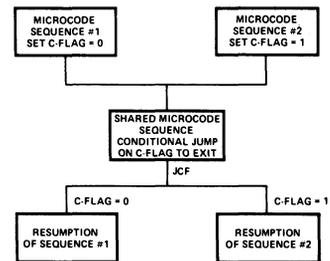


Figure 14. Microcode Subroutine Using the C-Flag to Determine Exit

The result is a number of “compare” or test micro-operations.

In general, row zero locations should be used sparingly because they are the only locations that can be reached from anywhere in microprogram memory using a single JZR micro-operation. During the first pass of the microprogram implementation, notes can be added to indicate where code might be saved if row zero locations are used.

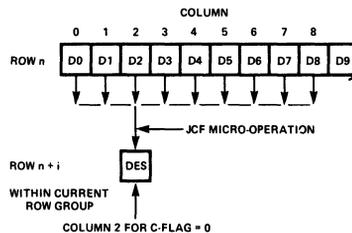
A common case of such microcode saving follows the execution of a JPR or JPX micro-operation. If the datum being tested by the JPR or JPX represents a macro-instruction operation code in which less than 16 modes are used, there is always the possibility that an invalid code might be encountered. Rather than have the machine behave unpredictably, it is better to have the machine execute some designated sequence for invalid macro-operation codes. As a result, all 16 locations reached by the JPX or JPR micro-operation must be considered occupied. Therefore, when it is desirable to have a single state follow each of several states reached by a single JPX or JPR micro-operation, two possible methods can be used which do not require additional jump micro-operations:

1. Locate the single state in the row zero
2. Locate the single state in a column reached by a JCF or JZF micro-instruction and insure the corresponding (C or Z) flag is in the desired state.

As an example of this situation, consider the following sequence of micro-instructions (only labels and jumps shown):

```
TST:   JPR (D0, D1, D2, D3, ..., D15)
D0:   JMP (D1A)
D1:
D1A:
```

In the sequence above, D0 through D15 occupy an entire row. The micro-instruction labeled D1A unconditionally follows both of those labeled D0 and D1. Since the row containing D0 through D15 is fully occupied, D1A cannot be assigned to that row. The only other unconditional jump which can reach a common location from more than one column is the JZR. However, such conditional jumps as JCF and JZF, where the condition is pre-set, can jump to a given location from up to eight sites in a given row, as illustrated in Figure 15.



**Figure 15. Special Use of the Conditional Jump Functions**

```
/* INITIALIZATION SEQUENCE
ZERO A, X, AND W */
```

```
INIT:   CLR(A);
        CLR(X);
        CLR(W);
```

```
/* ZERO T AS TEMPORARY POINTER, WRITE W TO INTERRUPT STRUCTURE */
```

```
CLR(T);
LMI(T);
ILR(W) ROT;
```

```
/* SET S = (0), T = 1 FOR NEXT OPERATION */
```

```
LMI(T) FF1 RRM;
ACM(AC) ;
SDR(S);
```

```
/* SET B = (1), T = 2 FOR NEXT OPERATION */
```

```
LMI(T) FF1 RRM;
ACM(AC);
SDR(B) STC;
/* THIS SETS THE C FLAG TO INSURE
A CORRECT JUMP TO XR TN */
```

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---

/\* GET (2), JUMP TO XR TN TO SET E = (2), P = (E) \*/

LMI(T) RRM;  
ACM(AC) JCF (\*,XR TN);

/\* FETCH SEQUENCE & START OF MACRO-INSTRUCTION PROCESSING  
P IS ISSUED TO MAR AND INCREMENTED, MACRO-INSTRUCTION  
IS FETCHED AND TESTED BY JPX MICRO-OPERATOR. NOTE  
FETCH IS IN LOCATION 15 TO STROBE INTERRUPT ON ENTRY. \*/

FETCH: LMI(P) FF1 RRM;

/\* LOAD DISPLACEMENT AND TEST FOR ZERO USING Z FLAG \*/

LTM(AC) STZ K00FF;

/\* SAVE DISPLACEMENT, TEST 4 BITS OF MACRO-OP. TEST IS  
DELAYED TO ALLOW PIPELINE PROPAGATION. ALSO C FLAG IS  
SET FOR LATER USE IN PSEUDO-SUBROUTINES. \*/

SDR(R9) STC JPX(NA0,JREL,JIG,IMMD,DMRF,IMRF,IXMA,IXMB,IND,  
INX,OTD,OTX,MVGP,SPFG,IRBM,NA15);

/\* UNASSIGNED OP-CODE GROUPS--NOPS FOR THIS VERSION \*/

NA0: NO.OP JZR(FETCH);  
NA15: NO.OP JZR(FETCH);

/\* IMMEDIATE GROUP OF MACRO-INSTRUCTIONS--TEST FOR LONG OR SHORT  
FORM--D IS IN AC AND R9--ADJUST AC BY -128 \*/

IMMD: LMI(AC) KFF80 JZF(IMML,IMMS);

/\* LONG FORM: FETCH NEXT WORD TO AC \*/

IMML: LMI(P) FF1 RRM;  
ACM(AC) JRL(ILGA,ILPX,NA11,NAI2);

/\* SHORT FORM: NO PROCESSING NEEDED \*/

IMMS: NO.OP JRL(ILGA,ILPX,NA11,NAI2);

/\* PREPROCESSING FOR ARITHMETIC AND LOGIC ROUTINES? NONE NEEDED \*/

ILGA: NO.OP JLL(NDA,ODA,XDA,ADA);  
ILPX: NO.OP JLL(LDA,LDX,PDS,ADX)

/\* NOTE: NAI1 AND NAI2 ARE NON-VALID INSTRUCTIONS!! THEY ARE  
MADE INTO NO-OPS IN THIS VERSION OF THE MACRO-MACHINE \*/

NAI1: NO.OP JZR(FETCH);  
NAI2: NO.OP JZR(FETCH);

/\* BASIC ARITHMETIC AND LOGIC PROCESSING--UPDATE C FF OF MACRO-  
MACHINE FOR ADA--TOGGLE IT ON CARRY FROM ADA \*/

ADA: ADR(A);  
ADA1: NO.OP JFL(NCY,SCY);  
NCY: NO.OP JZR(FETCH);  
SCY: LMI(W) K8000 JZR(FETCH);

/\* LOGICALS \*/

NDA: ANR(A) JZR(FETCH);  
ODA: ORR(A) JZR(FETCH);  
XDA: CMR(AC);  
XNR(A) JZR(FETCH);

```

/* LDA AND LDX OPERATIONS */

LDA:   SDR(A)           JZR(FETCH);
LDX:   SDR(X)           JZR(FETCH);

/* STACK PUSH-- ADVANCE STACK POINTER TO NEXT LOCATION (FOR THE
REVERSE DIRECTION STACK-- A DECREMENT OF S), THEN WRITE */

PDS:   DSM(S);
PDS1:  LMI(S) RWM       JZR(FETCH);

/* ADX -- SHARES CODE FOR ADA -- ALSO TOGGLES C FF OF MACRO MACHINE */

ADX:   ADR(X)           JMP(ADA1);

/* MEMORY REFERENCE INSTRUCTION GROUPS
DIRECT-- GET B+D INTO AC-- ALSO R9 */

DMRF:  ILR(B);
        ALR(R9)           JRL(MRV1,MRV2,MRAD,STPG);

/* INDIRECT-ABSOLUTE-- GET (B+D) INTO AC-- C FLAG USED FOR PSEUDO-SUBROUTINE */

IMRF:  ILR(B);
IMRF1: ALR(R9);
        LMI(R9) RRM       JCF(MADD,MLOAD);
MLOAD: ACM(AC)           JRL(MRV1,MRV2,MRAD,STPG);

/* NOTE: MADD WILL BE USED FOR OTHER INDIRECT OPERATIONS WHERE
B, X, ETC. HAS BEEN LOADED TO R8 */

MADD:  ACM(AC);
        ALR(R8)           JRL(MRV1,MRV2,MRAD,STPG);

/* INDIRECT INDEXED ABSOLUTE -- CLEAR C FLAG, MOVE X TO R8 */

IXMA:  ILR(X) STC;
        SDR(R8);

/* NOTING THAT ASSIGNMENT RULES WOULD NOT ALLOW THE DESIRED
JUMP TO IMRF UNLESS IXMA+1 WERE IN ROW ZERO-- AN EXTRA STATE
IS ADDED HERE */

IXMA2: ILR(B)             JMP(IMRF1);

/* INDIRECT INDEXED RELATIVE -- CLEAR C FLAG, PUT B+X IN R8 */

IXMB:  ILR(X) STC;
        SDR(R8);
        ILR(B);
        ADR(R8)           JMP(IMRF);

/* INDIRECT RELATIVE (TO B) -- CLEAR C FLAG, PUT B IN R8 */

IRBM:  ILR(B);

/* AGAIN ASSIGNMENT RULES PREVENT JUMPING TO IXMA+1 UNLESS IT IS
LOCATED IN ROW ZERO-- PLACEMENT THERE COULD FREE TWO WORDS */

        SDR(R8)           JMP(IXMA2);

/* THE FOLLOWING PROCEDURES IMPLEMENT THE BASIC PREPROCESSING FOR
VALUE AND ADDRESS LOADING.

VALUE-GROUP 1: GET (AC) IN AC */

MRV1:  LMI(AC) RRM;
        ACM(AC)           JLL(NDA,ODA,XDA,ADA);

```

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```

/* VALUE GROUP 2 */

MRV2:   LMI(AC) RRM;
        ACM(AC)                JLL(LDA,LDX,PDS,ADX);

/* MRAD GROUP INCLUDES ADDRESS LOADS AND SUBTRACT FROM A */

MRAD:   NO.OP                JLL(LAA,LAX,PAS,ISDA);

LAA:    SDR(A)                JZR(FETCH);
LAX:    SDR(X)                JZR(FETCH);
PAS:    DSM(S)                JMP(PDS1);

/* FOR SUBTRACT, ADD 1'S COMPLEMENT PLUS 1 */

ISDA:   LMI(AC) RRM;
        LCM(AC);
        ADR(A) FF1           JMP(ADA1);

/* STPG GROUP INCLUDES STORES AND SUBTRACT FROM X */

STPG:   LMI(AC)                JLL(SAM,SXM,PSM,SDX);

SAM:    ILR(A) RWM            JZR(FETCH);
SXM:    ILR(X) RWM            JZR(FETCH);

/* POP STACK TO MEMORY – SAVE ADDRESS, POP STACK */

PSM:    SDR(T);
        LMI(S) FF1 RRM;
        ACM(AC);
        LMI(T) RWM           JZR(FETCH);

/* SUBTRACT FROM X */

SDX:    LMI(AC) RRM;
        LCM(AC);
        ADR(X) FF1           JMP(ADA1);

```

Thus the initialization procedure requires 16 words of microcode, the fetch sequence 3, and the memory reference and immediate groups use a total of 57 words. In addition, two dummy locations (NAI1 and NAI2) are needed for unassigned macro-operation codes.

Sample execution times for some of the instructions may be estimated by counting the number of micro-instructions in the sequences and the number of read and write memory cycles. Allowing 150 nsec for each micro-instruction, and 400 nsec for each memory cycle, some representative execution times would be as shown in Table VII.

**Table VII. Representative Execution Times**

INSTRUCTION	MICROCYCLES	READ CYCLES	WRITE CYCLES	EXECUTION TIME
ADA, direct	10	2		2.3 $\mu$ S
ADI, short	9	1		1.75 $\mu$ S
LDA	8	2		2.0 $\mu$ S
LAI, short	7	1		1.45 $\mu$ S
LDA, indirect index relative	15	3		3.45 $\mu$ S

JUMP GROUP

The next section shows the realization of the jump group instructions. Two basic classes, a jump relative to the program counter and an indirect jump through a table stored at the beginning of the program are represented. Conditional jumps include  $A > 0$ ,  $A \geq 0$ ,  $A = 0$ ,  $A \neq 0$ ,  $A \leq 0$ ,  $A < 0$ ,  $X \neq A$ ,  $X > 0$ ,  $X \leq A$ ,  $C = 0$  and  $C \neq 0$ .

In addition, two classes of subroutine calls are provided; a local call which pushes P onto the stack, and jumps relative to E, and a global subroutine call which stores the W, B, E, and P registers on stack and computes new values for E, the program base register, and P. Also, included in this section of microcode is the operation that pushes both A and X onto the stack.

Table VIII shows the opcode assignments for the various jump operations implemented. Except for

the conditional jumps,  $X > A$ ,  $X \leq A$ ,  $X = A$  and  $X \neq A$  which share a common subroutine and exit via a JLL jump, the opcode values were assigned arbitrarily.

A flowchart representing the jump coding is shown in Figure 16. During the microcoding of the sequence, two methods were evaluated. One used the JRL, JLL sequence of testing 2 bits of macro-operation code at a time, while the one actually selected uses a JPR macro-operation. The JPR test selected uses no more code than the JRL, JLL sequence method, and executes more rapidly. At one point (for the  $X = A$ ,  $X \neq A$ ,  $X > A$ ,  $X \leq A$  tests), code is shared as if it were part of a subroutine, then a JLL instruction is used to resolve the exit. This method is another example of a pseudo-subroutine that saves microprogram memory. Use of this technique does put a constraint on the assignment of macro-operation codes.

Table VIII. Jump Instruction Group

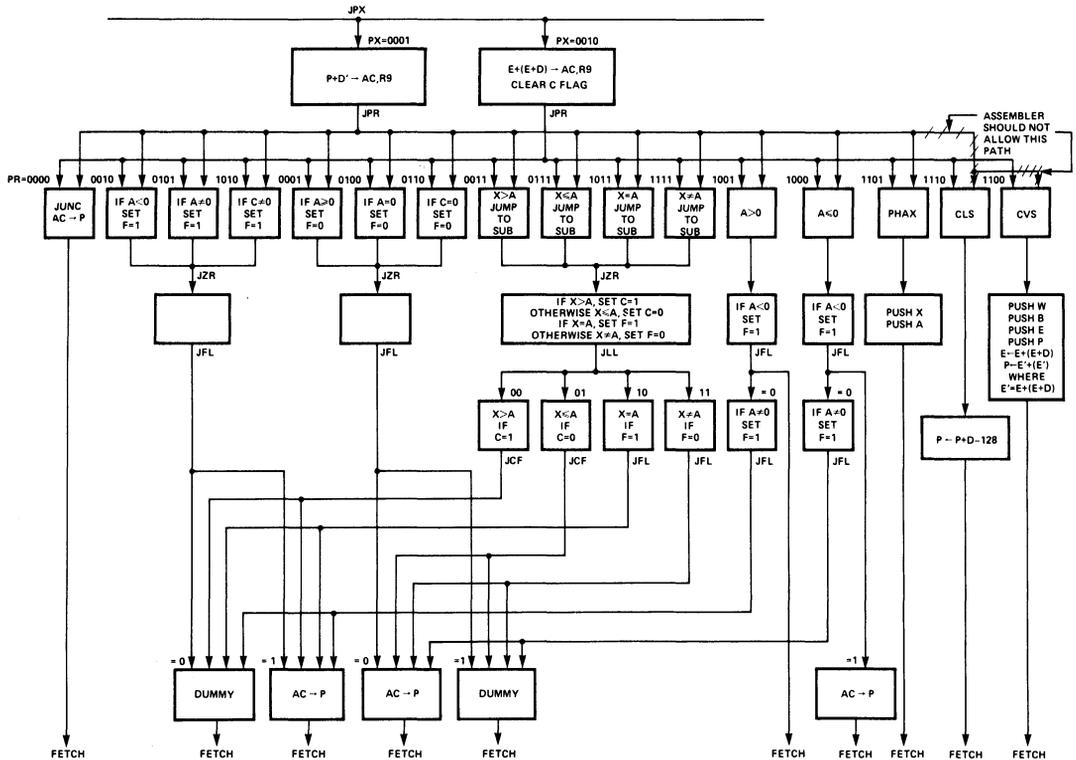
MNEMONIC	FUNCTION	RELATIVE		INDIRECT	
		M	O	M	O
JRU, JIU	Jump unconditional	0001	0000	0010	0000
JRGE, JIGE	Jump if $A \geq 0$	0001	0001	0010	0001
JRLT, JILT	Jump if $A < 0$	0001	0010	0010	0010
JRXG, JIXG	Jump if $X > A$	0001	0011	0010	0011
JREZ, JIEZ	Jump if $A = 0$	0001	0100	0010	0100
JRNZ, JINZ	Jump if $A \neq 0$	0001	0101	0010	0101
JRCZ, JICZ	Jump if $C = 0$	0001	0110	0010	0110
JRXL, JIXL	Jump if $X \leq A$	0001	0111	0010	0111
JRLE, JILE	Jump if $A \leq 0$	0001	1000	0010	1000
JRGT, JIGT	Jump if $A > 0$	0001	1001	0010	1001
JRCN, JICN	Jump if $C \neq 0$	0001	1010	0010	1010
JRXE, JIXE	Jump if $X = A$	0001	1011	0010	1011
CVS	Call subroutine, push W, B, E, P		N.A.	0010	1100
PHAX	Push A, X onto stack	0001	1101	0010	1101
CLS	Call subroutine, push P		N.A.	0010	1110
JRXN, JIXN	Jump if $X \neq A$	0001	1111	0010	1111

Subroutine calls

- Local: Push P to stack  
 $P = E + (E + D)$
- Value: Push W, B, E, P to stack  
 $E = E + (E + D)$   
 $P = E' + (E')$  where  $E' = E + (E + D)$

Unconditional and conditional jumps

- Relative:  $P = P + D'$  where  $D' = D - 128$
- Indirect:  $P = E + (E + D)$



**Figure 16. Jump Group Flowchart**

/\* JUMP GROUPS--USE JPR MICRO-OPERATION TO RESOLVE CONDITION SELECTION  
 DESTINATION ADDRESS IS COMPUTED FIRST--PLACED IN AC AND R9  
 JUMP RELATIVE TO P--ADDRESS=P+D-128 \*/

```
JREL:  ILR(P);
JRDR:  LMI(AC) KFF80;
        ALR(R9)                                JPR(JUNC,JAGE,JALT,JXGA,JA EQ,JANE,JCEZ,JXLA,
                                                JALE,JAGT,JCNZ,JXEA,CPSS,PXA,CLOP,JXNA);
```

/\* JUMP INDIRECT -- GET E+(E+D) IN AC AND R9 \*/

```
JIG:   ILR(E);
        ADR(R9);
        LMI(R9) RRM;
        AMA(AC);
        SDR(R9)                                JPR(JUNC,JAGE,JALT,JXGA,JA EQ,JANE,JCEZ,JXLA,
                                                JALE,JAGT,JCNZ,JXEA,CPSS,PXA,CLOP,JXNA);
```

/\* UNCONDITIONAL JUMP \*/

```
JUNC:  SDR(P)                                JZR(FETCH);
```

/\* TESTS FOR A.GE.0, ETC. \*/

```
JAGE:  TZR(A) K8000 INH                      JMP(TTRU);
JALT:  TZR(A) K8000 INH                      JMP(TFAL);
JAEQ:  TZR(A)                                JMP(TTRU);
JANE:  TZR(A)                                JMP(TFAL);
```

```

JAGT:  TZR(A) K8000 INH;
        TZR(A)                                JFL(APRE,ANPE);

APRE:  NO.OP                                  JFL(JNT2,JTR2);
ANPE:  NO.OP                                  JZR(FETCH);

JALE:  TZR(A) K8000 INH;
        TZR(A)                                JFL(APE2,AN2);

APE2:  NO.OP                                  JFL(JTR1,JNT1);
AN2:   SDR(P)                                JZR(FETCH);

/* TESTS OF C FLIP-FLOP (HIGH ORDER BIT OF W) */

JCEZ:  TZR(W) K8000 INH                       JMP(TTRU);
JCNZ:  TZR(W) K8000 INH                       JMP(TFAL);

/* TEST EXECUTION FOR ABOVE TESTS – ROW ZERO USED */

TTRU:  NO.OP                                  JFL(JTR1,JNT1);

JTR1:  SDR(P)                                  JZR(FETCH);
JNT1:  NO.OP                                  JZR(FETCH);

TFAL:  NO.OP                                  JFL(JNT2,JTR2,);

JNT2:  NO.OP                                  JZR(FETCH);
JTR2:  SDR(P)                                  JZR(FETCH);

/* TESTS FOR X.GT.A, X.LE.A, X.EQ.A, X.NE.A – SHARED PSEUDO-
SUBROUTINE USES JLL FOR AN EXIT TEST – ROUTINE ENTRY IN ROW 0
C FLAG IS SET FOR X.GT.A, FL TEST FOR X.EQ.A */

JXGA:  ILR(X)                                  JMP(XATS);
JXLA:  ILR(X)                                  JMP(XATS);
JXEA:  ILR(X)                                  JMP(XATS);
JXNA:  ILR(X)                                  JMP(XATS);

/* SAVE X AT T, FETCH AND COMPLEMENT A */

XATS:  SDR(T);
        ILR(A) STC;      /* CLEAR C FLAG */
        CMA(AC);

/* ADD HOB'S OF A' AND X – CARRY MEANS X NEG., A.GE.0 */

ADR(T) K8000;

/* EXECUTE PREVIOUS TEST, SET UP TO TEST HOB OF RESULT – IF 1,
THE SIGNS OF A AND X WERE THE SAME */

TZR(T) K8000 INH          JFL(TFEQ,TXNG);

/* TXNG IMPLIES X NEG AND A.GE.0 – I.E. X.NE.A AND X.LT.A – DO A
DUMMY OPERATION TO FORCE THE PROPER F FLAG */

TXNG:  ILR(A)                                JLL(JXGX,JXLX,JXEX,JXNX);

/* PERFORM A TEST ADDITION AND EXECUTE SIGN-EQUAL TEST
C WILL BE SET IF SIGNS WERE THE SAME AND X.GT.A */

TFEQ:  ADR(T) STC K7FFF                      JFL(SNEQ,SWEQ);

/* SNEQ IMPLIES SIGNS NOT EQUAL – I.E. X.GE.0, A NEG – X.GT.A */

SNEQ:  SDR(AC) STC;      /* DUMMY OP TO SET C FLAG */
        NO.OP                                JLL(JXGX,JXLX,JXEX,JXNX);

```

# CPU Design

---

```
/* FOR SIGNS EQUAL, IF X=A RESULT WOULD BE 1111...1. INCREMENT  
WILL GENERATE A CARRY IF SO */
```

```
SWEQ:   ILR(AC) FF1                JLL(JXGX,JXLX,JXEX,JXNX);
```

```
/* EXECUTION OF JUMP TESTS */
```

```
JXGX:   ILR(R9)                    JCF(JNT2,JTR2);  
JXLX:   ILR(R9)                    JCF(JTR1,JNT1);  
JXEX:   ILR(R9)                    JFL(JNT2,JTR2);  
JXNX:   ILR(R9)                    JFL(JTR1,JNT1);
```

```
/* SUBROUTINE CALLS
```

```
CALL LOCAL AND PUSH W, B, E, P =CPSS  
CALL LOCAL AND PUSH P ONLY=CLOP  
CL FLAG IS USED FOR EXIT TEST AFTER PUSHING P */
```

```
CPSS:   DSM(S);  
        ILR(W);
```

```
        LMI(S) RWM;
```

```
CPG2:   DSM(S);  
        ILR(B);  
        LMI(S) RWM;
```

```
        DSM(S);  
        ILR(E);  
        LMI(S) RWM;
```

```
        DSM(S);  
        ILR(P);
```

```
CLOP2:  LMI(S) RWM;
```

```
/* E+(E+D) INTO AC */
```

```
        ILR(R9)                    JCF(LRTN,XRTN);
```

```
XRTN:   SDR(E);  
        LMI(E) RRM;  
        AMA(AC);
```

```
LRTN:   SDR(P)                    JZR(FETCH);
```

```
CLOP:   DSM(S);  
        ILR(P) STC                 JMP(CLOP2);
```

```
/* PUSH INSTRUCTION */
```

```
PXA:    DSM(S);  
        ILR(X);  
        LMI(S) RWM;
```

```
        DSM(S);  
        ILR(A);  
        LMI(S) RWM                 JZR(FETCH);
```

## REGISTER MOVE AND SUBROUTINE RETURN GROUP

In this section of code, the Register Move and Subroutine Return group instructions are implemented. Both groups share the same JPX entry point, 1100B. Table X shows the opcode values assigned to the macro-instructions.

To simplify the decoding for register selection (S, B, E or W) in the Register Move group, the two low order bits of the PR latch are used to modify the micro-instruction as it is strobed into the pipeline register. By tying the two PR latch outputs of the 3001 to the two low order bits of the CPE control field, a JCE jump function (which enables the PR

latch outputs) can be used to provide a wire OR of PR0, PR1 and F0, F1 (see Figure 17).

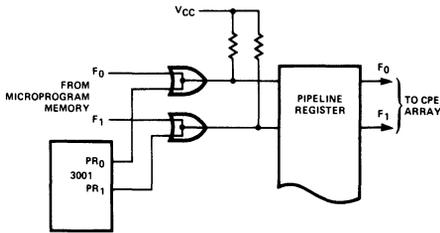


Figure 17. Wire-OR of PO<sub>0-1</sub> and F<sub>0-1</sub>

Thus, in the micro-instruction

SDR(R7) JCE (MXXI)

the register group field F0–F3 is modified as shown in Table IX.

The microprogram sequence is shown in Figure 18.

Table IX. Register Group Field F0–F3 Modification

MICROPROGRAM MEMORY OUTPUT (F0–F3)	PR LATCH OUTPUT	RESULT STORED IN PIPELINE REGISTER	SELECTED REGISTER
0111	00	0100	S
0111	01	0101	B
0111	10	0110	E
0111	11	0111	W

Table X. Register Move and Subroutine Return Group

MNEMONIC	FUNCTION	M	O
RLS	Pop P	1100	1111
RVS	Pop P, E, B, W	1100	1101
RSA	Pop A, X, P, E, B, W	1100	1100
PPAX	Pop A, X	1100	1110
MSX	Move S to X, adjust	1100	0100
MBX	Move B to X, adjust	1100	0101
MEX	Move E to X, adjust	1100	0110
MWX	Move W to X, adjust	1100	0111
MXS	Move X to S, adjust	1100	0000
MXB	Move X to B, adjust	1100	0001
MXE	Move X to E, adjust	1100	0010
MXW	Move X to W, adjust	1100	0011
NO.OP	Nothing implemented	1100	10XX

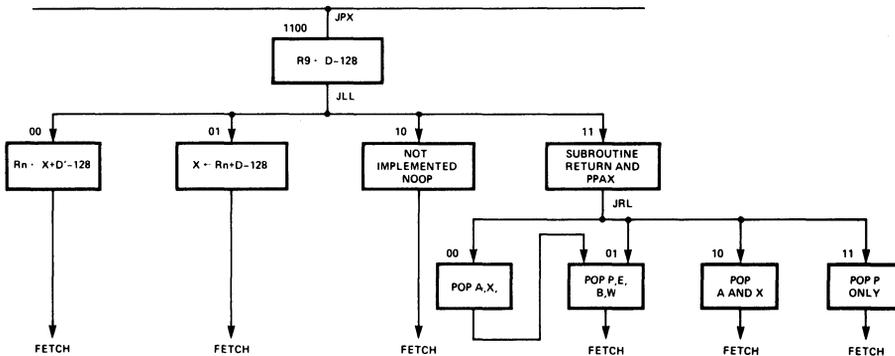


Figure 18. Register Move and Subroutine Return Group Flowchart

# CPU Design

---

/\* MOVE GROUP OF INSTRUCTIONS--USES JCE TO SELECT REGISTER--NOTE  
THAT REGISTER ASSIGNMENT BECOMES IMPORTANT  
FIRST MODIFY D TO GET D-128 \*/

MVGP: LMI(R9) KFF80 JLL(MVXR,MVRX,MOD,PGRP);

/\* MOVE X TO REG. -- GET X, MODIFY BY D'=D-128 \*/

MVXR: ILR(X);  
ALR(R9);  
SDR(R7) JCE(MXRX); /\* REGISTER OVERRIDE \*/  
MXRX: NO.OP JZR(FETCH);

/\* MOVE REG TO X -- FETCH REG USING JCE OVERRIDE \*/

MVRX: ILR(R7) JCE(MRXX);  
MRXX: ALR(R9) JMP(LDX);

/\* MOD NOT IMPLEMENTED IN THIS VERSION \*/

MOD: NO.OP JZR(FETCH);

/\* ADJUST STACK AND RETURN GROUP

PPAL--POPS A, X, P, E, B, AND W

PPRA--POPS P, E, B, AND W

PPAX--POPS ONLY A AND X

POPP--POPS ONLY P \*/

PGRP: ILR(R9);  
ADR(S) JRL(PPAL,PPRA,PPAX,POPP);

PPAL: LMI(S) FF1 RRM;  
ACM(AC);  
SDR(A);

LMI(S) FF1 RRM;  
ACM(AC) JCF(PAXE,PAXC);  
PAXC: SDR(X);

PPRA: LMI(S) FF1 RRM;  
ACM(AC);  
SDR(P);

LMI(S) FF1 RRM;  
ACM(AC);  
SDR(E);

LMI(S) FF1 RRM;  
ACM(AC);  
SDR(B);

LMI(S) FF1 RRM;  
ACM(AC);  
SDR(W);

/\* RESTORE INTERRUPT STRUCTURE \*/

CLR(T);  
LMI(T) ROT JZR(FETCH);

PAXE: SDR(X) JZR(FETCH);

PPAX: ILR(AC) STC JMP(PPAL);

POPP: LMI(S) FF1 RRM;  
ACM(AC) JMP(JUNC);

SPECIAL FUNCTION GROUP

The JPX entry point 1101B is used as an entry point for the special function groups which include byte load and store, register manipulation, and the absolute subroutine call and increment and skip if zero instructions. Table XI lists the opcode values assigned to the instructions. A flowchart of the sequences is shown in Figure 19.

In order to execute a byte load or store operation efficiently, a byte swap capability (which exchanges the high and low order byte positions) is necessary. By wiring the data outputs of the high order byte to the I inputs of the low order byte, and the low order outputs to the high order I inputs, a byte swap operation can be performed (see Figure 20).

Note that with the configuration shown in Figure 20, a byte swap can be performed on either a memory word or the AC register of the CPE array by reading data in on the I-Bus inputs while performing a memory read or enabling the D-Bus, respectively.

Table XI. Special Function Groups

MNEMONIC	FUNCTION	M	O
LBA	Load byte absolute	1101	0000
LBR	Load byte relative	1101	0100
SBA	Store byte absolute	1101	1000
SBR	Store byte relative	1101	1100
RAR	Rotate A right, include CFF	1101	0001
RAX	Rotate A and X right, include CFF	1101	0101
SAX	Shift A and X right, preserve sign	1101	1001
SAL	Shift A left, fill with zeros	1101	1101
ISZ	Increment and skip if zero	1101	XX10
CAS	Call absolute, push P, E, W, B P ← (D)	1101	XX11

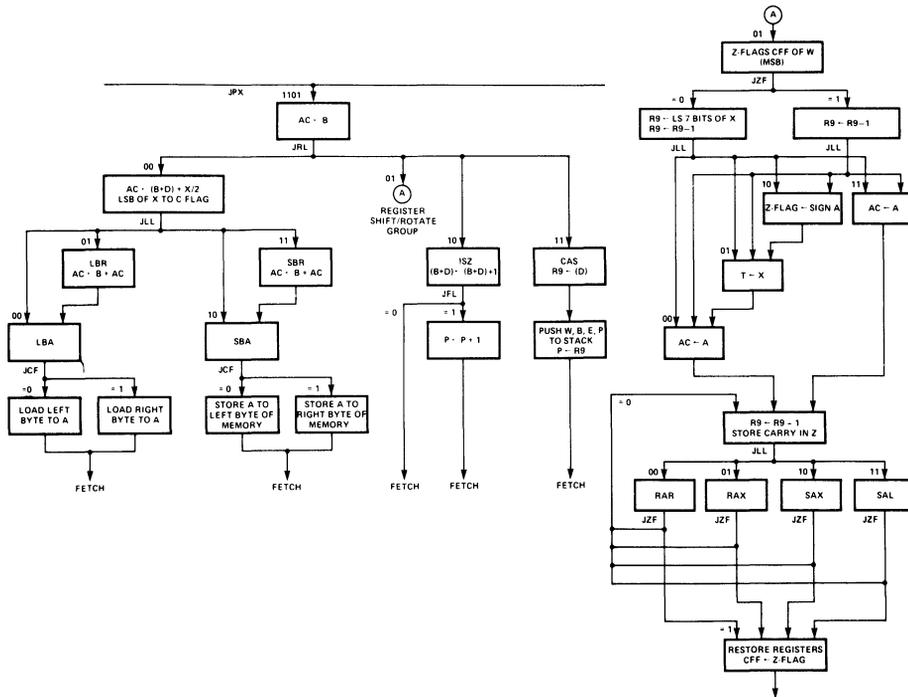


Figure 19. Special Function Groups Flowchart

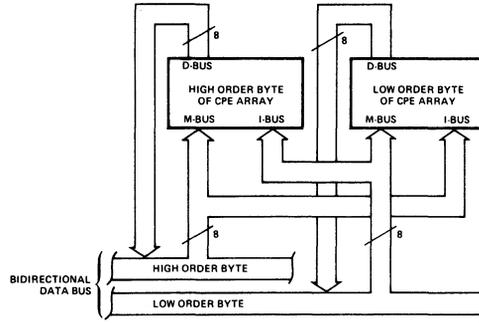


Figure 20. I-Bus Wired for Byte Swap

/\* SPECIAL FUNCTION GROUP

BYTE OPERATORS-- ADDR=(B+D)+B+X/2 OR (B+D)+X/2

CALL TO (D) AND PUSH ALL

SHIFT AND ROTATE GROUP

INCREMENT AND SKIP

FETCH B JUST IN CASE \*/

SPFG: ILR(B)

JRL(BYTE,RSGP,SCJG,ISJG);

/\* BYTE GROUP-- COMPUTE ADDR, STORE B IN CASE NEEDED \*/

BYTE: SDR(R8);

ADR(R9);

ILR(X);

SRA(AC) STC;

LMI(R9) RRM;

ACM(AC)

JLL(LBYA,LBYR,SBYA,SBYR);

LBYR: ALR(R8);

LBYA: LMI(AC) RRM

JCF(LBYT,RBYT);

LBYT: LDI(AC) FF1 K00FF

JMP(DBIA);

RBYT: LTM(AC) K00FF;

JZR(FETCH);

DBIA: SDR(A)

SBYR: ALR(R8);

SBYA: LMI(AC);

/\* LOAD MAR FOR LATER USE \*/

ILR(A);

TZR(AC) K00FF RRM

JCF(STLB,STRB);

STRB: LTM(T) KFF00;

SRB1: ALR(T) RWM

JZR(FETCH);

STLB: LTM(T) K00FF;

LDI(AC) FF1 CNB

JMP(SRB1);

/\* ROTATE GROUP

ROTATE A WITH C-- ROTATE A AND X WITH C-- SHIFT A, X RIGHT, FILL

WITH SIGN-- SHIFT A LEFT, FILL WITH ZEROES

AT ENTRY, Z FLAG IS ZERO IF D=0. DUE TO PIPELINED OPERATION, IT IS THIS CONDITION THAT IS TESTED BY THE FIRST JZF \*/

```
RSGP:  TZR(W) STZ K8000 INH      JZF(SZDS,SNZD);
SZDS:  ILR(X);
      SDR(R9) FF0 K007F          JLL(RACI, RAXI,SAXI,SLZI);
SNZD:  DSM(R9)                   JLL(RACI,RAXI,SAXI,SLZI);

RACI:  ILR(A)                     JMP(RUNR);
RAXI:  ILR(X);
      SDR(T)                     JMP(RACI);
SAXI:  TZR(A) STZ K8000 INH      JMP(RAXI);
SLZI:  ILR(A)                     JMP(RUNR);
```

/\* MAIN ROTATION LOOP \*/

```
RUNR:  DSM(R9) STC                JLL(RACR,RAXR,SAXR,SLZR);

RACR:  SRA(AC) FFZ STZ           JFL(RSEX,RUNR);
RAXR:  SRA(AC) FFZ STZ;
      SRA(T) FFZ STZ           JCF(RSEX,RUNR);
SAXR:  SRA(AC) FFZ STC;
      SRA(T) FFC              JCF(RSEX,RUNR);
SLZR:  ADR(AC) STZ              JFL(RSEX,RUNR);

RSEX:  SDR(A)                   JLL(RACF,RAXF,SAXF,SLZF);

RACF:  TZR(W) K7FFF             JZF(SNCF,SSCF);
SNCF:  NO.OP                    JZR(FETCH);
SSCF:  LMI(W) K8000            JZR(FETCH);
RAXF:  ILR(T);
RXF1:  SDR(X)                   JMP(RACF);
SAXF:  ILR(T)                   JMP(RXF1);
SLZF:  TZR(W) K7FFF            JZF(SNCF,SSCF);
```

/\* SPECIAL CALL AND JUMP GROUP--CURRENTLY CONTAINS ONLY THE CALL TO (D) AND PUSH W,B,E,P--ALL 4 OPCODES DO THE SAME THING \*/

```
SCJG:  LMI(R9) RRM;
      ACM(AC);
      SDR(R9)                   JMP(CPSS);
```

/\* INCREMENT AND SKIP GROUP--AGAIN 4 OPCODES ARE USED FOR ONE INSTRUCTION--LOCATION AT B+D IS INCREMENTED \*/

```
ISJG:  ALR(R9);
      LMI(R9) RMW;
      ACM(AC) FF1 RWM;
      NO.OP                      JFL(NOSK,SKIP);
NOSK:  NO.OP                      JZR(FETCH);
SKIP:  LMI(P) FF1                 JZR(FETCH);
```

## INPUT/OUTPUT GROUP

In this section of code, the input/output instructions are implemented. In conjunction with the memory address register, the bus control field

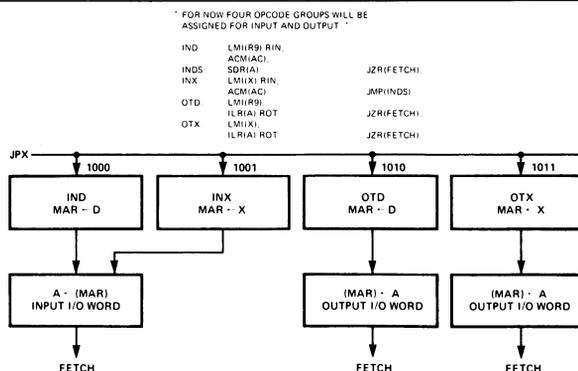
generates a Request Input or Request Output to select an I/O port and specify the operation to be performed. Table XII lists the opcode values assigned to the macro-instructions. The flowchart in Figure 21 shows the microcode sequence used.

**Table XII. Input/Output Group**

MNEMONIC	FUNCTION	M	O
IND	Input one word A ← (D)	1000	XXXX
OTD	Output one word (D) ← A	1001	XXXX
INX	Input one word A ← (X)	1010	XXXX
OTX	Output one word (X) ← A	1011	XXXX

## INTERRUPTS

A basic means for microcoding interrupts when using the 3214 Interrupt Control Circuit involves forcing an alternate microprogram address which then leads to an interrupt handling routine. The interrupt handling routine interrogates the interrupt structure to determine the interrupting level. This level is rewritten to the interrupt structure to block further interrupts at the interrupting priority level or lower levels while enabling interrupts at higher levels.



**Figure 21. Input/Output Flowchart**

/\* INTERRUPT--UTILIZED CALL ROUTINES FOR REGISTER SAVING  
I/O DEVICE #0 REPRESENTS EXTERNAL INTERRUPT STRUCTURE  
START BY PUSHING OLD VALUE OF STATUS \*/

```

INTER:  DSM(S);
         ILR(W);
         LMI(S) RWM;
    
```

/\* READ INTERRUPTING LEVEL FROM EXTERNAL STRUCTURE \*/

```

CLR(T);
LMI(T) RIN;
LTM(AC) K00FF ROT; /* NOTE LEVEL REWRITTEN */
    
```

/\* STORE PRIORITY IN W - SET C FLAG FOR PROPER LOADING OF REGISTERS \*/

```
SDR(W) STC;
```

/\* INTERRUPT ROUTINE STARTING ADDRESS IS COMPUTED IN R9 \*/

```

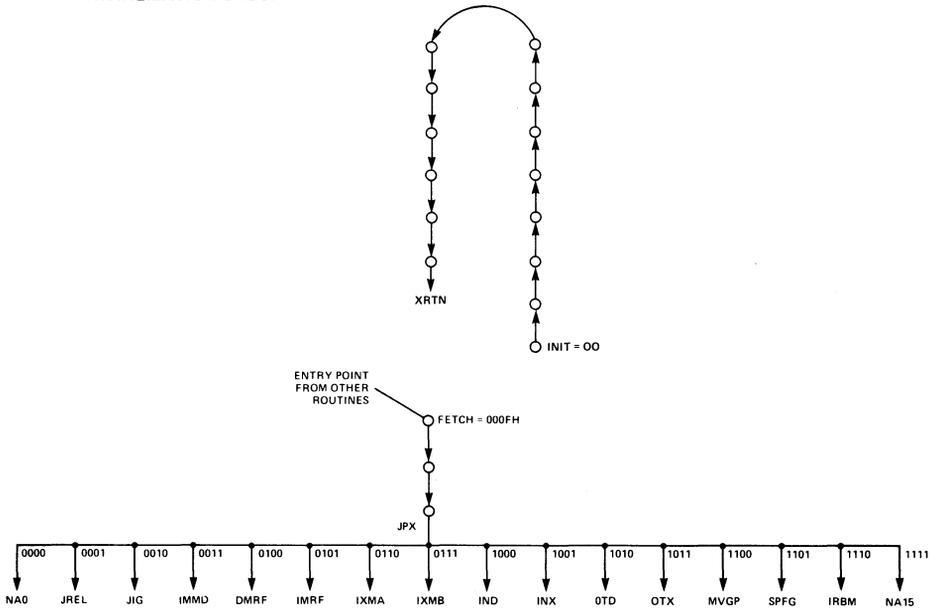
LMI(W) RRM;
ACM(AC);
SDR(R9)                JMP(CPG2);
    
```

## Microprogram Memory Assignment

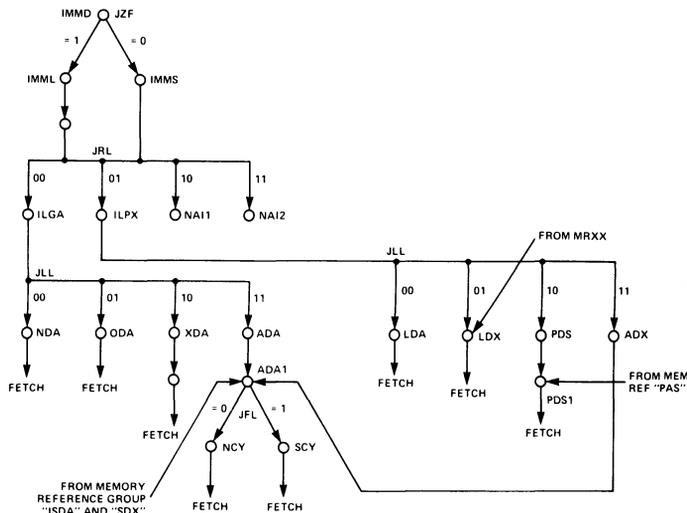
Having written the actual code with minimal regard to memory assignment, the actual assignment to ROM must be performed. To assist in this function, a complete state (i.e., microcode instruction) flowchart should be prepared. Each machine state is represented by a dot in the state diagrams shown

below. Conditional jumps should be labeled as to type and condition corresponding to each destination. This information will be necessary when performing an assignment. No other information is needed on the flowchart, but it is quite useful to show any symbolic label that may be associated with a state.

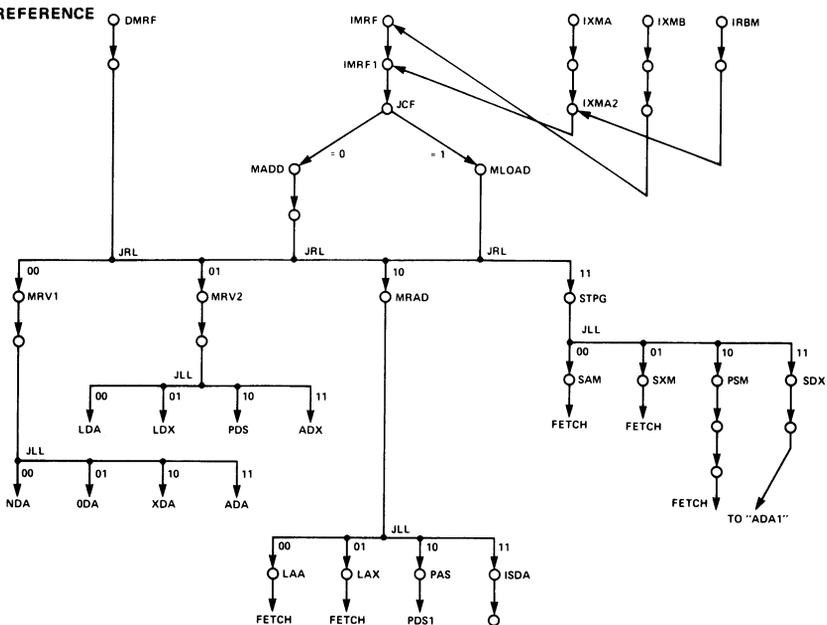
### INITIALIZATION GROUP



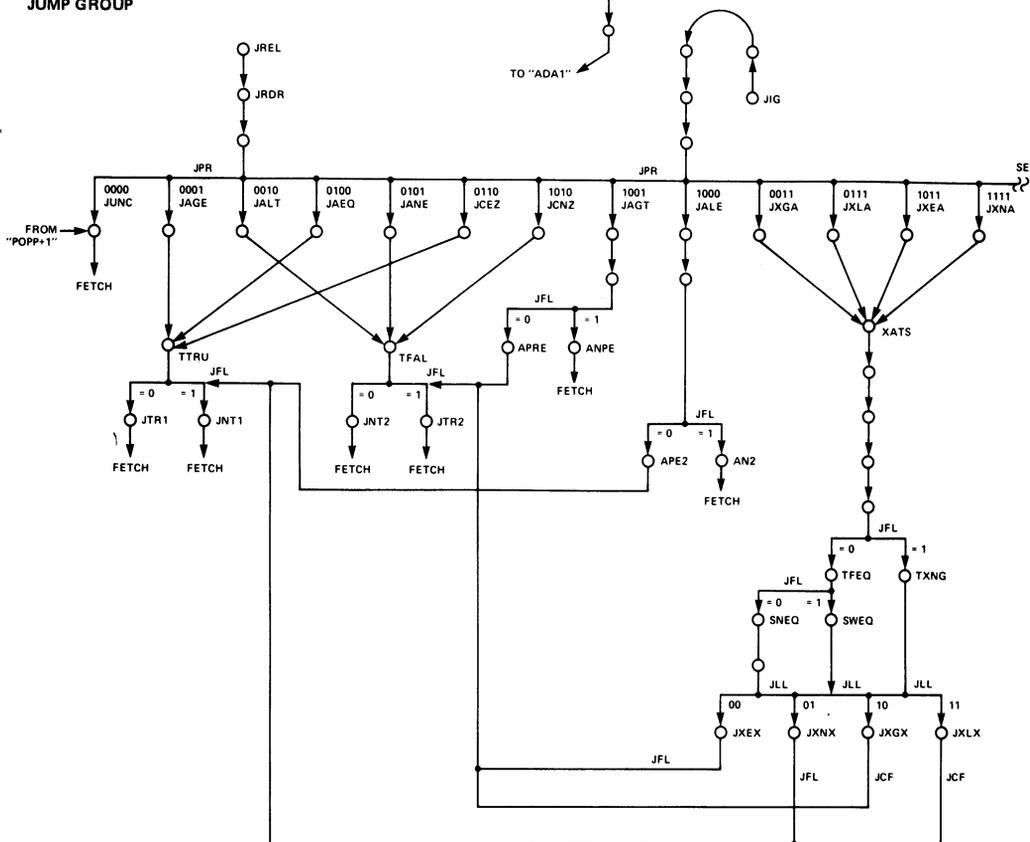
### IMMEDIATE GROUP



## MEMORY REFERENCE GROUP

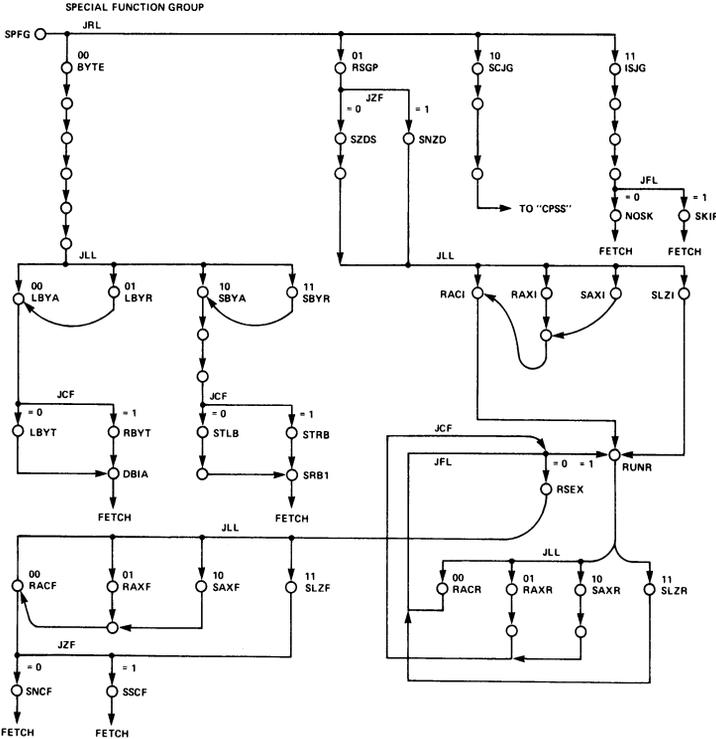


## JUMP GROUP

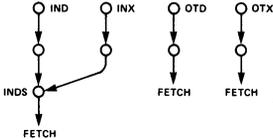




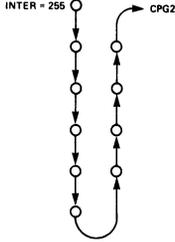
## SPECIAL FUNCTION GROUP



## I/O GROUP



## INTERRUPT SERVICE ROUTINE



Once all of the state diagrams have been prepared, a number of steps may be followed to simplify the assignment procedure. First, the basic hardware characteristics dictate that INIT, FETCH, and INTER be located in microprogram memory locations 0, 15, and 255 (decimal), respectively. Then, note that each conditional jump has a limited range. As a result, when several conditional jumps follow one another in sequence, all may have to be located within a restricted range in microprogram memory. For JCF, JZF, JLL and JRL micro-instructions, the calling instruction must be in the same block of eight rows as the destinations.

To do the best assignment, the most restricted set of micro-instructions should be assigned first. The most restricted groups of micro-instructions are usually associated with clusters of conditional jumps which must be located within a given range of memory. It is therefore very useful to catalog all such clusters of conditional jumps. Table XIII lists the clusters associated with this machine. In each case the conditional jump is identified by the jump micro-operation and the first of its destinations. Thus in Table XIII the symbol JLL(MRV1) really refers to the code JLL(MRV1, MRV2, MRAD, STPG). For this machine, there are only five clusters.

**Table XIII. Conditional Jump Clusters**

1.	JPX (NAO) JRL (ILGA), JRL (BYTE) JLL (NDA), JLL (LDA), JLL (MVXR), JLL (RACI) JZF (IMML), JZF (SZDS)
2.	JRL (MRV1) JLL (SAM), JLL (LAA) JCF (MADD)
3.	JLL (JXEX) JFL (JTR1), JCF (JNT2)
4.	JRL (PPAL) JCF (PAXC)
5.	JLL (RACR), JLL (RACF) JCF (RSEX) JZF (SNCF)

An examination of the flowcharts indicates that a simpler code might result if clusters one and five were combined because of the coupling between JLL(RACI) of cluster one and the JCF(RSEX) of cluster five. The combination of these two clusters represents the greatest degree of restriction, as within the same block of rows there would be one JPX, six JLL, two JRL, one JCF and three JZF micro-operations. In addition, the JLL(MVXR)

executes a JCE jump which uses an additional location within the JLL destination columns. However, the basic jump micro-operation characteristics do allow all of these conditional jumps to be placed within one block of eight rows.

To retain row zero, the conditional jumps of clusters one and five are placed in the last eight rows of the microprogram memory. In addition to the destinations, space must be reserved for the "calling" micro-instructions for each of the conditional jumps listed in the clusters.

Chart 1 shows an assignment of the conditional jumps of clusters one and five, together with some of the immediately related states. For the assignment procedure, a form like that of Chart 1 is used to show which microprogram memory locations are occupied and which are available. The format also aids visualization of valid jump micro-operations. As each state is assigned to its location in micro memory, the corresponding position on the state diagram is marked to show assignment. In this way, unassigned states are easily located on the state diagrams.

The information placed in the memory maps includes the state label or, for strings of states with no assigned label, the label of the nearest previously labeled state plus information to indicate how far from that labeled state the present state is. For example, INIT+2 is the second state after INIT.

The state assignment can proceed, with conditional jumps and short unconditional sequences being assigned before long unconditional sequences. Chart 2 shows the state assignment at a point when all states except those between INIT and FETCH, those between PPRA and FETCH, and those associated with IND, INX, OTD and OTX have been assigned.

For those states which have only one calling state (i.e., a state which has only one state jumping to it with a non-conditional jump) and only one target state (i.e., it makes a non-conditional jump to another state), two hexadecimal numbers are also written on the memory map. The number in the lower left-hand corner is the address of the calling state (first hex digit is the row, second hex digit is the column), and the number in the lower right-hand corner is the address of the target state. This information will tell the designer at a glance which states can be easily moved in the process of memory assignment, and to which locations they can be moved. For instance, a state with its calling state and target state in the same row (or column) can be moved anywhere in that row (or column), and a

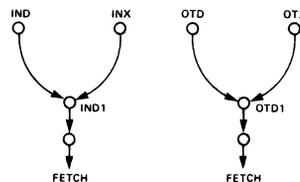
state with its target state in the row zero can be moved anywhere in the same row or column as its calling state.

As an example of how this information can be used, note that in Chart 2 state RAXI+1 has been assigned to location 090H. However, when the INIT sequence is assigned, it becomes convenient to locate INIT+1 somewhere in column 0. Since there are no available spaces in column 0, the designer notes that state RAXI+1 has both its calling and target states in row 9, and so RAXI+1 can be moved anywhere in row 9. In Chart 3, RAXI+1 has been reassigned to location 098H, and INIT+1 has been assigned to location 090H. This moving process will typically be frequently necessary in the assignment procedure, and thus it is quite useful to have this information right on the working memory map.

The final state assignments consist mostly of the long unconditional sequences. Row zero locations

may then be used freely. In those cases where extra states were used to avoid the use of row zero locations, the assignment may be reconsidered. For this machine, the operations IND, INX, OTD and OTX were rewritten to utilize row zero locations. Figure 22 shows the revised flow diagram for these four operations.

The final assignment is as shown in Chart 3. Two locations remain.



**Figure 22. IND, INX, OTD and OTX Revised Flow Diagram**

/\* INPUT AND OUTPUT--CURRENT VERSION DOES NOT DECODE INTO SUBGROUPS--ALSO ROW ZERO IS USED TO SAVE CODE \*/

IND:	LMI(R9) RIN;	
IND1:	ACM(AC);	
	SDR(A)	JZR(FETCH);
INX:	LMI(X) RIN	JMP(IND1);
OTD:	LMI(R9);	
OTD1:	ILR(A) ROT	JZR(FETCH);
OTX:	LMI(X)	JMP(OTD1);

## CONCLUSION

In the central processor design example described above, the final definition of the central processor macro-instruction set evolved as the microprograms were being implemented. In many instances, it was necessary to modify the macro-instruction opcode assignment in order to take full advantage of the capabilities of the Series 3000 architecture. Macro-instruction operations were also redefined to add more flexibility as microprogramming techniques improved.

The microprograms were implemented without regard to memory assignment except in cases where code sharing between micro-instruction opcode assignments were critical. Actual assignment of the micro-instructions to memory involved a very small portion of the design cycle. The 3001 MCU's

ability to decode macro-instruction opcodes and large repertoire of conditional and unconditional jump operations resulted in both efficient microprograms and complete memory utilization. Only two memory locations remained unused after the microcoding was complete.

The central processor developed in this application note is used as a design example only, and therefore does not represent a complete central processor or an instruction set designed for a specific application. However, because of the microprogrammability of the Series 3000 family, the same basic organization can be tailored to a wide range of operating environments from I/O processing to data processing and dedicated arithmetic computation.

Chart 1

		JFL, JCF, JZF COLUMN RESTRICT f,c,z=0 f,c,z=1		JLL COLUMN RESTRICT						JFL, JCF, JZF COLUMN RESTRICT f,c,z=0 f,c,z=1		JRL COLUMN RESTRICT				
	0	1	2	3	4	5	6	7	8	9	A	B	C	D	E	F
00	INIT															FETCH
01																
02																
03																
04																
05																
06																
07																
08	NA0	JREL	JIG	IMMD	DMRF	IMRF	IXMA	IXMB	IND	INX	OTD	OTX	MVGP	SPFG	IRBM	NA15
09	RAXI+1 95 94		RSEX	RUNR	RACI	RAXI	SAXI	SLZI		SZDS+1 9A	SZDS	SNZD				
0A	RAXR+1 A4	SAXR+1 A6	SNCF	SSCF	RACR	RAXR	SAXR	SLZR								
0B	RXFI	IMML+1 B2	IMML	IMMS	RACF	RAXF	SAXF	SLZF								
0C					MVXR	MVRX	MOD	PGRP					BYTE	RSGP	SCJG	ISJG
0D					NDA	ODA	XDA	ADA			PAXC	PAXE	PPAL	PPRA	PPAX	POPP
0E					LDA	LDX	PDS	ADX					ILGA	ILPX	NA11	NA12
0F						MRXX										INTER

Chart 2

		JFL, JCF, JZF COLUMN RESTRICT f,c,z=0 f,c,z=1		JLL COLUMN RESTRICT						JFL, JCF, JZF COLUMN RESTRICT f,c,z=0 f,c,z=1		JRL COLUMN RESTRICT				
0		1	2	3	4	5	6	7	8	9	A	B	C	D	E	F
00	INIT	JAGT+1	JTR1	JNT1	TFAL	TTRU		JALE+1		MADD+1	IMRF1+1	XATS		CLOP2		FETCH
01	SNEQ+1 12		SNEQ	SWEQ	LBYA	LBYR	SBYA	SBYR	SBYA+1 16 79	SBYA+2 18	STLB	STRB	STLB+1 1A 1D	SRBI		FETCH+1 0F 9F
02	DBIA		LBYT	RBYT	JXGX	JXLX	JXEX	JXNX						PPRA+1 DD 2F	BYTE+5 AE	
03	JUNC	JAGE	JALT	JXGA	JAEO	JANE	JCEZ	JXLA	JALE	JAGT	JCNZ	JXEA	CPSS	PXA	CLOP	JXNA
04	PXA+2 4D 70		APE2	AN2		IXMB+3 47 85	IXMA+1 86 56	IXMB+2 57 45				XATS+1 0B 5B	SCJG+2 4E 3C	PXA+1 3D 40	SCJG+1 CE 4C	
05	JIG+3 E0 60	XATS+4 5A	TFEQ	TXNG	DMRF+1 84	IMRF1	IXMA2	IXMB+1 87 47	INTER+3 5F 59	INTER+4 58 69	XATS+3 5B 51	XATS+2 4B 5A	CPSS+1 3C 5D	CPSS+2 5C AD	IRBM+1 8E 56	INTER+2 BF 58
06	JIG+4 50	JRDR+1 71	JNT2	JTR1	LAA	LAX	PAS	ISDA	ISDA+1 67 F8	INTER+5 59 6C	MADD	MLOAD	INTER+6 69 6D	INTER+7 6C 6F	CLOP+1 3E 0D	INTER+8 6D AF
07	PXA+3 40 F0	JRDR 81 61	APRE	ANPE	SAM	SXM	PSM	SDX	PSM+1 76 A8	SDX+1 77 F9	CPG2+2 AA 7B	CPG2+3 7A EB	MRV1	MRV2	MRAD	STPG
08	NAO	JRLE	JIG	IMMD	DMRF	IMRF	IXMA	IXMB	IND	INX	OTD	OTX	MVGP	SPFG	IRBM	NA15
09	RAXI+1 95 94		RSEX	RUNR	RACI	RAXI	SAXI	SLZJ		SZDS+1 9A	SXDS	SNZD	MRV1+1 7C	MRV2+1 7D		FETCH+2 1F
0A	RAXR+1 A4	SAXR+1 A6	SNCF	SSCF	RACR	RAXR	SAXR	SLZR	PSM+2 78 B8	ISJG+3 D9	CPG2+1 AD 7A	BYTE+3 AC AE	BYTE+2 BC AB	CPG2	BYTE+4 AB 2E	INTER+9 6F AD
0B	RXFI	IMML+1 B2	IMML	IMMS	RACF	RAXF	SAXF	SLZF	PSM+3 A8 0F	XRTN+2 B9 BA	LRTN	XRTN	BYTE+1 CC AC	CLOP2+1 0D	XRTN+1 BB B9	INTER+1 FF 5F
0C	MVXR+1 C4 C1	MVXR+2 C0	NCY	SCY	MVXR	MVRX	MOD	PGRP	PGRP+1 C7	ISJG+1 CF D9	NOSK	SKIP	BYTE	RSGP	SCJG	ISJG
0D	POPP+1 DF 30	XDA+1 D6 0F	CPG2+7 F2 0D	PPAL+1 DC D8	NDA	ODA	XDA	ADA	PPAL+2 D3 E8	ISJG+2 D9 A9	PAXE	PAXC	PPAL	PPRA	PPAX	POPP
0E	JIG+2 E2 50	MXRX	JIG+1 82 E0		LDA	LDX	PDS	ADX	PPAL+3 D8 E9	PPAL+4 E8		CPG2+4 7B FB	ILGA	ILPX	NAI1	NAI2
0F	PXA+4 70 F1	PXA+5 F0 0F	CPG2+6 FB D2			MRXX	PDS1	ADA1	ISDA+2 68 F7	SDX+2 79 F7		CPG2+5 EB F2				INTER

Chart 3

		JFL, JCF, JZF COLUMN RESTRICT f,c,z=0 f,c,z=1		JLL COLUMN RESTRICT						JFL, JCF, JZF COLUMN RESTRICT f,c,z=0 f,c,z=1		JRL COLUMN RESTRICT				
0		1	2	3	4	5	6	7	8	9	A	B	C	D	E	F
00	INIT	JAGT+1	JTR1	JNT1	TFAL	TTRU	OTD1	JALE+1	IND1	MADD+1	IMRF1+1	XATS	INIT+12 FC	CLOP2	PPRA+4 1E	FETCH
01	SNEQ+1 12	INIT+4 21 41	SNEQ	SWEQ	LBYA	LBYR	SBYA	SBYR	SBYA+1 16 79	SBYA+2 18	STLB	STRB	STLB+1 1A 1D	SRBI	PPRA+5 0E 9E	FETCH+1 0F 9F
02	DBIA	INIT+3 91 11	LBYT	RBYT	JXGX	JXLX	JXEX	JXNX	INDI+1 08 0F	PPRA+13 2B 0F	PPRA+11 EA 2B	PPRA+12 2A 29		PPRA+1 DD 2F	BYTE+5 AE	PPRA+2 2D 4F
03	JUNC	JAGE	JALT	JXGA	JAEO	JANE	JCEZ	JXLA	JALE	JAGT	JCNZ	JXEA	CPSS	PXA	CLOP	JXNA
04	PXA+2 4D 70	INIT+5 11 44	APE2	AN2	INIT+6 41 F4	IXMB+3 47 85	IXMA+1 86 56	IXMB+2 57 45	INIT+11 49 0C	INIT+10 4A 48	INIT+9 FA 49	XATS+1 0B 5B	SCJG+2 4E 3C	PXA+1 3D 40	SCJG+1 CE 4C	PPRA+3 2F 0E
05	JIG+3 E0 60	XATS+4 5A	TFEQ	TXNG	DMRF+1 84	IMRF1	IXMA2	IXMB+1 87 47	INTER+3 5F 59	INTER+4 58 69	XATS+3 5B 51	XATS+2 4B 5A	CPSS+1 3C 5D	CPSS+2 5C AD	IRBM+1 8E 56	INTER+2 BF 58
06	JIG+4 50	JRDR+1 71	JNT2	JTR1	LAA	LAX	PAS	ISDA	ISDA+1 67 F8	INTER+5 59 6C	MADD	MLOAD	INTER+6 69 6D	INTER+7 6C 6F	CLOP+1 3E 0D	INTER+8 6D AF
07	PXA+3 40 F0	JRDR 81 61	APRE	ANPE	SAM	SXM	PSM	SDX	PSM+1 76 A8	SDX+1 77 F9	CPG2+2 AA 7B	CPG2+3 7A EB	MRV1	MRV2	MRAD	STPG
08	NA0	JRLE	JIG	IMMD	DMRF	IMRF	IXMA	IXMB	IND	INX	OTD	OTX	MVGP	SPFG	IRBM	NA15
09	INIT+1 00 91	INIT+2 90 21	RSEX	RUNR	RACI	RAXI	SAXI	SLZJ	RAXI+1 95 94	SZDS+1 9A	SXDS	SNZD	MRV1+1 7C	MRV2+1 7D	PPRA+6 1E FE	FETCH+2 1F
0A	RAXR+1 A4	SAXR+1 A6	SNCF	SSCF	RACR	RAXR	SAXR	SLZR	PSM+2 78 B8	ISJG+3 D9	CPG2+1 AD 7A	BYTE+3 AC AE	BYTE+2 BC AB	CPG2	BYTE+4 AB 2E	INTER+9 6F AD
0B	RXFI	IMML+1 B2	IMML	IMMS	RACF	RAXF	SAXF	SLZF	PSM+3 A8 0F	XRTN+2 B9 BA	LRTN	XRTN	BYTE+1 CC AC	CLOP2+1 0D	XRTN+1 BB B9	INTER+1 FF 5F
0C	MVXR+1 C4 C1	MVXR+2 C0	NCY	SCY	MVXR	MVRX	MOD	PGRP	PGRP+1 C7	ISJG+1 CF D9	NOSK	SKIP	BYTE	RSGP	SCJG	ISJG
0D	POPP+1 DF 30	XDA+1 D6 0F	CPG2+7 F2 0D	PPAL+1 DC D8	NDA	ODA	XDA	ADA	PPAL+2 D3 E8	ISJG+2 D9 A9	PAXE	PAXC	PPAL	PPRA	PPAX	POPP
0E	JIG+2 E2 50	MXRX	JIG+1 82 E0	PPRA+9 F3 EA	LDA	LDX	PDS	ADX	PPAL+3 D8 E9	PPAL+4 E8	PPRA+10 E3 2A	CPG2+4 7B FB	ILGA	ILPX	NAI1	NAI2
0F	PXA+4 70 F1	PXA+5 F0 0F	CPG2+6 FB D2	PPRA+8 FE E3	INIT+7 44 FA	MRXX	PDS1	ADA1	ISDA+2 68 F7	SDX+2 79 F7	INIT+8 F4 4A	CPG2+5 EB F2	INIT+13 0C		PPRA+7 9E F3	INTER

## APPENDIX A

### THE DESIGN EXAMPLE INSTRUCTION SET

The basic machine uses a 16-bit word. All instructions are single word instructions except the long immediate forms. Macroprograms are fully relocatable without reassembly. The data segment is also independently relocatable. There are five basic instruction categories: memory reference, immediate data, jumps (including calls and returns), register moves and manipulations, and input-output functions.

The machine has seven registers as follows:

REGISTER	ASSIGNED CPE REGISTER
(A) Accumulator	R0
(X) Index Register	R1
(B) Data-Base Register	R5
(E) Program Execution Base Register	R6
(P) Program Counter	R3
(S) Stack Pointer	R4
(W) Status Word Register*	R7

\*A carry flip-flop designated C is the high order bit of the status word register W.

### Memory Reference Group

ADDRESS MODE	ADDRESS COMPUTATION	M-FIELD CODES
Direct	B+D	0100
Indirect	(B+D)	0101
Indirect Relative	(B+D)+B	1110
Indirect Indexed	(B+D)+X	0110
Indirect Indexed Relative	(B+D)+X+B	0111

### SUMMARY OF MEMORY REFERENCE MODES

Note: Values enclosed in ( ) designate indirect addresses.

The operations supported under these five modes are as follows:

MNEMONIC	FUNCTION	O
NDA	AND data to A	0000
LDA	Load data to A	0001
LAA	Load address to A	0010
SAM	Store A in memory	0011
ODA	OR data to A	0100
LDX	Load data to X	0101
LAX	Load address to X	0110
SXM	Store X in memory	0111
XDA	Exclusive OR data to A	1000
PDS	Push data to stack	1001
PAS	Push address to stack	1010
PSM	Pop stack to memory	1011
ADA	Add data to A	1100
ADX	Add data to X	1101
SDA	Subtract data from A	1110
SDX	Subtract data from X	1111

### Immediate Group

MNEMONIC	FUNCTION	M- FIELD	O- FIELD
LAI	Load to A immediate	0011	0001
AAI	Add to A immediate	0011	1100
NAI	AND to A immediate	0011	0000
OAI	OR to A immediate	0011	0100
XAI	Exclusive OR to A immediate	0011	1000
PSI	Push to stack immediate	0011	1001
LXI	Load to X immediate	0011	0101
AXI	Add to X immediate	0011	1101

If D is equal to zero, the contents of the memory location following the instruction is used as the immediate value.

Jump Group

MNEMONIC	FUNCTION	RELATIVE		INDIRECT	
		M	O	M	O
JRU,JIU	Jump unconditional	0001	0000	0010	0000
JRGE,JIGE	Jump if A.GE.O	0001	0001	0010	0001
JRLT,JILT	Jump if A.LT.O	0001	0010	0010	0010
JRXG,JIXG	Jump if X.GT.A	0001	0011	0010	0011
JREZ,JIEZ	Jump if A.EQ.O	0001	0100	0010	0100
JRNZ,JINZ	Jump if A.NE.O	0001	0101	0010	0101
JRCZ,JICZ	Jump if C.EQ.O	0001	0110	0010	0110
JRXL,JIXL	Jump if X.LE.A	0001	0111	0010	0111
JRLE,JILE	Jump if A.LE.O	0001	1000	0010	1000
JRGT,JIGT	Jump if A.GT.O	0001	1001	0010	1001
JRCN,JICN	Jump if C.NE.O	0001	1010	0010	1010
JRXE,JIXE	Jump if X.EQ.A	0001	1011	0010	1011
JRXN,JIXN	Jump if X.NE.A	0001	1111	0010	1111

Unconditional and conditional jumps:

Relative:  $P = P+D'$  where  $D'=D-128$

Indirect:  $P = E+(E+D)$

Subroutine Call Group

MNEMONIC	FUNCTION	ABSOLUTE			
		M	O	M	O
CAS	Call absolute, push P, E, W, B $P \leftarrow (D)$	1101	XX11		
CLS	Call local subroutine, push P		N.A.	0010	1110
CVS	Call global subroutine, push W, B, E, P		N.A.	0010	1100
Local:	Push P to stack $P = E+(E+D)$				
Value:	Push W, B, E, P to stack $E = E+(E+D)$ $P = E'+(E')$ where $E'=E+(E+D)$				

# CPU Design

## Subroutine Return Group

MNEMONIC	FUNCTION	M	O
RLS	Pop P	1100	1111
RVS	Pop P, E, B, W	1100	1101
RSA	Pop A, X, P, E, B, W	1100	1100

## Register Manipulation Group

MNEMONIC	FUNCTION	M	O
RAR	Rotate A right, include CFF	1101	0001
RAX	Rotate A and X right, include CFF	1101	0101
SAX	Shift A and X right, preserve sign	1101	1001
SAL	Shift A left, fill with zeros	1101	1101

## Byte Load and Store Group

MNEMONIC	FUNCTION	M	O
LBA	Load byte absolute	1101	0000
LBR	Load byte relative	1101	0100
SBA	Store byte absolute	1101	1000
SBR	Store byte relative	1101	1100

Absolute mode: Byte address =  $(B+D)+X/2$   
 Relative mode: Byte address =  $(B+D)+B+X/2$

## Special Memory Reference Instruction

MNEMONIC	FUNCTION	M	O
ISZ	Increment and skip if zero	1101	XX10

## Stack Push and Pop Group

MNEMONIC	FUNCTION	M	O	M	O
PHAX	Push A, X onto stack	0001	1101	0010	1101
PPAX	Pop A, X	1100	1110		

The shift count is given by D if D is non-zero or by the least significant seven bits of the X register if D is zero.

## Base and Status Register Move Group

MNEMONIC	FUNCTION	M	O
MSX	Move S to X, adjust	1100	0100
MBX	Move B to X, adjust	1100	0101
MEX	Move E to X, adjust	1100	0110
MWX	Move W to X, adjust	1100	0111
MXS	Move X to S, adjust	1100	0000
MXB	Move X to B, adjust	1100	0001
MXE	Move X to E, adjust	1100	0010
MXW	Move X to W, adjust	1100	0011
NO.OP	Nothing implemented	1100	10XX

The destination register is adjusted by D-128.

## Input/Output Group

MNEMONIC	FUNCTION	M	O
IND	Input one word $A \leftarrow (D)$	1000	XXXX
OTD	Output one word $(D) \leftarrow A$	1001	XXXX
INX	Input one word $A \leftarrow (X)$	1010	XXXX
OTX	Output one word $(X) \leftarrow A$	1011	XXXX

## APPENDIX B

MICROPROGRAM LISTING © Intel Corporation, 1975

RECORD  
NUMBER

```

1  /* BIPOLAR MICROCOMPUTER MACRO-MACHINE
2  REGISTER MACHINE--12/13/74
3  UPDATED 3/18/75
4
5  MACHINE HAS 7 REGISTERS AS FOLLOWS:
6  A      ACCUMULATOR      R0
7  X      INDEX REGISTER    R1
8  P      PROGRAM COUNTER  R3
9  S      STACK POINTER     R4
10 B      DATA BASE REG    R5
11 E      PROG. BASE REG.   R6
12 W      STATUS WORD       R7
13
14 C=CARRY, LINK FLIP-FLOP=HOB OF W
15
16 DEFINITION OF KBUS FIELD          */
17
18 KB      FIELD      LENGTH=4      DEFAULT=0
19          MICROPS(K0000=0  K007F=1  K00FF=3  K7FFF=7
20                  K8000=8  KFF00=12  KFF80=14  KFFFF=15);
21
22 KB      KBUS;
23
24
25 /* DEFINITION OF BUS CONTROL FIELD          */
26
27 MCF     FIELD      LENGTH=3      DEFAULT=0
28          MICROPS(NMG=000B  INH=001B  RMW=010B  CNB=011B
29                  RIN=100B  ROT=101B  RRM=110B  RWM=111B);
30
31 /*      NBO      NO BUS OPERATION
32 INH     INHIBIT CPE ARRAY
33 RMW     READ-MODIFY-WRITE
34 CNB     CPU NEEDS BUS
35 RIN     REQUEST INPUT
36 ROT     REQUEST OUTPUT
37 RRM     REQUEST READ MEM.
38 RWM     REQUEST WRITE MEM.
39
40 SET UP FOR SYMBOLIC REPRESENTATION OF REGISTER DESIGNATIONS */
41
42 A      STRING  'R0';
43 X      STRING  'R1';
44 P      STRING  'R3';
45 S      STRING  'R4';
46 B      STRING  'R5';
47 E      STRING  'R6';
48 W      STRING  'R7';
49
50 /* SET UP A SPECIAL NO.OP STRING */
51
52 NO.OP  STRING  'NOP(R2)';
53
54 /* NEXT WE SPECIFY A DEFAULT TO FF1 IN THE FO FIELD FOR THE SDR
55 MICROP IN THE CPE FIELD. SDR IS NORMALLY USED AS A STORE
56 OPERATION. WHEN A DECREMENT OPERATION IS ALSO DESIRED, FFO
57 WILL HAVE TO BE EXPLICITLY SPECIFIED */
58
59 SDR     IMPLY   FO=11B;
60

```

# CPU Design

## RECORD NUMBER

```
61
62
63
64 /* INITIALIZATION SEQUENCE
65     ZERO A, X, AND W */
66
67     000H:    INIT:    CLR(A);
68     090H:                CLR(X);
69     091H:                CLR(W);
70
71 /* ZERO T AS TEMPORARY POINTER, WRITE W TO INTERRUPT STRUCTURE */
72
73     021H:                CLR(T);
74     011H:                LMI(T);
75     041H:                ILR(W) ROT;
76
77 /* SET S = (0), T = 1 FOR NEXT OPERATION */
78
79     044H:                LMI(T) FF1 RRM;
80     0F4H:                ACM(AC) ;
81     0FAH:                SDR(S);
82
83 /* SET B = (1), T = 2 FOR NEXT OPERATION */
84
85     04AH:                LMI(T) FF1 RRM;
86     049H:                ACM(AC);
87     048H:                SDR(B) STC;      /* THIS SETS THE C FLAG TO INSURE
88                                           A CORRECT JUMP TO XRIN */
89
90 /* GET (2), JUMP TO XRIN TO SET E = (2), P = (E) */
91
92     00CH:                LMI(T) RRM;
93     0FCH:                ACM(AC)          JCF (*,XRIN);
94
95 /* FETCH SEQUENCE & START OF MACRO-INSTRUCTION PROCESSING
96     P IS ISSUED TO MAR AND INCREMENTED, MACRO-INSTRUCTION
97     IS FETCHED AND TESTED BY JPX MICRO-OPERATION. NOTE
98     FETCH IS IN LOCATION 15 TO STROBE INTERRUPT ON ENTRY. */
99
100    00FH:    FETCH:    LMI(P) FF1 RRM;
101
102 /* LOAD DISPLACEMENT AND TEST FOR ZERO USING Z FLAG */
103
104    01FH:                LTM(AC) STZ K00FF;
105
106 /* SAVE DISPLACEMENT, TEST 4 BITS OF MACRO-OP. TEST IS
107     DELAYED TO ALLOW PIPELINE PROPAGATION. ALSO C FLAG IS
108     SET FOR LATER USE IN PSEUDO-SUBROUTINES. */
109
110    09FH:                SDR(R9) STC      JPX(NA0,JREL,JIG,IMMD,DMRF,IMRF,IXMA,IXMB,IND,
111                                           INX,OTD,UTX,MVGP,SPFG,IRBM,NA15);
112
113 /* UNASSIGNED OP-CODE GROUPS--NOPS FOR THIS VERSION */
114
115    080H:    NA0:        NO.OP          JZR(FETCH);
116    08FH:    NA15:       NO.OP          JZR(FETCH);
117
118 /* IMMEDIATE GROUP OF MACRO-INSTRUCTIONS--TEST FOR LONG OR SHORT
119     FORM--D IS IN AC AND R9--ADJUST AC BY -128 */
120
121    083H:    IMMD:      LMI(AC) KFF80      JZF(IMML,IMMS);
122
123 /* LONG FORM: FETCH NEXT WORD TO AC */
124
125    0B2H:    IMML:      LMI(P) FF1 RRM;
```

RECORD  
NUMBER

```

126 0B1H:      ACM(AC)              JRL(ILGA,ILPX,NAI1,NAI2);
127
128 /* SHORT FORM: NO PROCESSING NEEDED */
129
130 0B3H:      IMMS:      NO.OP              JRL(ILGA,ILPX,NAI1,NAI2);
131
132 /* PREPROCESSING FOR ARITHMETIC AND LOGIC ROUTINES? NONE NEEDED */
133
134 0ECH:      ILGA:      NO.OP              JLL(NDA,ODA,XDA,ADA);
135 0EDH:      ILPX:      NO.OP              JLL(LDA,LDX,PDS,ADX);
136
137 /* NOTE: NAI1 AND NAI2 ARE NON-VALID INSTRUCTIONS!! THEY ARE
138    MADE INTO NO-UPS IN THIS VERSION OF THE MACRO-MACHINE */
139
140 0EEH:      NAI1:      NO.OP              JZR(FETCH);
141 0EFH:      NAI2:      NO.OP              JZR(FETCH);
142
143 /* BASIC ARITHMETIC AND LOGIC PROCESSING--UPDATE C FF OF MACRO-
144    MACHINE FOR ADA--TOGGLE IT ON CARRY FROM ADA */
145
146 0D7H:      ADA:      ADR(A);
147 0F7H:      ADA1:     NO.OP              JFL(NCY,SCY);
148 0C2H:      NCY:      NO.OP              JZR(FETCH);
149 0C3H:      SCY:      LMI(W) K8000      JZR(FETCH);
150
151 /* LOGICALS */
152
153 0D4H:      NDA:      ANK(A)              JZR(FETCH);
154 0D5H:      ODA:      ORR(A)              JZR(FETCH);
155 0D6H:      XDA:      CMR(AC);
156 0D1H:      XNR(A)              JZR(FETCH);
157
158 /* LDA AND LDX OPERATIONS */
159
160 0E4H:      LDA:      SDR(A)              JZR(FETCH);
161 0E5H:      LDX:      SDR(X)              JZR(FETCH);
162
163 /* STACK PUSH--ADVANCE STACK POINTER TO NEXT LOCATION (FOR THE
164    REVERSE DIRECTION STACK--A DECREMENT OF S), THEN WRITE */
165
166 0E6H:      PDS:      DSM(S);
167 0F6H:      PDS1:     LMI(S) RWM          JZR(FETCH);
168
169 /* ADX - SHARES CODE FOR ADA - ALSO TOGGLES C FF OF MACRO MACHINE */
170
171 0E7H:      ADX:      ADR(X)              JMP(ADA1);
172
173 /* MEMORY REFERENCE INSTRUCTION GROUPS
174    DIRECT--GET B+D INTO AC--ALSO R9 */
175
176 0B4H:      DMRF:     ILR(B);
177 054H:      ALR(R9)              JRL(MRV1,MRV2,MRAD,STPG);
178
179 /* INDIRECT-ABSOLUTE--GET (B+D) INTO AC--C FLAG USED FOR PSEUDO-SUBROUTINE */
180
181 0B5H:      IMRF:     ILR(B);
182 055H:      IMRF1:    ALR(R9);
183 00AH:      LMI(R9) RRM          JCF(MADD,MLOAD);
184 06BH:      MLOAD:    ACM(AC)              JRL(MRV1,MRV2,MRAD,STPG);
185
186 /* NOTE: MADD WILL BE USED FOR OTHER INDIRECT OPERATIONS WHERE
187    B, X, ETC. HAS BEEN LOADED TO R8 */
188
189 06AH:      MADD:     ACM(AC);
190 009H:      ALK(R8)              JRL(MRV1,MRV2,MRAD,STPG);
191
192 /* INDIRECT INDEXED ABSOLUTE - CLEAR C FLAG, MOVE X TO R8 */
193
194 0B6H:      IXMA:     ILR(X) STC;
195 046H:      SDR(R8);
196

```

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197 /* NOTING THAT ASSIGNMENT RULES WOULD NOT ALLOW THE DESIRED
198 JUMP TO IMRF UNLESS IXMA+1 WERE IN ROW ZERO--AN EXTRA STATE
199 IS ADDED HERE */
200
201 056H: IXMA2: ILR(B) JMP(IMRF1);
202
203 /* INDIRECT INDEXED RELATIVE - CLEAR C FLAG, PUT B+X IN R8 */
204
205 087H: IXMB: ILR(X) STC;
206 057H: SDR(R8);
207 047H: ILR(B);
208 045H: ADR(R8) JMP(IMRF);
209
210 /* INDIRECT RELATIVE (TO B) - CLEAR C FLAG, PUT B IN R8 */
211
212 08EH: IRBM: ILR(B);
213
214 /* AGAIN ASSIGNMENT RULES PREVENT JUMPING TO IXMA+1 UNLESS IT IS
215 LOCATED IN ROW ZERO--PLACEMENT THERE COULD FREE TWO WORDS */
216
217 05EH: SDR(R8) JMP(IXMA2);
218
219 /* THE FOLLOWING PROCEDURES IMPLEMENT THE BASIC PREPROCESSING FOR
220 VALUE AND ADDRESS LOADING.
221
222 VALUE-GROUP 1: GET (AC) IN AC */
223
224 07CH: MRV1: LMI(AC) RRM;
225 09CH: ACM(AC) JLL(NDA,ODA,XDA,ADA);
226
227 /* VALUE GROUP 2 */
228
229 07DH: MRV2: LMI(AC) RRM;
230 09DH: ACM(AC) JLL(LDA,LDX,PDS,ADX);
231
232 /* MRAD GROUP INCLUDES ADDRESS LOADS AND SUBTRACT FROM A */
233
234 07EH: MRAD: NO.OP JLL(LAA,LAX,PAS,ISDA);
235
236 064H: LAA: SDK(A) JZR(FEICH);
237 065H: LAX: SDK(X) JZR(FETCH);
238 066H: PAS: DSM(S) JMP(PDS1);
239
240 /* FOR SUBTRACT, ADD 1'S COMPLEMENT PLUS 1 */
241
242 067H: ISDA: LMI(AC) RRM;
243 068H: LCM(AC);
244 0F8H: ADR(A) FF1 JMP(ADA1);
245
246 /* STPG GROUP INCLUDES STORES AND SUBTRACT FROM X */
247
248 07FH: STPG: LMI(AC) JLL(SAM,SXM,PSM,SDX);
249
250 074H: SAM: ILR(A) RWM JZR(FEICH);
251 075H: SXM: ILR(X) RWM JZR(FETCH);
252
253 /* POP STACK TO MEMORY - SAVE ADDRESS, POP STACK */
254
255 076H: PSM: SUR(T);
256 078H: LMI(S) FF1 RRM;
257 0A8H: ACM(AC);
258 0B8H: LMI(T) RWM JZR(FETCH);
259
260 /* SUBTRACT FROM X */
261
262 077H: SDX: LMI(AC) RRM;
263 079H: LCM(AC);
264 0F9H: ADR(X) FF1 JMP(ADA1);
265
266 /* JUMP GROUPS--USE JPR MICRO-OPERATION TO RESOLVE CONDITION SELECTION
267 DESTINATION ADDRESS IS COMPUTED FIRST--PLACED IN AC AND R9
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268     JUMP RELATIVE TO P--ADDRESS=P+D-128 */
269
270 081H:  JREL:  ILR(P);
271 071H:  JRDR:  LMI(AC) KFF80;
272 061H:           ALR(R9)           JPR(JUNC, JAGE, JALT, JXGA, JAEQ, JANE, JCEZ, JXLA,
273                                     JALE, JAGT, JCNZ, JXEA, CPSS, PXA, CLOP, JXNA);
274
275 /* JUMP INDIRECT - GET E+(E+D) IN AC AND R9 */
276
277 082H:  JIG:   ILR(E);
278 0E2H:           ADR(R9);
279 0E0H:           LMI(R9) RRM;
280 050H:           AMA(AC);
281 060H:           SDR(R9)           JPR(JUNC, JAGE, JALT, JXGA, JAEQ, JANE, JCEZ, JXLA,
282                                     JALE, JAGT, JCNZ, JXEA, CPSS, PXA, CLOP, JXNA);
283
284 /* UNCONDITIONAL JUMP */
285
286 030H:  JUNC:  SDR(P)           JZR(FETCH);
287
288 /* TESTS FOR A.GE.0, ETC. */
289
290 031H:  JAGE:  TZR(A) K8000 INH  JMP(TTRU);
291 032H:  JALT:  TZR(A) K8000 INH  JMP(TFAL);
292 034H:  JAEQ:  IZR(A)           JMP(TTRU);
293 035H:  JANE:  TZR(A)           JMP(TFAL);
294
295 039H:  JAGT:  TZR(A) K8000 INH;
296 001H:           TZR(A)           JFL(APRE, ANPE);
297
298 072H:  APKE:  NO.OP           JFL(JNT2, JTR2);
299 073H:  ANPE:  NO.OP           JZR(FETCH);
300
301 038H:  JALE:  TZR(A) K8000 INH;
302 007H:           IZR(A)           JFL(APE2, AN2);
303
304 042H:  APE2:  NO.OP           JFL(JTR1, JNT1);
305 043H:  AN2:   SDR(P)           JZR(FETCH);
306
307 /* TESTS OF C FLIP-FLOP (HIGH ORDER BIT OF W) */
308
309 036H:  JCEZ:  TZR(W) K8000 INH  JMP(TTRU);
310 03AH:  JCNZ:  TZR(W) K8000 INH  JMP(TFAL);
311
312 /* TEST EXECUTION FOR ABOVE TESTS - ROW ZERO USED */
313
314 005H:  TTRU:  NO.OP           JFL(JTR1, JNT1);
315
316 002H:  JTR1:  SDR(P)           JZR(FETCH);
317 003H:  JNT1:  NO.OP           JZR(FETCH);
318
319 004H:  TFAL:  NO.OP           JFL(JNT2, JTR2);
320
321 062H:  JNT2:  NO.OP           JZR(FETCH);
322 063H:  JTR2:  SDR(P)           JZR(FETCH);
323
324 /* TESTS FOR X.GT.A, X.LE.A, X.EQ.A, X.NE.A--SHARED PSEUDO-
325     SUBROUTINE USES JLL FOR AN EXIT TEST--ROUTINE ENTRY IN ROW 0
326     C FLAG IS SET FOR X.GT.A, FL TEST FOR X.EQ.A */
327
328 033H:  JXGA:  ILR(X)           JMP(XATS);
329 037H:  JXLA:  ILR(X)           JMP(XATS);
330 03BH:  JXEA:  ILR(X)           JMP(XATS);
331 03FH:  JXNA:  ILR(X)           JMP(XATS);
332
333 /* SAVE X AT I, FETCH AND COMPLEMENT A */
334
335 00BH:  XATS:  SDR(T);
336 04BH:           ILR(A) STC;     /* CLEAR C FLAG */
337 05BH:           CMA(AC);
338

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339 /* ADD HOB'S OF A' AND X - CARRY MEANS X NEG., A.GE.0 */
340
341 05AH:          ADR(T) K8000;
342
343 /* EXECUTE PREVIOUS TEST, SET UP TO TEST HOB OF RESULT--IF 1,
344    THE SIGNS OF A AND X WERE THE SAME */
345
346 051H:          TZR(T) K8000 INH          JFL(TFEQ, TXNG);
347
348 /* TXNG IMPLIES X NEG AND A.GE.0--I.E. X.NE.A AND X.LT.A--DO A
349    DUMMY OPERATION TO FORCE THE PROPER F FLAG */
350
351 053H:  TXNG:   1LR(A)                   JLL(JXGX, JXLX, JXEX, JXNX);
352
353 /* PERFORM A TEST ADDITION AND EXECUTE SIGN-EQUAL TEST
354    C WILL BE SET IF SIGNS WERE THE SAME AND X.GT.A */
355
356 052H:  IFEQ:   ADR(T) STC K7FFF          JFL(SNEQ, SWEQ);
357
358 /* SNEQ IMPLIES SIGNS NOT EQUAL--I.E. X.GE.0, A NEG--X.GT.A */
359
360 012H:  SNEQ:   SDR(AC) STC;             /* DUMMY OP TO SET C FLAG */
361 010H:          NO.OP                    JLL(JXGX, JXLX, JXEX, JXNX);
362
363 /* FOR SIGNS EQUAL, IF X=A RESULT WOULD BE 1111...1. INCREMENT
364    WILL GENERATE A CARRY IF SO */
365
366 013H:  SWEQ:   1LR(AC) FF1              JLL(JXGX, JXLX, JXEX, JXNX);
367
368 /* EXECUTION OF JUMP TESTS */
369
370 024H:  JXGX:   1LR(R9)                   JCF(JNT2, JTR2);
371 025H:  JXLX:   1LR(R9)                   JCF(JTR1, JNT1);
372 026H:  JXEX:   1LR(R9)                   JFL(JNT2, JTR2);
373 027H:  JXNX:   1LR(R9)                   JFL(JTR1, JNT1);
374
375 /* SUBROUTINE CALLS
376    CALL LOCAL AND PUSH W, B, E, P =CPSS
377    CALL LOCAL AND PUSH P ONLY=CLOP
378    C FLAG IS USED FOR EXIT TEST AFTER PUSHING P */
379
380 03CH:  CPSS:   DSM(S);
381 05CH:          1LR(W);
382 05DH:          LMI(S) RWM;
383
384 0ADH:  CPG2:   DSM(S);
385 0AAH:          1LR(B);
386 07AH:          LMI(S) RWM;
387
388 07BH:          DSM(S);
389 0EBH:          1LR(E);
390 0FBH:          LMI(S) RWM;
391
392 0F2H:          DSM(S);
393 0D2H:          1LR(P);
394 00DH:  CLOP2:  LMI(S) RWM;
395
396 /* E+(E+D) INTO AC */
397
398 0BDH:          1LR(R9)                   JCF(LRTN, XRTN);
399
400 0BBH:  XRIN:   SDR(E);
401 0BEH:          LMI(E) RRM;
402 0B9H:          AMA(AC);
403
404 0BAH:  LRTN:   SDR(P)                   JZR(FETCH);
405
406 03EH:  CLOP:   DSM(S);
407 06EH:          1LR(P) STC               JMP(CLOP2);
408
409 /* PUSH INSTRUCTION */
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410
411 03DH:  PXA:  DSM(S);
412 04DH:      ILR(X);
413 040H:      LMI(S) RWM;
414
415 070H:      DSM(S);
416 0F0H:      ILR(A);
417 0F1H:      LMI(S) RWM          JZR(FETCH);
418
419 /* MOVE GROUP OF INSTRUCTIONS--USES JCE TO SELECT REGISTER--NOTE
420    THAT REGISTER ASSIGNMENT BECOMES IMPORTANT
421    FIRST MODIFY D TO GET D-128 */
422
423 08CH:  MVGP:  LMI(R9) KFF80          JLL(MVXR,MVRX,MOD,PGRP);
424
425 /* MOVE X TO REG. - GET X, MODIFY BY D'=D-128 */
426
427 0C4H:  MVXR:  ILR(X);
428 0C0H:      ALR(R9);
429 0C1H:      SDR(R7)          JCE(MRXX);      /* REGISTER OVERRIDE */
430 0E1H:  MXRX:  NO.OP          JZR(FETCH);
431
432 /* MOVE REG TO X - FETCH REG USING JCE OVERRIDE */
433
434 0C5H:  MVRX:  ILR(R7)          JCE(MRXX);
435 0F5H:  MRXX:  ALR(R9)          JMP(LDX);
436
437 /* MOD NOT IMPLEMENTED IN THIS VERSION */
438
439 0C6H:  MUD:   NO.OP          JZR(FETCH);
440
441 /* ADJUST STACK AND RETURN GROUP
442    PPAL--POPS A, X, P, E, B, AND W
443    PPRA--POPS P, E, B, AND W
444    PPAX--POPS ONLY A AND X
445    POPP--POPS ONLY P */
446
447 0C7H:  PGRP:  ILR(R9);
448 0C8H:      ADR(S)          JRL(PPAL,PPRA,PPAX,POPP);
449
450 0DCH:  PPAL:  LMI(S) FF1 RRM;
451 0D3H:      ACM(AC);
452 0D8H:      SDR(A);
453
454 0E8H:  LMI(S) FF1 RRM;
455 0E9H:  ACM(AC)          JCF(PAXE,PAXC);
456 0DBH:  PAXC:  SDR(X);
457
458 0DDH:  PPRA:  LMI(S) FF1 RRM;
459 0D0H:      ACM(AC);
460 02FH:  SDR(P);
461
462 04FH:  LMI(S) FF1 RRM;
463 00EH:  ACM(AC);
464 01EH:  SDR(E);
465
466 09EH:  LMI(S) FF1 RRM;
467 0FEH:  ACM(AC);
468 0F3H:  SDR(B);
469
470 0E3H:  LMI(S) FF1 RRM;
471 0EAH:  ACM(AC);
472 02AH:  SDR(W);
473
474 /* RESTORE INTERRUPT STRUCTURE */
475
476 02BH:      CLR(T);
477 029H:      LMI(T) NOT          JZR(FETCH);
478
479 0DAH:  PAXE:  SDR(X)          JZR(FETCH);
480

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481 0DEH:  PPAX:  ILR(AC) STC          JMP(PPAL);
482
483 0DFH:  POPP:  LMI(S) FF1 RRM;
484 0DOH:          ACM(AC)          JMP(JUNC);
485
486 /* SPECIAL FUNCTION GROUP
487   BYTE OPERATORS--ADDR=(B+D)+B+X/2 OR (B+D)+X/2
488   CALL TO (D) AND PUSH ALL
489   SHIFT AND ROTATE GROUP
490   INCREMENT AND SKIP
491   FETCH B JUST IN CASE */
492
493 08DH:  SPFG:  ILR(B)          JRL(BYTE,RSGP,SCJG,ISJG);
494
495 /* BYTE GROUP--COMPUTE ADDR, STORE B IN CASE NEEDED */
496
497 0CCH:  BYTE:  SDR(R8);
498 0BCH:          ADR(R9);
499 0ACH:          ILR(X);
500 0ABH:          SRA(AC) STC;
501 0AEH:          LMI(R9) RRM;
502 02EH:          AMA(AC)          JLL(LBYA,LBYR,SBYA,SBYR);
503
504 015H:  LBYR:  ALR(R8);
505 014H:  LBYA:  LMI(AC) RRM          JCF(LBYT,RBYT);
506 022H:  LBYT:  LDI(AC) FF1 KO0FF    JMP(DBIA);
507 023H:  RBYT:  LTM(AC) KO0FF;
508 020H:  DBIA:  SDR(A)          JZR(FETCH);
509
510 017H:  SBYR:  ALR(R8);
511 016H:  SBYA:  LMI(AC);          /* LOAD MAR FOR LATER USE */
512 018H:          ILR(A);
513 019H:          TZR(AC) KO0FF RRM    JCF(STLB,STRB);
514 01BH:  STMB:  LTM(T) KFF00;
515 01DH:  SRB1:  ALR(T) RWM          JZR(FETCH);
516
517 01AH:  STLB:  LTM(T) KO0FF;
518 01CH:  LDI(AC) FF1 CNB          JMP(SRB1);
519
520 /* ROTATE GROUP
521   ROTATE A WITH C--ROTATE A AND X WITH C--SHIFT A, X RIGHT, FILL
522   WITH SIGN--SHIFT A LEFT, FILL WITH ZEROES
523
524   AT ENTRY, Z FLAG IS ZERO IF D=0. DUE TO PIPELINED OPERATION, IT IS
525   THIS CONDITION THAT IS TESTED BY THE FIRST JZF */
526
527 0CDH:  RSGP:  TZR(W) STZ K8000 INH  JZF(SZDS,SNZD);
528 09AH:  SZDS:  ILR(X);
529 099H:          SDR(R9) FF0 KO07F    JLL(RACI,RAXI,SAXI,SLZI);
530 09BH:  SNZD:  DSM(R9)          JLL(RACI,RAXI,SAXI,SLZI);
531
532 094H:  RACI:  ILR(A)          JMP(RUNR);
533 095H:  RAXI:  ILR(X);
534 098H:          SDR(T)          JMP(RACI);
535 096H:  SAXI:  TZR(A) STZ K8000 INH  JMP(RAXI);
536 097H:  SLZI:  ILR(A)          JMP(RUNR);
537
538 /* MAIN ROTATION LOOP */
539
540 093H:  RUNR:  DSM(R9) STC          JLL(RACR,RAXR,SAXR,SLZR);
541
542 0A4H:  RACR:  SRA(AC) FFZ STZ          JFL(RSEX,RUNR);
543 0A5H:  RAXR:  SRA(AC) FFZ SIZ;
544 0A0H:          SRA(T) FFZ STZ          JCF(RSEX,RUNR);
545 0A6H:  SAXR:  SRA(AC) FFZ STC;
546 0A1H:          SRA(T) FFC          JCF(RSEX,RUNR);
547 0A7H:  SLZR:  ADR(AC) STZ          JFL(RSEX,RUNR);
548
549 092H:  RSEX:  SDR(A)          JLL(RACF,RAXF,SAXF,SLZF);
550
551 0B4H:  RACF:  TZR(W) K7FFF          JZF(SNCF,SSCF);
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552 0A2H: SNCF: NO.OP                JZR(FETCH);
553 0A3H: SSCF: LMI(W) K8000         JZR(FETCH);
554 0B5H: RAXF: ILR(T);
555 0B0H: RXF1: SDR(X)                JMP(RACF);
556 0B6H: SAXF: ILR(T)                JMP(RXF1);
557 0B7H: SLZF: TZR(W) K7FFF         JZF(SNCF,SSCF);
558
559 /* SPECIAL CALL AND JUMP GROUP--CURRENTLY CONTAINS ONLY THE
560 CALL TO (D) AND PUSH W,B,E,P--ALL 4 OPCODES DO THE SAME THING */
561
562 0CEH: SCJG: LMI(R9) RRM;
563 04EH:      ACM(AC);
564 04CH:      SDR(R9)                JMP(CPSS);
565
566 /* INCREMENT AND SKIP GROUP--AGAIN 4 OPCODES ARE USED FOR ONE
567 INSTRUCTION--LOCATION AT B+D IS INCREMENTED */
568
569 0CFH: ISJG: ALR(R9);
570 0C9H:      LMI(R9) RMW;
571 0D9H:      ACM(AC) FF1;
572 0A9H:      NO.OP RWM                JFL(NOSK,SKIP);
573 0CAH: NQSK: NO.OP                JZR(FETCH);
574 0CBH: SKIP: LMI(P) FF1           JZR(FETCH);
575
576 /* INPUT AND OUTPUT--CURRENT VERSION DOES NOT DECODE INTO
577 SUBGROUPS--ALSO ROW ZERO IS USED TO SAVE CODE */
578
579 088H: IND: LMI(R9) RIN;
580 008H: IND1: ACM(AC);
581 028H:      SDR(A)                JZR(FETCH);
582 089H: INX: LMI(X) RIN            JMP(IND1);
583 08AH: OTD: LMI(R9);
584 006H: OTD1: ILR(A) ROT           JZR(FETCH);
585 08BH: OTX: LMI(X)                JMP(OTD1);
586
587 /* INTERRUPT--UTILIZES CALL ROUTINES FOR REGISTER SAVING
588 I/O DEVICE #0 REPRESENTS EXTERNAL INTERRUPT STRUCTURE
589 START BY PUSHING OLD VALUE OF STATUS */
590
591 0FFH: INTER: DSM(S);
592 0BFH:      ILR(W);
593 05FH:      LMI(S) RWM;
594
595 /* READ INTERRUPTING LEVEL FROM EXTERNAL STRUCTURE */
596
597 058H:      CLR(T);
598 059H:      LMI(T) RIN;
599 069H:      LTM(AC) KOOFF ROT; /* NOTE LEVEL REWRITTEN */
600
601 /* STORE PRIORITY IN W - SET C FLAG FOR PROPER LOADING OF REGISTERS */
602
603 06CH:      SDR(W) STC;
604
605 /* INTERRUPT ROUTINE STARTING ADDRESS IS COMPUTED IN R9 */
606
607 06DH:      LMI(W) RRM;
608 06FH:      ACM(AC);
609 0AFH:      SDR(R9)                JMP(CPG2);
610
611
612 EOF

```

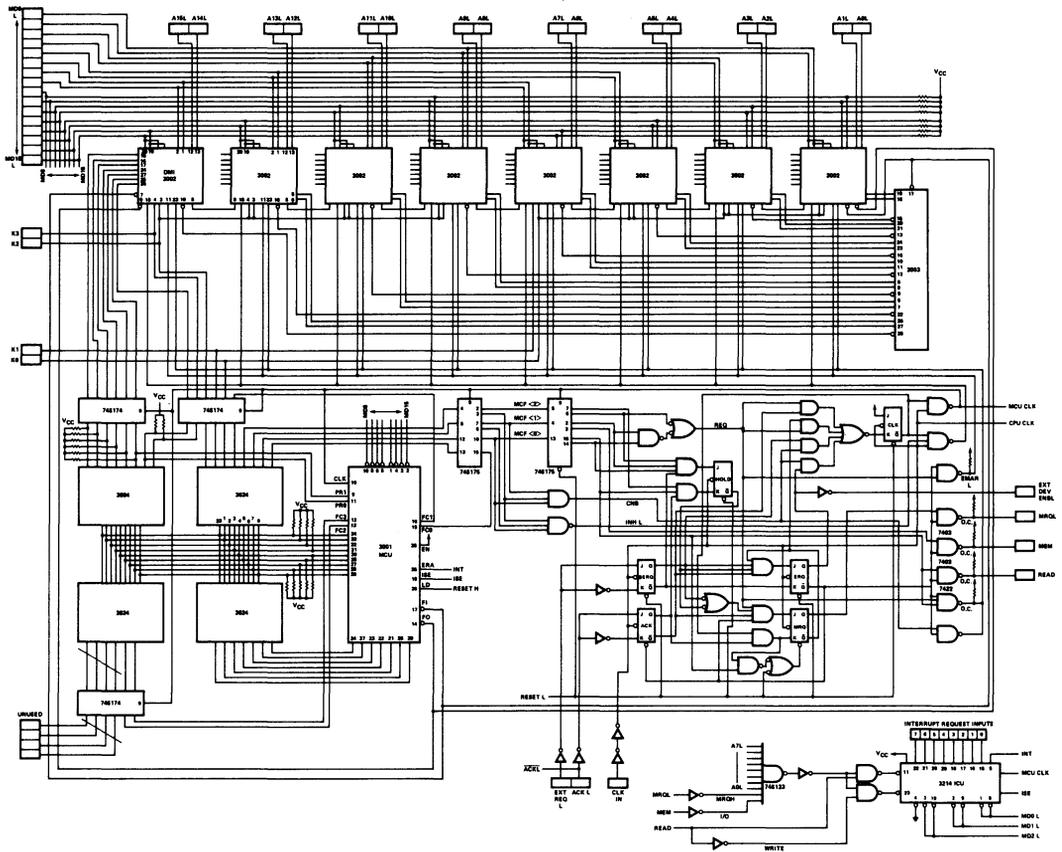
NO PROGRAM ERRORS  
END OF PROGRAM

MICROPROGRAM MEMORY IMAGE

	0H	1H	2H	3H	4H	5H	6H	7H	8H	9H	AH	BH	CH	DH	EH	FH
000H	JCC . 0090H	JFL * 0072H	JZR * 000FH	JZR * 000FH	JFL . 0062H	JFL . 0002H	JZR . 000FH	JFL = 0042H	JCC . 0028H	JRL * 007CH	JCF * 006AH	JCC * 004BH	JCC . 00FCH	JCC . 00BDH	JCC . 001EH	JCC . 001FH
	67 . 0	296 * 1	316 * 4	317 * 4	319 . 3	314 . 3	584 . 2	302 = 1	580 . 2	190 * 1	183 * 1	335 * 4	92 . 1	394 . 2	463 . 1	100 . 38
001H	JLL . 0024H	JCC * 0041H	JCP * 0010H	JLL * 0024H	JCF . 0022H	JCR . 0014H	JCR . 0018H	JCR = 0016H	JCR . 0019H	JCF * 001AH	JCR * 001CH	JCR * 001DH	JCR . 001DH	JZR . 000FH	JCEH . 009EH	JCC . 009FH
	361 . 1	74 * 1	360 * 1	366 * 1	505 . 2	504 . 1	511 . 2	510 = 1	512 . 1	513 * 1	517 * 1	514 * 1	518 . 1	515 . 2	464 . 1	104 . 1
002H	JZR . 000FH	JCC * 0011H	JCR * 0020H	JCR * 0020H	JCF . 0062H	JCF . 0002H	JFL . 0062H	JFL = 0002H	JZR . 000FH	JZK * 000FH	JCR * 002BH	JCR * 0029H		JCR . 002FH	JLL . 0014H	JCC . 004FH
	508 . 2	73 * 1	506 * 1	507 * 1	370 . 3	371 . 3	372 . 3	373 = 3	581 . 1	477 * 1	472 * 1	476 * 1		459 . 1	502 . 1	460 . 1
003H	JZK . 000FH	JZR * 0005H	JZR * 0004H	JZR * 0008H	JZK . 0005H	JZR . 0004H	JZR . 0005H	JZR = 0008H	JZR . 0007H	JZR * 0001H	JZR * 0004H	JCC * 000BH	JCC . 005CH	JCC . 004DH	JCC . 006EH	JZR . 000BH
	286 . 3	290 * 2	291 * 2	328 * 2	292 . 2	293 . 2	309 . 2	329 = 2	301 . 2	295 * 2	310 * 2	330 * 2	380 . 3	411 . 2	406 . 2	331 . 2
004H	JCC . 0070H	JCK * 0044H	JFL * 0002H	JZR * 000FH	JCC . 00F4H	JCC . 0085H	JCC . 0056H	JCR = 0045H	JZR . 000CH	JCR * 0048H	JCR * 0049H	JCC * 005BH	JCC . 003CH	JCR . 0040H	JCR . 004CH	JZK . 000EH
	413 . 1	75 * 1	304 * 1	305 * 1	79 . 1	208 . 1	195 . 1	207 = 1	87 . 1	86 * 1	85 * 1	336 * 1	564 . 1	412 . 1	563 . 1	462 . 1
005H	JCC . 0060H	JFL * 0052H	JFL * 0012H	JLL * 0024H	JRL . 007CH	JZR . 000AH	JCR . 0055H	JCC = 0047H	JCR . 0059H	JCC * 0069H	JCR * 0051H	JCR * 005AH	JCR . 005DH	JCC . 00ADH	JCR . 0056H	JCR . 0058H
	280 . 1	346 * 1	356 * 1	351 * 1	177 . 1	182 . 2	201 . 2	206 = 1	597 . 1	598 * 1	341 * 1	337 * 1	381 . 1	382 . 1	217 . 1	593 . 1
006H	JPR . 0030H	JPR * 0030H	JZK * 000FH	JZR * 000FH	JZR . 000FH	JZR . 000FH	JCC . 00F6H	JCR = 0068H	JCC . 00F8H	JCR * 006CH	JZR * 0009H	JRL * 007CH	JCR . 006DH	JCR . 006FH	JZR . 000DH	JCC . 00AFH
	281 . 1	272 * 1	321 * 4	322 * 4	236 . 1	237 . 1	238 . 1	242 = 1	243 . 1	599 * 1	189 * 1	184 * 1	603 . 1	607 . 1	407 . 1	608 . 1
007H	JCC . 00F0H	JCC * 0061H	JFL * 0062H	JZK * 000FH	JZR . 000FH	JZR . 000FH	JCR . 0078H	JCR = 0079H	JCC . 00A8H	JCC * 00F9H	JCR * 007BH	JCC * 00EBH	JCC . 009CH	JCC . 009DH	JLL . 0064H	JLL . 0074H
	415 . 1	271 * 1	298 * 1	299 * 1	250 . 1	251 . 1	255 . 1	262 = 1	256 . 1	263 * 1	386 * 1	388 * 1	224 . 3	229 . 3	234 . 3	248 . 3

MICROPROGRAM MEMORY IMAGE

	0H	1H	2H	3H	4H	5H	6H	7H	8H	9H	AH	BH	CH	DH	EH	FH
008H	JZR 000FH 115 1	JCC 0071H 270 1	JCC 00E2H 277 1	JZF 00B2H 121 1	JCC 0054H 176 1	JCC 0055H 181 2	JCC 0046H 194 1	JCC 0057H 205 1	JCC 0008H 579 1	JZR 0008H 582 1	JZR 0006H 583 1	JZR 0006H 585 1	JLL 00C4H 423 1	JRL 00CCH 493 1	JCC 005EH 212 1	JZR 000FH 116 1
009H	JCR 0091H 68 1	JCC 0021H 69 1	JLL 00B4H 549 4	JLL 00A4H 540 6	JCR 0093H 532 3	JCR 0098H 533 3	JCR 0095H 535 2	JCR 0093H 536 2	JCR 0094H 534 1	JLL 0094H 529 1	JCR 0099H 528 1	JLL 0094H 530 1	JLL 00D4H 225 1	JLL 00E4H 230 1	JCC 00FEH 466 1	JPX 0080H 110 1
00AH	JCF 0092H 544 1	JCF 0092H 546 1	JZR 000FH 552 2	JZR 000FH 553 2	JFL 0092H 542 1	JCR 00A0H 543 1	JCR 00A1H 545 1	JFL 0092H 547 1	JCC 00B8H 257 1	JFL 00CAH 572 1	JCC 007AH 385 1	JCR 00AEH 500 1	JCR 00ABH 499 1	JCR 00AAH 384 2	JCC 002EH 501 1	JCR 00ADH 609 1
00BH	JCP 00B4H 555 2	JRL 00ECH 126 1	JCR 00B1H 125 1	JRL 00ECH 130 1	JZF 00A2H 551 2	JCR 00B0H 554 1	JCR 00B0H 556 1	JZF 00A2H 557 1	JZR 000FH 258 1	JCR 00BAH 402 1	JZR 000FH 404 3	JCR 00BEH 400 2	JCC 00ACH 498 1	JCF 00BAH 398 1	JCP 00B9H 401 1	JCC 005FH 592 1
00CH	JCR 00C1H 428 1	JCE 00E1H 429 1	JZR 000FH 148 1	JZR 000FH 149 1	JCR 00C0H 427 1	JCE 00F5H 434 1	JZR 000FH 439 1	JCR 00C8H 447 1	JRL 00DCH 448 1	JCC 00D9H 570 1	JZR 000FH 573 1	JZR 000FH 574 1	JCC 00BCH 497 1	JZF 009AH 527 1	JCC 004EH 562 1	JCR 00C9H 569 1
00DH	JCC 0030H 484 1	JZR 000FH 156 1	JZR 000DH 393 1	JCR 00D8H 451 1	JZR 000FH 153 2	JZR 000FH 154 2	JCR 00D1H 155 2	JCC 00F7H 146 2	JCC 00E8H 452 1	JCC 00A9H 571 1	JZR 000FH 479 1	JCR 00DDH 456 1	JCR 00D3H 450 2	JCC 002DH 458 2	JCR 00DCH 481 1	JCR 00DDH 483 1
00EH	JCC 0050H 279 1	JZR 000FH 430 1	JCR 00E0H 278 1	JCR 00EAH 470 1	JZR 000FH 160 2	JZR 000FH 161 3	JCC 00F6H 166 2	JCC 00F7H 171 2	JCR 00E9H 454 1	JCF 00DAH 455 1	JCC 002AH 471 1	JCC 00FBH 389 1	JLL 00D4H 134 2	JLL 00E4H 135 2	JZR 000FH 140 2	JZR 000FH 141 2
00FH	JCR 00F1H 416 1	JZR 000FH 417 1	JCC 00D2H 392 1	JCC 00E3H 468 1	JCR 00FAH 80 1	JCC 00E5H 435 1	JZR 000FH 167 2	JFL 00C2H 147 4	JCR 00F7H 244 1	JCR 00F7H 264 1	JCC 004AH 81 1	JCR 00F2H 390 1	JCF 00BAH 93 1		JCR 00F3H 467 1	JCC 00BFH 591 0



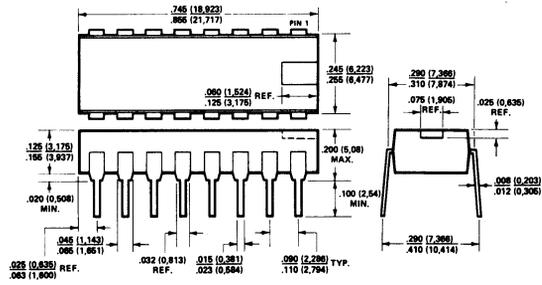
# ORDERING AND PACKAGING INFORMATION

## ORDERING INFORMATION

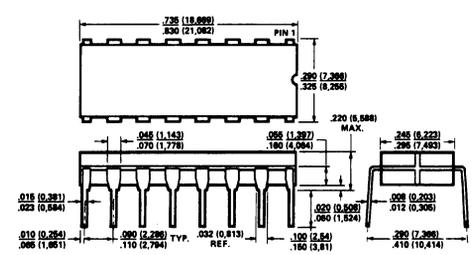
Component	No. Of Pins	Standard Package Type		
		Ceramic (C)	CerDIP (D)	Plastic (P)
3001 MC3001	40	Yes	Yes Yes	
3002 MC3002	28	Yes	Yes Yes	
3003 MC3003	28	Yes	Yes Yes	
3212 MD3212	24		Yes Yes	Yes
3214 MD3214	24	Yes	Yes Yes	Yes
3216/26 MD3216/26	16		Yes Yes	Yes

# PACKAGE OUTLINES

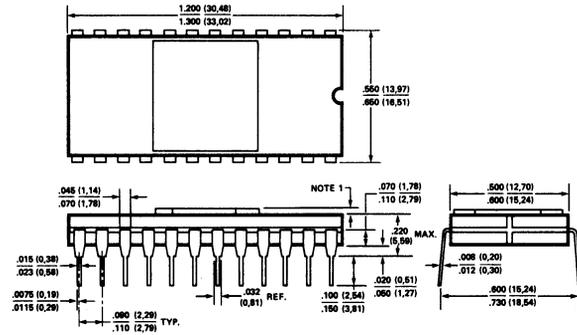
## 16-LEAD PLASTIC DUAL IN-LINE PACKAGE (P)



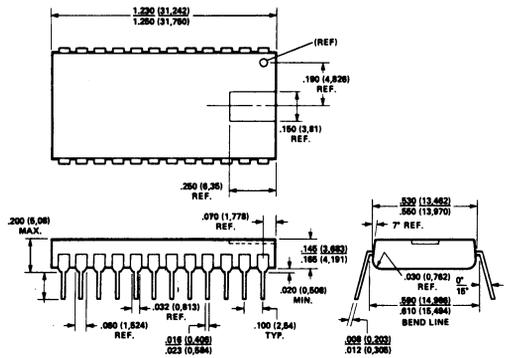
## 16-LEAD CerDIP DUAL IN-LINE PACKAGE (D)



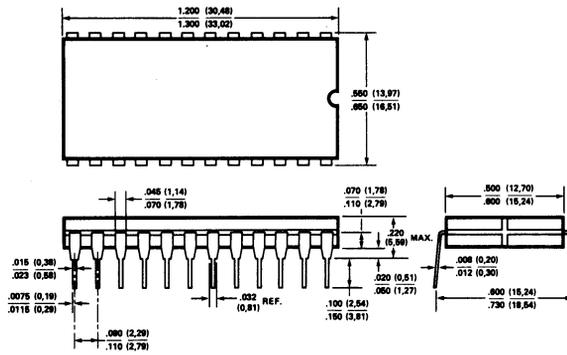
## 24-LEAD CERAMIC DUAL IN-LINE PACKAGE (C)



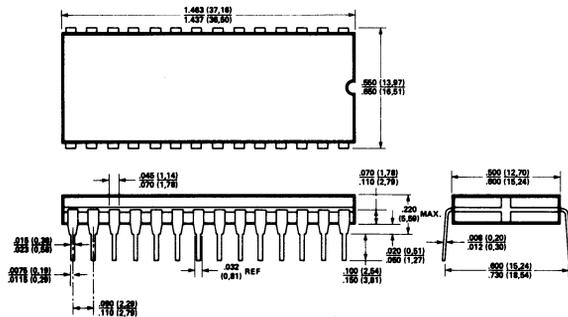
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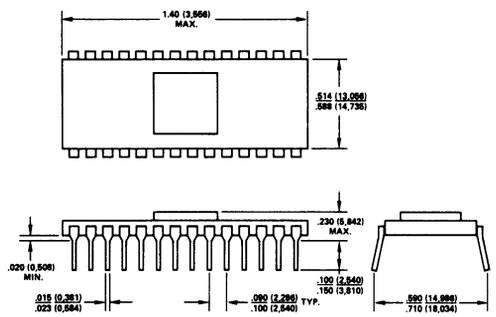
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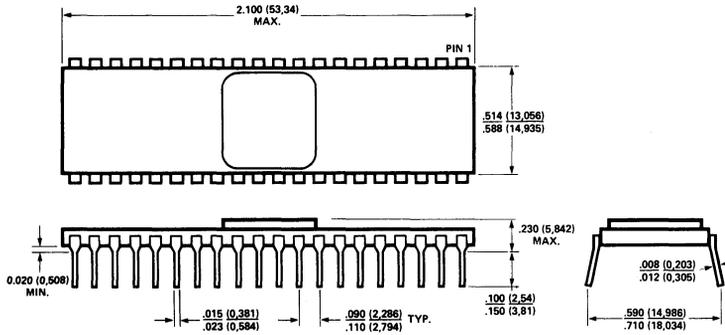
## 28-LEAD CerDIP DUAL IN-LINE PACKAGE (D)



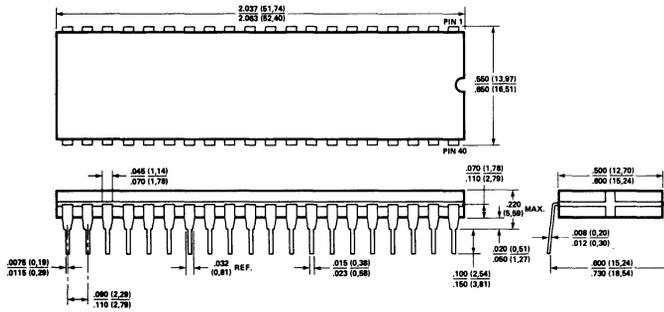
## 28-LEAD CERAMIC DUAL IN-LINE PACKAGE (C)



40-LEAD CERAMIC DUAL IN-LINE PACKAGE (C)



40-LEAD CerDIP DUAL IN-LINE PACKAGE (D)





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